# SPICE:

## User's Guide and Reference

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 $Edition \ 1.3$ 

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A manual created to support the development of  $fREEDA^{TMa}$  (http://www.freeda.org).

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## Preface

This book was begun to develop a multi-version of a SPICE manual to guide the development of the multiphysics simulator fREEDA<sup>T</sup>M, see http://www.freeda.org. The various version os Spice are not fully compatible which presents challenges in trying to make a new simulator compatible with Spice.

The contributions of Paul Franzon to Chapters 2 and 3 are gratefully acknowledged.

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## Chapter 1

## Introduction

#### 1.1 Introduction

SPICE is a general-purpose circuit simulation program for nonlinear DC, nonlinear transient, and small-signal AC analyses. Circuits may contain resistors, capacitors, inductors, mutual inductors, independent voltage and current sources, dependent sources, transmission lines, switches, and the five most common semiconductor devices: diodes, BJTs, JFETs, MESFETs, and MOSFETs. SPICE was developed at the University of California at Berkeley and after many years of effort culminated in the landmark SPICE2G6 version. This was the last FORTRAN language version of SPICE distributed by UC Berkeley and its syntax and analysis options have become a standard for SPICE-like simulators. With few exceptions, all commercial versions and University versions of SPICE are upwards compatible with SPICE2G6 in that they support the complete syntax and analyses of SPICE2G6. Since SPICE2G6 was released SPICE3 was developed at UC Berkeley initially as a C language equivalent of SPICE2G6. The new capabilities of SPICE3 include pole-zero analysis, and new transistor models for MESFETs and for short and narrow channel MOSFETs as well improved numerical methods. Many commercial versions of SPICE are based directly on SPICE3. However there is a group of commercial SPICE-like simulators that have significant advances over SPICE2G6 and SPICE3 in the areas of enhanced input syntax, improved convergence, better device models and more analysis types. Many of these enhanced SPICE programs were completely rewritten and not ports of the Berkeley software. As can be expected, the effort put into these commercial programs is reflected in their price. The first SPICE version for personal computers was the commercial program PSPICE by MicroSim corporation. PSPICEnow has the largest customer base of all commercial SPICE programs. Consequently the syntax of PSPICE has become a second "standard". The PSPICE syntax is upwards compatible to the SPICE2G6 syntax. However, there are some incompatibilities between the SPICE3 and PSPICE syntaxes as PSPICE was released before SPICE3 became available. The effect of this development is that all SPICE simulators (including commercial programs) accept a SPICE2G6 netlist but perhaps not a SPICE3 netlist. Conflicts with SPICE3 generally exist in the naming of additional elements and in the use of new models.

#### 1.2 How to use this book

This manual was used as a guide in developing the fREEDA simulator (see http://www.freeda.org). If you are generally unfamiliar with how to use SPICE, or are not familiar with all of its features then Chapter 2 and Chapter 3 are provided to get you started. The aim in Chapter 2 is just to help you write, run, and understand your first SPICE file. In Chapter 3, each of the major types of analyses SPICE can do for you are introduced, by example. In contrast, Chapter ?? is intended for those wishing to understand how SPICE works internally. Chapter 5 describes in the format of the SPICE input file or netlist. Part II (Chapters 6 and 7) describe the syntax of the SPICE language and the predefined expressions provided within it. Part III

summarizes the SPICE syntax, statements and elements in a quick look-up form suitable for the experienced user. Chapter 9 presents more elaborate SPICE examples. Also provided is a quick reference guide to SPICE's error messages and their meaning (Appendix E).

#### **1.3 What Spice Does**

Many different types of analyses are supported by different versionss of SPICE. Most versions allow all of the analysis types of SPICE2G6 plus a few additional analyses. One of the exceptions is the distortion analysis which proved to be unreliable in SPICE2G6. The table below identifies the analyses that are common to virtually all SPICE programs and the extended analyses by the SPICE3 and PSPICE versions included in this book.

COMMON SPICE ANALYSES			
.AC	AC Analysis		
.DC	DC Analysis		
.FOUR	Fourier Analysis		
.NOISE	Small-Signal Noise Analysis		
.OP	Operating Point Analysis		
.SENS	Sensitivity Analysis		
.TRAN	Transient Analysis		
AN	NALYSES SPECIFIC TO SPICE2G6		
.DISTO	Small-Signal Distortion Analysis		
A	NALYSES SPECIFIC TO SPICE3		
.DISTO	Small-Signal Distortion Analysis		
.PZ	Pole-Zero Analysis		
А	NALYSES SPECIFIC TO PSPICE		
.TF	Transfer Function Specification PSPICE Only		
.MC	Monte Carlo Analysis (PSPICE only)		
.SAVEBIAS	Save Bias Conditions		
.STEP	Parameteric Analysis		
.WCASE	Sensistivity and Worst Case Analysis		

#### 1.4 justspice versions

This book is a manual for five versions of SPICE: SPICE2G6, SPICE3, PSPICEand HSPICE. For these the input syntax, and models are described. Particularly emphasis is given to SPICE3 and PSPICE as these are the most widley used SPICE versions. For these the graphical user interface is also described.

The syntax, analysis types, and elements of SPICE2G6form a common denominator with the capabilities of SPICE3 and PSPICEbeing extensions. Adhering to the SPICE2G6 syntax ensures maximum portability of SPICE netlists. Major restrictions of this syntax compared to commercial versions include using integers to designate nodes. The SPICE3 syntax is just a small extension of the SPICE2G6 syntax and is fully upwards compatible from SPICE2G6. The PSPICEsyntax is a considerable enhancement over the SPICE2G6 syntax. Highlights of the enhanced syntax are that node names are allowed which greatly increases the readibility of the netlist, the use of symbolic expressions in place of numeric values, passing parameters to subcircuits, and many more analysis types. The PSPICE syntax has become a second "standard" syntax.

Part II of this book serves as a combined user and reference manual while Part III is a condensed reference manual aimed at the experiendenced user needing to check syntax. Descriptions of statements and elements are based on the SPICE2G6 syntax with the SPICE3 and PSPICE extensions clearly identified.

1.5. DOCUMENTATION CONVENTIONS

#### **1.5** Documentation Conventions

In this manual the general forms of statements and elements use the following conventions to identify the type of input required:

- 1. Actual characters that must be typed by the user are in a typewriter font.
- 2. Input that must be replaced by a word or a numeric value is italicized.
- 3. Optional input is enclosed between square brackets " [ ]".
- 4. Input that can be optionally repeated is followed by a string of dots "...".
- 5. As in SPICE input syntax a line is continued when a plus sign "+" appears in the first character position of the continued line.

As example the general form of resistor is

#### Rname $N_1 N_2$ + ResistorValue IC= $V_R$ ]

Here the first character on the first line is R which indicates that this line describes a resistor element. The full name of the resistor is Rname where name can be replaced by any alphanumeric character string that uniquely identifies the element. Thus "R1", "Rgate" and "ROP\_AMP\_16\_2" are names of resistors. It should be noted that SPICE does not distinguish between upper and lower case characters. *ResistorValue* must be replaced by the numeric value of the resistor possibly including a scale factor. Thus 1MEG, 1E6, and 1000000. The complete SPICE input syntax is described in Chapter 5. With the exception of the line continuation indicated by the leading + sign a SPICE element or statement must be fully contained on a single line.

# Chapter 2

# Getting Started

In this chapter, we simulate a small circuit in order to introduce you to SPICE. We describe the input file, or "circuit" file, showing you the generic structure of the file, and giving a number of examples. Though in each example we describe what is shown, we do not list all the options and variations for each item described. The reader is referred to the reference sections (chapters 6 and 7) for that. We then show you how to run SPICE and discuss the different features of the output file.

#### 2.1 The Input File

A typical input file, and a schematic of the circuit and input waveform it is simulating, is shown in Figure 2.1. The input file is created with a text editor and is typically named something like 'test.cir'. The file is made up of five types of lines:

- A *title line*, up to 80 characters long, placed at the start of the file.
- An .end statement at the end of the file. This statement can be safely omitted in many simulators but its usage is recommended for compatibility purposes.
- Any number of *comment lines*, each starting with '\*', can be placed anywhere after the title and before the end.
- Any number of *element lines* that describe the circuit to be simulated. The basic syntax of the element line is

name node node ... value

where *name* is the name that you assign to the element. The first character in the name identifies the type of circuit element being described, e.g. 'R' for a resistor. From one to seven characters must then be added to the name to identify it uniquely, e.g. 'R1', or 'Rpulldn'. Numbers are usually used. The *node*'s identify the nodes in the circuit to which the terminals or 'leads' of the circuit element are connected. For example, one terminal of the capacitor 'C1' is connected to the node numbered '0', which must be used for the ground (or common reference) node, and the other terminal is connected to node number '2'. In SPICE each circuit node is identified by a unique number. *value* describes the value(s) needed to describe the element.

• Any number of *control statement lines* that specify what type of circuit analysis is to be performed and how the results are to be reported.



Figure 2.1: Example circuit and corresponding input file.

#### 2.1. THE INPUT FILE

The elements and control statement lines can be written in any order, even intermixed.

The first two element lines describe a 1 k $\Omega$  resistor and a 5 fF capacitor. Almost-standard metric prefixes are used in SPICE, the prefix abbreviation, the full metric name, and the represented scale factors being as follows:

Spice Prefix	Metric equivalent	Scale
$\mathbf{F}$	femto	$10^{-15}$
Р	pico	$10^{-12}$
Ν	nano	$10^{-9}$
U	micro	$10^{-6}$
Μ	milli	$10^{-3}$
Κ	kilo	$10^{+3}$
MEG	mega	$10^{+6}$
G	giga	$10^{+9}$
Т	tera	$10^{+12}$

As SPICE does not differentiate between upper and lower case, 'MEG' (or 'meg') is used for 'mega' instead of the standard metric upper case 'M'.

The value of an element is specified in terms of the conventionally accepted units, e.g. resistance in Ohms, capacitance in Farads, and inductance in Henries. If you wish you can spell it out more fully, e.g.

C1	0	2	5f	or
C1	0	2	5fF	or
C1	0	2	5fFarad	or even
C1	0	2	5fthingies	

The last alternative is allowed as SPICE actually ignores whatever follows the 'f' and assumes Farads.

The element named 'Vin' is an example of an independent voltage source. In this case the voltage source produces a repeating pulse, as shown below:



vin 1 0 pulse (0 1 5 4ns 3ns 2ns 5ns 17ns)

The general format for a pulse independent source is:

#### Vname Node1 Node2 pulse (Initial-Value Pulsed-Value Delay-Time Rise-Time Fall-Time Pulse-Width Period)

The first control statement, .tran 200ps 34ns, specifies that a transient response simulation is to be run, i.e. we wish to know how the circuit behaves as a function of time. The total length of the simulation is to be 34 ns and the outputs are to be obtained every 500ps. The second control statement, .print tran v(1) v(2) i(vin), specifies that the output is to be in the format of a printed table (.print); that transient waveforms (tran) are to be tabulated as a function of time; and that we wish to know the values for the voltage at the input (node 1 v(1), the output (node 2 v(2)) and the current through the voltage source Vin

at the time steps specified in the .tran statement. Note that all control statements start with a period '.'. We are now ready to run the simulator.

#### 2.2 Running Spice and Viewing the Output

The details of how to run SPICE vary from system to system. On a computer running the Unix operating system, SPICE can be run with a command line like the following:

#### spice test.cir test.out

This will cause SPICE to read in the file and produce the output listing file 'test.out'. Parts of the test.out are shown in Figure 2.2. The first part of the file is a header. Then the input file is listed. Just like a human circuit analyzer, SPICE has to first calculate the initial DC conditions before running the transient analysis. The results of this calculation are shown next. Finally, the transient response is tabulated.

In this output, 'D' and 'E' both indicate scientific notation, e.g. 4.500D-09 means  $4.5 \times 10^{-9}$ .

There are other ways to view the output. For example if a .plot control statement is used instead of a .print statement, the voltages and currents are plotted using character 'graphics', an example of which is given in Figure 2.3.

Using appropriate graphical packages, the output can also be plotted as smooth curves. For example, gnuplot was used to create the graph shown in Figure 2.4.

#### 2.3 Error Messages

There are many ways to produce errors in SPICE. The most common error produced by novice users is to 'connect the circuit' up incorrectly. For example, in the SPICE input file discussed above, if we connect one of the nodes of the capacitor to node 1 instead of node 2, viz.

```
r1 1 2 1k
c1 0 1 5f
vin 1 0 pulse (0 1.5 4ns 3ns 5ns 2ns 17ns)
```

then we have not specified our circuit as drawn. In this case, we also leave one terminal of the resistor unconnected to anything else and SPICE detects the error and reports it in the output file:

```
O*ERROR*: LESS THAN 2 CONNECTIONS AT NODE 2
```

However, life is rarely so simple. In a complex circuit it is always easy to get one node number wrong on one element but leave all of the nodes connected to two or more elements. In this case SPICE might detect no errors. If the output looks 'wrong' for any reason, the first thing to do is to draw your circuit by looking at the SPICE file as written and check that against your intended circuit.

Another important thing to remember about error messages is that SPICE is not very good at drawing attention to them. SPICE output files tend to be long and are cryptic looking. Error and Warning messages can be found almost anywhere within them. Read the entire file. Errors are discussed further in Chapter 3 and Appendix A.

#### 2.3. ERROR MESSAGES

```
1******// ******* SPICE 2G.6 3/15/83 ******20:02:14*****
                                                          Header.
                                                          including
0 SIMPLE RC NETWORK
                                                          title from
0****
        INPUT LISTING
                               TEMPERATURE = 27.000 DEG C
                                                          circuit file
                                      *****
0*****Contents of circuit file (the 'input') listed here*
0****
            INITIAL TRNSIENT SOUTION
NODE
        VOLTAGE
                 NODE
                        VOLTAGE
 ( 1)
        -0.0000 (s)
                      0.0000
   VOLTAGE SOURCE CURRENTS
                                  Results of Initial Solution (DC
                                 Analysis) listed here
   NAME
          CURRENT
          0.00D+00
   VIN
∩****
             TRANSIENT ANALYSIS
TIME
          V(1)
                      V(2)
                                 I(VIN)
Х
                                              Output transient
                                              response tabulated
0.000E+00 0.000E+00 0.000E+00 0.000E+00
5.000E-10
           0.000E+00
                      0.000E+00
                                 0.000E+00
                                              as specified.
 . . . . . . .
         2.500E+01
4.500E-09
                      2.476E-01 -2.375E-06
. . . . . . .
3.400E-08
           0.000E+00 7.545E-05 7.545E-08
Y
0
   JOB CONCLUDED
```

Figure 2.2: Portions of the SPICE output file.

OLEGEND:					
*: V(1) +: V(2) =: I(VIN) X TIME	V(1)				
(=)	4.	000D-06		-2.000D-06	
0.000D+00	0.000D+00	*		+	
5.000D-10	0.000D+00	*		+	
1.000D-09	0.000D+00	*		+	
1.500D-09	0.000D+00	*		+	
4.500D-09	2.500D-01		*	= .	+

(Only part of the file is shown here: the legend, the 'y-axis' scale for I(VIN) (the 'y-axis' is left to right across the page) and part of the plot with the 'time' axis going down the page.)

Figure 2.3: Example of output produced by the .plot control statement.



Figure 2.4: Results plotted graphically.

# Chapter 3 Carrying On

In this chapter, we introduce the different element and control statement lines that SPICE allows you to use, starting with the different types of circuit elements. In particular we discuss inductors, active elements (diodes and transistors), and transmission lines. We then cover the different types of analyses you can do with SPICE, starting with the most common, the transient analysis, which is introduced in Chapter 2. The main role of the control statements is to specify these analyses.

Each implementation of SPICE differs in the range of elements and control statements used. In this chapter, we describe those elements and control statements found in all versions of SPICE, i.e. those found in SPICE2G6.

#### 3.1 Elements

Resistors and capacitors are described briefly in Chapter 2. We now look at the other elements, both passive and active. The most common form of the element is described only. For example, we do not describe how a temperature dependency could be specified. That sort of detail is found in the reference section (chapters 6 and 7).

#### 3.1.1 Inductors and Mutual Inductors

An example showing an inductor and a mutual inductor is shown below:



L2 3 2 40nH L3 4 5 40nH K L1 L2 0.90

Note how the 'dot' is placed on the first node of each inductor.

#### 3.1.2 Active Devices

Unlike passive devices, such as resistors, active, or semiconductor, devices can not be specified by one or a few parameter values. To save typing effort a separate .model line is created for every semiconductor device type that might appear in the circuit. In this part of the tutorial, we do not describe the meaning of the parameters in the model line. That can be found in the Reference section (chapters 6 and 7). Instead, we give examples showing how semiconductor devices are inserted into a SPICE circuit. We only describe the bipolar junction diode, bipolar junction transistor, and the MOS field effect transistor. Spice can also be used to describe junction field effect transistors and Gallium Arsenide but the process is the same.

#### **Diodes and Bipolar Transistors**

The schematic and partial SPICE net-list for a simple TTL inverter is shown in Figure 3.1. Note the following features in this circuit description:

- The format for bipolar junction transistors is: Qname NCollector NBase NEmitter [NSubstrate] ModelName [Area] [OFF] + [IC=Vbe, Vce] specifying a three terminal device.
- The format for diodes is: Dname  $n_1 n_2$  ModelName [Area] [OFF] [IC= $V_D$ ] specifying a two terminal device.
- The use of '+'s in the model lines to 'join' different lines in the file into one line for SPICE.

It is also possible to have an 'area' parameter in the diode and bipolar transistor element line. This area parameter is a scale factor, not an absolute measure. An area of '1.0' (which is the default) specifies that the model parameters are used unchanged. Specifying another area factor causes SPICE to change some of the model parameters to reflect a larger or smaller transistor. An area of '2.0' specifies a situation equivalent to two transistors operating in parallel.

#### MOSFETs

The MOSFET element line looks quite different than the element line for a bipolar transistor. There are two major differences. First, the MOSFET is a four terminal device. Three of the terminals (source, drain, gate) have analogous functions to the three terminals in a bipolar transistor. The current passes between the drain to the source (analogous to the emitter and collector) and is controlled by the voltage on the gate (analogous to the base). The fourth terminal is the 'substrate' referring to the bulk silicon in which the transistor sits. For correct functioning, the substrate must be connected to the ground or Vcc node, for n-channel and p-channel transistors respectively.

The second major difference is that the physical dimensions of the transistor are specified in the model line. Specifically, the channel length and width, and source and drain perimeters and areas are specified. These are the actual dimensions, as they appear on the chip. An example is shown in Figure 3.2. This example matches the usual general model format: Mname NDrain NGate NSsource NBulk ModelName [L=Length] [W=Width]

- + [AD=DrainDiffusionArea] [AS=SourceDiffusionArea]
- + [PD=DrainPerimeter] [PS=SourcePerimeter]
- + [OFF] [IC= $V_{DS}, V_{GS}, V_{BS}$ ]



Figure 3.1: TTL Circuit Description.



M1 0 1 2 0 nenh 1=0.8u w=1.6u ad=3.2p as=3.2p pd=5.2u ad=5.2u

Figure 3.2: Example of a MOSFET element specification.

where [] indicates optional parameters. PSPICE supports additional element parameters. (For the full general format please see the reference catalog.)

Note that though the *drain* and *source* have different physical meanings (the *source* is the source of the majority carrier – electrons for an n-channel [nmos] device and holes for a p-channel [pmos] device), no error is produced if they are interchanged in the SPICE circuit description. For example, in figure 3.2, using M1 2 1 0 0, produces the same simulation results as using M1 0 1 2 0.

An example of a CMOS digital inverter circuit, together with its SPICE model is given in Figure 3.3. Note the use of the .option line in this example to fix circuit-wide default values for L, W, AD, and AS.

#### 3.1.3 Transmission Lines

Though a transmission line is a four terminal device, two of the terminals are normally set to a common reference node, an example of which is shown in Figure 3.4. This lossless transmission line model supports only a single mode of propagation. If the two 'reference' terminals (nodes 0 in this example) correspond to two electrically different nodes in the physical circuit then two modes are excited and two transmission lines are required in the corresponding SPICE description.

If quick simulation times are important then it is necessary to limit the use of small transmission lines. In a transient simulation the minimum time step does not exceed half the propagation delay of the line. Smaller time steps result in longer simulation times. If this is a problem, remember that a transmission line can be safely replaced by the equivalent lumped inductor and capacitor if the length of the line is smaller than 1/10th of the shortest signal wavelength of interest.

#### 3.1.4 Voltage and Current Sources

#### Independent Sources

Spice supplies a number of independent voltage and current source types. As many of the source's features only make sense in the context of the analysis to be used, only some of the source's features are discussed

#### 3.1. ELEMENTS

here. In particular, we present those features that might be used in a transient analysis (see Chapter 2 and Section 3.2.1).

Voltage supplies are specified using DC independent sources, for example:

#### VCC 5 0 DC 5

for a 5 V DC power supply between nodes 5 and 0.

Any repeating non-sinusoidal waveform can be specified using the **pulse** waveform specification, an example of which was given in Chapter 2. **pulse** is often used to describe digital clocks, for example.

Non-repeating non-sinusoidal waveforms are specified using the piece-wise linear (pwl) waveform function. One period of the pulse example presented in Chapter 2 is shown below in the piece-wise linear format:



vin 1 0 pwl (Ons OV 4ns OV 7ns 1.5V 12ns 1.5V 14ns OV 17ns OV)

Sinusoidal and decaying sinusoidal waveforms are specified using the SIN function, for example:





Spice also allows you to specify exponential and single-frequency FM signals. Please see the reference catalog for details.

#### **Dependent Sources**

These are the most overlooked elements SPICE provides. Four different types of linear dependent sources can be specified in SPICE:

• Voltage-controlled voltage source and current-controlled current source:



E1 4 3 2 1 3.3 A voltage gain of 3.3. F1 6 5 Va 1.7 A current gain of 1.7

• Voltage-controlled current source and current-controlled voltage source:



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G1 4 3 2 1 15mmho A transconductance of  $15 \times 10^{-3}$  mho ( $\Omega^{-1}$ ). H1 6 5 Va 0.5k A transresistance of 500 Ohms

The above are linear sources. Non-linear sources can also be specified. For example, the following voltagecontrolled current source actually specifies a non-linear resistance that could be used as part of a non-linear Thevenin equivalent circuit:



Gout 2 1 2 0 0 1m -0.6m

The format used in this example is:

```
Gxxx node1 node2 ref-node1 ref-node2 C0 C1 C2
```

to produce a dependent source that obeys the equation:

$$I = C0 + C1(V(ref - node2) - V(ref - node1)) + C2(V(ref - node2) - V(ref - node1))^{2}.$$

In this case, the equation specifying the current is:

$$I = 0 + 1 \times 10^{-3} V_{out} - 0.6 \times 10^{-3} V_{out}^2$$

The above non-linear source is quadratic and dependent on only one other variable. The same format can be used to specify higher order polynomials. A source dependent on the voltages/currents on/in ND other nodes/branches can be specified by including a poly(nd) statement in the element line. For example, the following linear voltage-controlled voltage source specifies a gated sinusoidal source:



Vsine 1 0 sin (0 0.5 100k 5us) Vpulse 2 0 pwl (Ons OV 14us OV 15us 1V 65us 1V 66us OV) Egate 3 0 poly(2) 1 0 2 0 0 0 0 1

i.e. This source specifies a voltage,

 $\texttt{Vgate} = 0 + 0 \times \texttt{Vsine} + 0 \times \texttt{Vpulse} + 1 \times \texttt{Vpulse} \times \texttt{Vpulse}$ 

which has the following waveform:



In its general form, a polynomial of any complexity can be specified. e.g. The generalized voltage controlled voltage source,

EX <node> <node> poly(2) V1 V2 k0 k1 k2 k3 k4 k5 k6 k7

specifies a controlled voltage of the form

 $EX = k1 + k2 \times V1 + k3 \times V2 + k4 \times V1 \times V2 + k5V1^{2} + k6V2^{2} + k7V1^{2}V2^{2}$ 

This could be extended to create polynomials as a function of 3, 4, etc. variables. However, as a practical matter, it is very difficult to read and understand non-linear polynomials with more than two inputs. It is easier to create two-input polynomials separately and combine them with another polynomial.

#### 3.2 Analyses

#### 3.2.1 Transient Analysis

In the transient analysis response is observed with one or more time-varying inputs. A simple example is given in Chapter 2.

The first step performed by SPICE in a transient analysis is to compute the initial DC or bias point condition. During this computation it is assumed that the voltage across capacitors is zero, the current through inductors is zero, and the value for dependent sources is zero. SPICE then conducts the transient simulation by calculating all of the voltages and currents at a set of points in time. In the rest of this section, we discuss a number of issues related to transient analyses, starting with a treatment of convergence.

#### **DC** Convergence

During both the DC analysis and the following transient analysis iterative numerical techniques are used to obtain a solution. The objective of these techniques is to iterate on the value of the node voltages and branch currents until successive iterations only bring very small changes in their values, i.e. SPICE *converges* on a solution in the DC analysis and at every time step.

Sometimes SPICE can not converge on a solution. If this occurs during the DC analysis it will report this problem in the output file with a 'convergence problem' message like. Failure to converge in the DC analysis is usually due to an error in specifying node numbers, circuit values or model parameter values. These should be checked carefully before proceeding further. However, sometimes SPICE is having a genuine problem in converging and you might have to help it find a solution.

In many bistable circuits (e.g. flip-flops) and positive feedback circuits, SPICE will not converge in the DC analysis or will converge to an undesirable value (e.g. midway between logic-0 and logic-1 in a latch). One way to help SPICE converge to the correct value is to use the off option to turn off devices in the feedback path, e.g.,

#### MO 0 1 2 0 pd=5.2u ad=5.2u off

allowing SPICE to find a DC solution. Spice turns the devices back on during the transient analysis. Another approach is to use **nodeset** to provide 'hints' to SPICE or to specify initial conditions that force a solution.

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#### Nodeset and Initial Conditions

The basic difference between using nodeset and specifying initial conditions is that the latter forces nodes to the specified voltage while nodeset only provides hints. The values specified by the nodeset line are only used during the first part of the DC solution procedure and then ignored in the later parts. Thus if they are incorrect, or inconsistent, convergence is not prevented. As an example of nodeset, to use as follows in the the simple latch, will result in the output (node 2) converging to 5 V (assuming a CMOS latch):



.nodeset V(1)=0V

When initial conditions are set, they are used through the entire DC solution right to the start of the transient analysis. For example in the circuit above, the use of .IC V(1)=1V will result in V(1) starting at 1 V in the transient analysis while the use of .nodeset V(1)=1V would result in V(1) starting at 0 V. An error or inconsistency in specifying initial conditions with .IC might prevent SPICE from converging.

A second way to specify initial conditions is to specify them in the element lines. For example, the statement,

#### C1 6 0 IC=3.1

initializes the voltage across capacitor C1 to 3.1 V. For an inductor, the following statement will set the initial current flowing through it to 4.3 mA:

#### L3 4 5 IC=4.3m

If IC= statements are used then it is necessary to include a "Use IC=" (UIC) statement in the .tran statement, e.g.

#### .tran 200ps 34ns UIC

Specifying UIC commands SPICE to skip the DC bias calculation, making it is necessary for the initial conditions to be completely specified through a combination of IC= and .IC statements. Be careful.

#### Simulation Time Step Size

Using a smaller time step increases both the results accuracy and computer run-time of the simulation. One thing to be very aware of is if short transmission lines or very fast edges are specified then the simulation time step will be very short. For example, trying to obtain a 'step response' with a waveform/statement such as the following will greatly increase rise time (and also quite likely lead to convergence problems).



.Vin 4 0 PWL Ons OV 1ps 5V 40ns 5V

It is also possible to change the time step, and other step-related parameters, in the .options statement. Please see the reference catalog for details.

#### **Transient Analysis Convergence Problems**

SPICE might report a transient analysis convergence problem with a message like the following:

\*ERROR\*: Convergence problem in Transient Analysis at

TIME =

etc.

Sometimes SPICE is not so hopeful and just 'dumps' you part way through the analysis, e.g. part way into a 40 ns analysis SPICE might suddenly stop the analysis at 34 ns and end with:

3.400E-09 5.452E+00 6.602E+00 6.892E+00 Y O \*\*\*\*\* JOB ABORTED

In this case, the problem was a too-short implicit time step caused by a very short (62.3 ps delay) transmission line:

Tline3 10 0 11 0 z0=60 td=62.3ps

Replacing the line with its equivalent lumped circuit,

Lline3 10 11 7.48nH Cline3a 10 0 1.03pF Cline3b 11 0 1.03pF

solved the problem.

If your transient analysis convergence problem is not being caused by a too short a time step, then it is most likely caused by an error in specifying a circuit node number or parameter value. Your circuit and .model lines should be checked carefully. Often looking at the circuit description as specified in the output listing is more useful than looking at the file you typed in, as the output listing is describing what SPICE 'sees'.

However, SPICE is a numerical program and can be quirky. For example, one simulation driven by the pulse

V2 4 0 Pulse(OV 5V On 1.2n 1.2n 20n 40n)

would abort about half way through the simulation. However, turning the pulse 'up-side-down' (interchanging 0V and 5V),

V2 4 0 Pulse(5V 0V 0n 1.2n 1.2n 20n 40n)

allowed the simulation to complete.

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#### Spectral Analysis – Fourier Transform

The .Four control statement can be used to find the spectrum of any time-varying signal in a transient analysis. For example, in Chapter 2, we used the following time-domain signal as the input to an RC circuit:



vin 1 0 pulse (0 1.5 4ns 3ns 5ns 2ns 17ns)

The addition of the control statement,

#### .Four 58.82MegHz V(1) V(2)

to this file, specifies that the spectrum of the input (V(1)) and output (V(2)) voltage waveforms are also to be obtained. The frequency specified in this statement is the fundamental frequency of the waveform (1/17 ns = 58.82 MHz). As a result of this statement, the output file reports the magnitude and phase of the first nine harmonics for each signal. In this case, the output for V(1) is:

0****	FOURIER ANALY	ISIS	TEMP	27.000 DEG C						
0**********										
FOURIER COMPONENTS OF TRANSIENT RESPONSE V(1) ODC COMPONENT = 5.293D-01										
OHARMONIC NO	FREQUENCY (HZ)	FOURIER COMPONENT	NORMALIZED COMPONENT	PHASE (DEG)	NORMALIZED PHASE (DEG)					
1	5.882D+07	7.750D-01	1.000000	-91.352	0.000					
2	1.176D+08	2.561D-01	0.330483	99.249	190.601					
3	1.765D+08	7.623D-02	0.098364	16.321	107.673					
4	2.353D+08	2.980D-02	0.038451	-123.300	-31.947					
5	2.941D+08	2.502D-02	0.032282	-167.139	-75.786					
6	3.529D+08	6.971D-03	0.008994	-46.439	44.913					
7	4.118D+08	9.869D-03	0.012734	81.719	173.071					
8	4.706D+08	1.722D-02	0.022225	-9.729	81.623					
9	5.294D+08	1.346D-02	0.017363	-169.978	-78.625					

A similar table is obtained for V(2).

#### 3.2.2 DC Analyses

Spice enables you to conduct the following DC analyses:

- DC solution for a particular input voltage/current condition (.OP).
- DC solutions over a range of input conditions (.DC).
- Small signal DC transfer functions, including gain, input and output resistance (.TF).
- Sensitivity of the DC value of an output to some set of parametric variations (.SENS).

These are discussed in turn.

The insertion of a line with just

#### .OP

on it asks SPICE to determine the DC bias point of the circuit with inductors shorted and capacitors opened, just the same as the DC analysis conducted before a transient analysis. It might be used in situations where you wish to know the DC bias point but the analysis you are doing does not request it (e.g. such as when determining a frequency response).

A command line beginning with .DC instructs SPICE to sweep the specified voltage source over the specified range, reporting the DC bias point for each combination of input conditions. If more than one source is specified in the .DC statement, then the first source will be swept over its entire range for every value of the second source. An example is given in Figure 3.5 in which two analyses alternatives are presented at the bottom. The left hand alternative instructs SPICE to plot the transfer characteristics of the CMOS inverter, the right hand example instructs SPICE to plot the output V-I characteristics for when Vin is 5 V. Both examples specify that the voltage sweep is to be from 0 to 5 V in 0.1 V increments. The resulting output V-I characteristic (obtained using the statements on the right hand side of the Figure 3.5) is plotted in Figure 3.6.

Now, if you wish to find the small signal output resistance at say Vout = X V,

$$r_{out} = \left. \frac{\partial v}{\partial i} \right|_{V_{out} = X \ V}$$

then one way to obtain this would be to measure the slope of the plot shown in Figure 3.6 at Vout = 0.5 V. However, SPICE provides an easier way to get this result as a transfer function .TF:

#### .TF I(vout) Vout

There is no need for a .print statement with .TF. Running this produces the output:

OUTPUT RESISTANCE AT I(VOUT) = 2.247D+03

A DC sweep can also be done by specifying a slow moving input and a conducting a transient analysis. Sometimes this is necessary, for example in circuits with hysteresis, such as a Schmitt Trigger.

Sometimes we wish to know the sensitivities of various output parameters with respect to variations in circuit parameters. For example, we might wish to know whether to specify resistors to +/-10% or +/-1% in order to guarantee a certain bias point in a transistor amplifier. This is done with the .sens statement. The following example determines the sensitivity of the bias point of an amplifier to variations in resistance
values:



Extract from input file:

Common-Emitter Amplifier R1 2 5 40k R2 2 0 40k \* Measure the Base current Vbase 3 2 Q1 4 3 6 NQ1A RC1 5 4 4k RE1 6 0 100 \* AC source with unity magnitude and AC buffered Vin 1 0 AC Cbuff 1 2 100u Vcc 5 0 5V \* Find the bias point .OP  $\ast Find$  the sensitivity of the bias voltage at the collector .sens V(4) Extracts from output file reporting DC bias point and the sensitivity analysis:

NODE	VOLTAGE	NODE	VOLTAGE	NODE	VOLTAGE	NODE	VOLTAGE
NODE	VOLTAGE	NODE	VOLTAGE				

(	1) 0.0000	(2)	1.1432	(	3)	1.1432	(	4)	0.3220	(
5)	5.0000	(6)	0.1237							
ODC	SENSITIVITIES	OF OUTPU	T V(4)							
0	ELEMENT	E	LEMENT	EL	EMENT	NOR	MALIZ	ZED		
	NAME		VALUE	SENS	ITIVIT	Y SENS	SITIV	ITY		
				(VOLT	S/UNII	C) (VOLTS/	'PERCI	ENT)		
	D 1	4 0	000+04	1 1	140-06	: лл	57D-(	74		
	101	4.0	000+04	-2 2	020-07	· -1 2		)4 )4		
	nZ	4.0	000+04	-3.3		-1.3		J4		
	RC1	4.0	000+03	-7.0	100-05	-2.8	304D-0	13		
	RE1	1.0	00D+02	1.1	92D-03	3 1.1	92D-0	03		

In this case, if the value for RE1 changed by 100% the collector voltage would only change by only 119 mV.

#### 3.2.3 Small Signal AC Analysis

Analog circuits are often analyzed in terms of their frequency response to steady-state, sinusoidal, small-voltage, input signals. With small voltage swing signals, all of the circuit elements can be treated as being linear around some bias point. Three types of AC analysis can be done:

- 1. Obtain circuit response(s) as a function of frequency using the .AC analysis.
- 2. Conduct a noise analysis as a function of frequency using a .NOISE element together with a .AC element.
- 3. Analyze the circuit for harmonic distortion using the .DISTO element together with the .AC element.

In this section, we discuss the first two types of analysis only. The distortion analysis capability provided in SPICE2G6 somewhat limited and so is not presented.

Consider the frequency response of the LC filter described, with its SPICE file, in Figure 3.7. There are several features in this file that differentiate it from a file specifying a transient analysis. First the signal source Vin is specified as an AC source, not a source in the time domain. Here it specifies a sinusoid with a magnitude of 1 Volt. The .AC control statement specifies that we wish the frequency range to be swept over a frequency range of 100 Hz to 10 kHz in decade (dec) increments with 20 points per decade. i.e. The output contains a total of 40 frequency points, 20 between 100 Hz and 1 kHz and 20 between 1 KHz and 10 Hz. The .print statement specifies that this is an AC analysis and specifies that the magnitude of the voltage (VM) of node 3 with respect to node 0 be printed at each frequency point. Examples of other results that can also be obtained include:

Control statement Example	Meaning
.print AC VR V(2,3)	Real part of the voltage across the inductor
.print AC VI V(2,3)	Imaginary part of the voltage across the inductor
.print AC VP I(Vin)	Phase of current through the voltage source
.print AC VDB(3)	Voltage in dB, $10 \times log_{10}(magnitude)$

The results obtained by running the SPICE file specified in Figure 3.7 are shown in Figure 3.8. Note again that a DC analysis is carried out before the AC analysis so as to obtain the bias point (this is not shown).

In Section 3.2.2, we show how to obtain the (non-linear) output impedance as a function of the output voltage. For small voltage swing signals, all impedances are linear, so we are interested in input and output impedance as a function of frequency. For example, we could plot the output impedance of the LCR circuit above using the following SPICE file:

```
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```

```
RLC filter
*
*
* 'Short' input so that it does not form
* part of the output impedance
Vin 1 0 AC 0V
*
R1 1 2 150hm
L1 2 3 50mH
C1 3 0 1.5uF
*
.AC dec 20 100Hz 10kHz
*
*
* Measure output impedance with a current source
Iout 0 3 AC 1
*
* Measure Zout:
.print AC VM(3)
.end
```

The output impedance is plotted in Figure 3.9.

Spice is also capable of conducting a noise analysis as part of the AC analysis. This analysis is often useful as an aid to the design of analog circuits. For full details please see the .NOISE and .PRINT control statement descriptions in the reference catalog (Part III).

#### 3.2.4 Monte Carlo Analysis

The Monte Carlo analysis is a statistical analysis of the circuit causing the circuit to be analyzed many times with a random change of model parameters (parameters in a .MODEL statement). It is available in the PSPICE version only.

The form on the Monte Carlo analysis is PSPICEForm

```
.MC NumberOfRuns AnalysisType OutputSpecification OutputFunction [LIST]
```

+ [OUTPUT( *OutputSampleType*)] [RANGE(*LowValue*, *HighValue*)]

+ [SEED=SeedValue]

Monte Carlo analysis repeates DC analysis as specified by the .DC statement, AC small-signal analysis as specified by the .AC statement, or transient analysis as specified by the .TRAN statement. In the .MC statement the way in which the results of the multiple runs are interested is controlled by the *OutputSpecification*] and *OutputFunction* parameters.

A typical use of Monte Carlo analysis is to predict yield of a circuit by examining the effect of process variations such as length and width of transistors. As well the effect of temperature on circuit performance can be investigated.

The initial run uses the nominal parameter values given in the NETLIST. Subsequent runs statistically vary model parameters indicated as having either lot or device tolerances. These tolerances are specified in a .MODEL statement.

#### 3.2.5 Transfer Function Specification

The transfer function specifies a small-signal DC analysis from which a small-signal transfer function and input and output resistances are computed. The transfer function computed is the ratio of the DC value of the output quantity to the input quantity. In the above examples the following transfer functions are

computed:

EXAMPLE	Transfer Function
.TF V(10) VINPUT	V(10) VINPUT
.TF V(10,2) ISOURCE	V(10,2) ISOURCE
.TF I(VLOAD) ISOURCE	I(VLOAD) ISOURCE

- 3.2.6 Parameteric Analysis
- 3.2.7 Sensistivity and Worst Case Analysis



Figure 3.3: A CMOS inverter.



T1 1 0 2 0 Z0=50 TD=333ps

Figure 3.4: Example of a transmission line.



MOS Inverter \* MO 0 1 2 0 nenh 1=0.8u w=1.6u ad=3.2p as=3.2p pd=5.2u ad=5.2u M1 2 1 5 5 penh 1=0.8u w=1.6u ad=3.2p as=3.2p pd=5.2u ad=5.2u Vcc 5 0 DC 5V Vin 1 0 Vin 1 0 5V Vout 2 0 .DC Vin 0 5 0.1 .DC Vout 0 5 0.1

.print DC V(2)

Figure 3.5: DC response example. Two alternative analyses are presented at the bottom and are described in the text.

.print DC I(Vout)



Figure 3.6: Output V-I characteristics for CMOS inverter.



Figure 3.7: LC filter and the SPICE file specifying a frequency response analysis. (Comments in *emphasis* are not part of the file.)



Figure 3.8: Frequency response of the circuit shown in Figure 3.7.



Figure 3.9: Output impedance vs. frequency for LC circuit shown in in Figure 3.7.

## Chapter 4

# How Spice Works

## 4.1 Introduction

SPICE has three basic analyses: DC analysis — initiated by the .DC statement; AC analysis — initiated by the .AC statement; and transient analysis — initiated by the .TRAN statement. AC analysis involves incorporating the relations relating terminal voltages and device currents into a matrix equation. This matrix equation is called the network equation and embodies the topology of the network and the constitutive relations (that is, device equation) describing individual devices. It derives from a mathematical statement of Kirchoff's current law with device currents replaced by node voltages with the substitution achieved by using the constitutive relations of individual devices. Extensions to this basic form of the network equation (called the modal formulation of the network equation) is required for elements that can not be mathematical modeled as a current or currents in terms of voltages. AC analysis is the appropriate place to begin a technical exposition of the analysis algorithms in SPICE as it illustrates the method of development of network equation is used by all other analyses.

Transient analysis requires, as well, that a time-stepping numerical integration algorithm be incorporated into the network equations. A straight forward approach to transient analysis, which was used prior to the development of the "SPICE" approach, is to derive the state equations in state space (that is in differential form using the *s* operator) and apply the time discretization of a numerical integration method to the complete network equation. However, in SPICE the time discretization is incorporated in the constitutive relations before the network equation is developed. The time discretized network equation must be solved iteratively and the Newton iteration procedure is applied to the device equations along with the time-discretization step. This has proved to be a particularly robust approach and is the main reason SPICE is so widely accepted.

DC analysis is a special case of transient analysis without the time discretization step and so is discussed after transient analysis.

## 4.2 AC Small Signal Analysis

AC small signal analysis is initiated by the .AC statement (see page 53). The aim in AC analysis is to determine the AC voltage at every node in the circuit which is now linear because of the small-signal approximation. First of all a matrix equation is developed that relates node voltages to external current sources. Through Thevenin's theorem external voltage sources are converted to external current sources and node voltages are easily related to voltages across elements. This formulation of the network equation is called the nodal admittance formulation. Unfortunately there are several elements, such as the current controlled voltage source element, which do not have an admittance description as required in this approach. A method of circumventing this problem is discussed in section ?? and is a direct extension of the method discussed below.

Consider the general network  $\mathcal{N}$  in Figure 4.1(a) with N internal nodes in addition to the reference node.



Figure 4.1: Definition of networks: (a)  $\mathcal{N}$ ; and (b)  $\mathcal{N}'$ .

In general the reference node is not part of the circuit and the development of the network equations is simplified by treating all of the nodes (except the external reference node) in the same way.

All of the nodes of the network have external current sources J with  $J_n$  being the external current source between the n th node and the reference node. In practice most of the external current sources, the J's, are zero and those that are not are due to independent sources. The network equations used in SPICE relate the node voltages, the v's, and the J's. In matrix form

$$\mathbf{Y}\mathbf{v}_n = \mathbf{J}_n \tag{4.1}$$

where  $\mathbf{v}_n$  is the vector of node voltages, and  $\mathbf{J}_n$  is the vector of external currents. Solution of equation (??) enables the node voltages to be evaluated given the external current sources.

In SPICE the grounded reference node, node "0", is part of the network and so there is a linear dependence of the rows of  $\mathbf{Y}$  ( $|\mathbf{Y}| = 0$ ). Hence  $\mathbf{Y}$  is called the indefinite nodal admittance matrix. One row and one column can be deleted from  $\mathbf{Y}$  without the lossing any information to yield what is called the definite nodal admittance matrix. For now consider that the reference node is an arbitrary node. The correction required because the reference node is actually part of the circuit is discussed in section ??.

## 4.3 DC Analysis

C

The analysis of nonlinear resistive circuits, or equivalently the analysis of circuits at DC is an important first step in AC and transient analysis. In both cases nonlinear resistive analysis determines the initial starting point for further analysis incorporating energy storage elements such as capacitors and inductors.

DC analysis is SPICE is identical to transient analysis discussed in the previous section except that the contributions of capacitors and inductors are ignored. DC analysis has better convergence properties ithan transient analysis since energy storage elements, and thus resonant responses, are eliminated. As well the analysis is numericly efficient since only a steady-state response is required and calculated.

## 4.4 Discussion

SPICE supports several analyses other than those discussed above. Essentially these are extensions of the AC, DC and transient analyses.

#### 4.5. TO EXPLORE FURTHER

The transfer function analysis, initiated by the .TF statement, calculates a transfer function as the ratio of the DC value of an output quantity to the DC value of an input quantity over a range of values of the input quantity. A DC analysis at each value of the input quantity is performed.

With the .DISTO statement a distortion analysis is performed by dteremining the steady-state harmonic and intermodulation products for small input signal. Evaluation of the small-signal distortion is based on a third-order multi-dimensional Volterra series expansion of nonlinearities around their operating point. The method for calculating of the distortion products parallels AC analysis algorithm.

The sensitivity analysis calculates the DC small-signal sensitivities of each output quantity with respect to every circuit parameter. It is initiated by the .SENS statement. The transfer function computed is the sensitivity (or partial derivative) of the DC value of the output quantity with respect to the each and every circuit parameter.

If the .NOISE statement is included in the input file the noise generated by active devices and resistors is evaluated. All active devices and some passive devices have noise models consisting of uncorrelated noise current sources. These noise current sources are used as the external current sources in ACanalysis. One noise source at a time is considered and the response at the output terminals and sources specified are calculated. The contributions from each source are added in a root-mean-squared sense as they are uncorrelated. The noise analysis utilizes the network equation formulated and solved in AC analysis.

A Monte Carlo analysis is performed when the .MC statement is specified. In the Monte Carlo analysis either a DC, an AC, or a transient analysis is performed multiple times.

An operating point analysis initiated by the .OP statement is just a single DCanalysis.

The Fourier analysis performed when the .FOUR statement is used is not really a separate analysis at all. Really it is a way of examiing the results of a transient analysis by taking the Fourier transform of a voltage or current response.

## 4.5 To Explore Further

The essential aspects of SPICE are the models of devices and the algorithms for formulating and solving the network equations. The derivation of the AC model of devices is straightforward requiring the y parameters of the device. These are obtained from the analytic derivatives of the device equations calculated at the operating point of the circuit as determined from a DC analysis. For transient and DC analysis the associated discrete circuit model must be calculated from the device equations. The device equations of semiconductor devices are calculated from knowledge of the device physics. Derivation of the models used for semiconductor devices in SPICE2G6 and SPICE3 are described in [2] (Semiconductor Device Modeling with SPICE edited by P. Antognetti and G. Massobrio). Without fail the models in SPICE2G6 are available in all commercial versions of SPICE. SPICE3 and most commercial versions of SPICE provide additional or enhanced models. Derivations of more advanced models are described in [8] (Semiconductor Device Modeling for VLSI by K. Lee, M. Shur, T. Fjeldly and T. Ytterdal).

In SPICE the network equations are stored in sparse matrices to conserve memory usage. This also results in much faster solution of the network equations than if regular matrices were used. Greater detail than that provided in this chapter of the numerical algorithms used in SPICE can be found in [1] (*Fundamentals* of Computer-Aided Circuit Simulation," by W. J. McCalla).

# Chapter 5 Input File

## 5.1 Introduction

The operation of SPICE is controlled by statements which are embedded in an input file which includes as well descriptions of elements and their topology. The description of the elements and their topology is also known as a netlist. The output or results of a SPICE run are logged in an output file and in more modern versions of SPICE, in a data file for subsequent interactive plotting and analysis. With PSPICE the program for subsequent analysis is probe and with SPICE3 the comparable tool is NUTMEG.

## 5.2 Circuit Model

The model used by SPICE to represent circuits is as shown in Figure 5.1. SPICE supports a hierarchical description of a circuit with subcircuits. A large number of parameters are required for many elements, especially for active devices, and for these the model concept is introduced where most of the parameters of active elements can be defined separately from invocation of the element. This permits a single model description to be used by many elements. A model is specific to a particular element type but not all elements have models. Mostly models are used to set the parameters describing a semiconductor fabrication process and so are common to many elements.

When the input file is read subcircuits definitions and models are stored internally separately from the main circuit. Subcircuit calls are expanded if the subcircuits referenced are already defined and stored internally. If a referenced subcircuit is not defined then the subcircuit call is flagged as not being expanded and only when the input file has been completely read (up to the .END statement) is an attempt made to resolve incomplete expansions. In PSPICE library files (described in the .LIB statement discussion on page 68) are checked. The first time a library file is to be searched, an internal table of which subcircuits and models are available and where they can be found in the library files is constructed. Models are treated in a similar way, a model is used if it has been defined otherwise resolved references to models are expanded once the input file has been completely scanned (up to the .END statement). With PSPICE evaluation of expressions in subcircuits and models is only performed when on fully expanded subcircuits. Note that expressions and libraries are not supported in SPICE2G60r in SPICE3.

## 5.3 Input Lines

The input file of SPICE is essentially unstructured. It must begin with a TITLE line and should end in a .END statement although this is automaticlly assumed if the end of the input file is read. The string on the TITLE line is used as the banner in the output log file appearing at the top of each page. The .END statement marks the end of one circuit with the effect that several circuits can be specified in the file (at least for



Figure 5.1: The SPICE circuit representation.

#### 5.3. INPUT LINES

SPICE3 and PSPICE). In between the TITLE line and the .END statement can be any mix of statements — which control the operation of the simulator and the analysis to be performed; optional comment lines — for documenting the input file; and element lines — which specify the circuit elements. The input file can in fact contain no statements and the simulator will then perform an operating point .OP analysis. SPICE does not distinguish between upper and lower case characters.

Except for the TITLE line which is the first line of the input file, the type of input lines is distinguished by the first character on the line: statements begin with a period "."; element lines begin with an alphabetic character "A-Z" — with the letter identifying the element type (e.g. R for a resistor); and comment lines begin with an asterisk "\*". In older terminology, based on the original use of punched cards, statements are referred to as "dot cards" or "statement cards"; element lines are referred to as "element cards" or "device cards"; and comment lines as "comment cards."

PSPICE allows for in line comments indicated by a semicolon ";". The semicolon and everything following it on the same line are ignored except for purpose of echoing the input file in the output log file.

#### 5.3.1 Analysis Statements

.AC

AC Analysis

An analysis statement identifies the type of analysis to be performed. Any combination of analyses may be specified. Reporting of the results of an analysis is controlled by the .PRINT, .PLOT and, in with PSPICEby the .PROBE control statements. If no analysis statement is included in the input file then an operating point analysis (.OP) is performed by default. A brief description of the analysis options and the page on which a complete description can be found as follows.

Obtains the small-signal circuit response as a function of frequency. The .AC analysis is one of several small signal AC analyses.

.DC DC Analysis ..... Page 55 DC solutions over a range of input conditions (.DC).

.DISTO Small-Signal Distortion Analysis SPICE2G6 and SPICE3 Only ..... Page 58 Analyze the circuit for harmonic and intermodulation distortion. This analysis is available in SPICE2G6 and SPICE3 but is not available in PSPICE as it has proved to be unreliable. In SPICE2G6 the distortion analysis must be performed in conjunction with a .AC analysis.

.FOUR Fourier Analysis Page 64

The .FOUR control statement can be used to find the spectrum of any time-varying signal in a (.TRAN) transient analysis. The .FOUR statement is unlike other analysis statements as it does not initiate a simulation but interprets the result of a simulation initiated by the .TRAN sattement.

.MC Monte Carlo Analysis (PSPICE only) ..... Page 69 The Monte Carlo analysis is a statistical analysis of the circuit causing the circuit to be analyzed many times with a random change of model parameters (parameters in a .MODEL statement). The analyses specified in the .DC, .AC or .TRAN statements can be simulated multiple times.

.NOISE Small-Signal Noise Analysis ..... Page 77 Conduct a small-signal noise analysis as a function of frequency. In PSPICE this statement must be used in conjunction with a .AC statement.

.OPOperating Point AnalysisPage 82DC solution for a particular input voltage/current condition. This is the default analysis if no analysis is specified in the input file. This is the default analysis if not analysis type is specified in the input file.Page 82

.PZ Pole-Zero Analysis, SPICE3 Only ..... Page 99 In this analysis the poles and zeros of the small signal ACtransfer function of a two-port is evaluated.

Page 53

.SAVEBIAS	Save Bias Conditions	Page 100
.SENS	Sensitivity Analysis	Page 101
The sensitivity of t	he DC value of an output to some set of parametric variations is calculated.	
.STEP	Parameteric Analysis PSPICE Only	Page 102
.TF	Transfer Function Specification PSPICE Only	Page 107
Small signal DC tr	ansfer functions, including gain and input and output resistance are computed	
.TRAN	Transient Analysis	Page 109
In the transient an	alysis response is observed with one or more time-varying inputs.	
.WCASE	Sensistivity and Worst Case Analysis PSPICE Only	Page 112

## 5.3.2 Control Statements

.DISTRIBUTION	Distribution Specification (PSPICE only)	Page 61
This statement spe statement on page	ecifies the statistical tolerance distribution used in a Monte Carlo analysis (see 69).	the $\ensuremath{MC}$
.END	End Statement	Page 62
This statement ind	icates the end of the input of one circuit.	
.ENDS	End Subcircuit Statement	Page 63
The end subcircuit	statement indicates the end of a subcircuit definition.	
.FUNC	Function Definition PSPICEOnly	Page 65
Enables commonly	used expressions to be more conveniently defined as functions.	
.IC	Initial Conditions	Page 66
This statement is analyses.	used to set initial conditions for transient analysis. It has no effect on other	types of
.INC	Include Statement, PSPICE only	Page 67
Specifies the name	of a file which is to be treated as part of the input file.	
.LIB	Library Statement, PSPICE only	Page 68
Specifies the name	of a library file.	
.MODEL	Model Statement	Page 72
Specifies the param to many elements.	neters of elements that either are too numerous to put on the element line or are	common
.NODESET	Node Voltage Initialization	Page 76
Specifies the voltage	ge at one or more nodes to be used as an initial guess.	
.OPTIONS	Option Specification	Page 83
The options specifi and analyses.	cation provides the user control over the program and sets defaults for certain o	elements
.PARAM	Parameter Definition, PSPICE Only	Page 86
This statement def	ines parameters that can be used in subsequent statements and element lines.	

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.PLOT	Plot Specification	Page 88
The plot specification one way to view the	on controls the information that is plotted in the output file as a character plo e result of various analyses.	ot. This is
.PRINT	Print Specification	Page 92
The print specificat	ion controls the information that is reported as the result of various analyses.	
.PROBE	Data Output Specification, PSPICE Only	Page 98
This statement save	es the node voltages and device currents in a file for subsequent interactive plo	tting
.SUBCKT	Subcircuit Statement	Page 103
Indicates the start	of a subcircuit description and describes int interface to the subcircuit.	
.TEMP	Temperature Specification	Page 105
Specifies the tempe	rature(s) to perform the analysis at.	
.TEXT	Text Parameter Definition, PSPICE Only	Page 106
.WATCH	Watch Analysis Statement PSPICE Only	Page 111
.WIDTH	Width Specification	Page 114
Specifies the column	n width for the output file.	

#### 5.3.3 Elements

The general form for elements is device name, followed by a list of nodes, followed by the numeric value of the element, followed in some cases by the name of a model, and then by other keywords:

Name Node1 Node2 ... NodeN NumericValue ModelName

+ keyword=NumericValue ... InitialConditions.

For some elements initial conditions (*InitialConditions*) can also be specified which can be used to ensure that the desired initial state of astable circuits is obtained and also to aid in convergence. The first letter of the *Name* identifies the element. For example, if *Name* is **RTEST** then the element is a resistor.

The general form above is not the form for every element. The way in which SPICE evolved resulted in the syntax for element lines not being fully consistent. Commercial extensions, as with PSPICE, allowing alphabetic names for nodes rather than just an integer designation also result in syntaxical problems. With this extension it is not possible to use the fact that a field was alphabetic to distinguish between a node and a parameter name. However this change has necessitated no change to the the standard syntax as defined by SPICE2G6. The problem appears in conjunction with other extensions which allow for an arbitrary number of nodes in some statements. The result is that the syntax can be slightly different than would be expected. For these reasons the description of the form of a particular element or statement must be consulted to ensure that the syntax is correct.

#### **Passive Elements**

The passive devices supported in SPICE2G6, SPICE3 and PSPICE and where their descriptions can be found are as follows:

$\mathbf{C}$	Capacitor	Page 149
Κ	Mutual Inductor	Page 181
L	Inductor	Page 187
R	Resistor	Page 236

S	Voltage Controlled Switch	 Page 239
W	Current Controlled Switch	 Page 254

#### **Active Elements**

Form

Qname NCollector NBase NEmitter	[NSubstrate] Mod	lelName [Area] [OFF]
+ [IC= <i>Vbe</i> , <i>Vce</i> ]		

Unlike passive devices active devices can not be specified by one or a few parameter values. Since many of the parameter values are the same for many devices it is convenient to specify them in a .MODEL statement that can be reused many times. All active elements require a .MODEL statement and most allow an optional substrate node to be used on the element line.

The active devices supported in SPICE2G6, SPICE3 and PSPICE and where their descriptions can be found are as follows:

В	GaAs MESFET (PSPICE only)	Page 118
	(See Z element for Spice3equivalent)	264
D	Diode	Page 152
J	Junction Field-Effect Transistor	Page 175
М	MOSFET	Page 189
Ζ	MESFET	Page 264
(See	e B element for PSPICE equivalent)	118

## 5.3.4 Distributed Elements

The distributed devices and where they are described are as follows:

The convolution element enables a linear circuit described by a set of frequency dependent complex y parameters to be included in transient analysis.

Т	Transmission Line	•••••••••••••••••••••••••••••••••••••••	Page	242
U	Lossy RC Transmission Line			??

## 5.3.5 Source Elements

The sources supported and where they can be found are as follows:

Е	Voltage-Controlled Voltage Source	 Page 156
F	Current-Controlled Current Source	 Page 160
G	Voltage-Controlled Current Source	 Page 162
Н	Current-Controlled Voltage Source	 Page 166

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#### 5.4. INPUT GRAMMAR

Ι	Independent Current Source	 Page 168
V	Independent Voltage Source	 Page 246

The control of the E, F, G and H elements can be control by a polynomial function of voltage or current.

### 5.3.6 Interface Elements

The interface elements supported and where they can be found are as follows:

Ν	Digital Input Interface, PSPICE only	Page 221
Interfac	ces digital analog simulation by providing a means for a state transistion to control an analog	response.
0	Digital Output Interface, PSPICE only	Page 224
Determ	ines the equivalent digital state of an analog signal.	
Р	Port Element	Page 226
Element versions	t enabling the scattering parameters of a circuit to be directly calculated. (Available in c s of SPICE.	only a few
U	Digital Device	??
Х	Subcircuit Call	Page 257
Interfac	ces a circuit (or subcircuit) to a subcircuit.	

## 5.4 Input Grammar

Each input line contains fields which are delimited (separated) by one of a number of characters. The most obvious delimiter is simply a space but other characters are also treated as "*white space*" characters. White space is defined as one or any combination of the following characters:

"blank" "tab" (), = While the above characters appear in the input file they are ignored except that they are treated as a field delimiter. The "(", ")", "=" and "," characters are often used in the input file and are included in specifying the syntax for elements and statements but they serve only to add visual structure to the input.

Continuation lines begin with a plus "+" in the first column. For example

R1 1 2 1000 and R1 1 2 +1000

are equivalent.

Comment lines begin with an asterisk "\*" in the first position. In line comments are supported in PSPICE and these begin with a semicolon ";" and must be contained wholly on one line. For example \* This just shows off a comment

R1 1 2 1000 ;This shows of an in line comment

In nearly every situation where a numeric value is required in the input an algebraic expression can be used instead. Everything between a "{" character and the matching "}" character is treated as an algebraic expression. The evaluation of algebraic expressions are discussed in the ALgebraic Expressions section on on page ??.

#### 5.4.1 Prefixes and Units

Almost-standard metric prefixes are used in SPICE, the prefix abbreviation, the full metric name, and the represented scale factors being as follows:

Spice	Metric	Scale	
Prefix	Name	Factor	
F	femto	$10^{-15}$	
Р	pico	$10^{-12}$	
Ν	nano	$10^{-9}$	
U	micro	$10^{-6}$	
Μ	milli	$10^{-3}$	
Κ	kilo	$10^{+3}$	
MEG	mega	$10^{+6}$	
G	giga	$10^{+9}$	
Т	tera	$10^{+12}$	

As SPICE does not differentiate between upper and lower case, 'MEG' (or 'meg') is used for 'mega' instead of the standard metric upper case 'M'.

The value of an element is specified in terms of the conventionally accepted units, e.g. resistance in Ohms, capacitance in Farads, and inductance in Henries. If you wish you can spell it out more fully, e.g.

C1	0	2	5fF	or
C1	0	2	5fFarad	or even
C1	0	2	5fthingies	

The last alternative is allowed as SPICE actually ignores whatever follows the 'f' and assumes Farads.

## 5.5 Parameters

Parameters can be defined in two ways:

- In a parameter definition (.PARAM).
- As a subcircuit parameter in a .SUBCKT statement.

Parameters defined in a .PARAM statement can be used in subsequent statements and element lines by replacing a numeric value by an expression in which the parameter is used. The general form of the .PARAM statement is .PARAM [ParameterName = NumericValue ...]

+ [ParameterName = { Expression }  $\dots$  ]

Here the *ParameterName* is the name of a parameter with the first character being alphabetic (a-zA-Z) and can be assigned a numeric value *NumericValue* which may be followed immediately by a spice scale factor. For example, SMALL=1.E-9, SMALL=+1N, SMALL=1NV and SMALL=1.E-9V are equivalent and all establish a parameter SMALL with a value of  $10^{-9}$ . If *ParameterName* is the name of a previously defined parameter at the same level of subcircut expansion then the parameter value is changed. If the .PARAM statement is is in the top level circuit then the parameter value is global and is available any where in the netlist. If the .PARAM statement is in a subcircuit then the parameter value is local and can be used at the current subcircuit expansion level or lower in the subcircuit expansion hierarchy. The same idea applies to values of a parameter changed in a subcircuit. Value changes are local and are available in the current subcircuit and lower nested subcircuits. Libraries are searched for parameters not defined in the circuit NETLIST or in included files. A .PARAM statement does not have to be within a subcircuit in a library.

Instead of a numeric value an algebraic expression can be used to establish the value of the parameter. The expression is evaluated in the standard way for an algebraic expression replacing numeric values and is evaluated at the time of expansion rather than as the netlist is read. This ensures the correct hierarchical interpretation of the netlist. The treatment of expression is discussed in section 5.6 on page 46. Note that as always the expression must be enclosed in matching braces ( $\{ \dots \}$ ).

Parameters can be used nearly anywhere a numeric value is expected by including them in an expression evaluation even if the expression contains a single parameter. For example .PARAM rbig=10MEG

R1 1 2 {RBIG}

establishes a resistance R1 between nodes 1 and 2 with a value of  $10^6 \Omega$ .

Several predefined parameters are supported and the user must avoid defining these as unpredictable results may result. The predefined parameters are

Name	Value	Description
TEMP	not supported Reserved for future expansion	Analysis temperature.
VT	not supported Reserved for future expansion	Thermal voltage.

## 5.6 Expressions

In PSPICE most places where a numeric value is normally used an expression (within braces  $\{ \dots \}$ ) can be used instead. An expression can contain any supported mathematical operation, constant numeric values or expressions. Exceptions are

- Polynomial coefficients.
- $\bullet\,$  The values of the transmission line device parameters NL and F.
- The values of the piece-wise linear characteristic in the PWL form of the independent voltage (V) and current (I) sources.
- The values of the resistor device parameter TC.
- As node numbers.

#### and

• Values of most statements (such as .TEMP, .AC, .TRAN etc.)

Specifically included are

- The values of all other device parameters.
- The values in .IC and .NODESET statements.
- The values in .SUBCKT statements.

#### and

 $\bullet\,$  The values of all model parameters. F.

Operators that can be used in expressions are listed in Table 5.1.

#### 5.6. EXPRESSIONS

Operator	Syntax	Description
PLUS	x+y	plus
MINUS	x-y	minus
UNARY_PLUS	+ <i>x</i>	unary plus
UNARY_MINUS	-x	unary minus
MULTIPLY	x*y	multiply
DIVIDE	y/x	divide
POW	<i>xy</i> or <i>x</i> ** <i>y</i>	raise to a power, $x^y$
AND	x& y	AND
OR	$x \mid y$	OR
NOT	!x	NOT
XOR	x y	XOR (exclusive or)
SIN	sin(x)	sine, argument in radians
COS	$\cos(x)$	cosine, argument in radians
TAN	$\tan(x)$	tangent, argument in radians
ASIN	asin(x)	arcsine, argument in radians
ACOS	acos(x)	arccosine, argument in radians
ATAN	atan(x)	arctangent, argument in radians
SINH	$\sinh(x)$	hyperbolic sine
COSH	$\cosh(x)$	hyperbolic cosine
TANH	tanh(x)	hyperbolic tangent
EXP	$\exp(x)$	exponentiation, $e^x$
ASINH	asinh(x)	arc-hyberbolic sine
ACOSH	acosh(x)	arc-hyberbolic cosine
ATANH	atanh(x)	arc-hyberbolic tangent
ABS	abs(x)	absolute, $ x $
SQRT	sqrt(x)	square root, $\sqrt{x}$

Table 5.1: Expression operators.

## 5.6.1 Polynomials

Polynomial expressions can be used with the controlled source elements (E, F, G and H) to realize nonlinear controlled sources. The specification of the polynomial must be at the end of the input line and has two forms. The polynomial format for a voltage-controlled current source (the G element) or a voltage-controlled voltage source (the E element) is

POLY(N) 
$$(N_{C1+}, N_{C1-})$$
 ...  $(N_{CN+}, N_{CN-})$   $C_0$   $C_1$   $C_2$   $C_3$  ... where

- POLY is the keyword indicating that a polynomial description follows.
  - N is the degree of the polynomial.
- $N_{C1+}, N_{C1-}$  The voltage at the node  $N_{C1+}$  with respect to the voltage at the node  $N_{C1-}$  is the controlling voltage  $V_1$ .
- $N_{CN+}$ ,  $N_{CN-}$  The voltage at the node  $N_{CN+}$  with respect to the voltage at the node  $N_{CN-}$  is the controlling voltage  $V_N$ .
  - $C_0 C_1 \dots$  are the polynomial coefficients. Not all of the coefficients need be specified as the trailing coefficients that are not specified are treated as if they are zero.

Note that in spice parentheses, "(" and ")", and commas, ",", are treated as if they are spaces. The use of parentheses and commas serves only to make the netlist more easily read. The exception to this is their use in expressions (see section 5.6).

For voltage-controlled elements the output is calculated as

A one dimensional polynomial (with only one pair of controlling nodes) is evaluated as

OUTPUT = 
$$C_0 + C_1V_1 + C_2V_1^2 + C_3V_1^3 + \dots + C_NV_1^N$$

An example of a voltage-controlled voltage source is

E1 2 3 POLY(2) (10,0) (12,2) 0.5 1 1 0.2 0.3 0.2

and of a voltage-controlled current source is

G1 2 3 POLY(4) (10,0) (12,2) (11,0) (13,0) 0.5 1 1 1 1 0.2 0.3 0.2

The format for a current-controlled current source (the F element) or a current-controlled voltage source (the H element) is

#### 5.7. FUNCTION DEFINITION .FUNC PSPICE ONLY

POLY(N)  $VoltageSourceName_1 \ldots VoltageSourceName_N C_0 C_1 C_2 C_3 \ldots$  where

POLY is the keyword indicating that that a polynomial description follows.

N is the degree of the polynomial.

 $VoltageSourceName_1$  is the name of the voltage source the current through which is control current  $I_1$ .  $VoltageSourceName_N$  is the name of the voltage source the current through which is control current  $I_N$ .

 $C_0 C_1 \ldots$  are the polynomial coefficients.

For these elements the output is calculated as

An example of a current-controlled voltage source is:

H1 2 3 POLY(2) VIN V2 0.5 1 1 0.2 0.3 0.2

and of a current-controlled current source is:

F1 2 3 POLY(4) VIN V2 (11,0) (13,0) 0.5 1 1 1 1 0.2 0.3 0.2

#### 5.6.2 Laplace Expressions

5.6.3 Chebyschev

## 5.7 Function Definition .FUNC PSPICE Only

The .FUNC statement can be used to conveniently define commonly used expressions.

.FUNC FunctionName( [Argument1, Argument2, ... Argument10] ] ] ) = Function-Declaration

*FunctionName* is the name of the function being defined. It must begin with an alphabetic character (A-Z).

Argument1 is a function argument. There can be from 0 to 10 arguments.

FunctionDeclaration can be any regular algebraic expression (see section ?? on page ??) and can use previously defined functions and the Laplace variable s. The expression delimiters { and } need not be used. The FunctionDeclaration is automaticly enclosed within the expression delimiters { and }. The function declaration plus the two delimiters must be no more than 80 characters (one line) long.

The names of predefined functions must be avoided. The predefined functions are listed in section ?? on page ??.

Functions are treated as macros in the C programming language. when user defined functions are invoked a textual expansion is performed and the resultant expansion is evaluated as a regular expression. The FunctionDeclaration before and after expansion is enclosed within expression delimiters { and }. This defines how nested functions are treated.

It is faster to use predefined functions if available. Predefined functions also test the validity of the arguments and evaluate the correct asymptotic behavior.

## 5.8 Syntax Variations

Commercial versions have enhanced the syntax of Berkeley version of SPICE. In virtually all cases the syntax of SPICE2G6 and SPICE3 is a subset of the syntax of commercial versions of SPICE. Here we list some exceptions.

• Units. Spice does not allow units immediately following a quantity. For example, the following is acceptable in all versions.

VIN 1 0 DC 4 VIN 1 0 DC 4UV For example, the following is not acceptable in all SPICE2G6 and SPICE3 VIN 1 0 DC 4V

but is acceptable in HSPICE, PSPICE and SOMEVERSIONSOFSPICE.

# Chapter 6

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## Conventions

Square brackets "[ ... ] "indicate an optional quantity. Italics indicate a quantity that is replaced by a specific value.

.AC	AC Analysis
.AU	AC Analysis

The .AC statement initializes an AC small-signal analysis sweeping the frequency of the independent voltage and current sources.

Form

.AC DEC FrequenciesPerDecade FStart FStop

.AC OCT FrequenciesPerOctave FStart FStop

**DEC** is the decade sweep keyword specifying that the frequency  $F_1$  is to be swept logarithmically by decades.

FrequenciesPerDecade specifies the number of frequencies per decade.

**OCT** is the octave sweep keyword specifying that the frequency is to be swept logarithmically by octaves.

FrequenciesPerOctave specifies the number of frequencies per octave.

LIN is the linear sweep keyword specifying that the frequency is to be swept linearly.

NumberPoints specifies the total number of frequencies in a linear sweep.

FStart is the starting frequency of the frequency sweep. (Units: Hz; Required; FStart > 0)

FStop is the stopping frequency of the frequency sweep. (Units: Hz; Required;  $FStop \ge FStart$ )

#### Example

.AC DEC 10 1kHz 100Mhz .AC DEC 10 1kHz 100Mhz

#### Note

- 1. A DC analysis is automatically performed prior to an AC small-signal analysis to find the operating point. Using the DC values of voltage and current at the operating point the linearized, small-signal models of nonlinear devices are determined.
- 2. In AC analysis voltage sources without AC specifications are shorted and current sources without AC specifications are opened.

<sup>.</sup>AC LIN NumberPoints FStart FStop

## COMMENT

## Comment Card

Used to insert a comment in the circuit NETLIST. Form

\* a comment string

Note

- 1. A comment line begins with an asterisk "\*" in the first position of the line. There can be no leading white space.
- 2. Comment lines can appear anywhere in the input file and are ignored except that they are echoed in the output log file.
- 3. In PSPICEcomments can appear anywhere on following a semicolon ";". The remainder of the line (following the ";") is ignored except for purposes of echoing the input NETLIST in the log file.

.DC	DC Analysis
.DC	DC Analysis

In DC analysis the DC operating point of a circuit is determined for a range of values of up to two independent voltage or current sources.

Form

.D	C SourceName	1 StartValue1	Stop Value 1	ValueIncrement1
+	[SourceName2	StartValue2	Stop Value 2	ValueIncrement2]

#### PSPICEForm

.DC [LIN] Sweep VariableName1 StartValue1 StopValue1 ValueIncrement1 + [SourceName2 StartValue2 StopValue2 ValueIncrement2]

.DC DCT SweepVariableName1 StartValue1 StopValue1 PointsPerOctave1 + SweepVariableName2 StartValue2 StopValue2 PointsPerOctave2 ]

.DC DEC SweepVariableName1 StartValue1 StopValue1 PointsPerDecade1 + SweepVariableName2 StartValue2 StopValue2 PointsPerDecade2 ]

.DC Sweep VariableName1 LIST Value<sub>1,1</sub> [Value<sub>1,2</sub> ... Value<sub>1,N</sub>]

+ [Sweep VariableName2 LIST Value<sub>2,1</sub>] Value<sub>2,2</sub> ... Value<sub>2,N</sub>]]

- SourceName1 is the name of the first independent voltage (V element) or current (I element) source the value of which will be swept.
  - StartValue1 is the starting value of the sweep of the first voltage or current source.
  - Stop Value1 is the final value of the sweep of the first voltage or current source.
- ValueIncrement1 is the increment by which the value of the first voltage or current source is incremented.
  - SourceName2 is the name of the first independent voltage (V element) or current (I element) source the value of which will be swept.
    - Start Value2 is the starting value of the sweep of the second voltage or current source.
    - Stop Value2 is the final value of the sweep of the second voltage or current source.
- ValueIncrement2 is the increment by which the value of the second voltage or current source is incremented.
  - LIN is the linear sweep keyword. This is the default sweep type.
  - **DCT** is the octave sweep keyword specifying that the sweep variable or variables is to be swept logarithmically by octaves.
  - **DEC** is the decade sweep keyword specifying that the sweep variable or variables is to be swept logarithmically by decades.
- *PointsPerOctave1* is the number of points per octave in a OCT sweep type for the first sweep.
- *PointsPerDecade1* is the number of points per decade in a DEC sweep type for the first sweep.
- *PointsPerOctave2* is the number of points per octave in a OCT sweep type for the second sweep.
- *PointsPerDecade2* is the number of points per decade in a DEC sweep type for the second sweep.
- Sweep VariableName1 is the name of the first sweep variable. The sweep variable can be:
  - 1. the name of an independent voltage or current source. The *DCvalue* of the source is swept.
  - 2. the name of a parameter of a specific model specified in the form *ModelName(ParameterKeyword)*. For example to sweep the IS parameter of an NPN model of name MYNPN the *Sweep-VariableName* would be MYNPN(IS).
  - 3. the keyword TEMP which indicates that the analysis temperature in °C is swept. The model parameters are updated for each sweep value.
- SweepVariableName2 is the name of the second sweep variable. The properties are as for SweepVariable-Name1 as described above.
  - LIST indicates that the value of the *SweepVariable* will take the values, in order, in the following list rather than be swept.
  - $Value_{i,j}$  the *j*th value to be assigned to the *i*th sweep variable.

Example

<sup>.</sup>DC VIN 0.25 5.0 0.25 .DC VDS 0 10 .5 VGS 0 5 1 .DC VCE 0 10 .25 IB 0 10U 1U

#### DC Analysis

#### **PSPICE** Example

.DC VIN 0.25 5.0 0.25 .DC VDS 0 10 .5 VGS 0 5 1 .DC VCE 0 10 .25 IB 0 10U 1U .DC LIN VCE 0 10 .25 IB 0 10U 1U .DC DEC MYNPN(IS) 1.E-15 1.e-17 3 .DC TEMP -25 0 25 50 75 100 VIN 0.25 5.0 0.25

Note

- 1. The .DC statement initiates a DC operating point analysis.
- 2. In the DC analysis inductors are shorted and capacitors are open circuited.
- 3. A DC analysis over a range of source conditions can be used to produce the transfer characteristic of a circuit or current-voltage characteristics of a semiconductor device such as a transistor. An example of determining the transfer characteristic of an operational amplifier is given in section 8.5.1. An example of determining the current-voltage characteristics of a transistor is in section 8.5.1.
- 3 A DC analysis over a range of source conditions can also be used to provide biasing information in circuit design.
- 4 The specified independent voltage or current source or sources are stepped over a user-specified range and the DC output variables indicated by the .PRINT statement are stored for each source value.
- 5 When two sources are specified the first source is swept over its range for each value of the second source. For example, consider

.DC VDS 0 10 5 VGS 0 5 2.5 rements For each value of VGS V

VGS is swept from 0 to 5V in 2.5V increments. For each value of VGS VDS is swept from 0 to 10V in 5V increments so that that 9 DC analyses performed are

	RUN	VDS	VGS
ſ	1	0	0
	2	5	0
	3	10	0
	4	0	2.5
	5	5	2.5
	6	10	2.5
	7	0	5
	8	5	5
L	9	10	5

- 6 When the sweep is completed the original values are restored.
- 7 The sweep can go in either direction. That is, *StartValue* can be less than or greater than *StopValue* but *ValueIncrement* must be positive.

## .DISTO

## Small-Signal Distortion Analysis

In distortion analysis the steady-state harmonic and intermodulation products for small input signal are computed as a part of an AC analysis. One or two excitation frequencies,  $F_1$  and  $F_2$  may be specified. If only one excitation frequency,  $F_1$ , is specified the program evaluates the second and third harmonic distortions. If a second excitation frequency,  $F_2$ , is specified the three lowest order intermodulation distortion components are evaluated as well.

Form

```
.DISTO ResistorName [OutputInterval [F_2OverF_1 \ [F_1ReferencePower + [F_2ReferencePower]]]]
```

SPICE3Form

.DISTO DEC FrequenciesPerDecade  $F_1$ Start  $F_1$ Stop  $[F_2OverF_1]$ .DISTO OCT FrequenciesPerOctave  $F_1$ Start  $F_1$ Stop  $[F_2OverF_1]$ .DISTO LIN NumberPoints  $F_1$ Start  $F_1$ Stop  $[F_2OverF_1]$ 

- *ResistorName* the name of the output resistor. The power dissipated in this resistor is reported as the distortion measures. SPICE2G6 only.
- OutputInterval is the optional output reporting interval at which distortion components produced by all nonlinear components is reported. By default, or if omitted no detailed output is produced. SPICE2G6 only.
- $F_1ReferencePower$  power level of  $F_1$ . SPICE2G6 only. (Units: W; Optional; Default: 1.0E-3 (i.e. 1 mW or 1 dBm))
- $F_2ReferencePower$  power level of  $F_2$ . SPICE2G6 only. (Units: W; Optional; Default: 1.0E-3 (i.e. 1 mW or 1 dBm))
  - **DEC** is the decade sweep keyword specifying that the frequency  $F_1$  is to be swept logarithmically by decades.

Frequencies PerDecade specifies the number of frequencies per decade.

**DCT** is the octave sweep keyword specifying that the frequency  $F_1$  is to be swept logarithmically by octaves.

FrequenciesPerOctave specifies the number of frequencies per octave.

LIN is the linear sweep keyword specifying that the frequency  $F_1$  is to be swept linearly.

*NumberPoints* specifies the total number of frequencies in a linear sweep.

 $F_1Start$  is the starting frequency of the  $F_1$  sweep.

 $F_1Stop$  is the stopping frequency of the  $F_1$  sweep.

 $\begin{array}{l} F_2 \mathit{Over} F_1 & \text{is the ratio of } F_2 \text{ to } F_1. \\ & \text{In SPICE3} \text{, if } F_2 \mathit{Over} F_1 \text{ is omitted an harmonic analysis only is reported.} & \text{Otherwise} \\ & F_2 = F_2 \mathit{Over} F_1 \mathit{F_1} \mathit{Start} \\ & \text{In SPICE2G6} \text{, if } F_2 \mathit{Over} F_1 \text{ is omitted it defaults to } 0.9. \\ & F_2 = F_2 \mathit{Over} F_1 \mathit{F_1} \end{array}$ 

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#### Small-Signal Distortion Analysis

 $F_2 Over F_1$  should be an irrational number between 0.0 and 1.0. If it is a rational number the signals at  $F_1$  and  $F_2$  are harmonically related and the spectral analysis may in error. Since an irrational number can not actually be specified care should be excercised in choosing  $F_2 Over F_1$  so that  $F_1$  and  $F_2$  are not simple multiples of each other. For example, use 0.498 instead, if you want to set  $F_2 Over F_1$  to 0.5. The rule to follow is to keep the denominator in the fractional representation of  $F_2 Over F_1$  as large as possible with at least three digits for accurate results.

#### Example

.DISTO DEC 10 1kHz 100Mhz .DISTO DEC 10 1kHz 100Mhz 0.9

#### Note

- 1. In SPICE2G6 the distortion analysis must be performed in conjunction with an AC analysis. The .AC statement (see page 53) specifies the sweep parameters for  $F_1$ .
- 2. In SPICE3 the distortion analysis is also performed in conjunction with the AC analysis specified by the .AC statement. The amplitudes and relative phases of the input distortion components are specified in the .AC statement as the arguments of the DISTOF1 keyword for  $F_1$  and of the DISTOF2 keyword for  $F_2$ . This enables several sources to generate components at  $F_1$  and/or  $F_2$ . If the DISTOF1 or DISTOF2 keywords are missing from a source then this source is assumed to have no input at  $F_1$  or  $F_2$  respectively.

When a spectral analysis is performed (both  $F_1$  and  $F_2$  specified) the circuit is treated as having sinusoidal inputs at two different frequencies  $F_1$  and  $F_2$ .  $F_1$  is swept but  $F_2$  is fixed at  $F_2 OverF_1 FStart$ . Each independent source in the circuit can have two inputs at  $F_1$  and  $F_2$  for distortion analysis.

#### Note

- 3 Distortion analysis is not valid if switches (if present) change state under the small excitations used for distortion calculations.
- 4 Evaluation of the small-signal distortion of a circuit is based on a multi-dimensional Volterra series analysis. The nonlinearities are expanded in a third order multi-dimensional Taylor series around the operating point determined from an operating point (DC) analysis. Using this analysis the distortion components are evaluated symbolically

5 In SPICE2G6 the following distortion components are evaluated.

HD2	-	the magnitude of the second harmonic at frequency $2F_1$	
		assuming that $F_2$ is not present.	
HD3	-	the magnitude of the third harmonic at frequency $3F_1$ as-	
		suming that $F_2$ is not present.	
SIM2	-	the magnitude of the sum frequency $F_1 + F_2$	
DIM2	-	the magnitude of the difference frequency $F_1 - F_2$	
DIM3	-	the magnitude of the third order intermodulation fre-	
		quency $2F_1 - F_2$	

- 1. In SPICE3 the complex values of the above distortion components are computed at all nodes in the circuit. The distortion components at any node can be reported using the .PRINT statement (discussed on page 92) or the .PLOT statement (discussed on page 88). The running variable in the output is the frequency  $F_1$ .
- 2. The quantities reported are the actual AC voltages and currents and must be normalized by the user to the sources at  $F_1$  and  $F_2$  to obtain true distortion measures.
### .DISTRIBUTION

Distribution Specification

The .DISTRIBUTION statement specifies the statistical tolerance distribution used in Monte Carlo analysis (see the .MC statement on page 69). PSPICEForm

.DISTRIBUTION DistributionName (Deviation1, Probability1) + (Deviation2, Probability2) [(Deviation3, Probability3) ...]

*DistributionName* is the name the user assigns to the distribution defined by the succeeding values.

Deviation Relative deviation from nominal value.  $(-1 \le Deviation \le 1).$ 

 $\begin{array}{ll} Probability & \text{Probability of preceding deviation.} \\ & (Probability \geq 0) \end{array}$ 

- 1. Parentheses, '(' and ')', and commas, ',', in the NETLIST are ignored and are generally used to make the NETLIST more readable.
- 2. The pairs of values (*Deviation*, *Probability*) define a piecewise linear probability distribution curve used in calculating the random numbers used in Monte Carlo analysis.
- 3. The *Deviations* must be in ascending order: *Deviation1 < Deviation2 < Deviation3 < ...*
- 4. 100 (Deviation, Probability) pairs can be specified.

# .END End Statement

This statement indicates the end of the NETLIST of a circuit. While it is often inserted automatically by most SPICE simulators when the last statement of the NETLIST is read and it is not .END its usage is recommended as several circuits in one file are supported by some versions of SPICE including PSPICE. Form

.END

## .ENDS

The end subcircuit statement indicates the end of a subcircuit definition. Form

.ENDS [SubcircuitName]

SubcircuitName Indicates which subcircuit is being terminated. If omitted, all subcircuits being defined are terminated. Its use is required when nested subcircuit definitions are being made. It is good practise to use the full form of .ENDS.

Example

.ENDS NAND\_GATE

Note

1. See the definition of .SUBCKT on page 103.

## .FOUR

### Fourier Analysis

The Fourier analysis statement initiates a Fourier analysis of the results of a transient analysis. Form

.FOUR Frequency OutputSpecification [OutputSpecification ...]

- *Frequency* specifies the fundamental frequency of the transient waveform to be analyzed. It is used to determine the period of the waveform.
- *OutputSpecification* specifies the quantity to be reported as the result of the Fourier Analysis. It has the same format as the *OutputSpecification* in a .PRINT statement (see page 92).

Example

.FOUR 1M V(10,2) V(5) I(VLOAD)

- 1. Fourier analysis uses the transient output waveform in the time interval from TSTOP T to TSTOP. T is the period of the *Frequency* parameter (T = 1/Frequency) specified in the .FOUR statement. TSTOP is the final transient analysis time specified in the .TRAN statement (which is described on page 109.
- 2. Unlike most other analyses, a .PRINT, .PROBE or .PLOT statement is not required for the data to be reported.

## .FUNC

### Function Definition

In this statement commonly used expressions can be defined as more convenient functions.  $\operatorname{PSPICE}\!Form$ 

.FUNC FunctionName( [Argument1, Argument2, ... Argument10] ] ] ) = FunctionDeclaration

FunctionName is the name of the function being defined. It must begin with an alphabetic character (A-Z).

Argument1 is a function argument. There can be from 0 to 10 arguments.

FunctionDeclaration can be any regular algebraic expression (see section ?? on page ??) and can use previously defined functions and the Laplace variable s. The expression delimiters { and } need not be used. The FunctionDeclaration is automatically enclosed within the expression delimiters { and }. The function declaration plus the two delimiters must be no more than 80 characters (one line) long.

Example

.FUNC

- 1. The names of predefined functions must be avoided. The predefined functions are listed in section ?? on page ??.
- 2. Functions are treated as macros in the C programming language. when user defined functions are invoked a textual expansion is performed and the resultant expansion is evaluated as a regular expression. The FunctionDeclaration before and after expansion is enclosed within expression delimiters { and }. This defines how nested functions are treated.
- 3. It is faster to use predefined functions if available. Predefined functions also test the validity of the arguments and evaluate the correct as asymptotic behavior.

### Initial Conditions

The .IC statement is used to set initial conditions for transient analysis. It has no effect on other types of analyses.

Form

.IC V(NodeName1) = Voltage1 [V(NodeName2) = Voltage2 ... ]

V is the keyword specifying a node voltage

NodeName is the name of a node. Note that in SPICE2G6 and SPICE3 NodeName must be an integer.

*Voltage* is a numeric value.

#### Example

.IC V(11)=4.9 V(2)=2.5

Note

- 1. Initial conditions can be specified for the following elements: B (MESFET), C (capacitor), D (diode), Q (BJT), M (MOSFET) and J (JFET)
- 2. The .IC statement has two different effects depending on whether the UIC (use initial conditions) keyword is present on the .TRAN statement.
  - (a) If the UIC keyword is <u>specified</u> in the .TRAN statement: The initial conditions specified in the .IC statement are used to establish the initial conditions. Initial conditions specified for individual elements using the IC parameter on the element line will always have precedence over those specified in a .IC statement. No DC analysis is performed prior to a transient analysis. Thus it is important to establish the initial conditions at all nodes using the .IC statement or using the IC element parameter.
  - (b) If the UIC keyword is <u>not specified</u> in the .TRAN statement: A DC analysis is performed prior to a transient analysis. During the DC analysis the node voltages indicated in the .IC statement are held constant at the initial condition values. During transient analysis the nodes are not constrained to the initial condition values.

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### .IC

### .INC

Include Statement

Form

.INC FileName

Filename is the name of the file which is to be included.

Note

1. The contents of *Filename* are read as if it were part of the original file.

2. Libraries could be included using the .INC statement or by the .LIB statement discussed on page 68. The difference is that the .INC statement includes the contents of the library file (except for comments) in internal data structures. However a .LIB statement causes the library file to be scanned and an index constructed for model (.MODEL) and subcircuit (.SUBCKT) statements. The models subcircuits in the library file are included in internal data structures if they are referred to. Thus the use of .LIB statements is a much more efficient way of using library files leading to both a smaller program and faster library access, especially for large libraries. Library files can only contain models and subcircuits so that the type of files that can be incorporated using a .LIB statement is more restricted than the type of file that can be incorporated using a .INC statement.

### .LIB

### Library Statement

The .LIB statement is an efficient way to include .MODEL statements and subcircuits. Form

.LIB [FileName]

Filename is the name of the library file. (Optional; Default: NOM.LIB)

#### Note

- 1. The library file can only contain a restricted set of SPICE statements. It must contain only .MODEL statements, subcircuit definitions (between .SUBCKT and .ENDS statements), and .LIB statements.
- 2. The library file *Filename* is searched in the current directory and then in a list of directories specified by the environment variable PSPICELIB (for compatibility purposes the environment variable PSPICELIB is also supported).
- 3. If the DOS operating system is being used the library environment specification has the form

**SET PSPICELIB =** *Directory1* [; *Directory2*...]

The environment variable may be set in the AUTOEXEC.BAT file in the root DOS directory or before PSPICE is evoked. For example:

SET PSPICELIB = C:\SPICE\MYLIB;D:\SPICE\TILIB

4. If the UNIX operating system is being used the library environment specification has the form

setenv PSPICELIB = Directory1 [; Directory2...]

For example:

setenv PSPICELIB = /SPICE/MY\_LIB; /SPICE/TI\_LIB

5. Libraries could be included using the .INC statement or by the .LIB statement. The difference is that the .INC statement includes the contents of the library file (except for comments) in internal data structures. However a .LIB statement causes the library file to be scanned and an index constructed of model (.MODEL) and subcircuit (.SUBCKT) statements. The models subcircuits in the library file are included in internal data structures only if they are referred to. Thus the use of .LIB statements is a much more efficient way of using library files leading to both a smaller program and faster library access, especially for large libraries.

## Monte Carlo Analysis

The Monte Carlo analysis is a statistical analysis of the circuit causing the circuit to be analyzed many times with a random change of model parameters (parameters in a .MODEL statement). PSPICEForm

- .MC NumberOfRuns AnalysisType OutputSpecification OutputFunction [LIST]
- + [OUTPUT( *OutputSampleType*)]

**PSpice**Form

.MC

- .MC NumberOfRuns AnalysisType OutputSpecification OutputFunction [LIST]
- + [OUTPUT( *OutputSampleType*)] [RANGE(*LowValue*, *HighValue*)]
- + [SEED=SeedValue]

Number OfRuns is the total number of runs to do. This number includes the initial nominal run.

- AnalysisType is the type of analysis to be performed in the Monte Carlo runs after the initial nominal run (using the nominal values of model parameters). All analyses specified in the NETLIST are performed in the nominal run. The AnalysisType must be one of the following:
  - DC is a keyword indicating that the DC analysis as specified by the .DC statement is repeated. The sweep variable used in analyzing the output *OutputSpecification* is the value of the independent voltage or current source specified in the .DC statement (as discussed on page 55).
  - AC is a keyword indicating that the AC small-signal analysis as specified by the .AC statement is repeated. The sweep variable used in analyzing the output *OutputSpecification* is frequency.
  - TRAN is a keyword indicating that the transient analysis as specified by the .TRAN statement is repeated. The sweep variable used in analyzing the output *OutputSpecification* is time.

OutputSpecification specifies the quantity to be reported as the result of the Monte Carlo Analysis. It has the same format as the OutputSpecification in a .PRINT statement (see page 92). The result is the value of the OutputSpecification with respect to a sweep for DC and AC analysis, and as a waveform for TRAN analysis.

- OutputFunction indicates the function to be performed on the output indicated by OutputSpecification to reduce the sweep or waveform at each run to a single numeric value. The OutputSpecification must be one of the following keywords:
  - YMAX which produces the greatest deviation of the sweep or waveform from the nominal run.
  - MAX which results in the maximum value in each sweep or waveform.
  - MIN which results in the minimum value in each sweep or waveform.
  - RISE\_EDGE(Value) which reports as the result the first run when the waveform crosses above the threshold Value. The algorithm used requires that one point in the waveform be below Value and the succeeding point be above Value.
  - FALL\_EDGE (Value) which reports as the result the first run when the waveform crosses below the threshold Value. The algorithm used requires that one point in the waveform be above Value and the succeeding point be below Value.
  - LIST is an optional keyword that results in the model parameter values that are statistically varied being printed out prior to each run. If it is omitted then the statistically generated model parameter values are not produced prior to each run.
  - OUTPUT is an optional keyword indicating the type of output to be produced by runs after the initial nominal run. The output produced for each run sampled is determined by the .PLOT, .PRINT and .PROBE statements in the NETLIST. If this keyword is missing output is produced only for the nominal run.
- OutputSampleType indicates the method by which runs are selected for output reporting. The output produced for each run selected is determined by the .PLOT, .PRINT and .PROBE statements in the NETLIST. OutputSampleType must be one of the following:
  - ALL indicates that the output is to be produced for all runs.
  - FIRST Nruns indicates that the output is to be produced only for the first Nruns runs.
  - EVERY NthRun indicates that the output is to be produced for NthRunth run.
  - RUNS Run1 [Run2 ... [Run25]] indicates that the output is to be produced for the indicated runs. Up to 25 runs can be indicated.
  - **RANGE** is an optional range indicating the range of the sweep variable over which *OutputFunction* is to be performed. If this keyword is missing, output is produced but the range is not restricted. The range of the sweep variable to be considered is from *LowValue* to *HighValue* inclusive.
  - Low Value is the low end of the sweep variable to be considered in evaluating OutputFunction.
  - High Value is the low end of the sweep variable to be considered in evaluating OutputFunction.
    - SEED is the keyword for the seed of the random number generator used in Monte Carlo Analysis
  - SeedValue is the value of the seed used in the random number generator used to select sample runs at random. (Optional; Default: 17,533;  $1 \le SeedValue \le 32,767$ )

- 1. A typical use of Monte Carlo analysis is to predict yield of a circuit by examining the effect of process variations such as length and width of transistors.
- 2. A .TEMP statement also can result in multiple circuit simulations as the temperature is varied. In conjunction with a .MC statement a Monte Carlo analysis is performed for each temperature before the temperature is updated in a temperature sweep.
- 3. Only model parameters (parameters in a .MODEL statement) are varied.
- 4. If the *AnalysisType* is DC only one independent voltage or current source can be specified in the .DC statement (discussed on page 55).
- 5. The random number generator is the subtractive method generator described by Knuth [28, p. 171].
- 6. The initial run uses the nominal parameter values given in the NETLIST. Subsequent runs statistically vary model parameters indicated as having either lot LOT or device DEV tolerances. These tolerances are specified in a .MODEL statement (see page 72).

#### Method

The initial Run of a Monte Carlo Analysis uses the nominal values of the model parameters possibly updated to their new values if the analysis temperature is different from the the nominal temperature in effect when the .MODEL statement was read. The nominal values of the model parameters as well as their tolerances and type of statistical distribution are specified in a .MODEL statement (see page 72). If X(T) is the value of the model parameter at temperature T, r is a random number between -1 and +1 inclusive, and  $X_T$  is the tolerance of  $X(T_{\text{NOM}})$  is the nominal temperature, the value of X to be used in Monte Carlo analysis is

$$X'(T) = X(T)(1 + rX_T)$$
(6.1)

The random number r has a statistical distribution which has a type indicated in the .MODEL statement. The distribution type must be either one of the built-in distributions or specified by the user in a .DISTRIBUTION statement (see page 61). The tolerance is specified immediately following the distribution in a .MODEL statement. Specification of the distribution type and tolerance assignment are described on page 74.

# .MODEL Model Statement

Model statements specify the parameters of elements that either are too numerous to put on the element line or are common to many elements.

Form

.MODEL ModelName ModelType (Keyword=Value ... )

**PSpice**Form

.MODEL ModelName ModelType (Keyword=Value [ToleranceSpecification] ...)

ModelName is the name of the model specified by the user.

- *ModelType* is the model type which is specific to particular elements. The model types are given in the table below.
- *ToleranceSpecification* is the specification of the statistical distribution and tolerance of a parameter. This is used in a Monte Carlo simulation to assign random variations to the model parameter. *ToleranceSpecification* is discussed on page 74.

Keyword is the name of the model parameter which is discussed on the pages referred to below.

Value is the numeric value of the model parameter.

Example

.MODEL MOSFET1 MOS (LEVEL=2 VTO=-0.76 GAMMA=0.6 CGSO=3.35E-10)

MODEL	SPICE		ELEMENT	DESCRIPTION	PAGE		
TYPE	VERSION—		TYPE VERSION—		NAME		
PASSIVE DEVICE MODELS							
RES			R	resistor model	236, 237		
CAP			С	capacitor model	150, 150		
IND	Р	Spice	L	inductor model	187		
		SE	MICONDUCT	OR DEVICE MODELS			
D			D	diode model	152		
NPN			Q	NPN bit model	228		
PNP			õ	PNP bjt model	228		
LPNP	Р	Spice	õ	Lateral PNP bjt model	228		
NJF			Ĵ	N-channel junction FET (JFET)	175		
PJF			J	P-channel junction FET (JFET)	176		
GASFET	Р	Spice	В	N-channel GaAs MESFET	264.118		
NMF	S	PICE3	В	N-channel GaAs MESFET	,		
PMF	SI	PICE3	В	P-channel GaAs MESFET			
NMOS			М	N-channel MOSFET	191		
PMOS			М	P-channel MOSFET	191		
SWMODEL	S	PICE3			??		
URC	RC SPICE3		Т	Lossy RC transmission line	243		
		M	ISCELLANEO	US DEVICE MODELS			
CORE	Р	Spice	Κ	nonlinear, transformer (magnetic core)	183		
VSWITCH	VITCH PSPICE		S	voltage switch	240		
ISWITCH	Р	Spice	W	current switch	254		
SW	S	PICE3			??		
CSW	CSW Spic				??		
		]	DISTRIBUTE	D DEVICE MODELS			
URC	1			Uniform Distributed RC model	243		
MODEI		CDICE	ELEMENT	DECODIDITION	DACE		
MODEI	-	SPICE	ELEMEN I	DESCRIPTION	PAGE		
LIPE		VERSION	NAME				
DINDUT		DIGITAL IN	TERFACE AI	ND DIGITAL DEVICE MODELS	000		
DINPUT	T	PSPICE	IN O	digital input model	222		
	) T	PSPICE	U	digital output model	224		
		PSPICE	U	digital I/O model			
UGALE	,	PSPICE	U	standard gate			
UTGATE		PSPICE	U	tri-state gate			
UEFF		PSPICE		eage-triggerea nip-flop			
UGFF		FF PSPICE		gated nip-nop			
UWDTH	UWDTH			pulse width checker			
USUHD		PSPICE		setup and hold checker			
UDLY		PSPICE DC		digital delay line			
UADC		PSPICE		multi-bit analog-to-digital converter			
UDAC		PSPICE	U	multi-bit digital-to-analog converter			

Virtually all of the device model parameters have default values which generally result in typical operation.

Tolerance and Distribution Assignment

Immediately following the specification of a model parameter a statistical distribution and tolerance can be assigned. These are used in conjunction with Monte Carlo analysis which is controlled by the .MC statement described on page 69 The Monte Carlo analysis is a statistical analysis of the circuit causing the circuit to be analyzed many times with a random change of certain model parameters). The form of the tolerance and distribution assignment is

DEV [/DeviceTrackingIndex] [/DistributionType] Tolerance [%] + LOT [/LotTrackingIndex] [/DistributionType] Tolerance [%]

DEV is the keyword for the device tolerance specification.

DeviceTrackingIndex specifies which random number to use. It must be one of 1, 2, ... 10. Two parameters with the same DeviceTrackingIndex are correlated. Conversely if two parameters have different DeviceTrackingIndex then they are uncorrelated.

LotTrackingIndex and DeviceTrackingIndex refer to different random numbers and so choosing the same LotTrackingIndex and DeviceTrackingIndex does not correlate the LOT and DEV distributions.

(Units: none; Optional; Default: 1)

- Distribution Type is the type of the statistical distribution used in generating random numbers. There are two predefined distribution types and a user specified distribution type can be used. The allowable types are:
  - UNIFORM specifies a uniform distribution of random numbers between -1 and +1.
    - **GAUSS** specifies a Gaussian distribution of random numbers between  $\pm 4\sigma$ . In this case *Tolerance* specifies  $\sigma$ .
  - *DistributionName* is the name of a user specified distribution specified in a .DISTRIBUTION statement (see page 61).
  - Lot Tolerance is the lot tolerance specification. It may be specified as an absolute quantity or as a percentage if followed by %. It is converted to a fraction of the nominal value. The magnitude of the fractional value must be  $\leq 1$ .
    - LOT is the keyword for the lot tolerance specification.
- LotTrackingIndex specifies which random number to use. It must be one of 1, 2, ... 10. Two parameters with the same LotTrackingIndex are correlated. Conversely two parameters have different LotTrackingIndex's then they are uncorrelated. LotTrackingIndex and DeviceTrackingIndex refer to different random numbers and so choosing the same LotTrackingIndex and DeviceTrackingIndex does not correlate the LOT and DEV distributions. (Units: none; Optional; Default: 1)
  DeviceTrackingIndex is the device to be available to be available to be available to be available.
- Device Tolerance is the device tolerance specification. It may be specified as an absolute quantity or as a percentage if followed by %. It is converted to a fraction of the nominal value. The magnitude of the fractional value must be  $\leq 1$ .

.MODEL

74

Example

- 1. Both lot (LOT) and device (DEV) tolerances can be specified separately. Lot and device tolerances combine for the purposes of determining the total tolerance of a model parameter. The sum of device and lot tolerances must be less than the nominal model parameter value (i.e. is less than 100%).
- 2. A total of 20 random number are generated internally. Of these 10 are for lot tolerancing and 10 are for device tolerancing. Parameters with the same lot tolerance index (*LotToleranceIndex*) use the same random number to generate statistical variations and so are fully correlated. Similarly parameters with the same device tolerance index (*DeviceToleranceIndex*) use the same random number. However the random number for a lot and that for a device are always uncorrelated. If X(T) is the value of a model parameter at temperature T,  $R_{\text{LOT}}(LotToleranceIndex)$  is random number for lot variations and  $R_{\text{DEV}}(DeviceToleranceIndex)$  is random number for device variations,  $X_{\text{LOT}}$  is the fractional lot tolerance  $X_{\text{DEV}}$  is the fractional device tolerance, the value used in a Monte Carlo simulation is

 $X'(T) = X(T) \left(1 + R_{\text{LOT}}(LotTrackingIndex)X_{\text{LOT}} + R_{\text{DEV}}(DeviceTrackingIndex)X_{\text{DEV}}\right)$ (6.2)

## .NODESET

### Node Voltage Initialization

Form

.NODESET V(NodeName) = Voltage [V(NodeName) = Voltage ... ]

V is the keyword specifying a node voltage

NodeName is the name of a node. Note that in SPICE2G6 and SPICE3 NodeName must be an integer.

#### Example

.NODESET V(11)=4.9 V(2)=2.5

- 1. This statement can be used if convergence problems are encountered in a DC analysis. For most circuits SPICE will be able to determine the DC voltage or initial transient solution.
- 2. The statement can be used with a stable circuits such as multivibrators and flip flops to ensure that these circuits are initialized in a particular state.

## .NOISE

In noise analysis the noise generated by active devices and resistors is evaluated. Form

 $. \verb"NOISE" Output VoltageSpecification Input SourceName Output Interval$ 

#### SPICE3Form

.NOISE	Output	$VoltageS_{2}$	pecification	InputSourceName	e DEC
--------	--------	----------------	--------------	-----------------	-------

+ FrequenciesPerDecade FStart FStop [OutputInterval]

.NOISE OutputVoltageSpecification InputSourceName OCT + FrequenciesPerOctave FStart FStop [OutputInterval]

· irequenciesi eroceate i start i stop [Outputinterout]

 $. \verb"NOISE" Output VoltageSpecification Input SourceName \verb"Lin" output SourceName" "Lin" output SourceName" \verb"Lin" output SourceName" \verb"Lin" output SourceName" "Lin" output SourceName" \verb"Lin" output SourceName" "Lin" output SourceName" \verb"Lin" output SourceName" "Lin" output SourceName"" "Lin" output SourceName" "Lin" output SourceName"" "Lin" output SourceName""" "Lin" output SourceName""" "Lin" output SourceName""" "Lin$ 

- + NumberPoints FStart FStop OutputInterval
- Output Voltage Specification is a specification of an output voltage which is to be the output of the noise analysis. It acts as a summing point for the noise contributions of the individual noise current generators. The noise voltage appearing at the output for each noise generator is summed in the RMS sense. Any voltage specification may be used including the voltage at a node, e.g. using V(5), or the voltage between nodes, e.g. using V(5,3). The noise is reported in units of  $V/\sqrt{Hz}$ .
- InputSourceName is the name of the independent voltage (V) or current (I) source that is to be the input reference source to which equivalent input noise is referred. The input source does not produce noise itself. If the input source is an independent voltage source then the equivalent input noise is reported in units of  $V/\sqrt{Hz}$ . If the input source is an independent current source then the equivalent input noise is reported in units of  $A/\sqrt{Hz}$ .
- OutputInterval is the optional output reporting interval at which the values of the noise current generators internal to the elements of the circuit are reported. The report is produced every OutputInterval th frequency. If zero or omitted no detailed output is produced.
  - **DEC** is the decade sweep keyword specifying that the noise analysis is to be evaluated at a number of frequency points. The frequency is swept logarithmically by decades.

Frequencies PerDecade specifies the number of frequencies per decade.

**OCT** is the octave sweep keyword specifying that the noise analysis is to be evaluated at a number of frequency points. The frequency is swept logarithmically by octaves.

Frequencies PerOctave specifies the number of frequencies per octave.

- LIN is the linear frequency sweep keyword. At each frequency a noise analysis is performed.
- NumberPoints specifies the total number of frequencies in a linear sweep.
  - FStart is the starting frequency of the sweep.
  - FStop is the stopping frequency of the sweep.
- Example

.NOISE V(5) VIN DEC 10 1kHZ 100Mhz .NOISE V(5,3) V1 OCT 8 1.0 1.0e6 1

#### Example

.NOISE V(5) VIN .NOISE V(5,3) I1

#### Note

- 1. In noise analysis the noise generated by active devices and resistors is evaluated as a noise spectral density. The densities are integrated over the the range of frequencies to obtain a gross noise measure for the circuit (for the specified frequency range). The finer the frequency spacing the more accurate will be the noise analysis. The noise contributions of individual noise generators are summed at the node or branch specified by *OutputVoltageSpecification*. The noise at this output port is reported as well as the equivalent input noise (the output noise referred to the input) at the input source identified by *InputSourceName*.
- 2. Two types of output are produced by noise analysis:
  - (a) noise spectral density versus frequency, and
  - (b) total integrated noise over the specified frequency range.
- 3. In SPICE3 the AC frequency sweep for noise analysis must be specified in the .NOISE statement. In PSPICE the frequency sweep specified in the .AC statement is used.
- 4. The noise table is produced while analysis is being performed. Noise reporting is produced using the .PRINT and .PLOT statements.
- 5. Noise is generated by resistors and by semiconductor devices. Resistors generate thermal noise while the noise model of semiconductor devices includes thermal noise, shot noise and flicker noise. Noise models of individual elements are discussed in the element catalog beginning on page 115.

#### Two-Port Noise and Gain Calculations

This is supported in a few versions of Spice.

For all circuits the output ONOISE and effective input noise INOISE are calculated. Also the voltage gain GAIN is calculated as the output voltage devided by the voltage across the source. Extended gain and noise parameters are available if the circuit is defined as a two port. The two-port parameters that are calculated are defined in terms of the signal and noise powers shown in Fig. 6.1 The actual noise and signal powers that are delivered to the circuit are  $P_i$  and  $N_i$ . Also the actual noise and signal powers that are delivered to the load resistance are  $P_o$  an  $N_o$ . The available noise and signal powers are the powers that would be delivered to the circuit with ideal lossless matching networks. That is, when the input and output impedances equal the source  $(R_S)$  and load  $(R_L)$  resistances — so that  $P_i = P_{Ai}$  and  $P_o = P_{Ao}$ ; and  $N_I = N_A$  and  $N_O = N_A$ .

Two-port noise analysis yields the following quantities which can be specified in the .PRINT and .PLOT statements:

ONOISE	-	$V_{NO}$	RMS output noise voltage in $V/\sqrt{Hz}$
INOISE	-	$V_{NO}$	RMS equivalent input noise voltage in $V/\sqrt{Hz}$
GAIN	-	G	voltage gain
GT	-	$G_T$	transducer gain
NF	-	NF'	spot noise factor
SNR	-	$SNR_i$	output voltage signal-to-noise ratio
TNOISE	-	$T_{\rm NOISE}$	output noise temperature in celsius.



Figure 6.1: Signal and noise definitions for a two-port.

All of the quantities can be output in dB with the exception of  $T_{\text{NOISE}}$ . When DB(NF) is used the spot noise figure is obtained.

The transducer gain,  $G_T$ , for the two port is defined as

$$G_T = P_o/P_{Ai} \tag{6.3}$$

The most common measure of the noise performance of a two port is the noise factor or noise figure. The spot noise factor NF' of a linear two-port network is defined as the ratio of the noise power delivered by the network to the load impedance to the fraction of the noise power due to the input termination alone. This noise is calculated with the input termination,  $R_S$ , at the standard temperature  $T_0 = 290$  K. Note that this differs from the default analysis temperature of spice which is 300 K or 16.85 c. The noise power delivered to the output is the total noise power indicated by **ONOISE** less the noise power contributed to the output by  $R_L$  since it is not part of the two-port. These subtractions must be done using squared voltage quantities because the noises are uncorrelated. The noise power at the output due to  $R_S$  is the voltage gain squared multiplied by the square of the noise voltage in series with  $R_S$ . The noise factor calculated by SOMEVERSIONSOFSPICE is the spot noise factor as the noise powers are not averaged over frequency. The spot noise factor is

$$NF' = \frac{{}_{0}V_{NO}^2 - V_{NO,RL}^2}{{}_{0}V_{NO,RS}^2}$$
(6.4)

Here the leading zero subscript indicates that the noise is calculated with  $R_S$  at  $T_0$ .  $_0V_{NO}$  is the output noise voltage with  $R_S$  at  $T_0$ ,  $V_{NO,RL}$  is the component due to the noise generated by  $R_L$  and  $_0V_{NO,RS}$  is the component due to the noise generated by  $R_S$  at  $T_0$ .

The noise temperature in Kelvin is

$$T_{NOISE} = T_K (NF' - 1) \tag{6.5}$$

where  $T_K$  is the analysis temperature in Kelvin.



Figure 6.2: Circuit used as an example for specifying noise analysis.

The output voltage signal-to-noise ratio is the ratio of the signal voltage to the noise voltage:

$$SNR_o = \frac{V_O''}{V_{NO}''\sqrt{2}}$$
(6.6)

where the  $\sqrt{2}$  is required since noise voltages are specified in RMS terms but the signal voltages are specified as a peak voltage.  $V_O$  is the signal voltage at the output taking into account the signal-to-noise ratio, SNR<sub>i</sub>, at the input of the circuit. SNR<sub>i</sub> can either be specified on the voltage source line or, if not, calculated usnig the thermal voltage of  $R_S$ .

Three parameters affect the results of the noise analysis. These are the source resistance  $R_S$ , the load resistance,  $R_L$  and the input signal to noise ratio,  $SNR_i$ . The values used for the parameters are as follows:  $R_S =$  The resistance of port 1 (ZL, or if Port 1 is not defined,

7	=	The resistance of port 1 (ZL, or if Port 1 is not defined,
	=	The RS resistance specified on the source line, or if not specified.
	=	$50 \ \Omega.$

 $R_L$  = The resistance of port 2 (ZL, or if Port 2 is not defined. = The RL resistance specified on the source line, or if not specified,

 $= 50 \ \Omega.$ 

 $SNR_i$  = The SNR specified on the source line, or if not specified.

= it is calculated as the signal voltage specified on the input line devided by the thermal noise voltage of  $R_S$  with appropriate correction for the difference between RMS and peak quantities.

Example of Two-Port Noise and Gain Analysis

```
The netlist for performing a two-port noise and gain analysis of the circuit in Fig. 6.2 is as follows.
Gain and noise analysis of resistive attenuator
vin 1 0 AC 1u RS=50 SNR=100
RS 1 2 50
R1 2 0 55
R2 2 3 500
R3 3 0 55
RL 3 0 50
*The following sets the analysis temperature to the standard temperature
.TEMP 16.85
.AC DEC 1 1MEG 2G
.NOISE V(3,0) VIN 1
.PRINT NOISE nf db(nf) gt db(gt) gain snr inoise onoise
.END
```

The example below performs the same analysis using ports and also prints the scattering parameters of the circuit.

Small-Signal Noise Analysis

Gain and noise analysis of resistive attenuator using ports. vin 1 0 AC 1u SNR=100 PIN PNR=1 ZL=50 R1 2 0 55 R2 2 3 500 R3 3 0 55 POUT PNR=2 ZL=50 \*The following sets the analysis temperature to the standard temperature .TEMP 16.85 .AC DEC 1 1MEG 2G .NOISE V(3) VIN 1 .PRINT NOISE nf db(nf) gt db(gt) gain snr inoise onoise .PRINT AS S(1,1) S(1,2), S(2,1), S(2,2) .END

### .OP

### **Operating Point Analysis**

In the operating point analysis a  $\tt DC$  analysis is performed to determine the  $\tt DC$  voltages and currents without performing any sweeps.

Form

.OP

- 1. The operating point analysis is performed by default prior to AC small-signal (.AC) and transient (.TRAN) analyses to determine the operating point about which the circuit is linearized for AC analysis and as the initial starting point for transient analysis.
- 2. The (.OP) analysis is performed if no other analyses are specified.
- 3. The operating point analysis is performed with inductors shorted and capacitors opened.
- 4. Following DC analysis the nonlinear devices are linearized to determine their AC small-signal models.
- 5. A .TRAN analysis performs its own DC analysis to determine the initial conditions (or bias point) for transient analysis ignoring the bias point determined in a .OP analysis.

## .OPTIONS

Option Specification

The options specification provides the user control over the program and a way of setting defaults for certain elements and analyses.

Form

.OPTIONS [Keyword]  $\dots$  [Keyword=Value]  $\dots$ 

Multiple keywords can be included in a single .OPTIONS statement and in any order.

Keywords:

ACCT	Sets reporting of accounting and statistics. This option is a flag and does not have a value. (Default: not set)
ABSTOL = Value	Sets the absolute current error tolerance. (Default: 1 pA $(10^{-12})$ )
BYPASS	The bypass option. SPICE3 only.
CHGTOL = Value	Resets the charge tolerance of the program. (Units: C; Default: 10 fC $10^{-14}$ )
CPTIME=Value	Sets the maximum CPU-time. (Units: s; Default: $\infty$ ) SPICE2G6 only.
DEFAD=Value	Sets the default value of the MOS drain diffusion area $(\texttt{AD})$ used in the M element (see page 189). (Units: m² Default: 0)
DEFAS=Value	Sets the default value of the MOS source diffusion area (AS) used in the M element (see page 189). (Units: $m^2$ Default: 0)
DEFL=Value	Sets the value of the MOS channel length (L) used in the M element (see page 189). (Units: m; Default: $100\mu m$ (1E-4))
DEFW = Value	Resets the value for MOS channel width (W) used in the M element (see page 189). (Units: m; Default: 100 $\mu$ m (1E-4))
EXPAND	Reports in output logfile the devices and nodes created in subcircuit expansions. This option is a flag and does not have a value. (Default: no expansion) PSPICE only.
GMIN = Value	Resets the value of the minimum conductance $G_{\rm MIN}$ . The usage of $G_{\rm MIN}$ is controlled by the code implementing individual elements. Generally is the minimum conductance between nodes. It is used to aid convergence. (Units: S; Default: $10^{-12}$ (1E-12))

- ITL1=*IntegerValue* Sets the limit on the number of DC iterations. (Default: 100)
- ITL2=IntegerValue Sets the DC transfer curve iteration limit. (Default: 50)
- ITL3=IntegerValue Sets the minimum number of iterations used in transient analysis. (Default: 4) SPICE2G6 only.
- ITL4=IntegerValue Sets the maximum of transient iterations at each time point. (Default: 10) SPICE2G6 only.
- - LIBRARY Reports in output logfile the statements and devices extracted from a library file This option is a flag and does not have a value. (Default: no report) PSPICE only.
- LIMPTS=Value Sets the maximum number of points that can be printed or plotted in a DC , AC or transient analysis. (Default: 201) SPICE2G6 only.
- LIMTIM=Value Sets the maximum CPU time for generating plots. Used only if the program was terminated because the time specified by the CPTIME option was exceeded. (Units: s; Default: 10) SPICE2G6 only.
  - LIST Sets summary reporting of circuit elements in input NETLIST. (Default: not set)
- LVLCOD=IntegerValue Sets an internal option of the program when running on CDC computers. If LVLCOD=1 machine code for the matrix solution is generated. (Default: 2) SPICE2G6 only.
- LVLTIM=IntegerValue If LVLTIM=1 then iteration time step control is used. If LVLTIM=2 then the time step indicated by the truncation error is used. If METHOD=GEAR and MAXORD¿2 then LVLTIM is set to 2 by SPICE. (Default: 2) SPICE2G6 only.
- $$\begin{split} \texttt{MAXORD}{=} IntegerValue ~~ \texttt{Sets the maximum order of the integration method if \texttt{METHOD}{=}\texttt{GEAR} \\ & (\texttt{Default: 2; 2 \leq \texttt{MAXORD} \leq 6}) \\ & \texttt{SPICE2G6 only.} \end{split}$$

- METHOD=String Sets the numerical integration method to be used. If METHOD=GEAR then Gear's method is used. If METHOD=TRAPEZOIDAL then the trapezoidal method is used. (Default: TRAPEZOIDAL) SPICE2G6 only.
  - NODE Sets reporting of the node table. (Default: not set)
  - NOECHO Suppresses listing of input file in output log file. (Default: input lines listed.) PSPICE only.
  - [NOFREQ ] Number of frequency points to be used in simulation of distributed circuit. Must be a power of 2. (Default: 1024)
    - NOMOD Un-sets reporting of model parameters. (Default: set)
  - NOPAGE Un-sets page breaks in the output log file. Useful if the log file is to printed by a program which automatically paginates the output. This option is a flag and does not have a value. (Default: set)
- NUMDGT=IntegerValue Sets the number of significant digits used in printing values in the output log file. (Default: 4;  $0 < IntegerValue \le 8$ ) SPICE2G6 and PSPICE only.
  - **OPTS** Sets reporting of the option values. (Default: not set)
- PIVREL = Value Sets the minimum acceptable pivot value used in partial pivoting in the solution of the network equations (such as solving for the nodal voltages  $\mathbf{v}_n$  in (4.1) on page 34). PIVREL is the minimum acceptable ratio of an acceptable pivot value to the largest column entry. (Default: 0.001)
- PIVTOL = Value Sets the minimum value of a matrix element for it to be used as a pivot. (Default:  $10^{-13}$ )
- RELTOL=Value Sets the relative error tolerance of voltages and currents. (Default: 0.001)
  - TNOM= Value Sets the nominal temperature. This is assumed to be the temperature at which the model parameters were measured. In some cases it is overwritten by a temperature parameter in the .MODEL statement. (Units: °C; Default: 27°C (300K))
- TRTOL=Value Sets the factor by which the approximated truncation error evaluated in transient analysis
  is scaled.
  (Default: 7)
- $\begin{aligned} \texttt{VNTOL} = Value & \text{Sets the absolute voltage error tolerance.} \\ & (\text{Units: V; Default: } 1\mu\text{V} \text{ (1E-6)}) \end{aligned}$

## .PARAM

### **PSPICE** Only

Parameter Definition

This statement defines parameters that can be used in subsequent statements and element lines. PSPICEForm

.PARAM [ParameterName = NumericValue ...] [ParameterName = { Expression } ...]

- ParameterName Name of a parameter with first character being alphabetic (a-z). If this is the name of a previously defined parameter at the same level of subcircuit expansion then the parameter value is changed. If the .PARAM statement is is in the top level circuit then the parameter value is global. If the .PARAM statement is is in a subcircuit then the parameter value is local and can be used at the current subcircuit expansion level or lower in the subcircuit expansion hierarchy.
  - *Numeric Value* is a numeric value which can be an integer or floating point number followed by optional scale factor and/or unit. (e.g. 1.E-9, 1N, 1NV and 1.E-9V are equivalent.)
    - *Expression* is a standard expression as described in the Algebraic Expressions section on page ??. Note that the expression must be enclosed in braces ( $\{ \dots \}$ ).

#### Example

.PARAM VDD = 10V, VSS = 0 VREF = 2.5 .PARAM VREF = VDD/2 .PARAM LENGTH = 1.10\*L

#### **PSPICE** Only

1. Predefined parameters are supported and the user must avoid using these. Predefined parameters:

Name	Value	Description
TEMP	not supported	Analysis temperature.
	Reserved for future expansion	
VT	not supported Reserved for future expansion	Thermal voltage.

- 2. In PSPICE, in most places where a numeric value is required an expression (within braces { ... }) can be used instead. An expression can contain any support mathematical operation, constant numeric values or expressions. Exceptions are
  - Polynomial coefficients.
  - The values of the transmission line device parameters NL and F.
  - The values of the piece-wise linear characteristic in the PWL form of the independent voltage (V) and current (I) sources.

and

- The values of the resistor device parameter TC.
- As node numbers.
- Values of most statements (such as .TEMP, .AC, .TRAN etc.)

Specifically included are

- The values of all other device parameters.
- The values in .IC and .NODESET statements.
- The values in .SUBCKT statements.

and

- The values of all model parameters. F.
- 3. Hierarchical usage of .PARAM statements in subcircuits is supported. The parameters defined in a .PARAM statement are available in the subcircuit in which they are defined or in lower nested subcircuits. Thus parameters defined in a subcircuit are not available higher in the hierarchy. The same concept applies to values of a parameter changed in a subcircuit. Value changes are local and are available in the current subcircuit and lower nested subcircuits.
- 4. Libraries are searched for parameters not defined in the circuit NETLIST or in included files. A .PARAM statement does not have to be within a subcircuit in a library.

## .PLOT

### **Plot Specification**

The plot specification controls the information that is plotted as the result of various analyses. Form

PLOT TRAN OutputSpecification [PlotLimits]
+ [OutputSpecification [PlotLimits] ... ]
PLOT AC OutputSpecification [PlotLimits]
+ [OutputSpecification [PlotLimits]
+ [OutputSpecification [PlotLimits]
+ [OutputSpecification [PlotLimits] ... ]
PLOT NOISE NoiseOutputSpecification [(DistortionReportType)] [PlotLimits]
+ [NoiseOutputSpecification [(DistortionReportType)] [PlotLimits]
PLOT DISTO DistortionOutputSpecification [(DistortionReportType)] [PlotLimits]
+ [DistortionOutputSpecification [(DistortionReportType)] [PlotLimits]
[OutputSpecification [(DistortionReportType)] [PlotLimits]

#### PSPICEForm

.PLOT TRAN OutputSpecification [PlotLimits] + [OutputSpecification [PlotLimits] ...] .PLOT AC OutputSpecification [PlotLimits]

+ [OutputSpecification [PlotLimits] ...]

.PLOT DC OutputSpecification [PlotLimits] + [OutputSpecification [PlotLimits] ...]

.PLOT NOISE NoiseOutputSpecification [(DistortionReportType)] [PlotLimits] + [NoiseOutputSpecification [(DistortionReportType)] [PlotLimits]

- TRAN is the keyword specifying that this .PLOT statement controls the reporting of results of a transient analysis initiated by the .TRAN statement.
  - AC is the keyword specifying that this .PLOT statement controls the reporting of results of a small-signal AC analysis initiated by the .AC statement.
  - DC is the keyword specifying that this .PLOT statement controls the reporting of results of a DC analysis initiated by the .DC statement.
- NOISE is the keyword specifying that this .PLOT statement controls the reporting of results of a noise analysis initiated by the .NOISE statement.
- DISTO is the keyword specifying that this .PLOT statement controls the reporting of results of a small-signal AC distortion analysis initiated by the .DISTO statement.
- *OutputSpecification* specifies the voltage or current to be plotted against the sweep variable. The sweep variable is dependent on the type of analysis.

Many forms of OutputSpecification are supported by PSPICE . Below is a description of the basic forms that are supported both by SPICE2G6 and PSPICE . A comprehensive description of OutputSpecification supported by PSPICE is given in the section on output specification on page 94.

Voltages may be specified as an absolute voltage at a node: V(*NodeName*) or the voltage at one node with respect to that at another node, e.g. V(Node1Name, Node2Name).

For the reporting of the results of an AC analysis the following outputs can be specified by replacing the V as follows:

- VR real part
- VI imaginary part
- VM magnitude
- VP phase
- VDB  $10 \log(10 magnitude)$

In AC analysis the default is VM for magnitude.

<u>Currents</u> are specified by referencing the name of the voltage source through which the current is measured, e.g. I(*VoltageSourceName*).

For the reporting of the results of an AC analysis the following outputs can be specified by replacing the I as follows:

- IR real part
- II imaginary part
- IM magnitude
- IP phase

IDB -  $10 \log(10 magnitude)$ 

ysis the default is IM for magnitude.

- *PlotLimits* are optional and can be placed after any output specification. *PlotLimits* has the form (*LowerLimit*, *UpperLimit*). All quantities will be plotted using the same *PlotLimits*. The default is to automatically scale the plot and perhaps use different scales for each of the quantities to be plotted.
- NoiseOutputSpecification specifies the noise measure to be reported. The two options are ONOISE which reports the output noise and INOISE which reports the equivalent input noise. See the .NOISE statement on page 77 for a detailed explanation.

In AC anal-

It must be one of the following:

		0
ONOISE	-	magnitude of the output noise
DB(ONOISE)	-	output noise in dB
INOISE	-	magnitude of the equivalent input noise
DB(INOISE)	-	equivalent input noise in dB
GAIN	-	voltage gain
DB(GAIN)	-	voltage gain in dB (= $20 \log(GAIN)$
GT	-	transducer gain
DB(GT)	-	transducer gain in dB (= $10 \log(GT)$
NF	-	spot noise factor
DB(NF)	-	spot noise figure (= $10 \log(NF)$
SNR	-	output signal-to-noise ratio
DB(SNR)	-	output signal-to-noise ratio in dB (= $20 \log(SNR)$ )
TNOISE	-	output noise temperature.

SParameterOutputSpecification specifies the S-parameter output variables that are to be printed. Each variable must have one of the following forms:

S(i,j)	-	Magnitude of $S_{ij}$		
SR(i,j)	-	Real part of $S_{ij}$		
SI(i,j)	-	Imaginary part of $S_{ij}$		The port
SP(i,j)	-	Phase of $S_{ij}$ in degrees		The port
SDB(i,j)	-	Magnitude of $S_{ij}$ in dB (= 20 log(S(i,j)))		
SG(i,j)	-	Group delay of $S_{ij}$		
1	• 1		$(\mathbf{D}^{1})$	1

numbers are i, j which are specified using the PNR keywor when the port ('P') element is specified.

DistortionOutputSpecification specifies the distortion component to be reported in a tabular format of up to 8 columns plus an initial column with the sweep variable. The DistortionOutputSpecification is one of the following:

-	the second harmonic distortion	
-	the second harmonic distortion	
-	the sum frequency intermodulation component	See the .DISTO
-	the difference frequency intermodulation component	
-	the third order intermodulation component	
	- - - -	<ul> <li>the second harmonic distortion</li> <li>the second harmonic distortion</li> <li>the sum frequency intermodulation component</li> <li>the difference frequency intermodulation component</li> <li>the third order intermodulation component</li> </ul>

statement on page 58 for a description of these distortion components.

DistortionReportType specifies the format for reporting the distortion components. It must be one of the following:

	$\mathbf{R}$	-	real part	
	Ι	-	imaginary part	
	Μ	-	magnitude	The default
	Р	-	phase	
	DB	-	$10\log(10 magnitude)$	
is M for 1	nagni	tude		

Example

.PLOT TRAN V(10) V(5,3) I(VIN) .PLOT AC VM(10) VR(5,3) IP(VLOAD) .PLOT DC V(10) V(5,3) I(VIN) .PLOT NOISE ONOISE INOISE DB(ONOISE) DB(INOISE) .PLOT NOISE GAIN DB(GT) DB(NF) SNR TNOISE .PLOT AS SDB(1,1) SP(1,1) SDB(1,2) SP(1,2) .PLOT DISTO HD2 HD3 SIM2(DB)

- 1. There can be any number of .PLOT statements.
- 2. All of the output quantities specified on a single .PLOT statement will be plotted on the same graph using ASCII characters. An overlap will be indicated by the letter X. The plot produced by the .PLOT statement is a line printer plot. While plotting is primitive it can be plotted on any printer and is incorporated in the output log file.
- 3. The plot output of the results of an AC analysis always have a logarithmic vertical scale.
- 4. The current through any element can be found by inserting independent voltage sources in series with the elements. This is generally what is required in SPICE2G6and SPICE3. However PSPICE supports direct specification of the voltage and currents of most elements. See the section on page 94.
- 5. More elaborate plotting is available with SPICE3 using the NUTMEG plotting program described on the NUTMEG chapter beginning on page ??; and with PSPICE using the .PROBE statement described on page 98.

## .PRINT

### Print Specification

The print specification controls the information that is reported as the result of various analyses. Form

.PRINT	TRAN OutputSpecification [OutputSpecification]
.PRINT	AC OutputSpecification [OutputSpecification]
.PRINT	DC OutputSpecification [OutputSpecification]
.PRINT + [Dist	<b>DISTO</b> $DistortionOutputSpecification ( DistortionReportType )tortionOutputSpecification ( DistortionReportType ) ]$
TRAN	is the keyword specifying that this .PRINT statement controls the reporting of results of a transient analysis initiated by the .TRAN statement.
AC	is the keyword specifying that this <code>.PRINT</code> statement controls the reporting of results of a small-signal AC analysis initiated by the <code>.AC</code> statement.
DC	is the keyword specifying that this .PRINT statement controls the reporting of results of a DC analysis initiated by the .DC statement.
NOISE	is the keyword specifying that this .PRINT statement controls the reporting of results of a noise analysis initiated by the .NOISE statement.
DISTO	is the keyword specifying that this .PRINT statement controls the reporting of results of a small-signal AC distortion analysis initiated by the .DISTO statement.
OutputSpecificat	ion specifies the voltage or current to be reported in a tabular format of up to 8 columns plus an initial column with the sweep variable. Many forms of OutputSpecification are supported by PSPICE. Below is a description of the basic forms that are supported both by SPICE2G6 and PSPICE. A comprehensive description of OutputSpecification supported by PSPICE is given in the section on output specification on page 94.
	<pre>Voltages may be specified as an absolute voltage at a node: V(NodeName) or the voltage at one node with respect to that at another node, e.g. V(Node1Name,Node2Name). For the reporting of the results of an AC analysis the following outputs can be specified by replacing the V as follows:</pre>

<u>Currents</u> are specified by referencing the name of the voltage source through which the current is measured, e.g. I(V Voltage Source Name).

For the reporting of the results of an AC analysis the following outputs can be specified by replacing the I as follows:

- IR real part
- II imaginary part
- IM magnitude
- IP phase
- IDB  $10 \log(10 magnitude)$

ysis the default is IM for magnitude.

NoiseOutputSpecification specifies the noise measure to be reported. The two options are ONOISE which reports the output noise and INOISE which reports the equivalent input noise. See the .NOISE statement on page 77 for a detailed explanation.

It must be one of the following:

ONOISE	-	RMS output noise voltage
DB(ONOISE)	-	output noise voltage in dB (= $20 \log(\text{ONOISE})$
INOISE	-	RMS equivalent input noise voltage
DB(INOISE)	-	equivalent input noise voltage in dB (= $20 \log(INOISE)$
GAIN	-	voltage gain
DB(GAIN)	-	voltage gain in dB (= $20 \log(GAIN)$
GT	-	transducer gain
DB(GT)	-	transducer gain in dB (= $10 \log(GT)$
NF	-	spot noise factor
DB(NF)	-	spot noise figure (= $10 \log(NF)$
SNR	-	output signal-to-noise ratio
DB(SNR)	-	output signal-to-noise ratio in dB (= $20 \log(SNR)$ )
TNOISE	-	output noise temperature.

SParameterOutputSpecification specifies the S-parameter output variables that are to be printed. Each variable must have one of the following forms:

		0
S(i,j)	-	Magnitude of $S_{ij}$
SR(i,j)	-	Real part of $S_{ij}$
SI(i,j)	-	Imaginary part of $S_{ij}$
SP(i,j)	-	Phase of $S_{ij}$ in degrees
SDB(i,j)	-	Magnitude of $S_{ij}$ in dB (= 20 log(S(i,j)))
SG(i,j)	-	Group delay of $S_{ij}$

The port numbers are i, j which are specified using the PNR keyword when the port element is specified.

DistortionOutputSpecification specifies the distortion component to be reported in a tabular format of up to 8 columns plus an initial column with the sweep variable. The DistortionOutputSpecification is one of the following:

distortion	harmonic	the second	-	HD2
distortion	harmonic	the second	-	HD2

HD3	_	the	second	harmonic	distortion
IID O		UIIC	bucuna	mannonio	anoutron

SIM2 - the sum frequency intermodulation component

- DIM2 the difference frequency intermodulation component
- DIM3 the third order intermodulation component

In AC anal-

See the .DISTO statement on page 58 for a description of these distortion components.

DistortionReportType specifies the format for reporting the distortion components. It must be one of the following:

R	-	real part
Ι	-	imaginary part
Μ	-	magnitude
Р	-	phase
DB	-	$10 \log(10 magnitude)$

The default is M for magnitude.

#### Example

.PRINT TRAN V(10) V(5,3) I(VIN) .PRINT AC VM(10) VR(5,3) IP(VLOAD) .PRINT DC V(10) V(5,3) I(VIN) .PRINT NOISE ONOISE INOISE DB(ONOISE) DB(INOISE) .PRINT NOISE GAIN DB(GT) DB(NF) SNR TNOISE .PRINT AS SDB(1,1) SP(1,1) SDB(1,2) SP(1,2) .PRINT DISTO HD2 HD3 SIM2(DB)

Note

- 1. There can be any number of .PRINT statements.
- 2. The number of significant digits of the results reported is NUMDGT which is set in a .OPTIONS statement (see page 85).
- 3. The current through any element can be found by inserting independent voltage sources in series with the elements. This is generally what is required in SPICE2G6and SPICE3. However PSPICE supports direct specification of the voltage and currents of most elements. See the section on page 94.

Output Specification for PSPICE

PSPICE supports a relatively large variety of output specifications compared to that available with SPICE2G6

and SPICE3. The output specifications described in the following can be used .PRINT and .PLOT statements. The various forms of output specifications enable the current and voltages of virtually all devices to be examined.

#### DC and TRAN Reporting

The output specifications available for the DC sweep and transient analyses are

- I(DeviceName) Current through a two terminal device (such as a resistor R element) or the output of a controlled voltage or current source. e.g. I(R22) is the current flowing through resistor R22 from node  $N_1$  to  $N_2$  of R22.
- I TerminalName(*DeviceName*) Current flowing into terminal named *TerminalName* (such as B for gate) from the device named *DeviceName* (such as Q12). e.g. IB(Q12)
- I PortName (*TransmissionLineName*) Current at port named *PortName* (either A or B) of the transmission line device named *TransmissionLineName*
- V(NodeName) Voltage at a node of name NodeName.
  - $V(n_1, n_2)$  Voltage at node  $n_1$  with respect to the voltage at node  $n_2$ .
- V(DeviceName) Voltage across a two terminal device (such as a resistor R element) or at the output of a controlled voltage or current source.
- V TerminalName(*DeviceName*) Voltage at terminal named *TerminalName* (such as G for gate) of the device named *DeviceName* (such as M12). e.g. VG(M12)
- V TerminalName1 TerminalName2(*DeviceName*) Voltage at terminal named *TerminalName1* (such as G for gate) th respect to the terminal name *TerminalName2* (such as S for source) of the device named *DeviceName* (such as M12). e.g. VGS(M12)
- V PortName (TransmissionLineName) Voltage at port named PortName (either A or B) of the transmission line device named TransmissionLineName (such as T5). e.g. VA(M5)

#### Two Terminal Device Types Supported for DCand Transient Analysis Reporting

The single character identifier for the following elements as well as the rest of the device name can be used as the *DeviceName* in the I(*DeviceName*) and I(*DeviceName*) output specifications.

Element Type	Description
C	capacitor
D	diode
E	voltage-controlled voltage source
F	current-controlled current source
G	voltage-controlled current source
Н	current-controlled voltage source
I	independent current source
L	inductor
R	resistor
V	independent voltage source

#### Multi-Terminal Device Types Supported for DCand Transient Analysis Reporting

The single character identifier for the following elements as well as the rest of the device name can be used as the *DeviceName* in the I TerminalName(*DeviceName*), V TerminalName(*DeviceName*) and V TerminalName1 TerminalName2(*DeviceName*) output specifications.

Element Type	Description
В	GaAs MESFET Terminals:
	D - drain
	G - gate
	S - source
J	JFET Terminals:
	D - drain
	G - gate
	S - source
М	MOSFET Terminals:
	B — bulk or substrate
	D - drain
	G - gate
	S - source
Q	BJT Terminals
	m Ccollector
	B - base
	E - emitter
	S — source

#### AC Reporting

The output specifications available for reporting the results of an AC frequency sweep analysis includes all of the specification formats discussed above for DC and transient analysis together with a number of possible suffixes:

- DB  $10 \log(10 magnitude)$
- M magnitude
- P phase
- R real part
- I imaginary part
- **G** group delay =  $\partial \phi / \partial f$ 
  - where  $\phi$  is the phase of the quantity being reported and f is the analysis frequency.

In AC analysis the default suffix is M for magnitude.

#### Two-Terminal Device Types Supported for AC Reporting

The single character identifier for the following elements as well as the rest of the device name can be used as the DeviceName in the I(DeviceName) and I(DeviceName) output specifications.

Element Type	Description
C	capacitor
D	diode
I	independent current source
L	inductor
R	resistor
V	independent voltage source

#### Multi-Terminal Device Types Supported for DCand Transient Analysis Reporting
### $Print\ Specification$

The single character identifier for the following elements as well as the rest of the device name can be used as the *DeviceName* in the I TerminalName(*DeviceName*), V TerminalName(*DeviceName*) and V TerminalName1 TerminalName2(*DeviceName*) output specifications.

Element Type	Description
В	GaAs MESFET Terminals:
	D - drain
	G - gate
	S - source
J	JFET Terminals:
	D - drain
	G - gate
	S - source
М	MOSFET Terminals:
	B - bulk or substrate
	$\mathrm{D}-\mathrm{drain}$
	G - gate
	S — source
Q	BJT Terminals
	m Ccollector
	B - base
	E - emitter
	S - source

### .PROBE

### Data Output Specification

There is a big problem here — Probe is a trademark of Microsim corporation The .PROBE statement saves the node voltages and device currents in a file for subsequent probing. PSPICEForm

.PROBE [/CSDF] [OutputSpecification ...]

- /CSDF is a keyword resulting in the output probing file being written in ASCII format. By default the probing file is output in the more efficient binary format. However, only the ASCII formated is fully portable between computers and operating systems.
- OutputSpecification specifies a node voltage or device current to be included in the probe data file. The output specifications supported are those supported for the .PRINT and .PLOT statements. A comprehensive description of the OutputSpecification supported is given in the section on output specification on page 94.

If an *OutputSpecification* is not given then all node voltages and device currents are stored in the probing file.

#### Example

.PROBE V(10) V(5,3) I(VIN) .PROBE VM(10) VR(5,3) IP(VLOAD) .PROBE/CSDF V(10) IG(VIN) .PROBE The first exam-

ple will output data from .DC, .AC and .TRAN analyses.

The second example will output data only from a .AC analysis.

The third example will output the node voltage at node 10 for .DC, .AC and .TRAN analyses but output the group delay of the current in the independent voltage source VIN only from an .AC analysis. As well the data will be output in ASCII format.

The fourth example results in all node voltages and device currents being stored.

- 1. The probing data is stored in the file PROBE.DAT.
- 2. The results of DC, AC and transient analyses are saved. An *OutputSpecification* which is unique to a particular type of analysis is ignored when the the results of analyses are being selected to storage. An example is VI(10) which selects the imaginary part of the voltage at node 10 and so only applies for storage of the results for an AC small-signal analysis.
- 3. The results stored in the probe file can subsequently be viewed using the PROBEprogram described in chapter ??.

.PZ

# Pole-Zero Analysis

In pole zero analysis the poles and zeros of the small signal  $\texttt{AC}\mathsf{transfer}$  function of a two-port is evaluated. Form

.PZ Node1 Node2 Node3 Node4 CUR POL
.PZ Node1 Node2 Node3 Node4 CUR ZER
.PZ Node1 Node2 Node3 Node4 CUR PZ
.PZ Node1 Node2 Node3 Node4 VOL POL
.PZ Node1 Node2 Node3 Node4 VOL ZER
.PZ Node1 Node2 Node3 Node4 VOL PZ

*Node1* is the positive input node.

*Node2* is the negative input node.

*Node3* is the positive output node.

*Node4* is the negative output node.

CUR is the keyword to evaluate the transfer function (output voltage)/(input current)

VOL is the keyword to evaluate the transfer function (output voltage)/(input voltage)

POL is the keyword to evaluate the poles of the transfer function only.

ZERO is the keyword to evaluate the zeroes of the transfer function only.

PZ is the keyword to evaluate the poles and zeroes of the transfer function.

#### Example

.PZ 1 0 3 0 CUR POL .PZ 2 3 5 0 VOL ZER .PZ 4 1 4 1 CUR PZ

- 1. The pole-zero analysis works with resistors R, capacitors C, inductors L, linear controlled sources E,F,G and H; independent voltage and current sources V and I, bipolar junction transistors, Q; MOSFETs, M; JFETs J; and diodes D. In particular distributed devices such as Transmission lines are not supported as these do not have a pole-zero description.
- 2. In interactive mode, the command syntax is the same except that the first field is PZ instead of .PZ. To print the results, one should use the command "PRINT ALL".
- 3. The program first computes the DC operating point and then determines the linearized, small-signal models for all the nonlinear devices in the circuit. This circuit is then used to find the poles and zeros.

# .SAVEBIAS

Save Bias Conditions

# .SENS

Sensitivity Analysis

The sensitivity analysis calculates the  $\tt DC$  small-signal sensitivities of each output quantity with respect to every circuit parameter.

Form

.SENS OutputSpecification [OutputSpecification ...]

OutputSpecification is the specification of the small-signal output quantity. It has the same format as the OutputSpecification in a .PRINT statement (see page 92).

Example

.SENS V(10) V(10,2) I(VLOAD)

- 1. The .SENS statement initiates a small-signal AC analysis.
- 2. The transfer function computed is the sensitivity (or partial derivative) of the DC value of the output quantity with respect to the each and every circuit parameter. For example, if a resistor is specified with value x and a capacitor is specified with value c then, for the above examples the following sensitivities are computed:

$\partial V(10)$	$\partial \mathtt{V}(\mathtt{10},\mathtt{2})$	$\partial$ VLOAD	$\partial V(10)$	$\partial \mathtt{V}(\mathtt{10},\mathtt{2})$	$\partial$ VLOAD
$\partial x$	$\partial x$	$\partial x$	$\partial c$	$\partial c$	$\partial c$

# .STEP Parameteric Analysis

### .SUBCKT



Figure 6.3: Subcircuit.

### Form

.SUBCKT SubcircuitName  $N_1$  [ $N_2$   $N_3$  ...  $N_N$ ]

### **PSpice**Form

.SUBCKT SubcircuitName  $N_1$  [ $N_2$   $N_3$  ...  $N_N$ ] + [PARAMS: [Keyword = { Expression } ...] [Keyword = Value ...]]

PSPICEForm

.SUBCKT SubcircuitName  $N_1$  [ $N_2$   $N_3$  ...  $N_N$ ] + [PARAMS: [keyword = { Expression } ...] [Keyword = Value ...]]

SubcircuitName is the name of the subcircuit.

- $N_1$  is the first node of the subcircuit.
- $N_N$  is the Nth node of the subcircuit.
- PARAMS: indicates that parameters are to be passed to the subcircuit.
- *Keyword:* is a keyword which may be replaced by a value specified on a subcircuit call (X) element. (See page 257).
  - *Value:* is a numeric value.
- *Expression:* is an algebraic expression which evaluates to a numeric value. (See section ?? on page ?? for allowable expressions).

### Example

.SUBCKT MULTI 2 4 17 3 1

- 1. The global ground node, node 0 (or in PSPICE node GND) must not be one of the subcircuit nodes.
- 2. Subcircuits are incorporated by using the "X" element. The number of nodes of the "X" element must correspond to the number of nodes in the definition of the subcircuit (i.e. is in the .SUBCKT statement). See page 257 for a description of the X element.
- 3. The last line in a subcircuit definition is the .ENDS line (see page 63).
- 4. The only restriction on the statements within a subcircuit is that control lines such as .AC, .DC or .OPTIONS are not allowed. However, element lines, model statements and other subcircuit definitions and subcircuit calls are allowed.
- 5. Device models or subcircuit definitions included as part of a subcircuit definition are local only. Subcircuits and models that are to be "known" by all elements and subcircuits must be defined at the top level of the circuit hierarchy.
- 6. The nodes of elements in the subcircuit definition are local except for those that also appear on the .SUBCKT statement and for the ground (0) node. The local nodes are given the unique name SubcircuitName1:[SubcircuitName2: ...]LocalNodeName.

and local devices are given the unique name DeviceType:SubcircuitName1:[SubcircuitName2...]DeviceName. The .TEMP statement specifies the temperatures at which the circuit is to be simulated. Form

.TEMP  $T_1 [T_2 ... T_N]$ 

- $T_1$  is the first temperature at which the circuit is to be simulated.
- $T_N$  is the Nth temperature at which the circuit is to be simulated.

- 1. The circuit is first simulated at temperature  $T_1$  and then resimulated at temperature  $T_2$  and so on.
- 2. If the .TEMP statement is missing then  $T_1$  is assumed to be  $T_{\text{NOM}}$  specified in a .OPTIONS statement.
- 3. Model parameters are specified at  $T_{\text{NOM}}$  and prior to the simulation at a new temperature temperature dependent device parameters are reevaluated.

# .TEXT Text Parameter Definition

### Transfer Function Specification

The transfer function specifies a small-signal DC analysis from which a small-signal transfer function and input and output resistances are computed..

Form

.TF

 $. {\tt TF} \ Output Specification \ Input SourceName$ 

OutputSpecification is the specification of the small-signal output quantity. It has the same format as the OutputSpecification in a .PRINT statement (see page 92).

InputSourceName specifies the the name of the small-signal input independent voltage (V) or current (I) source.

Example

.TF V(10) VINPUT .TF V(10,2) ISOURCE .TF I(VLOAD) ISOURCE

- 1. The .TF statement initiates a small-signal DC analysis from which a small-signal transfer function and input and output resistances are computed.
- 2. The transfer function computed is the ratio of the DC value of the output quantity to the input quantity. In the above examples the following transfer functions are computed:

EXAMPLE	Transfer Function
.TF V(10) VINPUT	V(10) VINPUT
.TF V(10,2) ISOURCE	$\frac{V(10,2)}{ISOURCE}$
.TF I(VLOAD) ISOURCE	I(VLOAD) ISOURCE

TITLE	Title Line

The **TITLE** line must be the first line of the input file. The string on this line included as the banner in the output log file appearing at the top of each page.

In transient analysis the current and voltages in a circuit are computed as a function of time. General form:

#### Form

.TRAN TSTEP TSTOP [TSTART [TMAX]] [UIC]

- TSTEP is the time increment for reporting transient simulation results. (Units: s)
- TSTOP is the final analysis time. (Units: s)
- TSTART is the start time for reporting the transient results. Transient analysis always begins at time0. Before the time TSTART no results are recorded.(Units: s; Optional; Default: 0)
  - TMAX is the maximum step size used in incrementing the time during transient analysis. (Units: s; Optional; Default: the smaller of TSTEP and (TSTOP-TSTART)/50)
    - UIC is the optional keyword to use initial conditions specified on the element line, by a .IC statement or a .NODESET statement. Normally the operating point is determined (using a DC analysis) before a transient analysis is initiated. If the UIC keyword is present the initial DC analysis is omitted and instead the initial conditions specified by the IC parameter supported by certain elements, by the .IC statement, or by the .NODESET statement are used. In addition PSPICE supports using an operating point solution that was previously saved using the .SAVEBIAS statement.

### Example

.TRAN 1NS 100NS .TRAN 1NS 1000NS 500NS .TRAN 10NS 1US UIC

- 1. If the UIC keyword is <u>not present</u> a DC analysis is automatically performed prior to a transient (.TRAN) analysis to find the operating point of the circuit. All sources which are not time dependent (for example, power supplies) are set to their DC value. The transient time interval is specified on a .TRAN control line. The operating point solution is used as the initial conditions for a transient analysis. Individual operating point solutions are overridden by initial transient conditions specified on the .TRAN statement or by the initial conditions specified for specific elements by the IC keyword.
- 2. Normally the operating point is determined (using a DC analysis) before a transient analysis is initiated. If the UIC keyword is present the initial DC analysis is omitted and instead the initial conditions specified by the IC parameter supported by certain elements, by the .IC statement (see 66), or by the .NODESET statement (see 76) are used. In addition PSPICE supports using an operating point solution that was previously saved using the .SAVEBIAS statement described on page 100.
- 3. If the UIC keyword is <u>present</u> the initial conditions specified in the .IC statement (described on page 66) are used to establish the initial conditions. Initial conditions specified for individual elements using the IC parameter on the element line will always have precedence over those specified in a .IC statement. No DC analysis is performed prior to a transient analysis. Thus it is important to establish the initial conditions at all nodes using the .IC statement or using the IC element parameter.

# .WATCH

Watch Analysis Statement

### .WCASE

### Sensitivity and Worst Case Analysis

The sensitivity and worst case analysis is a statistical analysis of a circuit causing the circuit to analyzed many times with a random change of model parameters (parameters in a .MODEL statement). Form

.WCASE NumberOfRuns AnalysisType OutputSpecification OutputFunction [LIST]

+ [OUTPUT(OutputSampleType)] [RANGE(LowValue, HighValue)]

Number OfRuns is the total number of runs to do. This number includes the initial nominal run.

AnalysisType is the type of analysis to be performed in Monte Carlo runs after the initial nominal run. All analyses specified in the NETLIST are performed in the nominal run. The AnalysisType must be one of the following:

to be filled in

- DC is a keyword indicating that the DC analysis as specified by the .DC statement is repeated. The sweep variable used in analyzing the output *OutputSpecification* is the value of the independent voltage or current source specified in the .DC statement which is discussed on page 55.
- AC is a keyword indicating that the AC small-signal analysis as specified by the .AC statement is repeated. The sweep variable used in analyzing the output *OutputSpecification* is frequency.
- TRAN is a keyword indicating that the transient analysis as specified by the .TRAN statement is repeated. The sweep variable used in analyzing the output *OutputSpecification* is time.
- OutputSpecification specifies the quantity to be reported as the result of the Monte Carlo Analysis. It has the same format as the OutputSpecification in a .PRINT statement (see page 92). The result is the value of the OutputSpecification with respect to a sweep for DC and AC analysis, and as a waveform for TRAN analysis.
- OutputFunction indicates the function to be performed on the output indicated by OutputSpecification to reduce the sweep or waveform at each run to a single numeric value. The OutputFunction must be one of the following keywords:
  - YMAX which produces the greatest deviation of the sweep or waveform from the nominal run.
  - MAX which results in the maximum value in each sweep or waveform.
  - MIN which results in the minimum value in each sweep or waveform.
- RISE\_EDGE(Value) which reports as the result the first run when the waveform crosses above the threshold Value. The algorithm used requires that one point in the waveform be below Value and the succeeding point be above Value.

- FALL\_EDGE (Value) which reports as the result the first run when the waveform crosses below the threshold Value. The algorithm used requires that one point in the waveform be above Value and the succeeding point be below Value.
  - **RANGE** is an optional range indicating the range of the sweep variable over which *OutputFunction* is to be performed. If this keyword is missing output is produced the range is not restricted. The range of the sweep variable to be considered is from *LowValue* to *HighValue* inclusive.
  - Low Value is the low end of the sweep variable to be considered in evaluating OutputFunction.
  - HighValue is the low end of the sweep variable to be considered in evaluating OutputFunction.
    - LIST is an optional keyword that results in the model parameter values that are statistically varied being printed out prior to each run. If it is omitted then the the statistically generated model parameter values are not produced prior to each run.
    - OUTPUT is an optional keyword indicating the type of output to be produced by runs after the initial nominal run. The output produced for each run sampled is determined by the .PLOT, .PRINT and .PROBE statements in the NETLIST. If this keyword is missing output is produced only for the nominal run.
    - SEED is the keyword for the seed of the random number generator used in Monte Carlo Analysis
  - SeedValue is the value of the seed used in the random number generator used to select sample runs at random. (Optional; Default: 17,533;  $1 \le SeedValue \le 32,767$ )

- 1. If the *AnalysisType* is DC only one independent voltage or current source can be specified in the .DC statement (discussed on page 55).
- 2. The random number generator is the subtractive method generator described by Knuth [28, p. 171].
- 3. The initial run uses the nominal parameter values given in the NETLIST. Subsequent runs statistically vary model parameters indicated as having either lot LOT or device DEV tolerances. These tolerances are specified in a .MODEL statement (see page 72).

### .WIDTH

### Width Specification

Form

.WIDTH OUT= Column Width

- OUT is the keyword for column width of the output file.
- ColumnWidth is the column width of the output file. It must be either 80 or 132. If there is no .WIDTH statement the ColumnWidth defaults to 80.

Example

.WIDTH OUT=80 .WIDTH OUT=132

# Chapter 7

# **Element Catalog**

В	GaAs MESFET (PSPICE only)	118
	(See Z element for SPICE3 equivalent)	264
С	Capacitor	149
D	Diode	152
Е	Voltage-Controlled Voltage Source	156
F	Current-Controlled Current Source	160
G	Voltage-Controlled Current Source	162
Н	Current-Controlled Voltage Source	166
Ι	Independent Current Source	168
J	Junction Field-Effect Transistor	175
Κ	Mutual Inductor	181
L	Inductor	187
М	MOSFET	189
Ν	Digital Input Interface	221
0	Digital Output Interface	224
Р	Port Element	226
R	Resistor	236
S	Voltage Controlled Switch	239
Т	Transmission Line	242
U	Multiple Coupled Line Element	245
U	Digital Device	??
U	Lossy RC Transmission Line	??
V	Independent Voltage Source	246

W	Current Controlled Switch	254
Х	Subcircuit Call	257
Z	Distributed Discontinuity	264
Z	MESFET	264
(See B eler	ment for PSPICE equivalent)	118

### А

Form



Figure 7.1: A — convolution element.

Aname  $n_1 n_2 [n_3 \dots n_N]$  ModelName

- $n_1$  is the first node (required),
- $n_2$  is the second node (required),
- $n_3$  is the third node (optional),
- $n_N$  is the Nth node (optional),

ModelName is the model name which defines this convolution element.

### Example

ANET 1 2 3 4 NETWORK1

CONV

### **CONV** Model

Convolution Model

#### Form

.MODEL ModelName CONV( [  $[keyword = value] \dots$  ]

### Example

.MODEL CONV1 CONV( FILE = "coupledline.y" NFREQS = 500 + NPORTS = 4 ZM = 50 THRESHOLD = 0.01)

Convolution

Model Type

### В

GaAs MESFET

(VERSIONS: PSPICE)



Figure 7.2: B — GASFET element.

### PSPICEForm

Bname NDrain NGate NSource ModelName [Area]

NDrain 3	$\mathbf{is}$	the	drain	node
----------	---------------	-----	-------	------

*NGate* is the gate node

NSource is the source node

ModelName is the model name

Area is the area factor in dimensionless units (Units: none; Optional; Default: 1; Symbol: Area)

### Example

B1 1 2 3 GAAS12 B1 1 2 3 GAAS12 0.5

### Model Type

GASFET

### **GASFET** Model

GaAs MESFET Model

Form

.MODEL ModelName GASFET( [  $[keyword = value] \dots$  ] )

### Example

.MODEL GAAS12 GASFET( LEVEL=1 )

PSPICE provides three MESFET device models some microwave versions provide six. The parameter LEVEL specifies the model to be used:



Figure 7.3: Schematic of the GASFET model.  $V_{GS}$ ,  $V_{DS}$ , and  $V_{GD}$  are intrinsic gate-source, drain-source and gate-drain voltages between the internal gate, drain, and source terminals designated G, D, and Srespectively.  $R_I$  is not used in PSPICE.

LEVEL = 1	$\rightarrow$	Curtice Quadratic model This was the first widely accepted model for a GaAs MESFET and described in [11]. It uses rather simple empirical fits to measured data. See page 120. (VERSIONS: PSPICE)
LEVEL = 2	$\rightarrow$	Raytheon model This model is also known as the Statz model and model was de- veloped at Raytheon for the modeling of GaAs MESFETs used in digital circuits. It is also based on empirical fits to measured data [23]. See page 120. (VERSIONS: PSPICE)
LEVEL = 3	$\rightarrow$	TOM or TriQuint model The name of this model derives from <i>TriQuint's Own Model</i> [24]. See page 120. (VERSIONS: PSPICE)
LEVEL = 4	$\rightarrow$	Curtice-Ettenberg Cubic model This is a refinement on the LEVEL 1 model [12]. It also uses simple empirical fits to measured data. See page 120.
LEVEL = 5	$\rightarrow$	Materka-Kacprzak model [13] A distinguishing characteristic is that the drain-source current is analytic and so it has better convergence characteristics than the other models. See page 138.
LEVEL = 6	$\rightarrow$	Angelov model Another empirical GASFET model with analytic characteristics. See page 143.
LEVEL = -1	$\rightarrow$	TOM-2 model An improved model from TriQuint. Another empirical GASFET model with analytic characteristics. See page 136.

### LEVEL 1, 2, 3 and 4 GASFET models

Many parameters of the LEVEL 1, 2, 3 and 4 GASFET models are the same and so these models will be considered together. The parameter keywords are given in table ??. It is assumed that the model parameters were determined or measured at the nominal temperature  $T_{\text{NOM}}$  (default 27°C) specified in the most recent .OPTIONS statement preceding the .MODEL statement.

Name	Description	Units	Default
AO	drain saturation current for $V_{GS} = 0$ (LEVEL=4)	А	0.1
	(VERSION: SOMEVERSIONSOFSPICE) $(A_0)$		
A1	coefficient of $V_1$ (primary transconductance parameter)	A/V	0.05
	(LEVEL=4) (VERSION: SOMEVERSIONSOFSPICE) $(A_1)$		
A2	coefficient of $V_1^2$ (LEVEL=4) (VERSION:	$A/V^2$	0
	SOMEVERSIONSOFSPICE) $(A_1)$		
A3	coefficient of $V_1^3$ (LEVEL=4) (VERSION:	$A/V^3$	0
	SOMEVERSIONSOFSPICE) $(A_1)$		
AAO	temperature cofficient of AO (LEVEL=4)	А	0
	(VERSION: SOMEVERSIONSOFSPICE) $(A_{A0})$		
AA1	temperature cofficient of A1 (LEVEL=4)	А	0
	(VERSION: SOMEVERSIONSOFSPICE) $(A_{A1})$		
AA2	temperature cofficient of A2 (LEVEL=4)	А	0
	$(VERSION: SOMEVERSIONSOFSPICE) \qquad (A_{A2})$		-
AA3	temperature cofficient of A3 (LEVEL=4)	А	0
	$(VERSION: SOMEVERSIONSOFSPICE) \qquad (A_{A3})$	1	
AALF	linear temperature coefficient of ALPHA (LEVEL=1,2,3,-1)	$^{\circ}\mathrm{C}^{-1}$	0
	(VERSION: SOME VERSIONS OF SPICE) $(A_{\alpha})$		-
AB	linear temperature coefficient of B (LEVEL=2,3)	°C <sup>-1</sup>	0
	$(VERSION: SOMEVERSIONSOFSPICE) (A_B)$	M 10.0	
ABET	linear temperature coefficient of BETA	%/°C	0
1000	(VERSION: SOME VERSIONSOF SPICE) $(A_{\beta})$	0.0-1	0
ACGS	linear temperature coefficient of CGS (LEVEL=1,3,4,-1)	°C 1	0
	$(VERSION: SOME VERSIONSOFSPICE) (A_{CGS})$	0.00-1	0
ACGD	linear temperature coefficient of CGD (LEVEL=1,3,4,-1)	°C 1	0
	$(VERSION: SOME VERSIONSOFSPICE) (A_{CGD})$	0.00-1	0
ADEL	linear temperature coefficient of DELTA (LEVEL=3,-1)	°C 1	0
4.5	(VERSION: SOME VERSIONSOF SPICE) $(A_{\delta})$		1
AF	flicker noise exponent $(A_F)$	-	1
AGAM	(UPD SION: SOME VED SIONS (LEVEL=1,3,4)	%/°C	0
A.T. A.M.	(VERSION: SOME VERSIONSOF SPICE) $(A_{\lambda})$	07/00	0
ALAM	mean temperature coefficient of LAMBDA (LEVEL=1,2,3) (VERSION: SOME VERSION: $(4)$ )	70/ °C	U
	(VERSION: SOME VERSIONSOF SPICE) $(A_{\lambda})$	$V^{-1}$	2
ALPHA	saturation voltage parameter (LEVEL=1,2,3,-1) ( $\alpha$ )	v $v^{-1}$	2
ALFA	Alternative keyword of ALPHA (LEVEL=1,2,3,-1)	v	2
	(version: SOME versions OF SPICE) ( $\alpha$ )	Continuel	
		Commuea o	n next page

Table 1.2: MESFET model parameter	able 7.2:	.2: MESFET	[ model	parameter
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Name	Description	Units	Default
AQ	linear temperature coefficient of $Q$ (LEVEL=3)	$^{\circ}\mathrm{C}^{-1}$	0
	(VERSION: SOMEVERSIONSOFSPICE) $(A_Q)$		
AR1	linear temperature coefficient of R1 (LEVEL=1,4)	$^{\circ}\mathrm{C}^{-1}$	0
	(VERSION: SOMEVERSIONSOFSPICE) $(A_{R1})$		
AR2	linear temperature coefficient of R2 (LEVEL=1,4)	$^{\circ}\mathrm{C}^{-1}$	0
	$(VERSION: SOMEVERSIONSOFSPICE) \qquad (A_{R2})$		-
ALPHATCE	exponential temperature coefficient of ALPHA (LEVEL=-1)	%/°C	0
ARD	alternative keyword for TRD1 $(T_{C,\alpha})$	$^{\circ}\mathrm{C}^{-1}$	0
ARF	linear temperature coefficient of RF (LEVEL=1.4) $(A_{RF})$	$^{\circ}\mathrm{C}^{-1}$	0
ARG	alternative keyword for TRG1 $(A_{RG})$	$^{\circ}\mathrm{C}^{-1}$	0
ARI	linear temperature coefficient of RI $(A_{RI})$	$^{\circ}\mathrm{C}^{-1}$	0
ARS	alternative keyword for TRS1 $(A_{RS})$	$^{\circ}\mathrm{C}^{-1}$	0
AT	linear temperature coefficient of TAU $(A_{\tau})$	$^{\circ}\mathrm{C}^{-1}$	0
AU	linear temperature coefficient of U (LEVEL=1.3) $(A_{II})$	$^{\circ}\mathrm{C}^{-1}$	0
AVDS	linear temperature coefficient of VDS0 (LEVEL=4) $(A_{VDS0})$	$^{\circ}\mathrm{C}^{-1}$	0
AVBD	linear temperature coefficient of VBD $(A_{VBD})$	$^{\circ}\mathrm{C}^{-1}$	0
Αντο	(AVT-zero) linear temperature coefficient of VTO $(A_{VT0})$	$^{\circ}\mathrm{C}^{-1}$	0
В	doping tail extending parameter (B)	$V^{-1}$	0.3
_	(VERSION: PSPICE) (LEVEL=2)		
	(VERSION: SOMEVERSIONSOFSPICE) (LEVEL=2,3)		
BETA	transconductance coefficient (LEVEL=1,2,3) $(\beta)$	$A/V^2$	0.1
BETA	transconductance coefficient (LEVEL=4)	$1/V^2$	0
	(VERSION: SOMEVERSIONSOFSPICE) $(\beta)$	,	
BETATCE	exponential temperature coefficient of	%/°C	0
	BETA $(T_{C,\beta})$		
BRD	quadratic temperature coefficient of RD	$^{\circ}\mathrm{C}^{-2}$	0
	(VERSION: SOMEVERSIONSOFSPICE) $(B_{RD})$	8	
BRG	quadratic temperature coefficient of RG	$^{\circ}\mathrm{C}^{-2}$	0
	$(VERSION: SOMEVERSIONSOFSPICE) \qquad (B_{RG})$	- 9	
BRI	quadratic temperature coefficient of RI	$^{\circ}\mathrm{C}^{-2}$	0
	$(VERSION: SOME VERSIONS OF SPICE) \qquad (B_{RI})$	<sup>2</sup>	
BRS	quadratic temperature coefficient of RS	°C 2	0
DUTO	(VERSION: SOME VERSIONSOF SPICE) $(B_{RD})$	00-2	0
BALO	quadratic temperature coefficient of VTO $(P_{\text{L}})$	°C -	0
CDC	$(VERSION: SOME VERSIONSOFSPICE) (B_{VT0})$ $(C)$	Б	0
CDS	$\begin{array}{c} \text{drain-source capacitance} \\ \text{constraints} \\ c$	Г	0
CGD	zero-bias gate-dram p-n capacitance $(C_{GD})$	Г	0
CGDU	$(VERSION \cdot SOME VERSIONS OF Spice) $	T,	0
CGS	( $C_{GD}$ ) zero-bias gate-source p-n capacitance ( $C_{GD}$ )	F	0
CGSO	alternative keyword for CGS	F	0
5450	(VERSION: SOMEVERSIONSOFSPICE) $(C_{CCS})$		Š
DELTA	output feedback parameter (I.EVEL=3) $(\delta)$	$(AV)^{-1}$	0
DELTA	$\begin{array}{c} \text{output feedback parameter (LEVEL=-1)} \\ (\delta) \end{array}$	$(AV)^{-1}$	0.2
JULIA		Continued or	n next page
		Communa 0	

Table 7.2: MESFET model parameters.

Name	Description	Units	Default
DELT	alternative keyword for DELTA (LEVEL=3)	$(AV)^{-1}$	0
	(VERSION: SOMEVERSIONSOFSPICE) $(\delta)$		
DELT	alternative keyword for DELTA (LEVEL=-1)	$(AV)^{-1}$	0
	(VERSION: SOMEVERSIONSOFSPICE) $(\delta)$		
DLVL	breakdown model flag not used	-	1
	DLVL = 1 use original model		
	= 2 use enhanced model		
E	drain current power law coefficient	-	2
	(VERSION: SOMEVERSIONSOFSPICE) (LEVEL=1) $(E)$		
EG	bandgap voltage (barrier height) at 0 K $(E_G(0))$	eV	1.52
	Schottky Barrier Diode: 0.69		
	Silicon: 1.16		
	Gallium Arsenide: 1.52		
50	Germanium: $0.67$ (LEVEL=1,2,3,4)	17	1 1 1
EG	bandgap voltage (barrier height) at 0 K $(E_G(0))$	ev	1.11
	Schottky Barrier Diode: 0.69		
	Shicon: 1.10 Calliana Anamida, 1.52		
	Gamun Arsenide: 1.52		
EC	Germanum: 0.07 (LEVEL=-1)		0.5
FC CAMMA	$\begin{array}{c} \text{forward-bias depiction capacitance factor} & (F_C) \\ \text{Static feedback parameter also known as} \end{array}$	-	0.0
GAMMA	static recuback parameter also known as	-	0
	(VERSION: DSDICE) (LEVEL -2)		
	(VERSION: I SPICE) (LEVEL-3) (VERSION: SOME VERSIONS (VERSION: $(I = 1, 3)$ ) (a)		
GAMA	elternative keyword for GAMMA	_	0
UNIN	$(VERSION \cdot SOME VERSIONS OF SPICE)$ (LEVEL 1 3 -1)	-	0
	$(VERSION: SOME VERSIONSOFSFICE) (EEVEL 1,0, 1)$ $(\gamma)$		
GAMA	Slope of drain characteristic in the linear region	_	1.5
-	(LEVEL=4) (VERSION: SOMEVERSIONSOFSPICE) $(\gamma')$		-
GAMMATCE	exponential temperature coefficient of	%/°C	0
	GAMMA $(T_{C,\gamma})$	,	
GAP1	First bandgap correction factor $(F_{GAP1})$	eV/°C	0.000541
	Silicon: 0.000473	7	
	Old Value for Silicon: 0.000702		
	Gallium Arsenide: 0.000541		
	Germanium: 0.000456		
	(version: HSpice; SomeVersionsOfSpice)		
GAP2	Second bandgap correction factor $(F_{GAP2})$	$^{\circ}\mathrm{C}$	0.000204
	Silicon: 0.000636		
	Old Value for Silicon: 0.001108		
	Gallium Arsenide: 0.000204		
	Germanium: 0.000210		
	(VERSION: HSPICE; SOMEVERSIONSOFSPICE)		
GMAX	enhanced breakdown model parameter not used	S	0
IS	gate p-n saturation current $(I_S)$	А	1E-14
K1	enhanced breakdown model parameter not used	$V^{-1}$	0
		Continued of	n next page

Table 7.2: MESFET model parameters.

Name	Description	Units	Default
К2	enhanced breakdown model parameter not used	V	0
КЗ	enhanced breakdown model parameter not used	$V^2$	0
KF	flicker noise coefficient $(K_F)$	-	0
LAMBDA	channel-length modulation (LEVEL=1,2,3,-1) $(\lambda)$	$V^{-1}$	0
LAMB	alternative keyword for LAMBDA (LEVEL=1,2,3)	$V^{-1}$	0
	(VERSION: SOMEVERSIONSOFSPICE) $(\lambda)$		
LEVEL	model index $1 \rightarrow \text{Curtice quadratic model}$	-	1
	$2 \rightarrow \text{Raytheon model}$		
	$3 \rightarrow \text{TOM}$ (Triquint) model		
	$4 \rightarrow \text{Curtice cubic model}$		
	$5 \rightarrow Materka-Kacprzak model$		
	$6 \rightarrow \text{Angelov model}$		
-	LEVELS 4,5,6 SOMEVERSIONSOFSPICE only		
M	gate p-n grading coefficient $(M)$	-	0.5
MGS	gate-source p-n grading coefficient	-	М
	$(VERSION: SOME VERSIONS OF SPICE) \qquad (M_{GS})$		
MGD	gate-drain p-n grading coefficient	-	М
	(VERSION: SOME VERSIONS OF SPICE) $(M_{GS})$		1
N	gate p-n emission coefficient (n)	-	1
NG	constant part of threshold ideality factor LEVEL -1 SOMEV-	-	1
ND	ERSIONSOFSPICE ONly $(N_G)$	<b>V</b> 7-1	0
ND	part of threshold ideality factor that depends on $V_{DS}$	v -	0
NDI T	<b>LEVEL -1</b> SOME VERSIONS OF SPICE ONLY $(N_D)$		0
ML PI	(NOT USED) (VERSION: SOME VERSIONSOF SPICE) $(V_{GMN})$	5	0
Q	power-law parameter (LEVEL=3,-1) $(Q)$	-	2
R1	breakdown gate-drain resistance (LEVEL=1,4)	Ω	$\infty$
	(VERSION: SOMEVERSIONSOFSPICE) NOT USED $(R_1)$		
R2	breakdown dependency on channel current $(LEVEL=1,4)$	Ω	0
	(VERSION: SOMEVERSIONSOFSPICE) (LEVEL= $1,4$ ) Not		
	USED $(R_2)$		
RD	drain resistance $(R_D)$	Ω	0
RF	forward-biased gate-source resistance (LEVEL=1,4)	Ω	$\infty$
	(VERSION: SOMEVERSIONSOFSPICE) $(R_F)$		_
RG	gate resistance $(R_G)$	Ω	0
RI	channel resistance (NOT USED)	Ω	0
	(VERSION: SOMEVERSIONSOFSPICE) $(R_I)$		
RS	source resistance $(R_S)$	Ω	0
Т	alternative keyword for TAU	s	U
<b></b>	(VERSION: SOME VERSIONS OF SPICE) $(\tau)$		0
I.BE.I.	alternative keyword for BETATCE	s	U
<b>T</b> T	(VERSION: SOME VERSIONSOF SPICE) $(T_{C,\beta})$		0
11	Junction temperature (NOT USED)	s	U
TM	(VERSION: SOME VERSIONSOF SPICE) $(T_J)$		0
	(NOT USED) (VERSION: SOME VERSIONSOF SPICE) $(T_M)$	S	0
IME	(NOT USED) (VERSION: SOMEVERSIONSOFSPICE) $(T_{ME})$	S Clautin 1	0
		Continued of	n next page

Table 7.2: MESFET model parameters.

Name	Description	Units	Default
TNOM	nominal temperature (NOT USED)	s	0
	(VERSION: SOMEVERSIONSOFSPICE) $(T_{\text{NOM}})$		
TAU	conduction current delay time $(\tau)$	s	0
TRG1	linear temperature coefficient of RG $(A_{RG})$	$^{\circ}\mathrm{C}^{-1}$	0
TRD1	linear temperature coefficient of RD $(A_{RD})$	$^{\circ}\mathrm{C}^{-1}$	0
TRS1	linear temperature coefficient of RS $(A_{RS})$	$^{\circ}\mathrm{C}^{-1}$	0
U	critical field parameter for mobility degradation	V/m	0
	(LEVEL=1,2,3)		
	$(VERSION: SOMEVERSIONSOFSPICE) \qquad (U)$		
VBI	gate p-n potential $(V_{\rm BI})$	V	1
VBR	enhanced breakdown model parameter not used	$V^2$	$\infty$
VBD	breakdown voltage	V	$\infty$
	(VERSION: SOMEVERSIONSOFSPICE) $(A_{VBD})$		
VDELTA	capacitance transistion voltage	V	0.2
	$(\text{LEVEL}=2,3) \tag{V_{\Delta}}$		
VDSO	$V_{DS}$ at which BETA was measured	V	4
	$(\text{LEVEL}=4) \tag{V}_{\Delta}$		
VGMN	(NOT USED) $(V_{GMN})$	s	0
VGMX	(NOT USED) $(V_{GMN})$	s	0
VDMX	(NOT USED) $(V_{GMN})$	s	0
VMAX	capacitance limiting voltage	V	0.5
	$(\text{LEVEL=2,3})$ $(V_{\text{MAX}})$		
VTO	$(VT-oh)$ pinch-off voltage $(V_{T0})$	V	-2.5
VTO	(VT-0) alternative keyword for VTO	V	-2.5
	(VERSION: SOMEVERSIONSOFSPICE) $(A_{VDS0})$		
VTOTC	linear temperature coefficient of VTO $(T_{C,VT0})$	V/°C	0
XTI	temperature exponent of IS $(X_{TI})$	-	0
VBITC	linear temperature coefficient of VBI $(T_{C,BI})$	-	0

Table 7.2: MESFET model parameters.

Some versions of SPICE use incorrect default values for some of the parameters. One example is the default value for EG. The accepted value has changed with time. It is always a good idea not to rely on default values other than 0.

The physical constants used in the model evaluation are

k	Boltzmann's constant	$1.3806226  10^{-23} \; \mathrm{J/K}$
q	electronic charge	$1.6021918  10^{-19} \mathrm{C}$

### Standard Calculations

Absolute temperatures (in kelvins, K) are used. The thermal voltage  $V_{\rm TH} = kT/q$  and the band gap energy at the nominal temperature is

$$E_G(T_{\rm NOM}) = E_G(0) - F_{\rm GAP1} 4T_{\rm NOM}^2 / (T_{\rm NOM} + F_{\rm GAP2}).$$
(7.1)

Here  $E_G(0)$  is the parameter EG — the band gap energy at 0 K.  $F_{\text{GAP1}}$  and  $F_{\text{GAP2}}$  are not parameters in PSPICE. PSPICE documentation indicates that PSPICE uses  $F_{\text{GAP1}} = 0.000702$  and  $F_{\text{GAP2}} = 1108$ .

### Temperature Dependence

Temperature effects are incorporated as follows where T and  $T_{\rm NOM}$  are absolute temperatures in Kelvins (K).

$$\alpha(T) = \alpha(T_{\text{NOM}}) \left( 1.01^{\left( T_{C,\alpha} \left( T - T_{\text{NOM}} \right) \right)} + A_{\alpha} \left( T - T_{\text{NOM}} \right) \right)$$
(7.2)

$$\beta(T) = \beta(T_{\text{NOM}}) \left( 1.01^{(T_{C,\beta}(T - T_{\text{NOM}}))} + A_{\beta}(T - T_{\text{NOM}}) \right)$$
(7.3)

$$I_{S}(T) = I_{S}(T_{\text{NOM}})e^{\left(E_{G}(T)T/T_{\text{NOM}} - E_{G}(T)\right)/(nV_{\text{TH}})} (T/T_{\text{NOM}})^{\left(X_{TI}/n\right)}$$
(7.4)

$$C_{GS}'(T) = \begin{cases} C_{GS}(T_{\text{NOM}}) \left\{ 1 + M_{GS} \left[ 0.0004(T - T_{\text{NOM}}) + \left( 1 - \frac{V_{BI}(T)}{V_{BI}(T_{\text{NOM}})} \right) \right] \right\} \\ A_{CGS} \text{ not specified} \\ C_{GS}(T_{\text{NOM}})(1 + A_{CGS}(T - T_{\text{NOM}})) & A_{CGS} \text{ specified} \\ C_{GD}(T) = \begin{cases} C_{GD}(T_{\text{NOM}}) \left\{ 1 + M_{GD} \left[ 0.0004(T - T_{\text{NOM}}) + \left( 1 - \frac{V_{BI}(T)}{V_{BI}(T_{\text{NOM}})} \right) \right] \right\} \\ A_{CGD} \text{ not specified} \\ C_{GD}(T_{\text{NOM}})(1 + A_{CGD}(T - T_{\text{NOM}})) & A_{CGD} \text{ specified} \end{cases}$$

$$E_G(T) = E_G(0) - F_{\text{GAP1}} 4T^2 / (T + F_{\text{GAP2}})$$
(7.5)

$$\lambda(T) = \lambda(T_{\text{NOM}})(1 + A_{\lambda}(T - T_{\text{NOM}}))$$
(7.6)

$$\alpha(T) = \begin{cases} \alpha(T_{\text{NOM}})(1 + A_{\alpha}(T - T_{\text{NOM}})) \text{ LEVEL} = 1,2,3\\ \alpha(T_{\text{NOM}})(1.01^{T_{C,\alpha}(T - T_{\text{NOM}})} + A_{\alpha}(T - T_{\text{NOM}}))\\ A_{\alpha}(T - T_{\text{NOM}})) \text{ LEVEL} = -1 \end{cases}$$
(7.7)

$$U(T) = U(T_{\text{NOM}})(1 + A_U(T - T_{\text{NOM}}))$$
(7.8)

$$A_0(T) = A_0(T_{\text{NOM}})(1 + A_{A0}(T - T_{\text{NOM}}))$$
(7.9)

$$A_1(T) = A_1(T_{\text{NOM}})(1 + A_{A1}(T - T_{\text{NOM}}))$$
(7.10)

$$A_2(T) = A_2(T_{\text{NOM}})(1 + A_{A2}(T - T_{\text{NOM}}))$$
(7.11)

$$A_3(T) = A_3(T_{\text{NOM}})(1 + A_{A3}(T - T_{\text{NOM}}))$$
(7.12)

$$\delta(T) = \delta(T_{\text{NOM}})(1 + A_{\delta}(T - T_{\text{NOM}}))$$
(7.13)
(7.14)

$$\gamma(T) = \gamma(T_{\text{NOM}})(1 + A_{\gamma}(T - T_{\text{NOM}}))$$
(7.14)
$$Q(T) = Q(T_{\gamma})(1 + A_{\gamma}(T - T_{\gamma}))$$
(7.15)

$$Q(T) = Q(T_{\text{NOM}})(1 + A_Q(T - T_{\text{NOM}}))$$

$$(7.15)$$

$$P_{-}(T) = P_{-}(T_{-})(1 + A_{-}(T_{-}, T_{-}))$$

$$(7.16)$$

$$R_1(T) = R_1(T_{\text{NOM}})(1 + A_{R1}(T - T_{\text{NOM}}))$$

$$R_2(T) = R_2(T_{\text{NOM}})(1 + A_{R2}(T - T_{\text{NOM}}))$$
(7.10)
(7.17)

$$R_{\rm D}(T) = R_{\rm D}(T_{\rm NOM})(1 + A_{R2}(T - T_{\rm NOM}))$$

$$(7.11)$$

$$R_{\rm D}(T) = R_{\rm D}(T_{\rm NOM})(1 + A_{RD}(T - T_{\rm NOM}) + R_{RD}(T - T_{\rm NOM})^2)$$

$$(7.18)$$

$$R_D(T) = R_D(T_{\text{NOM}}) \left( 1 + A_{RD}(T - T_{\text{NOM}}) + B_{RD}(T - T_{\text{NOM}})^2 \right)$$
(7.18)  
$$R_-(T) = R_-(T_{\text{NOM}}) \left( 1 + A_{--}(T - T_{\text{NOM}}) \right)$$
(7.19)

$$R_F(T) = R_F(T_{\text{NOM}})(1 + A_{RF}(T - T_{\text{NOM}}))$$

$$(7.19)$$

$$P_{N}(T) = P_{N}(T_{NOM})(1 + A_{NF}(T - T_{NOM})) + P_{N}(T_{NOM})^{2}$$

$$(7.20)$$

$$R_G(T) = R_G(T_{\text{NOM}}) \left( 1 + A_{RG}(T - T_{\text{NOM}}) + B_{RG}(T - T_{\text{NOM}})^2 \right)$$
(7.20)

$$R_S(T) = R_S(T_{\text{NOM}}) \left( 1 + A_{RS}(T - T_{\text{NOM}}) + B_{RS}(T - T_{\text{NOM}})^2 \right)$$
(7.21)

$$R_I(T) = R_I(T_{\text{NOM}}) \left( 1 + A_{RI}(T - T_{\text{NOM}}) + B_I(T - T_{\text{NOM}})^2 \right)$$
(7.22)

$$\tau(T) = \tau(T_{\text{NOM}})(1 + A_{\tau}(T - T_{\text{NOM}}))$$
(7.23)

$$V_{BD}(T) = V_{BD}(T_{\rm NOM})(1 + A_{VBD}(T - T_{\rm NOM}))$$
(7.24)

$$V_{BI}(T) = \begin{cases} V_{BI}(T_{\text{NOM}})T/T_{\text{NOM}} - 3V_{\text{TH}}\ln\left(T/T_{\text{NOM}}\right) \text{ LEVEL } \neq -1\\ V_{BI}(T_{\text{NOM}})T/T_{\text{NOM}} + T_{C,VBI}(T - T_{\text{NOM}})\text{ LEVEL } = -1\\ + E_G(T_{\text{NOM}})T/T_{\text{NOM}} - E_G(T) \end{cases}$$
(7.25)

$$V_{DS0}(T) = V_{DS0}(T_{\rm NOM})(1 + A_{VDS0}(T - T_{\rm NOM}))$$
(7.26)

$$V_{T0}(T) = V_{T0} \left( 1 + A_{VT0} (T - T_{NOM}) + B_{VT0} (T - T_{NOM})^2 \right)$$

$$+T_{C,VT0}(T-T_{NOM})$$
 (7.27)

$$V_{VMAX}(T) = V_{VMAX}(T_{\text{NOM}}) + T_{C,VMAX}(T - T_{\text{NOM}}) \text{LEVEL} = -1$$
(7.28)

Parasitic Resistances

The resistive parasities  $R'_S$ , and  $R'_D$  are calculated from the sheet resistivities  $RS (= R_S)$  and  $RD (= R_D)$ , and the Area specified on the element line.  $RG (= R_G)$  is used as supplied.

$$R'_D = R_D / Area \tag{7.29}$$

$$R'_{G} = \begin{cases} R_{G} & \text{PSPICE} \\ R_{G}/4rea & \text{SOMEVERSIONSOFSPICE} \end{cases}$$
(7.30)

$$\frac{n_G}{Area} = \frac{1}{2} \frac{n_G}{Area}$$

$$R_S = R_S / Area \tag{7.31}$$

The parasitic resistance parameter dependencies are summarized in figure 7.4. Leakage Currents

Current flows across the normally reverse biased gate-source and gate-drain junctions. The gate-source leakage current  $I_{GS} = Area I_S e^{(V_{GS}/V_{TH} - 1)}$  (7.32) and the gate-drain leakage current  $I_{GD} = Area I_S e^{(V_{GD}/V_{TH} - 1)}$  (7.33)

The dependencies of the parameters describing the leakage current are summarized in figure 7.5.

KEY	WORD	+	GEOMETRY	$\rightarrow$	DEVICE
PARAM	METERS		PARAMETER		PARAMETERS
RD	$R_D$		Area		$R'_D = f(Area, R_D)$
RG	$R_G$				$R'_G = f(Area, R_G)$
RS	$R_S$				$R'_S = f(Area, R_S)$

Figure 7.4: MESFET parasitic resistance parameter relationships.

KEYWORD	+	GEOMETRY	$\rightarrow$	DEVICE
PARAMETERS		PARAMETER		PARAMETERS
IS $I_S$		Area		$I_{GS} = f(I_S, Area)$
				$I_{GD} = f(I_S, Area)$

Figure 7.5: GASFET leakage current parameter dependencies.

#### LEVEL 1 (Curtice Model)

LEVEL 1 (Curtice Model) I/V Characteristics

The LEVEL 1 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point. Curtice [11] proposed two DC current models: a quadratic channel current model and a cubic channel current model. The quadratic channel model is implemented as the LEVEL 1 model.

Normal Mode:  $(V_{DS} \ge 0)$ 

The regions of operation are defined as follows with 
$$V_{GST} = V_{GS} - (V_{T0} - \gamma V_{DS})$$
 (7.34)  
cutoff region:  $V_{GST}(t-\tau) \leq 0$   
linear and saturation regions:  $V_{GST}(t-\tau) > 0$ 

Then

$$I_{DS} = \begin{cases} 0 & \text{cutoff region} \\ Area \frac{\beta (1 + \lambda V_{DS})}{1 + U V_{GST} (t - \tau)} V_{GST}^E (t - \tau) \tanh (\alpha V_{DS}) & \text{linear, saturation regions} \end{cases}$$
(7.35)

Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the MESFET I/V characteristics are evaluated as in the normal mode (7.35) but with the drain and source subscripts exchanged, and  $V_{GD}$  is the controlling voltage instead of  $V_{GS}$ .

The relationships of the parameters describing the I/V characteristics for the LEVEL 1 model are summarized in figure 7.6.

### LEVEL 1 (Curtice Model) Capacitances

KEYWO	ORD	+	GEOMETRY	$\rightarrow$	DEVICE
PARAME	TERS		PARAMETER		PARAMETERS
ALPHA	$\alpha$		Area		$I_{DS} = f(Area, \alpha, \beta, \lambda, U, V_{T0})$
BETA	$\beta$				
LAMBDA	$\lambda$				
U	U				
VTO	$V_{T0}$				

Figure 7.6: LEVEL 1 (Curtice model) I/V dependencies.

The drain-source capacitance

$$C_{DS}' = Area C_{DS} \tag{7.36}$$

The gate-source capacitance

$$C_{GS}' = \begin{cases} Area C_{GS} \left(1 - \frac{V_{GS}}{V_{BI}}\right)^{-M_{GS}} & V_{GS} \le F_C V_{BI} \\ Area C_{GS} \left(1 - F_C\right)^{-(1+M_{GS})} \left[1 - F_C (1+M_{GS}) + M_{GS} \frac{V_{GS}}{V_{BI}}\right] & V_{GS} > F_C V_{BI} \end{cases}$$
(7.37)

The gate-drain capacitance

$$C'_{GD} = \begin{cases} Area C_{GD} \left(1 - \frac{V_{GD}}{V_{BI}}\right)^{-M_{GD}} & V_{GD} \le F_C V_{BI} \\ Area C_{GD} \left(1 - F_C\right)^{-(1 + M_{GD})} \left[1 - F_C (1 + M_{GD}) + M_{GD} \frac{V_{GD}}{V_{BI}}\right] & V_{GS} > F_C V_{BI} \end{cases}$$
(7.38)

The LEVEL 1 capacitance parameter dependencies are summarized in figure 7.7.



Figure 7.7: LEVEL 1 (Curtice model) capacitance dependencies.

### LEVEL 2 (Raytheon Model)

LEVEL 2 (Raytheon Model) I/V Characteristics

The LEVEL 2 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point.

Normal Mode:  $(V_{DS} \ge 0)$ 

(7.39)

The regions of operation are defined as follows with  $V_{GST} = V_{GS} - V_{T0}$ 

cutoff region:  $V_{GST}(t-\tau) \leq 0$ linear region:  $V_{GST}(t-\tau) > 0$  and  $V_{DS} \leq 3/\alpha$ saturation region:  $V_{GS}(t-\tau) > V_{T0}$  and  $V_{DS} > 3/\alpha$ 

Then

$$I_{DS} = \begin{cases} 0 & \text{cutoff region} \\ Area \frac{\beta}{1 + UV_{GST}} (1 + \lambda V_{DS}) \frac{V_{GST}(t - \tau)^2}{1 + BV_{GST}(t - \tau)} \text{Ktanh} & \text{linear and saturation} \\ & \text{regions} \end{cases}$$
(7.40)

where

$$Ktanh = \begin{cases} 1 - \left(1 - V_{DS}\frac{\alpha}{3}\right)^3 & \text{linear region} \\ 1 & \text{saturation regions} \end{cases}$$
(7.41)

is a Taylor series approximation to the tanh function of the LEVEL 1 model.

Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the MESFET I/V characteristics are evaluated as in the normal mode (7.40) but with the drain and source subscripts exchanged, and  $V_{GD}$  is the controlling voltage instead of  $V_{GS}$ .

The relationships of the parameters describing the I/V characteristics of the LEVEL 2 model are summarized in figure 7.8.



Figure 7.8: LEVEL 2 (Raytheon model) I/V dependencies.

LEVEL 2 (Raytheon Model) Capacitances

### $GaAs\ MESFET$

This is a symmetrical capacitance model. The drain-source capacitance  $C'_{DS} = Area C_{DS}$  (7.42) The gate-source capacitance

$$C'_{GS} = Area \left[ C_{GS} F_1 F_2 \left( 1 - \frac{V_{\rm NEW}}{V_{BI}} \right)^{-\frac{1}{2}} + C_{GD} F_3 \right]$$
(7.43)

The gate-drain capacitance

$$C'_{GD} = Area \left[ C_{GS} F_1 F_3 \left( 1 - \frac{V_{\rm NEW}}{V_{BI}} \right)^{-\frac{1}{2}} + C_{GD} F_2 \right]$$
(7.44)

where

$$F_{1} = \frac{1}{2} \left\{ 1 + \frac{V_{\rm EFF} - V_{T0}}{\sqrt{(V_{\rm EFF} - V_{T0})^{2} + V_{\Delta}^{2}}} \right\}$$
(7.45)

$$F_2 = \frac{1}{2} \left\{ 1 + \frac{V_{GS} - V_{GD}}{\sqrt{(V_{GS} - V_{GD})^2 + \alpha^{-2}}} \right\}$$
(7.46)

$$F_3 = \frac{1}{2} \left\{ 1 - \frac{V_{GS} - V_{GD}}{\sqrt{(V_{GS} - V_{GD})^2 + \alpha^{-2}}} \right\}$$
(7.47)

$$V_{\rm EFF} = \frac{1}{2} \left\{ V_{GS} + V_{GD} + \sqrt{\left(V_{GS} - V_{GD}\right)^2 + \alpha^{-2}} \right\}$$
(7.48)

$$V_{\text{NEW}} = \begin{cases} A_1 & A_1 < V_{\text{MAX}} \\ V_{\text{MAX}} & A_1 \ge V_{\text{MAX}} \end{cases}$$
(7.49)

$$A_1 = \frac{1}{2} \left[ V_{\rm EFF} + V_{T0} + \sqrt{(V_{\rm EFF} - V_{T0})^2 + V_{\Delta}^2} \right]$$
(7.50)

The capacitance parameter dependencies are summarized in figure 7.9. The above capacitance model

KEYWORD PARAMETERS		+	GEOMETRY PARAMETER	$\rightarrow$	DEVICE PARAMETERS
ALPHA	$\alpha$		Area		$C_{DS}' = f(Area, C_{DS})$
CGD	$C_{GD}$				$C'_{GD} = f(Area, C_{GD}, \alpha,$
CGS	$C_{GS}$				$B, F_C, V_{BI}, V_{T0})$
CDS	$C_{DS}$				$C'_{GS} = f(Area, C_{GS}, \alpha,$
VBI	$V_{BI}$				$B, F_C, V_{BI}, V_{T0})$
VTO	$V_{T0}$				
VDELTA	$V_{\Delta}$				
VMAX	$V_{\rm MAX}$				

Figure 7.9: LEVEL 2 (Raytheon model) capacitance dependencies.

does not satisfy drain-source charge conservation. Over a cycle, charge can be pumped from the drain to the source. In practice this is often not a problem when this capacitance model is used buyt the user must be ware. If it is a problem the user will see a periodic reponse can not be obtained even if the excotation is periodic. For a further discussion see References [26,27].

The above capacitance model does not satisfy drani-source charge conservation. Over a cycle charge can be pumped from the drain to the source. In practice this is often not a problem when this capacitance model is used but the user must be wary. If it is a problem the user will see that a periodic response can not be obtained even if the excitation is periodeic. For a further discussion see References [26] and [27]. **LEVEL 3 (TOM Model)** 

The LEVEL 3 model is an implementation of the TOM model ("Triquint's Own Model) [24].

### LEVEL 3 (TOM Model) I/V Characteristics

The LEVEL 3 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point. Normal Mode: ( $V_{DS} \ge 0$ )

The regions of operation are defined as follows with  $V_{GST} = V_{GS} - V_P$  (7.51) and  $V_P = V_{T0} - \gamma V_{DS}$  (7.52)

 $\begin{array}{ll} \text{cutoff region:} & V_{GST}(t-\tau) \leq 0 \\ \text{linear region:} & V_{GST}(t-\tau) > 0 \text{ and } V_{DS} \leq 3/\alpha \\ \text{saturation region:} & V_{GST}(t-\tau) > 0 \text{ and } V_{DS} > 3/\alpha \end{array}$ 

Then

$$I_{DS} = Area I_{DS0} / (1 + \delta I_{DS0} V_{DS})$$

$$(7.53)$$

$$I_{DS0} = \begin{cases} 0 & \text{cutoff region} \\ \beta(1+\lambda V_{DS})V_{GST}^Q(t-\tau)\text{Ktanh} & \text{linear and saturation regions} \end{cases}$$
(7.54)

Ktanh = 
$$\begin{cases} 1 - \left(1 - V_{DS} \frac{\alpha}{3}\right)^3 & \text{linear region} \\ 1 & \text{saturation region} \end{cases}$$
(7.55)

Ktanh is a taylor series approximation to the tanh function of the LEVEL 1 model.

Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the MESFET I/V characteristics are evaluated as in the normal mode (7.75) but with the drain and source subscripts exchanged, and  $V_{GD}$  used as the controlling voltage instead of  $V_{GS}$ . The following description does apply to SuperSpice.

The relationships of the parameters describing the I/V characteristics of the LEVEL 3 model are summarized in figure 7.13.

### LEVEL 3 (TOM MODEL) CAPACITANCES
KEYWORD		
PARAMETERS		
ALPHA	$\alpha$	
BETA	$\beta$	
DELTA	$\delta$	
GAMMA	$\gamma$	
LAMBDA	$\lambda$	
U	$\mu$	
VTO	$V_{T0}$	

\_\_\_\_\_

	DEVICE	$\rightarrow$	GEOMETRY	+
	PARAMETERS		PARAMETER	
	$I_{DS} = f(Area, \alpha, \beta, \delta, \gamma,$		Area	
))	$\lambda, UV_{T0})$			
-	$I_{DS} = f(Area, \alpha, \beta, \delta, \gamma, \lambda, UV_{TC})$		Area	

Figure 7.10: LEVEL 3 (TOM model) I/V dependencies.

\_\_\_\_\_

The drain-source capacitance  $C'_{DS} = Area C_{DS}$ The gate-source capacitance

$$C'_{GS} = Area \left[ C_{GS} F_1 F_2 \left( 1 - \frac{V_{\rm NEW}}{V_{BI}} \right)^{-\frac{1}{2}} + C_{GD} F_3 \right]$$
(7.57)

The gate-drain capacitance is given by

$$C'_{GD} = Area \left[ C_{GS} F_1 F_3 \left( 1 - \frac{V_{\text{NEW}}}{V_{BI}} \right)^{-\frac{1}{2}} + C_{GD} F_2 \right]$$
(7.58)

$$F_{1} = \frac{1}{2} \left\{ 1 + \frac{V_{\text{EFF}} - V_{P}}{\sqrt{(V_{\text{EFF}} - V_{T0})^{2} + V_{\Delta}^{2}}} \right\}$$
(7.59)

$$F_{2} = \frac{1}{2} \left\{ 1 + \frac{V_{GS} - V_{GD}}{\sqrt{(V_{GS} - V_{GD})^{2} + \alpha^{-2}}} \right\}$$
(7.60)

$$F_{3} = \frac{1}{2} \left\{ 1 - \frac{V_{GS} - V_{GD}}{\sqrt{\left(V_{GS} - V_{GD}\right)^{2} + \alpha^{-2}}} \right\}$$
(7.61)

$$V_{\rm EFF} = \frac{1}{2} \left\{ V_{GS} + V_{GD} + \sqrt{\left(V_{GS} - V_{GD}\right)^2 + \alpha^{-2}} \right\}$$
(7.62)

$$V_{\text{NEW}} = \begin{cases} A_1 & A_1 < V_{\text{MAX}} \\ V_{\text{MAX}} & A_1 \ge V_{\text{MAX}} \end{cases}$$
(7.63)

$$A_{1} = \frac{1}{2} \left[ V_{\rm EFF} + V_{P} + \sqrt{(V_{\rm EFF} - V_{P})^{2} + V_{\Delta}^{2}} \right]$$
(7.64)

The capacitance parameter dependencies are summarized in figure 7.14.

# LEVEL -1 (TOM-2 Model)

The LEVEL -1 model is an enhancement of the LEVEL 3 TOM model.

LEVEL -1 (TOM Model) I/V Characteristics

(7.56)

KEYW	ORD	+	GEOMETRY	$\rightarrow$	DEVICE
PARAM	ETERS	·	PARAMETER		PARAMETERS
ALPHA	$\alpha$		Area		$C'_{DS} = f(Area, C_{DS})$
CGD	$C_{GD}$				$C'_{GD} = f(Area, C_{GD},$
CGS	$C_{GS}$				$\alpha, B, F_C, V_{BI}, V_{T0})$
CDS	$C_{DS}$				$C'_{GS} = f(Area, C_{GS},$
VBI	$V_{BI}$				$\alpha, B, F_C, V_{BI}, V_{T0})$
VTO	$V_{T0}$				
LAMBDA	$V_{T0}$				
VMAX	$V_{\rm MAX}$				
VDELTA	$V_{\Delta}$				

Figure 7.11: LEVEL 3 (TOM model) capacitance dependencies.

The LEVEL -1 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point.

Normal Mode:  $(V_{DS} \ge 0)$ 

The regions of operation are defined as follows with  $V_{GST} = V_{GS} - V_P$  (7.65) and  $V_P = V_{T0} - \gamma V_{DS}$  (7.66)

 $\begin{array}{ll} \text{cutoff region:} & V_{GST}(t-\tau) \leq 0 \\ \text{linear region:} & V_{GST}(t-\tau) > 0 \text{ and } V_{DS} \leq 3/\alpha \\ \text{saturation region:} & V_{GST}(t-\tau) > 0 \text{ and } V_{DS} > 3/\alpha \end{array}$ 

Then

$$I_{DS} = Area I_{DS0} / (1 + \delta I_{DS0} V_{DS})$$

$$(7.67)$$

$$I_{DS0} = \begin{cases} 0 & \text{cutoff region} \\ \frac{\beta}{1 + UV_{GST}} V_{GST}^Q (t - \tau) F_d(\alpha V_{DS}) & \text{linear and saturation regions} \end{cases}$$
(7.68)

$$F_d(\alpha V_{DS}) = \frac{x}{\sqrt{1+x^2}} \tag{7.69}$$

$$V_G = QV_{ST} \ln \left[ exp \left( V_{GST} / (QV_{ST}) + 1 \right) \right]$$
(7.70)

$$V_{ST} = N_{ST}(kT/q) \tag{7.71}$$

$$N_{ST} = N_G + N_D V_{DS} \tag{7.72}$$

Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the MESFET I/V characteristics are evaluated as in the normal mode (7.92) but with the drain and source subscripts exchanged, and  $V_{GD}$  used as the controlling voltage instead of  $V_{GS}$ .

The relationships of the parameters describing the I/V characteristics of the LEVEL -1 model are summarized in figure 7.15.

# LEVEL -1 (TOM-2 MODEL) CAPACITANCES

These are evaluated the same way the LEVEL 3 capacitanceaas described on 135 are evaluated. LEVEL -1 (TOM2 Model)



Figure 7.12: LEVEL -1 (TOM-2 model) I/V dependencies.

The LEVEL -1 model is an implementation of the TOM model ("Triquint's Own Model) [24]. LEVEL -1 (TOM2 Model) I/V Characteristics

The LEVEL -1 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point.

Normal Mode:  $(V_{DS} \ge 0)$ 

The regions of operation are defined as follows with  $V_{GST} = V_{GS} - V_P$  (7.73) and  $V_P = V_{T0} - \gamma V_{DS}$  (7.74)

 $\begin{array}{ll} \text{cutoff region:} & V_{GST}(t-\tau) \leq 0 \\ \text{linear region:} & V_{GST}(t-\tau) > 0 \text{ and } V_{DS} \leq 3/\alpha \\ \text{saturation region:} & V_{GST}(t-\tau) > 0 \text{ and } V_{DS} > 3/\alpha \end{array}$ 

Then

$$I_{DS} = Area I_{DS0} / (1 + \delta I_{DS0} V_{DS})$$
(7.75)

$$I_{DS0} = \begin{cases} 0 & \text{cutoff region} \\ V_G^Q(t-\tau)F_d(\alpha V_{DS}) & \text{linear and saturation regions} \end{cases} (7.76)$$

$$F_d(x) = \frac{x}{\sqrt{1+x^2}}$$
(7.77)

$$V_G = QV_{ST} \ln\left[\exp\left(\frac{V_{GST}}{QV_{ST}}\right) + 1\right]$$
(7.78)

$$V_{ST} = N_{ST} \left(\frac{kT}{q}\right) \tag{7.79}$$

$$N_{ST} = N_G + N_D V_{DS} \tag{7.80}$$

Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the MESFET I/V characteristics are evaluated as in the normal mode (7.75) but with the drain and source subscripts exchanged, and  $V_{GD}$  used as the controlling voltage instead of  $V_{GS}$ . The relationships of the parameters describing the I/V characteristics of the LEVEL -1 model are summarized in figure 7.13.

KEYWORD		
PARAMET	TERS	
ALPHA	$\alpha$	
BETA	$\beta$	
DELTA	$\delta$	
GAMMA	$\gamma$	
LAMBDA	$\lambda$	
U	$\mu$	
VTO	$V_{T0}$	

GEOMETRY
PARAMETER
Area

DEVICE
PARAMETERS
$I_{DS} = f(Area, \alpha, \beta, \delta, \gamma,$
$\lambda, UV_{T0})$

Figure 7.13: LEVEL 3 (TOM model) I/V dependencies.

# LEVEL -1 (TOM2 MODEL) CAPACITANCES

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The LEVEL -1 (TOM2 Model) capacitances are identical to that of the LEVEL 3 model. This capacitance model is based on the model proposed by Statz as used in the level 2 model. This is a charge conserving symmetrical capacitance model.

The drain-source capacitance 
$$C'_{DS} = Area C_{DS}$$
 (7.81)

The gate-source capacitance

$$C'_{GS} = Area \left[ C_{GS} F_1 F_2 \left( 1 - \frac{V_{\rm NEW}}{V_{BI}} \right)^{-\frac{1}{2}} + C_{GD} F_3 \right]$$
(7.82)

The gate-drain capacitance is given by

$$C'_{GD} = Area \left[ C_{GS} F_1 F_3 \left( 1 - \frac{V_{\rm NEW}}{V_{BI}} \right)^{-\frac{1}{2}} + C_{GD} F_2 \right]$$
(7.83)

$$F_{1} = \frac{1}{2} \left\{ 1 + \frac{V_{\rm EFF} - V_{P}}{\sqrt{(V_{\rm EFF} - V_{T0})^{2} + V_{\Delta}^{2}}} \right\}$$
(7.84)

$$F_2 = \frac{1}{2} \left\{ 1 + \frac{V_{GS} - V_{GD}}{\sqrt{(V_{GS} - V_{GD})^2 + \alpha^{-2}}} \right\}$$
(7.85)

$$F_3 = \frac{1}{2} \left\{ 1 - \frac{V_{GS} - V_{GD}}{\sqrt{(V_{GS} - V_{GD})^2 + \alpha^{-2}}} \right\}$$
(7.86)

$$V_{\rm EFF} = \frac{1}{2} \left\{ V_{GS} + V_{GD} + \sqrt{\left(V_{GS} - V_{GD}\right)^2 + \alpha^{-2}} \right\}$$
(7.87)

$$V_{\text{NEW}} = \begin{cases} A_1 & A_1 < V_{\text{MAX}} \\ V_{\text{MAX}} & A_1 \ge V_{\text{MAX}} \end{cases}$$
(7.88)

and

$$A_1 = \frac{1}{2} \left[ V_{\rm EFF} + V_P + \sqrt{(V_{\rm EFF} - V_P)^2 + V_\Delta^2} \right]$$
(7.89)

The capacitance parameter dependencies are summarized in figure 7.14.

KEYWORD				
PARAM	ETERS			
ALPHA	$\alpha$			
CGD	$C_{GD}$			
CGS	$C_{GS}$			
CDS	$C_{DS}$			
VBI	$V_{BI}$			
VTO	$V_{T0}$			
LAMBDA	$V_{T0}$			
VMAX	$V_{\rm MAX}$			
VDELTA	$V_{\Delta}$			

GEOMETRY PARAMETER Area

DEVICE
PARAMETERS
$C'_{DS} = f(Area, C_{DS})$
$C'_{GD} = f(Area, C_{GD},$
$\alpha, B, F_C, V_{BI}, V_{T0})$
$C'_{GS} = f(Area, C_{GS},$
$\alpha, B, F_C, V_{BI}, V_{T0})$

Figure 7.14: LEVEL 3 (TOM model) capacitance dependencies.

### LEVEL -1 (TOM-2 Model)

The LEVEL -1 model is an enhancement of the LEVEL 3 TOM model.

# LEVEL -1 (TOM Model) I/V Characteristics

+

The LEVEL -1 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point.

Normal Mode:  $(V_{DS} \ge 0)$ 

The regions of operation are defined as follows with  $V_{GST} = V_{GS} - V_P$  (7.90) and  $V_P = V_{T0} - \gamma V_{DS}$  (7.91)

 $\begin{array}{ll} \text{cutoff region:} & V_{GST}(t-\tau) \leq 0 \\ \text{linear region:} & V_{GST}(t-\tau) > 0 \text{ and } V_{DS} \leq 3/\alpha \\ \text{saturation region:} & V_{GST}(t-\tau) > 0 \text{ and } V_{DS} > 3/\alpha \end{array}$ 

Then

$$I_{DS} = Area I_{DS0} / (1 + \delta I_{DS0} V_{DS})$$
(7.92)  

$$\int 0$$
cutoff region

$$I_{DS0} = \begin{cases} \frac{\beta}{1+UV_{GST}} V_{GST}^Q(t-\tau) F_d(\alpha V_{DS}) & \text{linear and saturation region} \end{cases}$$
(7.93)

$$F_d(\alpha V_{DS}) = \frac{x}{\sqrt{1+x^2}} \tag{7.94}$$

$$V_G = QV_{ST} \ln \left[ exp \left( V_{GST} / (QV_{ST}) + 1 \right) \right]$$
(7.95)

$$V_{ST} = N_{ST}(kT/q) \tag{7.96}$$

$$N_{ST} = N_G + N_D V_{DS} \tag{7.97}$$

Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the MESFET I/V characteristics are evaluated as in the normal mode (7.92) but with the drain and source subscripts exchanged, and  $V_{GD}$  used as the controlling voltage instead of  $V_{GS}$ .

The relationships of the parameters describing the I/V characteristics of the LEVEL -1 model are summarized in figure 7.15.

# LEVEL -1 (TOM-2 MODEL) CAPACITANCES

KEVWC	BD		CEOMETRY		DEVICE
		+		$\rightarrow$	
PARAME	TERS		PARAMETER		PARAMETERS
ALPHA	$\alpha$		Area		$I_{DS} = f(Area, \alpha, \beta, \delta, \gamma,$
BETA	$\beta$				$\lambda, UV_{T0})$
DELTA	$\delta$				
GAMMA	$\gamma$				
LAMBDA	$\lambda$				
U	$\mu$				
VTO	$V_{T0}$				

Figure 7.15: LEVEL -1 (TOM-2 model) I/V dependencies.

These are evaluated the same way the LEVEL 3 capacitanceas described on 135 are evaluated. LEVEL 4 (Curtice Cubic Model)

LEVEL 4 (Curtice Cubic Model) I/V Characteristics

The LEVEL 4 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$ or inverted:  $V_{DS} < 0$  and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point. Curtice [11] proposed two DC current models: a quadratic channel current model and a cubic channel current model. The quadratic channel model is implemented as the LEVEL 4 model.

Normal Mode:  $(V_{DS} \ge 0)$ 

The regions of operation are defined as follows with with 
$$V_{GST} = V_{GS} - V_{T0}$$
 (7.98)  
cutoff region:  $V_{GS}(t-\tau) < V_{T0}$   
linear and saturation regions:  $V_{GS}(t-\tau) > V_{T0}$ 

Then the drain source current is given by

$$I_{DS} = \begin{cases} 0 & \text{cutoff region} \\ Area \left( A_0 + A_1 V_x + A_2 V_x^2 + A_3 V_x^3 \right) \tanh \left( \gamma V_{DS} \right) & \text{linear and saturation} \\ \text{regions} \\ V_x = V_{GS} (t - \tau) \left[ 1 + \beta (V_{DS0} - V_{DS}) \right] \end{cases}$$
(7.100)

$$V_x = V_{GS}(t-\tau) \left[ 1 + \beta (V_{DS0} - V_{DS}) \right]$$
(7.

Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the MESFET I/V characteristics are evaluated as in the normal mode (7.99) but with the drain and source subscripts exchanged, and  $V_{GD}$  is the controlling voltage instead of  $V_{GS}$ .

The relationships of the parameters describing the I/V characteristics for the LEVEL 4 model are summarized in figure 7.16.

#### LEVEL 4 (Curtice Cubic Model) Capacitances



Figure 7.16: LEVEL 4 (Curtice cubic model) I/V dependencies.

The drain-source capacitance  $C'_{DS} = Area C_{DS}$ the gate-source and gate-drain capacitances are

,

$$C'_{GS} = \begin{cases} Area C_{GS} \left(1 - \frac{V_{GS}}{V_{BI}}\right)^{-M_{GS}} & V_{GS} \le F_C V_{BI} \\ Area C_{GS} \left(1 - F_C\right)^{-} (1 + M_{GS}) \left[1 - F_C (1 + M_{GS}) + M_{GS} \frac{V_{GS}}{V_{BI}}\right] & V_{GS} > F_C V_{BI} \end{cases}$$
(7.102)  

$$C_{GD} = \begin{cases} Area C_{GD} \left(1 - \frac{V_{GD}}{V_{BI}}\right)^{-M_{GD}} & V_{GD} \le F_C V_{BI} \\ Area C_{GD} \left(1 - F_C\right)^{-} (1 + M_{GD}) \left[1 - F_C (1 + M_{GD}) + M_{GD} \frac{V_{GD}}{V_{BI}}\right] & V_{GS} > F_C V_{BI} \end{cases}$$

The LEVEL 4 capacitance parameter dependencies are summarized in figure 7.17.

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Figure 7.17: LEVEL 4 (Curtice Cubic model) capacitance dependencies.

# LEVEL 5 (Materka-Kacprzak Model)

The parameter keywords of the Materka-Kacprzak model are given in table 7.3.

(7.101)

Table 7.3: GASFET level 5 (Materka-Kacprzak) model keywords. SOMEVERSIONSOFSPICE only. Parameters that are NOT USED are reserved for future expansion.

AC10temperature coefficient of C10 $(A_{C10})$ $^{\circ}C^{-1}$ 0ACF0temperature coefficient of CP0 $(A_{C10})$ $^{\circ}C^{-1}$ 0AFflicker noise exponent $(A_P)$ -1AEtemperature coefficient of E $(A_E)$ $V^{-1}$ 0AFA6slope factor of breakdown current ( $\geq 0$ ) $(A_{FAG})$ $V^{-1}$ 0AFA6slope factor of gate conduction current ( $A_{FAG}$ ) $V^{-1}$ 0AFA6slope factor of gate conduction current ( $A_{FAG}$ ) $V^{-1}$ 0ADD5linear temperature coefficient of IDSS $(A_A)$ $\%/^{\circ}C^{-1}$ 0AKEtemperature coefficient of KE $(A_{KE})$ $^{\circ}C^{-1}$ 0AKGalternative keyword for TB01 $(A_{RD})$ $^{\circ}C^{-1}$ 0ARGalternative keyword for TB1 $(A_{RG})$ $^{\circ}C^{-1}$ 0ARSalternative keyword for TB1 $(A_{RD})$ $^{\circ}C^{-1}$ 0ARSalternative keyword for TB1 $(A_{RD})$ $^{\circ}C^{-1}$ 0ARSalternative keyword for TB1 $(A_{RD})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of S1 $(A_{SD})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of T $(A_{TD})$ $^{\circ}C^{-1}$ 0AVEClinear temperature coefficient of VDC $(A_{VDO})$ $^{\circ}C^{-1}$ 0AVEClinear temperature coefficient of VGD $(A_{VDO})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V$	Name	Description	Units	Default
ACFOtemperature coefficient of CFO $(A_{CFO})$ $^{\circ}C^{-1}$ 0AFflicker noise exponent $(A_F)$ -1AEtemperature coefficient of E $(A_F)$ -1AFABslope factor of breakdown current ( $\geq 0$ ) $(A_{FAG})$ $\nabla^{-1}$ 0AFACslope factor of gate conduction current $(A_{FAG})$ $\nabla^{-1}$ 0AFACtemperature coefficient of CG $(A_{KE})$ $^{\circ}C^{-1}$ 0AKEtemperature coefficient of KC $(A_{KE})$ $^{\circ}C^{-1}$ 0ARGalternative keyword for TB01 $(A_{RS})$ $^{\circ}C^{-1}$ 0ARGalternative keyword for TB1 $(A_{RS})$ $^{\circ}C^{-1}$ 0ARItemperature coefficient of SL $(A_{SS})$ $^{\circ}C^{-1}$ 0ASItemperature coefficient of SS $(A_{SS})$ $^{\circ}C^{-1}$ 0ASItemperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVBClinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVBClinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V_{CD}$ $V_{CD}$ 0C11capacitance norpone	AC10	temperature coefficient of C10 $(A_{C10})$	$^{\circ}\mathrm{C}^{-1}$	0
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	ACFO	temperature coefficient of CF0 $(A_{CF0})$	$^{\circ}\mathrm{C}^{-1}$	0
AEtemperature coefficient of E $(A_E)$ $V^{-1}$ 0AFABslope factor of breakdown current ( $\geq 0$ ) $(A_{FAB})$ $^{\circ}C^{-1}$ 0AFAGslope factor of gate conduction current $(A_{FAB})$ $V^{-1}$ 38.696AGAMtemperature coefficient of GAMA $(A_T)$ $^{\circ}C^{-1}$ 0AIDSlinear temperature coefficient of IDSS $(A_{\lambda})$ $^{\circ}K^{\circ}C^{-1}$ 0AKEtemperature coefficient of KE $(A_{KE})$ $^{\circ}C^{-1}$ 0AKGtemperature coefficient of KG $(A_{KE})$ $^{\circ}C^{-1}$ 0ARGalternative keyword for TRD1 $(A_{RG})$ $^{\circ}C^{-1}$ 0ARGalternative keyword for TRS1 $(A_{ARS})$ $^{\circ}C^{-1}$ 0ARI0temperature coefficient of SL $(A_{SL})$ $^{\circ}C^{-1}$ 0ASItemperature coefficient of SS $(A_{SS})$ $^{\circ}C^{-1}$ 0ASItemperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VDO $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VDO $(A_{VBC})$ $^{\circ}C^{-1}$ 0CIOgate-drain feedback capacitance for $V_{GD} = 0$ $(C_{1S})$ $(C_{1S})$ 0CIDEdrain-source capacitance NOT USED $(C_{DE})$ F00CIDEdrain-source capacitance NOT USED $(C_{DE})$ F0<	AF	flicker noise exponent $(A_F)$	-	1
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	AE	temperature coefficient of E $(A_E)$	$V^{-1}$	0
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	AFAB	slope factor of breakdown current $(\geq 0)$ $(A_{FAB})$	$^{\circ}\mathrm{C}^{-1}$	0
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	AFAG	slope factor of gate conduction current $(A_{FAG})$	$V^{-1}$	38.696
$ \begin{array}{c cccc} \operatorname{AIDS} & \operatorname{linear temperature coefficient of IDSS} & (A_{\lambda}) & \%/^{\circ} \mathrm{C} & 0 \\ \operatorname{AKE} & \operatorname{temperature coefficient of KE} & (A_{KE}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{AKG} & \operatorname{temperature coefficient of KG} & (A_{KG}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{ARD} & \operatorname{alternative keyword for TRD1} & (A_{RD}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{ARG} & \operatorname{alternative keyword for TRS1} & (A_{RS}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{ARS} & \operatorname{alternative keyword for TRS1} & (A_{RS}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{ARI} & \operatorname{temperature coefficient of R10} & (A_{RI0}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{ASL} & \operatorname{temperature coefficient of SS} & (A_{SL}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{ASS} & \operatorname{temperature coefficient of SS} & (A_{SL}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \end{array} \\ \operatorname{ASS} & \operatorname{temperature coefficient of VDC} & (A_{VBC}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{AVBC} & \operatorname{linear temperature coefficient of VDC} & (A_{VBC}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \end{array} \\ \operatorname{AVPO} & \operatorname{linear temperature coefficient of VDC} & (A_{VBC}) & \circ^{\circ} \mathrm{C}^{-1} & 0 \\ \operatorname{CI0} & \operatorname{gate-source Schottky barrier capacitance for} & F & 0 \\ & V_{GS} = 0 & (C_{10}) & & \\ \end{array} \\ \operatorname{CFO} & \operatorname{gate-drain feedback capacitance for V_{GD} = 0 & (C_{F0}) & F & 0 \\ \operatorname{CIS} & \operatorname{constant parasitic component of gate-source capacitance} & F & 0 \\ \end{array} \\ \operatorname{CDE} & \operatorname{drain-source electrode capacitance NOT USED} & (C_{DS}) & F & 0 \\ \operatorname{CDS} & \operatorname{drain-source capacitance} NOT USED & (C_{DS}) & F & 0 \\ \end{array} \\ \operatorname{CGSO} & \operatorname{zero-bias gate-source p-n capacitance NOT USED} & (C_{DS}) & F & 0 \\ \operatorname{CGSO} & \operatorname{zero-bias gate-source p-n capacitance NOT USED} & F & 0 \\ \operatorname{CGSO} & \operatorname{zero-bias gate-source p-n capacitance in Raytheon capaci- F & 0 \\ \operatorname{tance model} & \operatorname{Usel if CLVL} = 2 & (C_{GS}) \\ \end{array} \\ \operatorname{CGDO} & \operatorname{zero-bias gate-source p-n capacitance in Raytheon capaci- F & 0 \\ \operatorname{tance model} & \operatorname{Usel if CLVL} = 2 & (C_{GS}) \\ \end{array} \\ \operatorname{CGDO} & \operatorname{zero-bias gate-source p-n capacitance in Raytheon capaci- F & 0 \\ \operatorname{tance model} & \operatorname{Usel if CLVL} = 2 & (C_{GS}) \\ \end{array} \\ \operatorname{CLVLV} & = 1 use Materka-Kaeprak capacitance model & (C_{LVL}) \\ \end{array} \\ \operatorname{E} & constant part of drain current power &$	AGAM	temperature coefficient of GAMA $(A_{\gamma})$	$^{\circ}\mathrm{C}^{-1}$	0
AKEtemperature coefficient of KE $(A_{KE})$ $^{\circ}C^{-1}$ 0AKGtemperature coefficient of KG $(A_{KG})$ $^{\circ}C^{-1}$ 0ARDalternative keyword for TRD1 $(A_{RD})$ $^{\circ}C^{-1}$ 0ARSalternative keyword for TRS1 $(A_{RG})$ $^{\circ}C^{-1}$ 0ARSalternative keyword for TRS1 $(A_{RG})$ $^{\circ}C^{-1}$ 0ARSalternative coefficient of SL $(A_{SL})$ $^{\circ}C^{-1}$ 0ASItemperature coefficient of SS $(A_{SL})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of T $(A_{V})$ $^{\circ}C^{-1}$ 0AVEClinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VDO $(A_{VPO})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V_{GS} = 0$ .F0C50gate-drain feedback capacitance for $V_{GD} = 0$ . $(C_{10})$ F0C11constant parasitic component of gate-source capacitance $(C_{DE})$ F00CD2drain-source electrode capacitance NOT USED $(C_{DE})$ F0CD3drain-source electrode capacitance NOT USED $(C_{DE})$ F0CD4low frequency trapping capacitance NOT USED $(C_{DE})$ F0CD5drain-source electrode capacitance NOT USED $(C_{DE})$ F0CD5drain-source electrode capacitance NOT USED $(C_{DS})$ -1CU5<	AIDS	linear temperature coefficient of IDSS $(A_{\lambda})$	%/°C	0
AKGtemperature coefficient of KG $(A_{KG})$ $\circ$ C^{-1}0ARDalternative keyword for TRD1 $(A_{RD})$ $\circ$ C^{-1}0ARGalternative keyword for TRS1 $(A_{RG})$ $\circ$ C^{-1}0ARSalternative keyword for TRS1 $(A_{RAS})$ $\circ$ C^{-1}0AR10temperature coefficient of S1 $(A_{R10})$ $\circ$ C^{-1}0AS1temperature coefficient of S1 $(A_{SL})$ $\circ$ C^{-1}0AS2temperature coefficient of S2 $(A_{SS})$ $\circ$ C^{-1}0ATtemperature coefficient of VD $(A_{VR0})$ $\circ$ C^{-1}0AVPOlinear temperature coefficient of VDC $(A_{VP0})$ $\circ$ C^{-1}0AVPOlinear temperature coefficient of VPO $(A_{VP0})$ $\circ$ C^{-1}0C10gate-source Schottky barrier capacitance forF00 $V_{GS} = 0$ . $(C_{10})$ CC0C11gate-drain feedback capacitance for $V_{GD} = 0$ . $(C_{D0})$ F0C12constant parasitic component of gate-source capacitanceF00CDEdrain-source electrode capacitance NOT USED $(C_{DSD})$ F0CDSdrain-source capacitanceNOT USEDF00CDSgate-source p-n capacitance NOT USED $(C_{DS})$ F0CDSdrain-source electrode capacitance NOT USEDF00CDSgate-source p-n capacitance In Raytheon capaci-F00CGSO <td< td=""><td>AKE</td><td>temperature coefficient of KE <math>(A_{KE})</math></td><td><math>^{\circ}\mathrm{C}^{-1}</math></td><td>0</td></td<>	AKE	temperature coefficient of KE $(A_{KE})$	$^{\circ}\mathrm{C}^{-1}$	0
ARDalternative keyword for TRD1 $(A_{RD})$ $^{\circ}C^{-1}$ 0ARGalternative keyword for TRG1 $(A_{RG})$ $^{\circ}C^{-1}$ 0ARSalternative keyword for TRS1 $(A_{RI0})$ $^{\circ}C^{-1}$ 0AR10temperature coefficient of R10 $(A_{R10})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of SS $(A_{SS})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0ATtemperature coefficient of VDC $(A_{VPO})$ $^{\circ}C^{-1}$ 0AVEClinear temperature coefficient of VDC $(A_{VPO})$ $^{\circ}C^{-1}$ 0AVEClinear temperature coefficient of VDC $(A_{VPO})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V_{GS} = 0$ .F0C11gate-source Schottky barrier capacitance for $V_{GD} = 0$ . $(C_{I0})$ F0C12constant parasitic component of gate-source capacitanceF00CDEdrain-source electrode capacitance NOT USED $(C_{DE})$ F0CDSdrain-source capacitanceNOT USED $(C_{DE})$ F0CDSdrain-source electrode capacitance NOT USED $(C_{DE})$ F0	AKG	temperature coefficient of KG $(A_{KG})$	$^{\circ}\mathrm{C}^{-1}$	0
ARGalternative keyword for TRG1 $(A_{RG})$ $^{\circ}C^{-1}$ 0AR10temperature coefficient of R10 $(A_{R10})$ $^{\circ}C^{-1}$ 0AR10temperature coefficient of S1 $(A_{R10})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of SS $(A_{SL})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of SS $(A_{SL})$ $^{\circ}C^{-1}$ 0ATtemperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVBClinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VPO $(A_{VBC})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V_{GS} = 0$ .F0C11gate-drain feedback capacitance for $V_{GD} = 0$ . $(C_{10})$ F0C12constant parasitic component of gate-source capacitance $(C_{DE})$ F00C13constant parasitic component of gate-source capacitance $(C_{DE})$ F00CDEdrain-source capacitance NOT USED $(C_{DS})$ F0CDSdrain-source capacitance $(CDS)$ F00CDSdrain-source electrode capacitance NOT USED $(C_{DS})$ F0CGEgate-source electrode capacitance NOT USED $(C_{DS})$ F0CGS0zero-bias gate-source p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 $(C_{CS})$ -1CUVLcapacitance model flag CLVL = 1 use Materka	ARD	alternative keyword for TRD1 $(A_{RD})$	$^{\circ}\mathrm{C}^{-1}$	0
ARSalternative keyword for TRS1 $(A_{RS})$ $^{\circ}C^{-1}$ 0AR10temperature coefficient of R10 $(A_{R10})$ $^{\circ}C^{-1}$ 0ASItemperature coefficient of SI $(A_{SL})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of SS $(A_{SL})$ $^{\circ}C^{-1}$ 0ATtemperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVBClinear temperature coefficient of VDC $(A_{VP0})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VPO $(A_{VP0})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V_{GS} = 0$ .F0CF0gate-drain feedback capacitacne for $V_{CD} = 0$ . $(C_{I0})$ F0C11constant parasitic component of gate-source capacitance $(C_{IS})$ F00CDEdrain-source capacitance NOT USED $(C_{DE})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source epactance $(C_{DS})$ F0CGEgate-source lectrode capacitance NOT USED $(C_{DE})$ F0CGS0zero-bias gate-source p-n capacitance in Raytheon capaci- tance model.Ised if CLVL = 2 $(C_{GS})$ CGD0zero-bias gate-drain p-n capacitance in Raytheon capaci- tance model.Ised if CLVL = 2 $(C_{GS})$ CGD0zero-bias gate-drain p-n capacitance model cLVLV = 1 use Materka-Kacprzak capacitance model cLVLV = 2 use Raytheon capacitance model-1 <td< td=""><td>ARG</td><td>alternative keyword for TRG1 <math>(A_{RG})</math></td><td><math>^{\circ}\mathrm{C}^{-1}</math></td><td>0</td></td<>	ARG	alternative keyword for TRG1 $(A_{RG})$	$^{\circ}\mathrm{C}^{-1}$	0
$ \begin{array}{c cccc} \operatorname{AR10} & \operatorname{temperature coefficient of R10} & (A_{R10}) & \circ \operatorname{C}^{-1} & 0 \\ \operatorname{ASL} & \operatorname{temperature coefficient of SL} & (A_{SL}) & \circ \operatorname{C}^{-1} & 0 \\ \operatorname{ASS} & \operatorname{temperature coefficient of SS} & (A_{SS}) & \circ \operatorname{C}^{-1} & 0 \\ \end{array} \\ \operatorname{AT} & \operatorname{temperature coefficient of TDC} & (A_{YBC}) & \circ \operatorname{C}^{-1} & 0 \\ \end{array} \\ \operatorname{AVPO} & \operatorname{linear temperature coefficient of VDC} & (A_{VBC}) & \circ \operatorname{C}^{-1} & 0 \\ \end{array} \\ \operatorname{AVPO} & \operatorname{linear temperature coefficient of VPO} & (A_{VPO}) & \circ \operatorname{C}^{-1} & 0 \\ \end{array} \\ \operatorname{C10} & \operatorname{gate-source Schottky barrier capacitance for} & F & 0 \\ \end{array} \\ \operatorname{C10} & \operatorname{gate-drain feedback capacitacne for V_{GD} = 0. & (C_{F0}) & F & 0 \\ \end{array} \\ \operatorname{C12} & \operatorname{constant parasitic component of gate-source capacitance} & F & 0 \\ \end{array} \\ \operatorname{CDE} & \operatorname{drain-source electrode capacitance NOT USED} & (C_{DGE}) & F & 0 \\ \end{array} \\ \operatorname{CDE} & \operatorname{drain-source capacitance} & \operatorname{NOT} USED & (C_{DGE}) & F & 0 \\ \end{array} \\ \operatorname{CDS} & \operatorname{drain-source capacitance} & \operatorname{NOT} USED & (C_{DS}) & F & 0 \\ \end{array} \\ \operatorname{CCSD} & \operatorname{low frequency trapping capacitance NOT USED} & (C_{DS}) & F & 0 \\ \end{array} \\ \operatorname{CGE} & \operatorname{gate-source electrode capacitance NOT USED} & (C_{DSD}) & F & 0 \\ \end{array} \\ \operatorname{CGE} & \operatorname{gate-source electrode capacitance NOT USED} & (C_{DSD}) & F & 0 \\ \end{array} \\ \operatorname{CGE} & \operatorname{gate-source electrode capacitance NOT USED} & (C_{DSD}) & F & 0 \\ \end{array} \\ \operatorname{CGE} & \operatorname{gate-source electrode capacitance NOT USED} & (C_{DSD}) & F & 0 \\ \operatorname{CGE} & \operatorname{gate-source electrode capacitance NOT USED} & (C_{DSD}) & F & 0 \\ \end{array} \\ \operatorname{CGE} & \operatorname{gate-source electrode capacitance in Raytheon capacitance F & 0 \\ & \operatorname{tance model} & \operatorname{Used} \text{ if } \operatorname{CLVL} = 2 & (C_{GS}) & F \\ \operatorname{CLVL} & \operatorname{capacitance model flag} & - & 1 \\ \operatorname{CLVLV} & \operatorname{tance model} & \operatorname{Ised} \text{ if } \operatorname{CLVL} = 2 & (C_{GS}) & F \\ \operatorname{CLVLV} & \operatorname{tance model} \text{ lased therka-Kacprzak capacitance model} & \\ \operatorname{CLVLV} & \operatorname{tance model} \text{ lased if CLVL} = 2 & (C_{GS}) & F \\ \operatorname{capacitance model} \text{ fag} & - & 1 \\ \operatorname{CLVLV} & \operatorname{tance model} \text{ lased if CLVL} = 2 & (C_{GS}) & \\ \operatorname{capacitance model} \text{ lased if CLVL} & - & 2 \\ \operatorname{capacitance model} \text{ lased if CLVL} & & 0 \\ c$	ARS	alternative keyword for TRS1 $(A_{RS})$	$^{\circ}\mathrm{C}^{-1}$	0
ASLtemperature coefficient of SL $(A_{SL})$ $^{\circ}C^{-1}$ 0ASStemperature coefficient of SS $(A_{SS})$ $^{\circ}C^{-1}$ 0ATtemperature coefficient of T $(A_{T})$ $^{\circ}C^{-1}$ 0AVBClinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVP0linear temperature coefficient of VPO $(A_{VP0})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V_{CS} = 0$ .F0C70gate-drain feedback capacitacne for $V_{GD} = 0$ . $(C_{10})$ F0CDEconstant parasitic component of gate-source capacitance $(C_{1S})$ F0CDEdrain-source electrode capacitance NOT USED $(C_{DGE})$ F0CDSdrain-source capacitance $(C_{DS})$ F00CDSdrain-source capacitance NOT USED $(C_{DSD})$ F0CCGEgate-source electrode capacitance NOT USED $(C_{DSD})$ F0CCS0zero-bias gate-source p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 $(C_{GS})$ -1CLVLcapacitance model fig CLVLV = 1 use Materka-Kacprzak capacitance model CLVLV = 2 use Raytheon capacitance model CLVLV = 2-2FCC $(C_{DS})$ A0IB0current parameter of pinch-off voltage source ( $\geq 0$ )A0IB0current parameter of gate-drai	AR10	temperature coefficient of R10 $(A_{R10})$	$^{\circ}\mathrm{C}^{-1}$	0
ASStemperature coefficient of SS $(A_{SS})$ $^{\circ}C^{-1}$ 0ATtemperature coefficient of T $(A_T)$ $^{\circ}C^{-1}$ 0AVEClinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VPO $(A_{VBC})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance forF0 $V_{GS} = 0.$ $(C_{10})$ $(C_{10})$ $(C_{10})$ CF0gate-drain feedback capacitace for $V_{GD} = 0.$ $(C_{10})$ $(C_{15})$ CDEconstant parasitic component of gate-source capacitanceF0CDEdrain-source electrode capacitance NOT USED $(C_{DE})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance NOT USED $(C_{DS})$ F0CGS0zero-bias gate-source p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 $(C_{GS})$ -1CLVLcapacitance model flag CLVL * 1 use Materka-Kacprzak capacitance model CLVLV * 1 use Materka-Kacprzak capacitance model CLVL * 2 use Raytheon capacitance model CLVL * 2 use Raytheon capacitance model CLVL * 2 use Raytheon capacitance model CLVL * 1-2Econstant part of drain current power $(E)$ -2GAMA <td>ASL</td> <td>temperature coefficient of SL <math>(A_{SL})</math></td> <td><math>^{\circ}\mathrm{C}^{-1}</math></td> <td>0</td>	ASL	temperature coefficient of SL $(A_{SL})$	$^{\circ}\mathrm{C}^{-1}$	0
ATtemperature coefficient of T $(A_T)$ $^{\circ}C^{-1}$ 0AVBClinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VPO $(A_{VPO})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $F$ 0 $V_{GS} = 0.$ $(C_{10})$ F0CF0gate-drain feedback capacitacne for $V_{GD} = 0.$ $(C_{10})$ F0C11constant parasitic component of gate-source capacitanceF00CDEdrain-source electrode capacitance NOT USED $(C_{DE})$ F0CDGEdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance NOT USED $(C_{DSD})$ F0CGEgate-source electrode capacitance NOT USED $(C_{DSD})$ F0CGS0zero-bias gate-source p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 $(C_{GS})$ F0CGD0zero-bias gate-drain p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 $(C_{GS})$ -1CLVLcapacitance model flag CLVLV = 1 use Materka-Kacprzak capacitance model CLVLV = 2 use Raytheon capacitance model CLVLV = 2-2FCC $(F_{CC})$ -0GAMAVoltage slope parameter of pinch-off voltage source ( $\geq 0$ ) $(I_{DS})$ A0IDSSfrain saturation cur	ASS	temperature coefficient of SS $(A_{SS})$	$^{\circ}\mathrm{C}^{-1}$	0
AVEClinear temperature coefficient of VDC $(A_{VBC})$ $^{\circ}C^{-1}$ 0AVPOlinear temperature coefficient of VPO $(A_{VP0})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V_{GS} = 0$ .F0CFOgate-drain feedback capacitacne for $V_{GD} = 0$ . $(C_{10})$ F0C13constant parasitic component of gate-source capacitance $(C_{1S})$ F00CDEdrain-source electrode capacitance NOT USED $(D_{EE})$ F0CDGEdrain-source capacitance $(C_{DS})$ F00CDSdrain-source capacitance $(CDS)$ F00CDSdrain-source capacitance $(NOT USED)$ F00CGEgate-source electrode capacitance (NOT USED) $(C_{DSD})$ F00CGEgate-source p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 $(C_{GS})$ F00CGD0zero-bias gate-drain p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 $(C_{GS})$ F00CLVLVcapacitance model flag $CLVLV = 1$ use Materka-Kacprzak capacitance model $CLVLV = 2$ use Raytheon capacitance model $(C_{LVL})$ -1E FCCconstant part of drain current power source ( $\geq 0$ ) $(I_{DS})$ A0IB0 source ( $\geq 0$ ) $(I_{B0})$ A0IDSSfrain saturation current for $V_{GS} = 0$ $(I_{DSS})$ A0.1	AT	temperature coefficient of T $(A_T)$	$^{\circ}\mathrm{C}^{-1}$	0
AVPOlinear temperature coefficient of VPO $(A_{VPO})$ $^{\circ}C^{-1}$ 0C10gate-source Schottky barrier capacitance for $V_{GS} = 0$ . $F$ 0CF0gate-drain feedback capacitacne for $V_{GD} = 0$ . $(C_{10})$ $F$ 0C13constant parasitic component of gate-source capacitance $(C_{1S})$ $F$ 0CDEdrain-source electrode capacitance NOT USED $(C_{DE})$ $F$ 0CDEdrain-gate electrode capacitance NOT USED $(C_{DS})$ $F$ 0CDSdrain-source capacitance $(C_{DS})$ $F$ 0CDSdrain-source capacitance $(C_{DS})$ $F$ 0CDSdrain-source capacitance $(C_{DS})$ $F$ 0CDSdrain-source capacitance $(C_{DS})$ $F$ 0CGEgate-source electrode capacitance NOT USED $(C_{DE})$ $F$ 0CGS0zero-bias gate-source p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 $(C_{GS})$ $C_{GS}$ CLVLcapacitance model fig CLVL = 1 use Materka-Kacprzak capacitance model CLVLV = 1 use Materka-Kacprzak capacitance model CLVLV = 2 use Raytheon capacitance model CLVLV $C_{LVL}$ $-$ 1Econstant part of drain current power $(E)$ $-$ 2FCC $(F_{CC})$ $ 0.8$ GAMAVoltage slope parameter of pinch-off voltage source ( $\geq 0$ ) $(I_{DS})$ $A$ $0.1$ IDSSfrain saturation current for $V_{GS} = 0$ $(I_{DSS})$ $A$ $0.1$ </td <td>AVBC</td> <td>linear temperature coefficient of VDC <math>(A_{VBC})</math></td> <td><math>^{\circ}\mathrm{C}^{-1}</math></td> <td>0</td>	AVBC	linear temperature coefficient of VDC $(A_{VBC})$	$^{\circ}\mathrm{C}^{-1}$	0
C10gate-source Schottky barrier capacitance for $V_{GS} = 0.$ F0CF0gate-drain feedback capacitance for $V_{GD} = 0.$ $(C_{10})$ F0C11constant parasitic component of gate-source capacitance $(C_{1S})$ F0CDEdrain-source electrode capacitance NOT USED $(C_{DE})$ F0CDEdrain-gate electrode capacitance NOT USED $(C_{DE})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source electrode capacitance NOT USED $(C_{DE})$ F0CGEgate-source electrode capacitance NOT USED $(C_{DE})$ F0CGS0zero-bias gate-source p-n capacitance in Raytheon capacitance model. Used if CLVL = 2 $(C_{GS})$ F0CLVLcapacitance model flag-111CLVL = 2 use Raytheon capacitance model $(C_{LVL})$ 11CLVL = 2 use Raytheon capacitance model-11CLVL = 2 use Raytheon capacitance model $(C_{LVL})$ 222FCC(F_{CC})-0.830GAMAVoltage slope parameter of pinch-off voltage $(\gamma)$ V^{-1}0IB0current parameter of gate-drain breakdown source ( $\geq 0$ )(I_{DSS})A0.1CDSfrain saturation current for $V_{GS} = 0$ (I_{DSS})A0.	AVPO	linear temperature coefficient of VPO $(A_{VP0})$	$^{\circ}\mathrm{C}^{-1}$	0
$V_{GS} = 0.$ $(C_{10})$ CF0gate-drain feedback capacitace for $V_{GD} = 0.$ $(C_{F0})$ F0C1Sconstant parasitic component of gate-source capacitanceF0 $(C_{1S})$ $(C_{1S})$ F0CDEdrain-source electrode capacitance NOT USED $(C_{DE})$ F0CDEdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source capacitance $(C_{DS})$ F0CDSdrain-source electrode capacitance (NOT USED)F0CGEgate-source electrode capacitance in Raytheon capacitanceF0CGS0zero-bias gate-source p-n capacitance in Raytheon capacitance model. Used if CLVL = 2 $(C_{GS})$ CCGD0zero-bias gate-drain p-n capacitance in Raytheon capacitance model. Used if CLVL = 2 $(C_{GS})$ -1CLVLcapacitance model flag-1-1CLVLV = 1 use Materka-Kacprzak capacitance model $(C_{LVL})$ -2FCC $(F_{CC})$ -0.8-2FCC $(F_{CC})$ -0.8-1IB0current parameter of gate-drain breakdown source ( $\geq 0$ )A00IDSSfrain saturation current for $V_{GS} = 0$ $(I_{DSS})$ A0.1	C10	gate-source Schottky barrier capacitance for	F	0
$\begin{array}{c cccc} {\rm CF0} & {\rm gate-drain feedback capacitance for } V_{GD} = 0. & (C_{F0}) & {\rm F} & 0 \\ {\rm C1S} & {\rm constant parasitic component of gate-source capacitance } & {\rm F} & 0 \\ {\rm CDE} & {\rm drain-source electrode capacitance NOT USED} & (C_{DE}) & {\rm F} & 0 \\ {\rm CDGE} & {\rm drain-source capacitance NOT USED} & (C_{DGE}) & {\rm F} & 0 \\ {\rm CDS} & {\rm drain-source capacitance} & ({\rm NOT USED} & (C_{DGE}) & {\rm F} & 0 \\ {\rm CDS} & {\rm drain-source capacitance} & ({\rm NOT USED}) & {\rm F} & 0 \\ {\rm CDS} & {\rm drain-source capacitance} & ({\rm NOT USED}) & {\rm F} & 0 \\ {\rm CDS} & {\rm drain-source capacitance} & ({\rm NOT USED}) & {\rm F} & 0 \\ {\rm CDS} & {\rm drain-source capacitance} & ({\rm NOT USED}) & {\rm F} & 0 \\ {\rm CCSD} & {\rm low frequency trapping capacitance (NOT USED} & {\rm F} & 0 \\ {\rm CGSO} & {\rm zero-bias gate-source p-n capacitance in Raytheon capaci- } & {\rm F} & 0 \\ {\rm cance model. Used if CLVL = 2} & (C_{GS}) & {\rm I} \\ {\rm CCDD} & {\rm zero-bias gate-drain p-n capacitance in Raytheon capaci- } & {\rm F} & 0 \\ {\rm tance model. Used if CLVL = 2} & (C_{GS}) & {\rm I} \\ {\rm CLVL} & {\rm capacitance model flag} & {\rm -} & {\rm I} \\ {\rm CLVLV = 1 use Materka-Kacprzak capacitance model} \\ {\rm CLVLV = 1 use Materka-Kacprzak capacitance model} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm CLVLV = 2 use Raytheon capacitance model} & {\rm (} \\ {\rm (} \\$		$V_{GS} = 0.  (C_{10})$		
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	CFO	gate-drain feedback capacitacne for $V_{GD} = 0.$ ( $C_{F0}$ )	F	0
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	C1S	constant parasitic component of gate-source capacitance	F	0
$\begin{array}{c c} \mbox{CDE} & drain-source electrode capacitance NOT USED} & (C_{DE}) & F & 0 \\ \hline \mbox{CDGE} & drain-gate electrode capacitance NOT USED} & (C_{DGE}) & F & 0 \\ \hline \mbox{CDS} & drain-source capacitance} & (NOT USED) & F & 0 \\ \hline \mbox{CDSD} & low frequency trapping capacitance (NOT USED)} & F & 0 \\ \hline \mbox{CDSD} & low frequency trapping capacitance NOT USED} & (C_{DSD}) & F \\ \hline \mbox{CGE} & gate-source electrode capacitance NOT USED} & (C_{DE}) & F & 0 \\ \hline \mbox{CGS0} & zero-bias gate-source p-n capacitance in Raytheon capaci- F & 0 \\ \hline \mbox{tance model. Used if CLVL} = 2 & (C_{GS}) & \\ \hline \mbox{CGD0} & zero-bias gate-drain p-n capacitance in Raytheon capaci- F & 0 \\ \hline \mbox{tance model. Used if CLVL} = 2 & (C_{GS}) & \\ \hline \mbox{CLVL} & capacitance model flag & - & 1 \\ \hline \mbox{CLVLV} & = 1 use Materka-Kacprzak capacitance model \\ \hline \mbox{CLVLV} & = 2 use Raytheon capacitance model & (C_{LVL}) & \\ \hline \mbox{E} & constant part of drain current power & (E) & - & 2 \\ \hline \mbox{FCC} & (F_{CC}) & - & 0.8 \\ \hline \mbox{GAMA} & Voltage slope parameter of pinch-off voltage & (\gamma) V^{-1} & 0 \\ \hline \mbox{IB0} & source (\geq 0) & (I_{B0}) & \\ \hline \mbox{IDSS} & frain saturation current for V_{GS} = 0 & (I_{DSS}) & A & 0.1 \\ \hline \end{tabular}$		$(C_{1S})$		
$\begin{array}{c c} \mbox{CDGE} & drain-gate electrode capacitance NOT USED} & (C_{DGE}) & F & 0 \\ \hline \mbox{CDS} & drain-source capacitance} & (C_{DS}) & F & 0 \\ \hline \mbox{CDSD} & low frequency trapping capacitance} (NOT USED) & F & 0 \\ \hline \mbox{CDSD} & (C_{DSD}) & & \\ \hline \mbox{CGE} & gate-source electrode capacitance NOT USED} & (C_{DE}) & F & 0 \\ \hline \mbox{CGS0} & zero-bias gate-source p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 & (C_{GS}) & \\ \hline \mbox{CGD0} & zero-bias gate-drain p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 & (C_{GS}) & \\ \hline \mbox{CGD0} & zero-bias gate-drain p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2 & (C_{GS}) & \\ \hline \mbox{CLVL} & capacitance model flag & - & 1 \\ \hline \mbox{CLVLV} & = 1 use Materka-Kacprzak capacitance model & \\ \hline \mbox{CLVLV} & = 2 use Raytheon capacitance model & (C_{LVL}) & \\ \hline \mbox{E} & constant part of drain current power & (E) & - & 2 \\ \hline \mbox{FCC} & & & (F_{CC}) & - & 0.8 \\ \hline \mbox{GAMA} & Voltage slope parameter of pinch-off voltage & (\gamma) & V^{-1} & 0 \\ \hline \mbox{IB0} & current parameter of gate-drain breakdown \\ source (\geq 0) & (I_{B0}) & \\ \hline \mbox{IDSS} & frain saturation current for V_{GS} = 0 & (I_{DSS}) & A & 0.1 \\ \hline \end{tabular}$	CDE	drain-source electrode capacitance NOT USED $(C_{DE})$	F	0
$\begin{array}{c c} \mbox{CDS} & \mbox{drain-source capacitance} & (C_{DS}) & \mbox{F} & 0 \\ \hline \mbox{CDSD} & \mbox{low frequency trapping capacitance (NOT USED)} & \mbox{F} & 0 \\ \hline \mbox{(}C_{DSD}) & & \mbox{(}C_{DSD}) & \mbox{F} & 0 \\ \hline \mbox{(}CGE & \mbox{gate-source electrode capacitance NOT USED} & (C_{DE}) & \mbox{F} & 0 \\ \hline \mbox{CGS0} & \mbox{zero-bias gate-source p-n capacitance in Raytheon capaci-} & \mbox{frame model. Used if CLVL} = 2 & (C_{GS}) & \mbox{(}CGS) & \mbox{zero-bias gate-drain p-n capacitance in Raytheon capaci-} & \mbox{frame model. Used if CLVL} = 2 & (C_{GS}) & \mbox{frame model. Used if CLVL} = 2 & (C_{GS}) & \mbox{frame model. Used if CLVL} = 2 & (C_{GS}) & \mbox{frame model. Used if CLVL} = 2 & (C_{GS}) & \mbox{frame model. Used if CLVL} = 2 & (C_{GS}) & \mbox{frame model. Used if CLVL} = 2 & (C_{GS}) & \mbox{frame model} & \mbox{frame model flag} & \mbox{frame model flag} & \mbox{frame model flag} & \mbox{frame model} & \mbox{frame model flag} & \mbox{frame model} & \mbox{frame model} & \mbox{frame model frame model frame capacitance model} & \mbox{frame model} & \mbox{frame model frame model frame capacitance model} & \mbox{frame model frame model frame model frame model} & \mbox{frame model frame model} & \mbox{frame model frame model} & \mbox{frame frame model frame capacitance model} & \mbox{frame model} & \mbox{frame model frame model} & \\mbox{frame frame frame model} & \\mbox{frame frame frame model} & \\mbox{frame frame model} & \\mbox{frame frame frame frame model} & \\mbox{frame frame frame frame model} & \\mbox{frame frame frame frame frame model} & \\mbox{frame frame frame frame frame frame model} & \\mbox{frame frame frame frame model} & \\mbox{frame frame frame frame frame frame frame model} & \\mbox{frame frame frame frame frame frame frame model} & \\mbox{frame frame frame frame frame model} & \frame frame$	CDGE	drain-gate electrode capacitance NOT USED $(C_{DGE})$	F	0
$\begin{array}{c c} \mbox{CDSD} & \mbox{low frequency trapping capacitance (NOT USED)} & \mbox{F} & 0 \\ \hline (C_{DSD}) & & \mbox{Constraints} & \mbox$	CDS	drain-source capacitance $(C_{DS})$	F	0
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	CDSD	low frequency trapping capacitance (NOT USED)	F	0
CGEgate-source electrode capacitance NOT USED $(C_{DE})$ F0CGS0zero-bias gate-source p-n capacitance in Raytheon capacitance model. Used if CLVL = 2 $(C_{GS})$ $F$ 0CGD0zero-bias gate-drain p-n capacitance in Raytheon capacitance model. Used if CLVL = 2 $(C_{GS})$ $F$ 0CLVLcapacitance model flag-11CLVLV = 1 use Materka-Kacprzak capacitance model $(C_{LVL})$ $-$ 1Econstant part of drain current power $(E)$ -2FCC $(F_{CC})$ -0.8 $-$ GAMAVoltage slope parameter of pinch-off voltage $(\gamma)$ $V^{-1}$ 0IB0current parameter of gate-drain breakdown source $(\geq 0)$ $(I_{B0})$ A0.1Constinued on part parameter for $V_{GS} = 0$ $(I_{DSS})$ A0.1		$(C_{DSD})$	_	-
$\begin{array}{c c} CGS0 & \end{picture} pictur$	CGE	gate-source electrode capacitance NOT USED $(C_{DE})$	F	0
tance model. Used if $CLVL = 2$ $(C_{GS})$ $(C_{GS})$ CGD0zero-bias gate-drain p-n capacitance in Raytheon capaci- tance model. Used if $CLVL = 2$ $(C_{GS})$ $F$ $0$ CLVLcapacitance model flag $CLVLV = 1$ use Materka-Kacprzak capacitance model $CLVLV = 2$ use Raytheon capacitance model $CLVLV = 2$ use Raytheon capacitance model $CLVLV = 2$ use Raytheon capacitance model $(C_{LVL})$ $ 1$ Econstant part of drain current power $(E)$ $ 2$ FCC $(F_{CC})$ $ 0.8$ GAMAVoltage slope parameter of pinch-off voltage source ( $\geq 0$ ) $(V)$ $V^{-1}$ $0$ IDSSfrain saturation current for $V_{GS} = 0$ $(I_{DSS})$ $A$ $0.1$	CGSO	zero-bias gate-source p-n capacitance in Raytheon capaci-	F,	0
CGD0zero-bias gate-drain p-n capacitance in Raytheon capaci- tance model. Used if CLVL = 2F0CLVLcapacitance model flag-1CLVL = 1 use Materka-Kacprzak capacitance model CLVL = 2 use Raytheon capacitance model CLVL = 2 use Raytheon capacitance model CLVL = 2 use Raytheon capacitance model (CLVL)-1Econstant part of drain current power(E)-2FCC(F_{CC})-0.8GAMAVoltage slope parameter of pinch-off voltage source ( $\geq 0$ )(I_{B0})0IDSSfrain saturation current for $V_{GS} = 0$ (I_{DSS})A0.1		tance model. Used if $CLVL = 2$ ( $C_{GS}$ )	- F	
tance model. Used if $CLVL = 2$ $(C_{GS})$ CLVLcapacitance model flag CLVLV = 1 use Materka-Kacprzak capacitance model CLVLV = 2 use Raytheon capacitance model CLVLV = 2 use Raytheon capacitance model ( $C_{LVL}$ )-Econstant part of drain current power $(E)$ -2FCC $(F_{CC})$ -0.8GAMAVoltage slope parameter of pinch-off voltage source ( $\geq 0$ ) $(V)$ V^{-1}0IDSSfrain saturation current for $V_{GS} = 0$ $(I_{DSS})$ A0.1	CGDO	zero-bias gate-drain p-n capacitance in Raytheon capaci-	F.	0
CLVLcapacitance model flag CLVLV = 1 use Materka-Kacprzak capacitance model CLVLV = 2 use Raytheon capacitance model CLVLV = 2 use Raytheon capacitance model ( $C_{LVL}$ )-1Econstant part of drain current power( $E$ )-2FCC( $F_{CC}$ )-0.8GAMAVoltage slope parameter of pinch-off voltage source ( $\geq 0$ ) $\sqrt{V^{-1}}$ 0IB0current parameter of gate-drain breakdown source ( $\geq 0$ )A0IDSSfrain saturation current for $V_{GS} = 0$ ( $I_{DSS}$ )A0.1		tance model. Used if $CLVL = 2$ ( $C_{GS}$ )		1
CLVLV = 1 use Materka-Kacprzak capacitance model $(C_{LVL})$ Ecurrent part of drain current power $(E)$ -2FCC $(F_{CC})$ -0.8GAMAVoltage slope parameter of pinch-off voltage $(\gamma)$ $V^{-1}$ 0IB0current parameter of gate-drain breakdown source ( $\geq 0$ )A0IDSSfrain saturation current for $V_{GS} = 0$ $(I_{DSS})$ A0.1	CLVL	Current and the second	-	1
Econstant part of drain current power $(C_{LVL})$ -2FCC $(F_{CC})$ -0.8GAMAVoltage slope parameter of pinch-off voltage $(\gamma)$ $V^{-1}$ 0IB0current parameter of gate-drain breakdown source ( $\geq 0$ )A0IDSSfrain saturation current for $V_{GS} = 0$ $(I_{DSS})$ A0.1		CLVLV = 1 use Materia-Kacprzak capacitance model $CLVLV = 2$ use Baytheon capacitance model ( $C_{TVLV}$ )		
Interpret of that current power(D)InterpretInterpretFCC( $F_{CC}$ )-0.8GAMAVoltage slope parameter of pinch-off voltage( $\gamma$ )V <sup>-1</sup> 0IB0current parameter of gate-drain breakdown source ( $\geq 0$ )A0IDSSfrain saturation current for $V_{GS} = 0$ ( $I_{DSS}$ )A0.1	F	CLVLV = 2 use flay theor capacitatice model $(CLVL)$		2
<b>GAMA</b> Voltage slope parameter of pinch-off voltage $(\gamma)$ $V^{-1}$ $0.3$ <b>IBO</b> current parameter of gate-drain breakdown source ( $\geq 0$ )A $0$ <b>IDSS</b> frain saturation current for $V_{GS} = 0$ $(I_{DSS})$ A $0.1$	FCC	(E)	_	0.8
Unitage stope parameter of parameter of parameter of parameter of parameter of gate-drain breakdown source $(\geq 0)$ V0IB0current parameter of gate-drain breakdown source $(\geq 0)$ A0IDSSfrain saturation current for $V_{GS} = 0$ $(I_{DSS})$ A0.1	GAMA	$\frac{(\Gamma CC)}{Voltage slope parameter of pinch-off voltage}$	$V^{-1}$	0.0
Interpretation of gate dram breakdownInterpretationsource ( $\geq 0$ )( $I_{B0}$ )IDSSfrain saturation current for $V_{GS} = 0$ ( $I_{DSS}$ )A0.1Continued on part page	TBO	current parameter of gate-drain breakdown	A	0
IDSSfrain saturation current for $V_{GS} = 0$ (IB0)IDSSfrain saturation current for $V_{GS} = 0$ (IDSS)A0.1	100	source $(> 0)$ $(I_{DO})$	**	
Continued on part name	IDSS	frain saturation current for $V_{CS} = 0$ (180)	А	0.1
Commed on next bage			Continued or	n next page

Table 7.3: GASFET level 5 (Materka-Kacprzak) model keywords. SOMEVERSIONSOFSPICE only. Parameters that are NOT USED are reserved for future expansion.

Name	Description	Units	Default
IGO	saturation current of gate-source schottky	А	0
	barrier $(I_{G0})$		
K1	slope parameter of gate-source capacitance $(K_1)$	$V^{-1}$	1.25
KE	dependence of drain current power on $V_{GS}$ ( $K_E$ )	$V^{-1}$	0
KF	slope parameter of gate-drain feedback capacitance $(K_F)$	-	0
KFL	flicker noise coefficient $(K_{FL})$	-	0
KG	linearregion drain current $V_{GS}$ dependence $(K_G)$	$V^{-1}$	0
KR	slope factor of intrinsic channel resistance $(K_R)$	$V^{-1}$	0
LEVEL	model index must be 5	-	1
М	gate p-n grading coefficient $(M)$	-	0.5
MGS	gate-source p-n grading coefficient $(M_{GS})$	-	М
MGD	gate-drain p-n grading coefficient $(M_{GS})$	-	М
R10	intrinsic channel resistance for $V_{GS} = 0.$ (R <sub>10</sub> )	Ω	$\infty$
RD	drain resistance $(R_D)$	Ω	0
RDSD	channel trapping resistance NOT USED $(R_{DSD})$	Ω	$\infty$
RG	gate resistance $(R_G)$	Ω	0
RS	source resistance $(R_S)$	Ω	0
SL	slope of $V_{GS} = 0$ drain current, linear region $(S_L)$	S	0.15
SS	slope of $V_{GS} = 0$ drain current, saturated region $(S_S)$	S	0
Т	channel transit time delay $(\tau)$	s	0
TJ	junction temperature (VERSION: SOMEVERSIONSOF-	Κ	298
	SPICE) $(T_J)$		
TNOM	model reference temperature $(> 0)$ (VERSION: SOMEVER-	Κ	298
	SIONSOFSPICE) $(T_{NOM})$		
TRG1	temperature coefficient of RG $(A_{RG})$	$^{\circ}\mathrm{C}^{-1}$	0
TRD1	temperature coefficient of RG $(A_{RD})$	$^{\circ}\mathrm{C}^{-1}$	0
TRS1	temperature coefficient of RG $(A_{RS})$	$^{\circ}\mathrm{C}^{-1}$	0
VBC	breakdown voltage ( $\geq 0$ ( $V_{BC}$ )	V	$\infty$
VBI	gate p-n potential in Raytheon capacitance model. Used	V	1
	if $CLVL = 2.$ (V <sub>BI</sub> )		
VPO	(VP-zero) pinch-off voltage for $V_{DS} = 0$ ( $V_{P0}$ )	V	-2.5

# Temperature Dependence

The Materka-Kacprzak temperature effects are as follows where T and  $T_{\text{NOM}}$  are absolute temperatures in Kelvins (K).

$$\begin{split} I_{DSS}(T) &= I_{DSS}(T_{\rm NOM} \left(1 + A_{IDSS}(T - T_{\rm NOM})\right) & (7.104) \\ C_{10}(T) &= C_{10}(T_{\rm NOM} \left(1 + A_{C10}(T - T_{\rm NOM})\right) & (7.105) \\ C_{F0}(T) &= C_{F0}(T_{\rm NOM} \left(1 + A_{CF0}(T - T_{\rm NOM})\right) & (7.106) \\ E(T) &= E(T_{\rm NOM} \left(1 + A_{E}(T - T_{\rm NOM})\right) & (7.107) \\ K_{E}(T) &= K_{E}(T_{\rm NOM} \left(1 + A_{KE}(T - T_{\rm NOM})\right) & (7.108) \\ K_{G}(T) &= K_{G}(T_{\rm NOM} \left(1 + A_{KG}(T - T_{\rm NOM})\right) & (7.109) \\ \gamma(T) &= \gamma(T_{\rm NOM} \left(1 + A_{R10}(T - T_{\rm NOM})\right) & (7.110) \\ R_{10}(T) &= R_{10}(T_{\rm NOM} \left(1 + A_{RG}(T - T_{\rm NOM})\right) & (7.112) \\ R_{D}(T) &= R_{D}(T_{\rm NOM} \left(1 + A_{RG}(T - T_{\rm NOM})\right) & (7.112) \\ R_{D}(T) &= R_{S}(T_{\rm NOM} \left(1 + A_{RG}(T - T_{\rm NOM})\right) & (7.113) \\ R_{S}(T) &= R_{S}(T_{\rm NOM} \left(1 + A_{RS}(T - T_{\rm NOM})\right) & (7.115) \\ S_{S}(T) &= S_{S}(T_{\rm NOM} \left(1 + A_{SS}(T - T_{\rm NOM})\right) & (7.116) \\ \tau(T) &= \tau(T_{\rm NOM} \left(1 + A_{SS}(T - T_{\rm NOM})\right) & (7.117) \\ V_{BC}(T) &= V_{BC}(T_{\rm NOM} \left(1 + A_{VBC}(T - T_{\rm NOM})\right) & (7.118) \\ V_{P0}(T) &= V_{P0}(T_{\rm NOM} \left(1 + A_{VP0}(T - T_{\rm NOM})\right) & (7.119) \\ \end{split}$$

# Parasitic Resistances

The resistive parasities  $R'_S$ , and  $R'_D$  are calculated from the sheet resistivities  $RS (= R_S)$  and  $RD (= R_D)$ , and the Area specified on the element line.  $RG (= R_G)$  is used as supplied.

$$R'_D = R_D / Area \tag{7.120}$$

$$R'_{G} = \begin{cases} R_{G} & \text{PSPICE} \\ R_{G}/Area & \text{SOMEVERSIONSOFSPICE} \end{cases}$$
(7.121)

$$R'_G = R_G / Area \tag{7.122}$$

$$R'_S = R_S / Area \tag{7.123}$$

The parasitic resistance parameter dependencies are summarized in figure 7.18.

KEYWORD PARAMETERS	+	GEOMETRY PARAMETER	$\rightarrow$	DEVICE PARAMETERS
$\begin{array}{c c} \hline \textbf{RD} & R_D \end{array}$		Area		$\frac{R'_D = f(Area, R_D)}{R'_D = f(Area, R_D)}$
RG $R_G$ RS $R_S$				$\begin{array}{l} R_G' = f(Area, R_G \\ R_S' = f(Area, R_S) \end{array}$

Figure 7.18: MESFET parasitic resistance parameter relationships.

# LEVEL 5 (Materka-Kacprzak Model) I/V Characteristics

 $GaAs\ MESFET$ 

The LEVEL 5 current/voltage characteristics are analytic except for the channel resistance  $R_I$  determination.

$$I_{DS} = AreaI_{DSS} \left[ 1 + S_S \frac{V_{DS}}{I_{DSS}} \right] \left[ 1 - \frac{V_{GS}(t-\tau)}{V_{P0} + \gamma V_{DS}} \right]^{(E+K_E V_{GS}(t-\tau))} \times \tanh \left[ \frac{S_L V_{DS}}{I_{DSS}(1-K_G V_{GS}(t-\tau))} \right]$$
(7.124)

$$I_{GS} = Area I_{G0} \left[ e^{A_{FAG} V_{GS}} - 1 \right] - I_{B0} \left[ e^{-A_{FAB} \left( V_{GS} + V_{BC} \right)} \right]$$
(7.125)

$$I_{GD} = Area I_{G0} \left[ e^{A_{FAG} V_{GD}} - 1 \right] - I_{B0} \left[ e^{-A_{FAB} (V_{GD} + V_{BC})} \right]$$
(7.126)

$$R_{I} = \begin{cases} R_{10}(1 - K_{R}V_{GS})/Area & K_{R}V_{GS} < 1.0\\ 0 & K_{R}V_{GS} \ge 1.0 \end{cases}$$
(7.127)

The relationships of the parameters describing the I/V characteristics for the LEVEL 5 model are summarized in figure ??.

KEY	WORD	+	GEOMETRY	$\rightarrow$	DEVICE
PARAMETERS			PARAMETER		PARAMETERS
AFAG	$A_{FAG}$		Area		$I_{DS} = f(Area, E, \gamma, I_{DSS},$
AFAB	$A_{FAB}$				$K_E, K_G, S_L, S_S, \tau, V_{P0})$
GAMA	$\gamma$				$I_{GS} = f(Area, A_{FAB}, A_{FAG},$
IDSS	$I_{DSS}$				$I_{B0}, I_{G0}, V_{BC})$
IBO	$I_{B0}$				$I_{GD} = f(Area, A_{FAB}, A_{FAG},$
IGO	$I_{G0}$				$I_{B0}, I_{G0}, V_{BC})$
KG	$K_G$				$R_I = f(Area, K_R, R_{10}, V_{GS})$
KE	$K_E$				
KR	$K_R$				
R10	$R_{10}$				
SS	$S_S$				
SL	$S_L$				
Т	au				
VBC	$V_{BC}$				
VPO	$V_{P0}$				

Figure 7.19: LEVEL 5 (Materka-Kacprzak model) I/V dependencies.

#### LEVEL 5 (Materka-Kacprzak Model) Capacitances

Two capacitance models are available depending on the value of the  $C_{LVL}$  (CLVL) parameter. With  $C_{LVL} = 1$  (default) the standard Materka capacitance model described below is used. With  $C_{LVL} = 0$  the Raytheon capacitance model described on page 129 is used. The Materka-Kacprzak capacitances are

$$C'_{DS} = Area C_{DS} \tag{7.128}$$

$$C'_{GS} = \begin{cases} Area \left[ C_{10} (1 - K_1 V_{GS})^{M_{GS}} + C_{1S} \right] & K_1 V_{GS} < F_{CC} \\ Area \left[ C_{10} (1 - F_{CC})^{M_{GS}} + C_{1S} \right] & K_1 V_{GS} \ge F_{CC} \end{cases}$$
(7.129)

$$C'_{GD} = \begin{cases} Area \left[ C_{F0} (1 - K_1 V_1)^{M_{GD}} \right] & K_1 V_1 < F_{CC} \\ Area \left[ C_{F0} (1 - F_{CC})^{M_{GD}} \right] & K_1 V_1 \ge F_{CC} \end{cases}$$
(7.130)

The LEVEL 5 capacitance parameter dependencies are summarized in figure 7.20.

KEYV	WORD	+	GEOMETRY	$\rightarrow$	DEVICE
PARAMETERS			PARAMETER		PARAMETERS
CGD	$C_{GD}$		Area		$C'_{DS} = f(Area, C_{DS})$
CGS	$C_{GS}$				$C_{GD}' = f(Area, C_{10}, C_{1S},$
CDS	$C_{DS}$				$F_{CC}, K_1, V_{GS}, M_{GS})$
FC	$F_C$				$C'_{GS} = f(Area, C_{F0}, C_{1S},$
VBI	$V_{BI}$				$F_{CC}, K_1, V_1, V_{GS}, M_{GS})$
М	M				

Figure 7.20: LEVEL 5 (Materka-Kacprzak model) capacitance dependencies.

# LEVEL 6 (Angelov Model)

The parameter keywords of the Materka-Kacprzak model are given in table 7.4.

<b></b>			TT •/	
Name	Description		Units	Default
AF	flicker noise exponent	$(A_F)$	-	1
ACGS	linear temperature coefficient of CGS	$(A_{CGS})$	$^{\circ}\mathrm{C}^{-1}$	0
ACGD	linear temperature coefficient of CGD	$(A_{CGD})$	$^{\circ}\mathrm{C}^{-1}$	0
ALFA	saturation voltage parameter $(\geq 0)$	$(\alpha)$	$V^{-1}$	1.5
ARI	linear temperature coefficient of RI	$(A_{RI})$	$^{\circ}\mathrm{C}^{-1}$	0
ARG	linear temperature coefficient of RG	$(A_{RG})$	$^{\circ}\mathrm{C}^{-1}$	0
ARD	linear temperature coefficient of RD	$(A_{RD})$	$^{\circ}\mathrm{C}^{-1}$	0
ARS	linear temperature coefficient of RS	$(A_{RS})$	$^{\circ}\mathrm{C}^{-1}$	0
B1	unsaturated coefficient of P1	$(B_1)$	-	0
B2	drain voltage slope parameter for B1	$(B_2)$	-	3.0
BCGD	quadratic temperature coefficient of CGD	$(B_{CGD})$	$^{\circ}\mathrm{C}^{-2}$	0
BCGS	quadratic temperature coefficient of CGS	$(B_{CGS})$	$^{\circ}\mathrm{C}^{-2}$	0
BRI	quadratic temperature coefficient of RI	$(B_{RI})$	$^{\circ}\mathrm{C}^{-2}$	0
BRG	quadratic temperature coefficient of RG	$(B_{RG})$	$^{\circ}\mathrm{C}^{-2}$	0
BRS	quadratic temperature coefficient of RS	$(B_{RS})$	$^{\circ}\mathrm{C}^{-2}$	0
BRD	quadratic temperature coefficient of RD	$(B_{RD})$	$^{\circ}\mathrm{C}^{-2}$	0
CGDO	gate-source capacitance at $\Psi_3 = \Psi_4 = 0$ ( $\xi = 0$ )	$(C_{GD0})$	F	0
CGSO	gate-source capacitance at $\Psi_1 = \Psi_2 = 0$ ( $i = 0$ )	$(C_{GS0})$	F	0
EG	barrier height at 0 K	$(E_G)$	V	0.8
GAMA	voltage slope parameter for pinch-off		$V^{-1}$	0
	(NO LONGER USED)			
IBO	breakdown saturation current $(\geq 0)$	$(I_{B0})$	А	0
IPK	drain current at peak $g_m \ (\geq 0)$	$(I_{PK})$	А	0.1
IS	diode saturation current $(\geq 0)$	$(I_S)$	А	0
LAMB	slope of the drain characteristic	$(\lambda)$	$V^{-1}$	0
			Continued of	n next page

Table 7.4: GASFET model 6 (Angelov) keywords. Parameters that are NOT USED are reserved for future expansion.

Name	Description		$\mathbf{Units}$	Default
LEVEL	model index	must be 6	-	1
N	diode ideality factor $(> 0$	(N)	-	1
NR	breakdown ideality factor $(> 0$	$(N_R)$	-	10
P2	polynomial coefficient of channel current	$(P_2)$	$V^{-2}$	0
РЗ	polynomial coefficient of channel current	$(P_3)$	$V^{-3}$	0
P4	polynomial coefficient of channel current	$(P_4)$	$V^{-4}$	0
P5	polynomial coefficient of channel current	$(P_5)$	$V^{-5}$	0
P6	polynomial coefficient of channel current	$(P_6)$	$V^{-6}$	0
P7	polynomial coefficient of channel current	$(P_{7})$	$V^{-7}$	0
P8	polynomial coefficient of channel current	$(P_{7})$	$V^{-8}$	0
P10	polynomial coefficient of g-s capacitance	$(P_{10})$	-	0
P11	polynomial coefficient of g-s capacitance	$(P_{11})$	$V^{-1}$	0
P12	polynomial coefficient of g-s capacitance	$(P_{12})$	$V^{-2}$	0
P13	polynomial coefficient of g-s capacitance	$(P_{13})$	$V^{-3}$	0
P14	polynomial coefficient of g-s capacitance	$(P_{14})$	$V^{-4}$	0
P20	polynomial coefficient of g-s capacitance	$(P_{20})$	-	0
P21	polynomial coefficient of g-s capacitance	$(P_{21})$	$V^{-1}$	0
P22	polynomial coefficient of g-s capacitance	$(P_{22})$	$V^{-2}$	0
P23	polynomial coefficient of g-s capacitance	$(P_{23})$	$V^{-3}$	0
P24	polynomial coefficient of g-s capacitance	$(P_{24})$	$V^{-4}$	0
P30	polynomial coefficient of g-d capacitance	$(P_{30})$	-	0
P31	polynomial coefficient of g-d capacitance	$(P_{31})$	$V^{-1}$	0
P32	polynomial coefficient of g-d capacitance	$(P_{32})$	$V^{-2}$	0
P33	polynomial coefficient of g-d capacitance	$(P_{33})$	$V^{-3}$	0
P34	polynomial coefficient of g-d capacitance	$(P_{34})$	$V^{-4}$	0
P40	polynomial coefficient of g-d capacitance	$(P_{40})$	-	0
P41	polynomial coefficient of g-d capacitance	$(P_{41})$	$V^{-1}$	0
P42	polynomial coefficient of g-d capacitance	$(P_{42})$	$V^{-2}$	0
P43	polynomial coefficient of g-d capacitance	$(P_{43})$	$V^{-3}$	0
P44	polynomial coefficient of g-d capacitance	$(P_{44})$	$V^{-4}$	0
P1CC	polynomial coefficient of g-d capacitance	$(P_{1CC})$		0
PSAT	polynomial coefficient of channel current PSAT	$(P_1)$	$V^{-1}$	1.3
RI	channel resistacne ( $\geq 0$ ) NOT USED	$(R_I)$		0
Т	channel time delay $(\geq 0)$	( au)	S	0
TJ	junction temperature	$(T_J)$	Κ	298
TM	$I_{DS}$ linear temperature coefficient	$(T_M)$		0
TME	$I_{DS}$ power law temperature coefficient	$(T_{ME})$		0
TNOM	model reference temperature $(> 0)$	$(T_{NOM})$	K	298
VBD	breakdown voltage	$(V_{BD})$		0
VPKO	gate-source voltage for unsaturated peak $g_m$	$(V_{PK0})$	V	-0.5
VPKS	gate-source voltage for peak $g_m$	$(V_{PKS})$	V	0
XTI	saturation current temperature exponent	$(X_{TI})$		2

Table 7.4: GASFET model 6 (Angelov) keywords. Parameters that are NOT USED are reserved for future expansion.

Temperature Dependence

Temperature effects are incorporated as follows where T and  $T_{\text{NOM}}$  are absolute temperatures in Kelvins (K) and the thermal voltage  $V_{\rm TH} = kT/q$ .

$$\alpha(T) = \alpha(T_{\text{NOM}}) \left( 1 + A_{\alpha}(T - T_{\text{NOM}}) \right)$$
(7.131)

$$C_{GS0}(T) = C_{GS0}(T_{\rm NOM}) \left( 1 + A_{CGS}(T - T_{\rm NOM}) + B_{CGS}(T - T_{\rm NOM})^2 \right)$$
(7.132)

$$C_{GD0}(T) = C_{GD0}(T_{\text{NOM}}) \left( 1 + A_{CGD}(T - T_{\text{NOM}}) + B_{CGD}(T - T_{\text{NOM}})^2 \right)$$
(7.133)

$$E_G(T) = E_G(0) - F_{\text{GAP1}} 4T^2 / (T + F_{\text{GAP2}})$$
(7.134)

$$\gamma(T) = \gamma(T_{\text{NOM}}) \left( 1 + A_{\gamma}(T - T_{\text{NOM}}) \right) \tag{7.135}$$

$$I_{PK}(T) = I_{PK}(T_{\text{NOM}}) \left(1 + A_{IPK}(T - T_{\text{NOM}})\right)$$
(7.136)

$$R_{I}(T) = R_{I}(T_{\text{NOM}}) \left(1 + A_{RI}(T - T_{\text{NOM}}) + B_{RI}(T - T_{\text{NOM}})^{2}\right)$$
(7.137)  
$$R_{G}(T) = R_{G}(T_{\text{NOM}}) \left(1 + A_{RG}(T - T_{\text{NOM}}) + B_{RG}(T - T_{\text{NOM}})^{2}\right)$$
(7.138)

$$_{G}(T) = R_{G}(T_{\text{NOM}}) \left( 1 + A_{RG}(T - T_{\text{NOM}}) + B_{RG}(T - T_{\text{NOM}})^{2} \right)$$
(7.138)

$$R_D(T) = R_D(T_{\text{NOM}}) \left( 1 + A_{RD}(T - T_{\text{NOM}}) + B_{RD}(T - T_{\text{NOM}})^2 \right)$$
(7.139)  
$$R_D(T) = R_D(T_{\text{NOM}}) \left( 1 + A_R(T - T_{\text{NOM}}) + B_R(T - T_{\text{NOM}})^2 \right)$$
(7.140)

$$R_{S}(T) = R_{S}(T_{\text{NOM}}) \left( 1 + A_{RS}(T - T_{\text{NOM}}) + B_{RS}(T - T_{\text{NOM}})^{2} \right)$$
(7.140)  
$$V_{RK}(T) = V_{RK}(T_{\text{NOM}}) \left( 1 + A_{VRK}(T - T_{\text{NOM}}) \right)$$
(7.141)

$$V_{PK}(T) = V_{PK}(T_{\text{NOM}}) \left(1 + A_{VPK}(T - T_{\text{NOM}})\right)$$
(7.141)  

$$V_{PK}(T) = V_{PK}(T_{\text{NOM}}) \left(1 + A_{VPK}(T - T_{\text{NOM}})\right)$$
(7.142)

$$V_{BD}(T) = V_{BD}(T_{\rm NOM}) \left(1 + A_{VBD}(T - T_{\rm NOM})\right)$$
(7.142)

$$\mathsf{TM}I_{DS}\mathsf{TME}???? \tag{7.143}$$

# Parasitic Resistances

The resistive parasities  $R'_S$ , and  $R'_D$  are calculated from the sheet resistivities RS (=  $R_S$ ) and RD (=  $R_D$ ), and the Area specified on the element line.  $RG (= R_G)$  is used as supplied.

$$R'_D = R_D / Area \tag{7.144}$$

$$R'_G = R_G/Area \tag{7.145}$$

$$R'_S = R_S / Area \tag{7.146}$$

The parasitic resistance parameter dependencies are summarized in Figure 7.21.



Figure 7.21: MESFET parasitic resistance parameter relationships.

LEVEL 6 (Angelov Model) I/V Characteristics

# $GaAs\ MESFET$

The  $\tt LEVEL~6~current/voltage~characteristics$  are analytic:

 $P_1$ 

$$I_{DS} = I_{PK}[1 + \tanh(\Psi)][1 + \lambda V_{DS}] \tanh(\alpha V_{DS})$$
(7.147)

$$\Psi = P_1 (V_{GS} - V_{PK}) + P_2 (V_{GS} - V_{PK})^2 + P_3 (V_{GS} - V_{PK})^3 + P_4 (V_{GS} - V_{PK})^4 + P_5 (V_{GS} - V_{PK})^5 + P_6 (V_{GS} - V_{PK})^6$$

$$+P_7 \left(V_{GS} - V_{PK}\right)^7 + P_8 \left(V_{GS} - V_{PK}\right)^8 \tag{7.148}$$

$$= P_{\text{SAT}} \left[ 1 + B_1 / \left( \cosh^2(B_2 V_{DS}) \right) \right]$$
(7.149)

$$V_{PK} = V_{PK0} + (V_{PKS} - V_{PK0}) \tanh(\alpha V_{DS})$$
(7.150)

$$I_{GS} = I_{S} \left[ e^{V_{GS}/(NV_{\text{TH}})} - 1 \right] - I_{B0} \left[ e^{-(V_{GS} + V_{BD})/(N_{R}V_{\text{TH}})} \right]$$
(7.151)

$$I_{GD} = I_S \left[ e^{V_{GD}/(NV_{\text{TH}})} - 1 \right] - I_{B0} \left[ e^{-(V_{GD}+V_{BD})/(N_R V_{\text{TH}})} \right]$$
(7.152)

$$R_I = R'_I / Area \tag{7.153}$$

The relationships of the parameters describing the I/V characteristics for the LEVEL 6 model are summarized in figure ??.

KEYV	NORD	+	GEOMETRY	$\rightarrow$	DEVICE
PARAM	1ETERS		PARAMETER		PARAMETERS
IPK	$I_{PK}$		Area		$I_{DS} = f(Area, I_{PK}, \lambda, \alpha,$
LAMB	$\lambda$				$P_1, P_2, P_3, P_4, P_5, P_6, P_7, P_8,$
ALFA	$\alpha$				$V_{PK0}, V_{PKS}, )$
P1	$P_1$				$I_{GS} =$
P2	$P_2$				$f(Area, I_S, N, I_{B0}, V_{BD}, N_R)$
РЗ	$P_3$				$I_{GS} =$
P4	$P_4$				$f(Area, I_S, N, I_{B0}, V_{BD}, N_R)$
P5	$P_5$				
P6	$P_6$				
P7	$P_7$				
P8	$P_8$				
IS	$I_S$				
Ν	N				
IBO	$I_{B0}$				
NR	$N_R$				
VBD	$V_{BD}$				
VPKO	$V_{PK0}$				
VPKS	$V_{PKS}$				

Figure 7.22: LEVEL 6 (Angelov model) I/V dependencies.

LEVEL 6 (Angelov Model) Capacitances

The Angelov capacitances are

$$C'_{DS} = Area C_{DS} \tag{7.154}$$

$$C'_{GS} = Area C_{GS0} \left[ 1 + \tanh(\Psi_1) \right] \left[ 1 + \tanh(\Psi_2) \right]$$
(7.155)

$$\Psi_{1} = P_{10} + P_{11}V_{GS} + P_{12}V_{GS}^{2} + P_{13}V_{GS}^{3} + P_{14}V_{GS}^{4}$$

$$\Psi_{2} = P_{20} + P_{14}V_{DG} + P_{20}V_{C}^{2} + P_{20}V_{C}^{3} + P_{24}V_{C}^{4}$$
(7.156)
(7.157)

$$\Psi_2 = P_{20} + P_{11}V_{DS} + P_{22}V_{DS}^2 + P_{23}V_{DS}^3 + P_{24}V_{DS}^4$$
(7.157)

$$C'_{GD} = AreaC_{GD0} \left[1 + \tanh(\Psi_3)\right] \left[1 - \tanh(\Psi_4)\right]$$

$$\Psi_3 = P_{30} + P_{31}V_{GS} + P_{32}V^2_{GS} + P_{33}V^3_{GS} + P_{34}V^4_{GS}$$
(7.159)

$$\Psi_4 = P_{40} + (P_{41} + P_{1CC}V_GS)V_{DS} + P_{42}V_{DS}^2 + P_{43}V_{DS}^3 + P_{44}V_{DS}^4$$
(7.160)

The LEVEL 6 capacitance parameter dependencies are summarized in figure 7.23.



Figure 7.23: LEVEL 6 (Angelov model) capacitance dependencies.

AC Analysis The AC analysis uses the model of figure 7.24 with the capacitor values evaluated at the DC



Figure 7.24: Small signal GASFET model showing noise sources  $I_{n,G}$ ,  $I_{n,D}$ ,  $I_{n,S}$ , and  $I_{n,DS}$  used in the noise analysis.  $R_I$  is not used in PSPICE.

operating point with  $g_m = \frac{\partial I_{DS}}{\partial V_{GS}}$   $R_{GD} = \frac{\partial I_{GD}}{\partial V_{GD}}$   $R_{GS} = \frac{\partial I_{GS}}{\partial V_{GS}}$   $R_{DS} = \frac{\partial I_{DS}}{\partial V_{DS}}$ (7.161) Noise Analysis

# Noise Analysis

The MESFET noise model, see figure 7.24, accounts for thermal noise generated in the parasitic resistances and shot and flicker noise generated in the drain source current generator. The rms (root-mean-square) values of thermal noise current generators shunting the three parasitic resistance  $R_D$ ,  $R_G$  and  $R_S$  are

$$I_{n,D} = \sqrt{4kT/R'_D} \, \mathrm{A}/\sqrt{\mathrm{Hz}}$$
(7.162)

$$I_{n,G} = \sqrt{4kT/R'_G A/\sqrt{\text{Hz}}}$$
(7.163)

$$I_{n,S} = \sqrt{4kT/R'_S} \, \mathrm{A}/\sqrt{\mathrm{Hz}}$$
(7.164)

Shot and flicker noise are modeled by a noise current generator in series with the drain-source current generator  $I_{DS}$ . The rms value of this noise generator is given by

$$I_{n,DS} = \sqrt{I_{\text{SHOT},DS}^2 + I_{\text{FLICKER},DS}^2} \quad A/\sqrt{\text{Hz}}$$
(7.165)

$$I_{\text{SHOT},DS} = \sqrt{4kTg_m \frac{2}{3}} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.166)

$$I_{\text{FLICKER},DS} = \sqrt{\frac{K_F I_{DS}^{A_F}}{f}} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.167)

where f is the analysis frequency.

Capacitor

# С

Form



Figure 7.25: C — capacitor element.

# SPICE3Form

 $\texttt{Cname N}_1 \ N_2 \ [\textit{ModelName} ] \ \textit{CapacitorValue} \ [\texttt{IC=V}_C] \ [\texttt{L= Length}] \ [\texttt{W= Width}]$ 

#### PSPICEForm

Cname  $N_1 N_2$  [ModelName ] CapacitorValue [IC= $V_C$ ]

- $N_1$  is the positive element node,
- $N_2$  is the negative element node, and
- *ModelName* is the optional model name.
- CapacitorValue is the capacitance. This is modified if ModelName is specified. (Units: F; Required; Symbol: CapacitorValue)
  - L is the length Length of the integrated capacitor. (Units: m; Required in SPICE3 if ModelName specified; Symbol: L;)
  - W is the width Length of the integrated capacitor.
     (Units: m; Optional; Default: Default width DEFW specified in model ModelName; Symbol:
     L;)
  - IC is the optional initial condition specification Using  $IC=V_C$  is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired with an initial voltage  $V_C$  across the capacitor rather than the quiescent operating point. Specification of the transient initial conditions using the .IC statement (see page 66) is preferred and is more convenient.

#### Example

CAP1 1 GND 12.3PF C1 node1 0 ((12.3 + 2.1)/2)

## Model Type

CAP

Capacitor

# CAP Model

# Spice3 Only

Capacitor Model

## Form

.MODEL ModelName CAP( [  $[keyword = value] \dots$  ] )

Example

.MODEL SMALLCAP CAP( CJ CJSW DEFW $10^{-6}$  NARROW)

#### Model Keywords

Name	Description		Units	Default
CJ	junction bottom capacitance	$(C_J)$	$F/m^2$	REQUIRED
CJSW	junction sidewall capacitance	$(C_{J,SW})$	F/m	REQUIRED
DEFW	default device width	$(W_{DEF})$	meters	$10^{-6}$
NARROW	narrowing due to side etching	$(X_{NARROW})$	meters	0

The SPICE3 capacitance model is a process model for a monolithicly fabricated capacitor enabling the capacitance to be determined from geometric information. If the parameter W is not specified on the element line then Width defaults to  $DEFW = W_{DEF}$ . The effective dimensions are reduced by etching so that the effective length of the capacitor is

$$L_{\rm EFF} = (Length - X_{\rm NARROW}) \tag{7.168}$$

and the effective width is

$$W_{\rm EFF} = (Width - X_{\rm NARROW}) \tag{7.169}$$

The new value of the capacitance

$$NewCapacitorValue = C_J L_{\rm EFF} W_{\rm EFF} + 2C_{J,\rm SW} (L_{\rm EFF} + W_{\rm EFF})$$
(7.170)

CAP Model	PSPICE Only	Capacitor Model
Form		
.MODEL ModelName	CAP( $[keyword = value] \dots ]$ )	

Example

.MODEL SMALLCAP GASFET(C=2.5 VC1=0.01 VC2=0.001 TC1=0.02 TC2=0.005)

# Model Keywords

Name	Description		Units	Default
С	capacitance multiplier	$(C_{MULTIPLIER})$	-	1
VC1	linear voltage coefficient	$(V_{C1})$	1/V	0
VC2	quadratic voltage coefficient	$(V_{C2})$	1/V	0
TC1	linear temperature coefficient	$(T_{C1})$	$1/^{\circ}C$	0
TC2	quadratic temperature coefficient	$(T_{C1})$	$1/^{\circ}C$	0

The PSPICE capacitance model is a nonlinear temperature dependent capacitor model. It is assumed that the model parameters were determined or measured at the nominal temperature  $T_{\text{NOM}}$  (default 27°C) specified in the most recent .OPTIONS statement preceeding the .MODEL statement.

If the CAP model is specified then a new capacitance is evaluated as

$$C = Capacitor Value C_{\text{MULTIPLIER}} \left[ 1 + V_{C1}V_C + V_{C2}V_C^2 \right]$$
(7.171)

$$\times \left[ 1 + T_{C1} (T - T_{\text{NOM}}) + T_{C2} (T - T_{NOM})^2 \right]$$
(7.172)

where  $V_C$  is the voltage across the capacitor as in figure 7.25 and T is the current temperature. If PSPICE CAP model is not specified then the capacitance specified on the element line is used.







Form

Dname  $n_1 n_2$  ModelName [Area] [OFF] [IC= $V_D$ ]

**PSpice**Form

 $Dname n_1 n_2 ModelName [Area] [OFF]$ 

- $n_1$  is the positive (anode) diode node.
- $n_1$  is the negative (cathode) diode node.

*ModelName* is the model name.

- Area is an optional relative area factor. (Units: none; Optional; Default: 1, Symbol: Area)
- OFF indicates an (optional) starting condition on the device for DC operating point analysis. If specified the DC operating point is calculated with the terminal voltages set to zero. Once convergence is obtained, the program continues to iterate to obtain the exact value of the terminal voltages. The OFF option is used to enforce the solution to correspond to a desired state if the circuit has more than one stable state.
- IC is the (optional) initial condition specification. Using  $IC = V_D$  is intended for use with the UIC option on the other than the quiescent operating point. Specification of the transient initial conditions using the .IC statement (see page 66) is preferred and is more convenient.

#### Example

DBRIDGE 2 10 DIODE1 DCLMP 3 7 DMOD 3.0 IC=0.2

# Model Type

DIODE

# **DIODE** Model

Diode Model

Note



Figure 7.27: Schematic of diode element model.

- 1. In some SPICE implementations XTI is called PT and VJ is called PB.
- 2. It is assumed that the model parameters were determined or measured at the nominal temperature  $T_{\text{NOM}}$  (default 27°C) specified in the most recent .OPTIONS statement preceeding the .MODEL statement.

The physical constants used in the model evaluation are

k	Boltzman's constant	$1.3806226  10^{-23}  \mathrm{J/K}$
q	electronic charge	$1.6021918  10^{-19} \mathrm{C}$

### Temperature Dependence

Temperature effects are incorporated as follows where T and  $T_{\text{NOM}}$  are absolute temperatures in Kelvins (K). The thermal voltage

$$V_{\rm TH} = \frac{kT}{q} \tag{7.173}$$

and

$$I_S(T) = I_S e^{\left(E_g(T)\frac{T}{T_{\text{NOM}}} - E_G(T)\right)/(nV_{\text{TH}})} \left(\frac{T}{T_{\text{NOM}}}\right)$$
(7.174)

$$\phi_J(T) = \phi_J \frac{T}{T_{\text{NOM}}} - 3V_{\text{TH}} \ln \frac{T}{T_{\text{NOM}}} + E_G(T_{\text{NOM}}) \frac{T}{T_{\text{NOM}}} - E_G(T)$$
(7.175)

$$C_{J0}(T) = C_{J0} \{ 1 + M[0.0004(T - T_{\text{NOM}}) + (1 - \phi_J(T)/\phi_J)] \}$$
(7.176)

(7.177)

# Parasitic Resistance

The parasitic diode series resistance  $R_S$ , is calculated by scaling the sheet resistivity  $R'_S$  (= RS) by the Area parameter on the element line

$$R_S = R'_S / Area \tag{7.178}$$

## <u>Current Characteristics</u>

$$I_{D} = \begin{cases} AreaI_{S}\left(e^{\frac{V_{D}}{nV_{\mathrm{TH}}}}-1\right) + V_{D}G_{\mathrm{MIN}} & V_{D} \ge -10nV_{\mathrm{TH}} \\ -AreaI_{S} + V_{D}G_{\mathrm{MIN}} & -30V_{\mathrm{TH}} - V_{B} \le V_{D} < -10nV_{\mathrm{TH}} \\ -Area\left(I_{BV}e^{-\frac{V_{B} + V_{D}}{V_{\mathrm{TH}}}}-I_{S}\right) + V_{D}G_{\mathrm{MIN}} & V_{D} < -30V_{\mathrm{TH}} - V_{B} \end{cases}$$
(7.179)

where  $G_{\text{MIN}}$  is GMIN, the minimum conductance between nodes. GMIN is set by a .OPTIONS statement (see page ??.) Capacitance

# Diode

## Table 7.5: DIODE model parameters.

Name	Description	Units	Default	Area
AF	flicker noise exponent $(A_F)$	-	1	
BV	magnitude of reverse breakdown voltage (positive) $(V_B)$	V	$\infty$	
CJO	zero-bias $p$ - $n$ junction capacitance per unit area (CJ-oh)	F	0	*
	$(C_{J0})$			
EG	bandgap voltage (barrier height) at 0 K $(E_G(0))$	eV	1.11	
	Schottky Barrier Diode: 0.69			
	Silicon: 1.16			
	Gallium Arsenide: 1.52			
	Germanium: 0.67			
FC	forward-bias depletion capacitance $(F_C)$	-	0.5	
FC	coefficient for forward-bias depletion capacitance formula	-		
	$(F_C)$			
IBV	magnitude of current at breakdown voltage per unit area	A	$110^{-10}$	*
	(positive) $(I_{BV})$			
IS	saturation current per unit area $(I_S)$	A	$110^{-14}$	*
KF	flicker noise coefficient $(K_F)$	-	0	
М	$p-n$ junction grading coefficient $(M_J)$	-	0.5	
N	emission coefficient ( <i>n</i> )	-	1	
RS	ohmic resistance per unit area $(R_S)$	Ω	0	*
TT	transit time $(\tau_T)$	S	0	
VJ	junction potential $(\phi_J)$	V	1	
XTI	saturation current $(I_S)$ temperature exponent $(X_{TI})$	-	3.0	

$$C = Area(C_J + C_D) \tag{7.180}$$

and the depletion capacitance at the junction per unit area is

$$C_J = \begin{cases} C_{J0} \left( 1 - \frac{V_D}{\phi_J} \right)^{-M} & V_D < F_C \phi_J \\ \frac{C_{J0}}{F_2} \left( F_3 + \frac{mV_D}{\phi_J} \right) & V_D \ge F_C \phi_J \end{cases}$$
(7.181)

where  $\phi_J,\,F_C,\,M$  and  $C_{J0}$  are the model parameters VJ, FC, M and CJO, and

$$F_2 = (1 - F_C)^{(1+m)} (7.182)$$

$$F_3 = 1 - F_C(1+m) \tag{7.183}$$

The diffusion capacitance per unit area due to charges in transit in the depleted region is

$$C_D = \tau \frac{\partial I_D}{\partial V_D} \tag{7.184}$$

where  $\tau$  is the transit time model parameter TT.

# AC Analysis

The AC analysis uses the model of figure 7.46 with the capacitor values evaluated at the DC operating point with the current source replaced by a linear resistor

$$R_D = \frac{\partial I_D}{\partial V_D} \tag{7.185}$$

# Noise Analysis

The DIODE noise model accounts for thermal noise generated in the parasitic series resistance and shot and flicker noise generated in the the junction. The rms (root-mean-square) value of the thermal noise current generators shunting  $R_S$  is

$$I_{n,S} = \sqrt{4kT/R_S} \text{ A}/\sqrt{\text{Hz}}$$
(7.186)

The RMS value of noise current generators shunting  $R_D$  in the AC model is

$$I_{n,J} = \left(I_{\text{SHOT}}^2 + I_{\text{FLICKER}}^2\right) \tag{7.187}$$

where the RMS shot noise current is

$$I_{\rm SHOT} = \sqrt{2qI_D} \quad A/\sqrt{\rm Hz} A/\sqrt{\rm Hz}$$
(7.188)

and the RMS flicker noise current is

$$I_{\rm FLICKER} = \sqrt{\frac{K_F I_D^{A_F}}{f K_{\rm CHANNEL}}} \quad A/\sqrt{\rm Hz}$$
(7.189)

where f is the analysis frequency and  $R_D$  is the ACjunction resistance in (7.185)

INPUT  $\begin{array}{c} N_{C_+} & & & & \\ & V_{C_+} & & & & \\ & & v_c & & \\ N_{C_-} & & & & & \\ & & & & N_- \end{array}$  OUTPUT



Form

Ename  $N_+$   $N_ N_{C+}$   $N_{C-}$  Gain Ename  $N_+$   $N_-$  POLY ( D )  $N_{C+}$   $N_{C-}$  PolynomialCoefficients

## PSPICEForm

 $\begin{array}{l} \mbox{Ename $N_+$ $N_-$ $N_{C+}$ $N_{C-}$ $Gain} \\ \mbox{Ename $N_+$ $N_-$ $POLY($D$) $(N_{C1+}$ $N_{C1-}$) $\dots$ $(N_{CD+}$ $N_{CD-}$) $PolynomialCoefficients $\mbox{Ename $N_+$ $N_-$ $VALUE= { Expression } $} \\ \mbox{Ename $N_+$ $N_-$ $TABLE { Expression }=($ $TableInput $, $TableOutput $) $\dots$ \\ \mbox{Ename $N_+$ $N_-$ $LAPLACE { Expression }=($ $TransformExpression $} \\ \mbox{Ename $N_+$ $N_-$ $FREQ { Expression }=($ $Frequency, $Magnitude, $Phase $) $\dots$ \\ \mbox{Ename $N_+$ $N_-$ $CHEBYSHEV { Expression }= $Type, $CutoffFrequency $\dots$ $, $Phase $\dots$ } \\ \end{array}$ 

# Е

- $N_+$  is the positive voltage source node.
- $N_{-}$  is the negative voltage source node.
- $N_{C+}$  is the positive controlling node.
- $N_{C-}$  is the negative controlling node.
- Gain is the voltage gain.
- POLY is the identifier for the polynomial form of the element.
  - D is the degree of the poynomial. The number of pairs of controlling nodes must be equal to *Degree*.
- $N_{Ci+}$  the positive node of the *i* th controlling node pair.
- $N_{Ci-}$  the negative node of the *i* th controlling node pair.
- *PolynomialCoefficients* is the set of polynomial coefficients which must be specified in the standard polynomial coefficient format discussed on page 47.
  - VALUE is the identifier for the value form of the element.
  - *Expression* This is an expression of the form discussed on page 47.

TABLE is the identifier for the <u>table form</u> of the element.

- TableInput This is the independent input of the table. See the TABLE parameter above.
- TableInput This is the dependent output of the table. See the TABLE parameter above.

LAPLACE is the identifier for the laplace form of the element.

#### Transform Expression

FREQ is the identifier for the frequency form of the element.

Frequency

Magnitude

Phase

CHEBYSHEV is the identifier for the chebyshev form of the element.

Type

#### CutoffFrequency

Phase

#### Example

E1 2 3 14 1 2.0

Note

1. Several form of the voltage-controlled voltage source element are supported in addition to the <u>Linear Gain</u> form which is the default. The other forms are selected based on the the identifier POLY, VALUE, TABLE, LAPLACE, FREQ or CHEBYSHEV.

Linear Gain Instance

Ename 
$$N_+ N_- N_{C+} N_{C-}$$
 Gain

The value of the voltage generator is linearly proportional to the controlling voltage:

$$v_o = Gain \, v_c \tag{7.190}$$

POLYnomial Instance

Ename 
$$N_+ N_-$$
 POLY( D) ( $N_{C1+} N_{C1-}$ ) ... ( $N_{CD+} N_{CD-}$ ) PolynomialCoefficients

The value of the voltage generator is a polynomial function of the controlling voltages:

$$v_o = f(v_{c1}, \dots, v_{ci}, \dots v_{cD}) \tag{7.191}$$

where the number of controlling voltages is D — the degree of the polynomial specified on the element line.  $v_{ci}$  is the *i*th controlling voltage and is the voltage of the  $n_{ci+}$  node with respect to the  $n_{ci+}$  node.

VALUE Instance — PSPICE92 only

Ename  $N_+$   $N_-$  VALUE= { Expression }

The value of the voltage generator is the resultant of an expression evaluation.

$$v_o = f(v_c) \tag{7.192}$$

<u>TABLE Instance</u> — PSpice92 only

Ename  $N_+ N_-$  TABLE { Expression }=( TableInput , TableOutput ) ...

$$v_o = f(v_c) \tag{7.193}$$

#### LAPLACE Instance — PSPICE92 only

Ename  $N_+ N_-$  LAPLACE { Expression }={ TransformExpression }

$$v_o = f(v_c) \tag{7.194}$$

FREQ - PSPICE92 only

Ename  $N_+ N_-$  FREQ { Expression }=( Frequency, Magnitude, Phase ) ...

$$v_o = f(v_c) \tag{7.195}$$

 $\underline{\texttt{CHEBYSHEV}} - \underline{\texttt{PSpice92}} \text{ only}$ 

Ename  $N_+$   $N_-$  CHEBYSHEV { Expression }= Type, CutoffFrequency  $\ldots$  , Phase  $\ldots$ 



Figure 7.29: F — current-controlled current source element.

#### Form

F

Fname  $N_+$   $N_-$  VoltageSourceName Gain Fname  $N_+$   $N_-$  POLY ( D ) VoltageSourceName\_1 ... VoltageSourceName\_D PolynomialCoefficients

 $N_+$  is the positive voltage source node.

 $N_{-}$  is the negative voltage source node.

VoltageSourceName is the name of the voltage source the current through which is the controlling current. The voltage source must be a V element.

- Gain is the current gain.
- POLY is the identifier for the polynomial form of the element
  - D is the degree of the poynomial. The number of pairs of controlling nodes must be equal to *Degree*.

 $VoltageSourceName_i$  is the name of the voltage source the current through which is the *i*th controlling current. The voltage source must be a V element.

*PolynomialCoefficients* is the set of polynomial coefficients which must be specified in the standard polynomial coefficient format discussed on page 47.

#### Example

E1 2 3 14 1 2.0

Linear Gain Instance

Fname  $N_+$   $N_ N_{C+}$   $N_{C-}$  Gain

The value of the voltage generator is linearly proportional to the controlling current:

$$v_o = Gain \, v_c \tag{7.196}$$

#### POLYnomial Instance

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Fname  $N_+ N_-$  POLY(D) ( $N_{C1+} N_{C1-}$ ) ... ( $N_{CD+} N_{CD-}$ ) PolynomialCoefficients

The value of the voltage generator is a polynomial function of the controlling voltages:

$$v_o = f(i_{c1}, \dots, i_{ci}, \dots i_{cD}) \tag{7.197}$$

where the number of controlling currents is D — the degree of the polynomial specified on the element line.  $i_{ci}$  is the *i*th controlling current and is the current flowing from the + terminal to the – terminal in the *i*th voltage source of name *VoltageSourceName*.

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Voltage-Controlled Current Source



Figure 7.30: G — voltage-controlled current source element.

#### Form

#### **PSpice**Form

 $\begin{array}{l} \texttt{Gname } N_+ \ N_- \ N_{C+} \ N_{C-} \ Transconductance \\ \texttt{Gname } N_+ \ N_- \ \texttt{POLY}(\ D\ ) \ (N_{C1+} \ N_{C1-}) \ \dots \ (N_{CD+} \ N_{CD-}) \ PolynomialCoefficients \\ \texttt{Gname } N_+ \ N_- \ \texttt{VALUE} = \left\{ \ Expression \right\} \\ \texttt{Gname } N_+ \ N_- \ \texttt{TABLE} \ \left\{ \ Expression \right\} = ( \ TableInput \ , \ TableOutput \ ) \ \dots \\ \texttt{Gname } N_+ \ N_- \ \texttt{LAPLACE} \ \left\{ \ Expression \right\} = \left\{ \ TransformExpression \right\} \\ \texttt{Gname } N_+ \ N_- \ \texttt{FREQ} \ \left\{ \ Expression \right\} = ( \ Frequency, \ Magnitude, \ Phase \ ) \ \dots \\ \texttt{Gname } N_+ \ N_- \ \texttt{CHEBYSHEV} \ \left\{ \ Expression \right\} = Type, \ CutoffFrequency \ \dots \ , \ Phase \ \dots \end{array}$ 

- $N_+$  is the positive voltage source node.
- $N_{-}$  is the negative voltage source node.
- $N_{C+}$  is the positive controlling node.
- $N_{C-}$  is the negative controlling node.

Transconductance is the transconductance.

- POLY is the identifier for the polynomial form of the element
  - D is the degree of the poynomial. The number of pairs of controlling nodes must be equal to *Degree*.
- $N_{Ci+}$  the positive node of the *i* th controlling node pair.
- $N_{Ci-}$  the negative node of the *i* th controlling node pair.
- *PolynomialCoefficients* is the set of polynomial coefficients which must be specified in the standard polynomial coefficient format discussed on page 47.

VALUE is the identifier for the value form of the element.

*Expression* This is an expression of the form discussed on page 47.

TABLE is the identifier for the <u>table form</u> of the element.

- TableInput This is the independent input of the table. See the TABLE parameter above.
- TableInput This is the dependent output of the table. See the TABLE parameter above.

LAPLACE is the identifier for the laplace form of the element.

#### Transform Expression

FREQ is the identifier for the frequency form of the element.

Frequency

Magnitude

Phase

CHEBYSHEV is the identifier for the chebyshev form of the element.

Type

#### CutoffFrequency

Phase

#### Example

G1 2 3 14 1 2.0

#### Note

1. Several form of the voltage-controlled voltage source element are supported in addition to the Linear Transconductance form which is the default. The other forms are selected based on the the identifier POLY, VALUE, TABLE, LAPLACE, FREQ or CHEBYSHEV.

Linear Transconductance Instance

Gname  $N_+$   $N_ N_{C+}$   $N_{C-}$  Transconductance

The value of the voltage generator is linearly proportional to the controlling voltage:

$$v_o = Transconductance \, v_c \tag{7.198}$$

POLYnomial Instance

Gname 
$$N_+ N_-$$
 POLY(D) ( $N_{C1+} N_{C1-}$ ) ... ( $N_{CD+} N_{CD-}$ ) PolynomialCoefficients

The value of the voltage generator is a polynomial function of the controlling voltages:

$$v_o = f(v_{c1}, \dots, v_{ci}, \dots v_{cD}) \tag{7.199}$$

where the number of controlling voltages is D — the degree of the polynomial specified on the element line.  $v_{ci}$  is the *i*th controlling voltage and is the voltage of the  $n_{ci+}$  node with respect to the  $n_{ci+}$  node.

VALUE Instance — PSPICE92 only

Gname  $N_+$   $N_-$  VALUE= { Expression }

The value of the voltage generator is the resultant of an expression evaluation.

$$v_o = f(v_c) \tag{7.200}$$

<u>TABLE Instance</u> — PSPICE92 only

Gname  $N_+ N_-$  TABLE { Expression }=( TableInput , TableOutput ) ...

$$v_o = f(v_c) \tag{7.201}$$

#### LAPLACE Instance — PSPICE92 only

Gname  $N_+ N_-$  LAPLACE { Expression }={ TransformExpression }

$$v_o = f(v_c) \tag{7.202}$$

FREQ - PSPICE92 only

Gname  $N_+ N_-$  FREQ { Expression }=( Frequency, Magnitude, Phase ) ...

$$v_o = f(v_c) \tag{7.203}$$

 $\underline{\texttt{CHEBYSHEV}} - \underline{\texttt{PSpice92}} \text{ only}$ 

Gname  $N_+$   $N_-$  CHEBYSHEV { Expression }= Type, CutoffFrequency  $\ldots$  , Phase  $\ldots$ 

# Current-Controlled Voltage Source



Figure 7.31: H — current-controlled voltage source element.

#### Form

Hname  $N_+$   $N_-$  VoltageSourceName Transresistance Hname  $N_+$   $N_-$  POLY( D ) VoltageSourceName\_1  $\ldots$  VoltageSourceName\_D PolynomialCoefficients

 $N_+$  is the positive voltage source node.

 $N_{-}$  is the negative voltage source node.

VoltageSourceName is the name of the voltage source the current through which is the controlling current. The voltage source must be a V element.

Transresistance is the Transresistance of the element.

- POLY is the identifier for the polynomial form of the element
  - D is the degree of the poynomial. The number of pairs of controlling nodes must be equal to *Degree*.

 $VoltageSourceName_i$  is the name of the voltage source the current through which is the *i*th controlling current. The voltage source must be a V element.

*PolynomialCoefficients* is the set of polynomial coefficients which must be specified in the standard polynomial coefficient format discussed on page 47.

#### Example

E1 2 3 14 1 2.0

Linear Transresistance Instance

Hname  $N_+$   $N_ N_{C+}$   $N_{C-}$  Transresistance

The value of the voltage generator is linearly proportional to the controlling current:

$$v_o = Transresistance \, v_c \tag{7.204}$$

POLYnomial Instance

# Η

Hname  $N_+ N_-$  POLY(D) ( $N_{C1+} N_{C1-}$ ) ... ( $N_{CD+} N_{CD-}$ ) PolynomialCoefficients

The value of the voltage generator is a polynomial function of the controlling voltages:

$$v_o = f(i_{c1}, \dots, i_{ci}, \dots i_{cD}) \tag{7.205}$$

where the number of controlling currents is D — the degree of the polynomial specified on the element line.  $i_{ci}$  is the *i*th controlling current and is the current flowing from the + terminal to the – terminal in the *i*th voltage source of name *VoltageSourceName*.




Figure 7.32: I — independent current source.

## Form

Ι

Iname N<sub>+</sub> N<sub>-</sub> [ [DC] [DCvalue] + [AC [ACmagnitude [ACphase] ] ] + [DISTOF1 [F1Magnitude [F1Phase] ] ] + [DISTOF2 [F2Magnitude [F2Phase] ] ]

# SPICE3Form

PSPICEForm

```
Iname N_+ N_- [ [DC] [DCvalue] [AC [ACmagnitude [ACphase] ]]
```

+ [TransientSpecification]

# Example

IBIAS 1 0 1.0M ICLOCK 20 5 PULSE(OM 10M 1N 2N 1.5N 21.9N 5N 20N) ISSIGNAL AC 1U 90

- $N_+$  is the positive current source node. (Current flow is out of the positive to the negative node
- $N_{-}$  is the negative current source node.
- DC is the optional keyword for the DC value of the source.
- DCvalue is the DC current value of the source. (Units: A; Optional; Default: 0; Symbol:  $I_{DC}$ )
  - AC is the keyword for the AC value of the source.
- ACmagnitude is the AC magnitude of the source used during ACanalysis. That is, it is the peak AC current so that the AC signal is  $ACmagnitude \sin(\omega t + \text{ACphase})$ . ACmagnitude is ignored for other types of analyses. (Units: A; Optional; Default: 1; Symbol:  $I_{AC}$ )
  - ACphase is the ac phase of the source. It is used only in AC analysis. (Units: Degrees; Optional; Default: 0; Symbol:  $\phi_{AC}$ )
  - DISTOF1 is the distortion keyword for distortion component 1 which has frequency F1. (see the description of the .DISTO statement on page 58).
- F1magnitude is the magnitude of the distortion component at F1. See .DISTOF1 keyword above. (Units: A; Optional; Default: 1; Symbol:  $I_{F1}$ )
  - *F1phase* is the phase of the distortion component at F1. See .DISTOF1 keyword above. (Units: Degrees; Optional; Default: 0; Symbol:  $\phi_{F1}$ )
  - DISTOF2 is the distortion keyword for distortion component 2 which has frequency F2. (see the description of the .DISTO statement on page 58).
- F2magnitude is the magnitude of the distortion component at F2. See .DISTOF2 keyword above. (Units: A; Optional; Default: 1; Symbol:  $I_{F2}$ )
  - *F2phase* is the phase of the distortion component at F2. See .DISTOF2 keyword above. (Units: Degrees; Optional; Default: 0; Symbol:  $\phi_{F2}$ )

TransientSpecification is the optional transient specification described more fully below.

#### Note

- 1. The independent current source has three different sets of parameters to describe the source for DC analysis (see .DC on page 55), AC analysis (see .AC on page 53), and transient analysis (see .TRAN on page 109). The DC value of the source is used during bias point evaluation and DC analysis is *DCValue*. It is also the constant value of the current source if no *TransientSpecification* is supplied. It may also be used in conjunction with the PWL transient specification if a time zero value is not provided as part of the transient specification. The AC specification, indicated by the keyword AC is independent of the DC parameters and the *Transient Specification*.
- 2. The original documentation distributed with SPICE2G6 and SPICE3 incorrectly stated that if a *TransientSpecification* was supplied then the time-zero transient current was used in DC analysis and in determiniong the operating point.

# **Transient Specification**

#### Independent Current Source

Five transient specification forms are supported: pulse (PULSE), exponential (EXP), sinusoidal (SIN), piece-wise linear (PWL), and single-frequency FM (SFFM). The default values of some of the parameters of these transient specifications include TSTEP which is the printing increment and TSTOP which is the final time (see the .TRAN statement on page 109 for further explanation of these quantities). In the following t is the transient analysis time. **Exponential:** 

Form

EXP( $I_1 I_2 [T_{D1}] [\tau_1] [T_{D2}] [\tau_2]$ )								
Name	Description	Units	Default					
$I_1$	initial current	А	REQUIRED					
$I_2$	pulsed current	А	REQUIRED					
$T_{D1}$	rise delay time	S	0.0					
$ au_1$	rise time constant	S	TSTEP					
$T_{D2}$	fall delay time	S	$T_{D1} +$					
			TSTEP					
$ au_2$	fall time constant	S	TSTEP					

The exponential transient is a single-shot event specifying two exponentials. The current is  $I_1$  for the first  $T_{D1}$  seconds at which it begins increasing exponentially towards  $I_2$  with a time constant of  $\tau_1$  seconds. At time  $T_{D2}$  the current exponentially decays towards  $I_1$  with a time constant of  $\tau_2$ . That is,



Figure 7.33: Current source exponential (EXP) waveform for EXP(0.1 0.8 1 0.35 2 1)

# Single-Frequency FM:

Form

SFFM(  $V_O~V_A~F_C~\mu~F_S$  )

Name	Description	Units	Default
$I_O$	offset current	A	
$I_A$	peak amplitude of AC current	A	
$F_C$	carrier frequency	Hz	1/TSTOP
$\mu$	modulation index	-	0
$F_S$	signal frequency	Hz	1/TSTOP

The single frequency frequency modulated transient response is described by

$$i = I_O + I_A \sin(2\pi F_C t + \mu \sin(2\pi F_S t))$$
(7.207)



Figure 7.34: Current source single frequency frequency modulation (SFFM) waveform for SFFM(0.2 0.7 4 0.9 1)

# Pulse:

Form

PULSE(  $V_1 V_2 [T_D] [T_R] [T_F] [W] [T]$ )

Name	Description	Units	Default
$I_1$	initial current	А	REQUIRED
$I_2$	pulsed current	А	REQUIRED
$T_D$	delay time	S	0.0
$T_R$	rise time	S	TSTEP
$T_F$	fall time	S	TSTEP
W	pulse width	S	TSTOP
Т	period	S	TSTOP

The pulse transient waveform is defined by

$$i = \begin{cases} I_1 & t \leq T_D \\ I_1 + \frac{t'}{T_R} (I_2 - I_1) & 0 < t' \leq T_R \\ I_2 & T_R < t' < (T_R + W) \\ I_2 - \frac{t' - W}{T_F} (I_1 - I_2) & (T_R + W) < t' < (T_R + W + T_F) \\ I_1 & (T_R + W + T_F) < t' < T \end{cases}$$
(7.208)

where

$$t' = t - T_D - (n-1)T \tag{7.209}$$

and t is the current analysis time and n is the cycle index. The effect of this is that after an initial time delay  $T_D$  the transient waveform repeats itself every cycle.



Figure 7.35: Current source transient pulse (PULSE) waveform for PULSE(0.3 1.8 1 2.5 0.3 1 0.7)

## **Piece-Wise Linear:**

Form

PWL(  $T_1 \ I_1 \ [T_2 \ I_2 \ \dots \ T_i \ I_i \ \dots \ T_N \ ]$  )

Each pair of values  $(T_i, I_i)$  specifies that the value of the source is  $I_i$  at time  $= T_i$ . At times between  $T_i$  and  $T_{i+1}$  the values are linearly interpolated. If  $T_1 > 0$  then the current is constant at *DCValue* (specified on the element line) until time  $T_1$ .

$$i = \begin{cases} DCvalue & t < T_1 \\ I_i & t = T_i \\ I_{i+1} & t = T_{i+1} \\ I_i + \left(\frac{t-T_i}{T_{i+1}-T_i}\right) (I_{i+1} - I_i) & T_i < t \le T_{i+1} \\ I_N & t > T_N \end{cases}$$
(7.210)



Figure 7.36: Current source transient piece-wise linear (PWL) waveform for PWL(1 0.25 1 1 2 0.5  $\dots$  3 0.5 4 1  $\dots$  4.5 1.25  $\dots$ ) with DCValue = 0.25.

# Sinusoidal:

# Form

SIN( V <sub>O</sub> V <sub>A</sub>	[F]	$[T_D]$	[ heta ] )

**PSpice**Form

 $SIN(V_O V_A [F] [T_D] [\theta \phi])$ 

#### PSPICEForm

 $SIN(V_O V_A [F] [T_D] [\theta \phi])$ 

Name	Description	Units	Default
$I_O$	current offset	А	REQUIRED
$I_A$	current amplitude	A	REQUIRED
F	frequency	Hz	1/TSTOP
$T_D$	time delay	S	0
Θ	damping factor	1/s	0
$\phi$	phase	degree	0

The sinusoidal transient waveform is defined by

$$i = \begin{cases} I_0 & t \le T_D \\ I_0 + I_1 e^{-[(t - T_D)\Theta]} \sin 2\pi [F(t - T_D) + \phi/360] & t > T_D \end{cases}$$
(7.211)



Figure 7.37: Current source transient sine (SIN) waveform for SIN(0.1 0.8 2 1 0.3 ).

# Junction Field-Effect Transistor



Figure 7.38: J — Junction field effect transistor element: (a) n channel JFET; (b) p channel JFET.

#### Form

Jname NDrain NGate NSource ModelName [Area] [OFF]  $[IC=V_{DS}, V_{GS}]$ 

#### PSPICEForm

Jname NDrain NGate NSource ModelName [Area]

#### Example

J1 7 2 3 JM1 OFF

- NDrain is the drain node
- NGate is the gate node
- NSource is the source node
- ModelName is the model name
  - Area is the area factor. (Units: none; Optional; Default: 1; Symbol: Area)
  - **DFF** indicates an (optional) initial condition on the device for **DC** operating point analysis. If specified the **DC** operating point is calculated with the terminal voltages set to zero. Once convergence is obtained, the program continues to iterate to obtain the exact value of the terminal voltages. The OFF option is used to enforce the solution to correspond to a desired state if the circuit has more than one stable state.
  - IC is the optional initial condition specification. Using  $IC=V_{DS}$ ,  $V_{GS}$  is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired starting from other than the quiescent operating point. Specification of the transient initial conditions using the .IC statement (see page 66) is preferred and is more convenient.

NJF Model

N-Channel JFET Model

J

# PJF Model



Figure 7.39: Schematic of the JFET model.  $V_{GS}$ ,  $V_{DS}$ , and  $V_{GD}$  are intrinsic gate-source, drain-source and gate-drain voltages between the internal gate, drain, and source terminals designated G, D, and Crespectively.

The parameters of the *n*-channel (NJF) and of the *p*-channel (PJF) models are the same and are given in table 7.6.

The parameters of the JFET can be completely specified in the model *ModelName*. This facilitates the use of standard transistors by using absolute quantities in the model. Alternatively scalable process parameters can be specified in the model *ModelName* and these scaled by the *Area* parameter on the JFET element line. The parameters that can be scaled by *Area* are BETA, CGS, CGD, IS, RD and RS.

The physical constants used in the model evaluation are

k	Boltzman's constant	$1.3806226  10^{-23}  \mathrm{J/K}$
q	electronic charge	$1.6021918  10^{-19} \mathrm{C}$

# Standard Calculations

Absolute temperatures (in kelvins, K) are used. The thermal voltage

$$V_{\rm TH} = \frac{kT_{\rm NOM}}{q}.$$
(7.212)

The silicon bandgap energy

$$E_G = 1.16 - 0.000702 \frac{4T_{\rm NOM}^2}{T_{\rm NOM} + 1108}.$$
(7.213)

Temperature Dependence

Table 7.6:	NJF	and	PJF	model	keywor	ds for	the	junction	field	effect	transisto	r. The	Area	column	indicates
parameter	s that	t are	scale	ed by A	Area.										

Name	Description		Units	Default	Area
AF	flicker noise exponent	$(A_F)$	-	1	
BETA	transconductance parameter	$(\beta)$	$A/V^2$	1.0E-4	*
CGS	zero-bias G-S junction capacitance per unit area	F	0	*	
CGD	zero-bias G-D junction capacitance per unit area	$(C_{GD}')$	F	0	*
FC	coefficient for forward-bias depletion		-	0.5	
	capacitance formula	$(F_C)$			
IS	gate junction saturation current	$(I_S)$	А	1.0E-14	*
KF	flicker noise coefficient	$(K_F)$	-	0	
LAMBDA	channel length modulation parameter	$(\lambda)$	1/V	0	
PB	gate junction potential	$(\phi_J)$	V	1	
RD	drain ohmic sheet resistance	$(R_D)$	Ω	0	*
RS	source ohmic sheet resistance	$(R_S)$	Ω	0	*
VTO	threshold voltage (VT-oh)	$(V_{T0})$	V	-2.0	
	VTO $<$ 0 indicates a depletion mode JFET				
	VTO $\geq$ 0 indicates an enhancement mode JFET				
BETATC	temperature coefficient of the transconductance	parameter	%/°C	0	
	BETA	$(T_{C,\beta})$			
М	gate $p$ - $n$ junction grading coefficient	( <i>M</i> )	-	0.5	
VTOTC	temperature coefficient of threshold voltage VTO	$(T_{C,VT0})$	V/°C	0	

Temperature effects are incorporated as follows where T and  $T_{\text{NOM}}$  are absolute temperatures in Kelvins (K).

$$V_{\rm TH} = \frac{kT}{q} \tag{7.214}$$

$$I_{S}(T) = I_{S}e^{\left(E_{g}(T)\frac{T}{T_{\text{NOM}}} - E_{G}(T)\right)/(nV_{\text{TH}})}$$
(7.215)

$$V_{BI}(T) = V_{BI} \frac{T}{T_{\text{NOM}}} - 3V_{\text{TH}} \ln \frac{T}{T_{\text{NOM}}} + E_G(T_{\text{NOM}}) \frac{T}{T_{\text{NOM}}} - E_G(T)$$
(7.216)

$$C'_{GS}(T) = C'_{GS}\{1 + M[0.0004(T - T_{\text{NOM}}) + (1 - V_{BI}(T)/V_{BI})]\}$$
(7.217)

$$C'_{GD}(T) = C'_{GD} \{ 1 + M[0.0004(T - T_{\text{NOM}}) + (1 - V_{BI}(T)/V_{BI})] \}$$
(7.218)

$$\beta(T) = \beta 1.01^{T_{C,\beta}(T-T_{\text{NOM}})}$$
(7.219)

$$V_{T0}(T) = V_{T0} + T_{C,VT0} \left( T - T_{\text{NOM}} \right)$$
(7.220)

# Parasitic Resistances

The parasitic resistances are calculated from the sheet resistivities RS, RG, RD, and the *Area* specified on the element line.

$$R_S = R'_S Area \tag{7.221}$$

$$R_G = R'_G Area \tag{7.222}$$

$$R_D = R'_D Area \tag{7.223}$$

The parasitic resistance parameter dependencies are summarized in figure 7.40.

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PROCESS	+	GEO	METRY	$\rightarrow$		DEVICE
PARAMETERS		PARA	METERS			PARAMETERS
RSH $R_{\rm SH}$		NRS	$N_{RS}$		RD	$R_D = f(R_{\rm SH}, N_{RD})$
	, ,	NRD	$N_{RD}$		RS	$R_S = f(R_{\rm SH}, N_{RS})$
		NRG	$N_{RG}$		RG	$R_B = f(R_{\rm SH}, N_{RG})$
		NRB	$N_{RB}$		RB	$R_B = f(R_{\rm SH}, N_{RB})$

Figure 7.40: JFET parasitic resistance parameter relationships.

# Leakage Currents

Current flows across the normally reverse biased source-bulk and drain-bulk junctions. The gate-source leakage current

$$I_{GS} = Area \, I_S e^{(V_{GS}/V_{\rm TH} - 1)} \tag{7.224}$$

and the gate-source leakage current

$$I_{GD} = Area I_{Se} (V_{GD} / V_{TH} - 1)$$
(7.225)

The dependencies of the parameters describing the leakage current in the JFET model are summarized in figure 7.41.



Figure 7.41: JFET leakage current parameter dependecies.

# I/V Characteristics

The current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point.

Normal Mode:  $(V_{DS} \ge 0)$ 

The regions are as follows:

cutoff region:	$V_{GS} < V_{T0}$
linear region:	$V_{GS} \ge V_{T0}$ and $V_{GS} > V_{DS} + V_{T0}$
saturation region:	$V_{GS} \ge V_{T0}$ and $V_{GS} \le V_{DS} + V_{T0}$

Then

$$I_{D} = \begin{cases} 0 & \text{cutoff region} \\ Area \beta (1 + \lambda V_{DS}) V_{DS} [2 (V_{GS} - V_{T0}) - V_{DS}] & \text{linear region} \\ Area \beta (1 + \lambda V_{DS}) (V_{GS} - V_{T0})^{2} & \text{saturation region} \end{cases}$$
(7.226)

Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the JFET I/V characteristics are evaluated as in the normal mode (7.226) but with the drain and source subscripts exchanged. The relationships of the parameters describing the I/V characteristics are summarized in figure 7.42.

$$\begin{array}{c|c} PROCESS \\ PARAMETERS \\ \hline ALPHA & \alpha \\ BETA & \beta \\ LAMBDA & \lambda \\ VTO & V_{T0} \end{array} \end{array} + \begin{array}{c} GEOMETRY \\ PARAMETERS \\ \hline \\ Optional \\ \hline \\ Area \end{array} \rightarrow \begin{array}{c} DEVICE \\ PARAMETERS \\ \hline \\ I_D = f(Area, \beta, \lambda, V_{T0}, \alpha) \} \end{array}$$

Figure 7.42: I/V dependencies.

Capacitances

The drain-source capacitance

$$C_{DS} = Area \, C'_{DS} \tag{7.227}$$

The gate-source capacitance

$$C_{GS} = \begin{cases} Area C'_{GS} \left(1 - \frac{V_{GS}}{\phi_J}\right)^{-M} & V_{GS} \le F_C \phi_J \\ Area C'_{GS} \left(1 - F_C\right)^{-(1+M)} \left[1 - F_C (1+M) + M \frac{V_{GS}}{\phi_J}\right]^{-M} & V_{GS} > F_C \phi_J \end{cases}$$
(7.228)

models charge storage at the gate-source depletion layer. The gate-drain capacitance

$$C_{GD} = \begin{cases} Area \, C'_{GD} \left(1 - \frac{V_{GD}}{\phi_J}\right)^{-M} & V_{GD} \leq F_C \phi_J \\ Area \, C'_{GD} \left(1 - F_C\right)^{-(1+M)} \left[1 - F_C (1+M) + M \frac{V_{GD}}{\phi_J}\right]^{-M} & V_{GD} > F_C \phi_J \end{cases}$$
(7.229)

models charge storage at the gate-drain depletion layer. The capacitance parameter dependencies are summarized in figure 7.43.

# AC Analysis

The AC analysis uses the model of figure 7.46 with the capacitor values evaluated at the DC operating point with

$$g_m = \frac{\partial I_{DS}}{\partial V_{GS}} \tag{7.230}$$

and

$$R_{DS} = \frac{\partial I_{DS}}{\partial V_{DS}} \tag{7.231}$$

Noise Analysis

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#### Junction Field-Effect Transistor

The JFET noise model accounts for thermal noise generated in the parasitic resistances and shot and flicker noise generated in the drain source current generator. The rms (root-mean-square) values of thermal noise current generators shunting the four parasitic resistance  $R_D$ ,  $R_G$  and  $R_S$  are

$$I_{n,D} = \sqrt{4kT/R_D} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.232}$$

$$I_{n,S} = \sqrt{4kT/R_S} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.233}$$

Shot and flicker noise are modeled by a noise current generator in series with the drain-source current generator. The rms value of this noise generator is

$$I_{n,DS} = \left(I_{\text{SHOT},DS}^2 + I_{\text{FLICKER},DS}^2\right) \tag{7.234}$$

$$I_{\text{SHOT},DS} = \sqrt{4kTg_m \frac{2}{3}} \quad A/\sqrt{\text{Hz}} \quad A/\sqrt{\text{Hz}}$$
(7.235)

$$I_{\text{FLICKER},DS} = \sqrt{\frac{K_F I_{DS}^{A_F}}{f}} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.236)

where the transconductance

$$g_m = \frac{\partial I_{DS}}{\partial V_{GS}} \tag{7.237}$$

is evaluated at the DC operating point, and f is the analysis frequency.



Figure 7.43: JFET capacitance dependencies.

# Mutual Inductor



Figure 7.44: K — Mutual inductor element.

# Form

Kname Lname1 Lname2 CouplingValue

# PSPICEForm

Kname	Lname1 Lname2 [ LnameN ] CouplingValue
Kname	Lname1 [Lname2 LnameN ] CouplingValue [ [ModelName [size ] ]
Lname1	is the name of the first inductor of the coupled inductor list. The first node of Lname1 is dotted using the dot convention. In the mutual coupled inductor model (the default model) the value of Lname1 is the self inductance $L_1$ . In the transformer CORE model (which is used if a <i>ModelName</i> is supplied) the value of Lname1 is the number of turns $N_1$ . (Note, <i>ModelName</i> can not be specified with the SPICE2G6 and SPICE3 simulators.) (Required)
Lname2	is the name of the second inductor in the coupled inductor list. The first node of Lname1 is dotted using the dot convention. In the mutual coupled inductor model the value of Lname1 is the self inductance $L_2$ . In the transformer CORE model (which is used if a ModelName is supplied the value of Lname2 is the number of turns $N_2$ . (SPICE2G6 and SPICE3: Required.) (PSPICE: Required if Modelname not supplied; Optional if Modelname supplied.)
LnameN	is the name of Nth inductor in the coupled inductor list. The first node of LnameN is dotted using the dot convention. In the mutual inductor model the value of LnameN is the self inductance $L_N$ . In the transformer CORE model (which is used if a ModelName is supplied the value of Lname2 is the number of turns $N_N$ . Not valid in SPICE2G6 or SPICE3 for $N > 2$ . (PSPICE: Optional if Modelname supplied.)
Coupling Value	is the coefficient of mutual coupling of the inductors. (Units: none; Required; Symbol: $K_{\text{COUPLING}}$ ; $0 < K_{\text{COUPLING}} \leq 1$ )
ModelName	is the optional model name. PSPICE only.
Size	is the size scaling factor. It scales the magnetic cross-section and represents the number of lamination layers. (Units: none; Optional; Default: 1; Symbol: <i>Size</i> )

Example

К

K43 LAA LBB 0.999 KXFRMR L1 L2 0.87

## $PSpice \ Example$

KTFMR LAA LBB LCC LDD TRANSFORMER 2.5

Model Type

IND

 $\mathbf{PSPICE}$  only

#### Note

1. The mutual coupled inductor model represents coupled inductors by self inductances  $L_i$  and mutual inductances  $M_{ij}$ . This is the model used in SPICE2G6 and spicthree and in PSPICE if a CORE model is not supplied. Here  $L_i$  is the self inductance of the *i*th inductor element and  $M_{ij}$  is the mutual inductance of the *i*th and *j*th inductor elements. The mathematical model of the coupled element consists of voltage sources controlled by the time derivatives of current. If two inductors are coupled

$$V_1 = L_1 \frac{dI_1}{dt} + M_{12} + \frac{dI_2}{dt}$$
(7.238)

and

$$V_2 = L_2 \frac{dI_2}{dt} + M_{21} + \frac{dI_1}{dt}$$
(7.239)

If N inductors are coupled, as supported in PSPICE, the mathematical model is

Note

$$V_{i} = L_{i}\frac{dI_{i}}{dt} + \sum_{\substack{j=1\\ i\neq i}}^{N} M_{ij}\frac{dI_{j}}{dt}$$

$$(7.240)$$

2 The mutual inductance  $M_{ij}$  is determined from the self-inductances  $L_i$  and  $L_j$  of the inductors and the coupling coefficient  $K_{\text{COUPLING}}$  supplied as an element parameter by

$$K_{\rm COUPLING} = \sqrt{\frac{M_{ij}}{L_i L_j}} \tag{7.241}$$

 $K_{\text{COUPLING}}$  may have any value between 0 and 1 including 1. Ferrite core provides almost ideal coupling with K = 0.999 or higher.

3 In SPICE2G6 and SPICE3 a transformer with several coils must be represented by several K elements. For example, a transformer with one primary and two secondaries is specified as \* PRIMARY

L1 1 2 100U \* FIRST SECONDARY L2 3 4 100U \* SECOND SECONDARY L3 5 6 100U \* TRANSFORMER K1 L1 L2 0.999 K2 L1 L3 0.999 K2 L2 L3 0.999

4 In PSPICE the transformer above can be either represented using the SPICE2G6 and SPICE3 format above or by the more compact format

\* PRIMARY L1 1 2 100U \* FIRST SECONDARY L2 3 4 100U \* SECOND SECONDARY L3 5 6 100U \* TRANSFORMER K1 L1 L2 L3 0.999

```
CORE ModelPSPICE OnlyMagnetic Core Model
```

Form

.MODEL ModelName CORE( [[keyword = value] ... ])

#### Example

.MODEL TRANSFORMER CORE(AREA=1 PATH=9.8 GAP=0.1 MS=1.250M)

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Name	Description		Units	Default
А	shape parameter	(A)	A/M	$10^{3}$
ALPHA	$(\alpha)$ interdomain coupling p	arameter	-	0.001
AREA	mean magnetic crossection	$\rm cm^2$	0.1	
GAMMA	domain damping parameter.	-	$\infty$	
C	domain flexing parameter	-	0.2	
GAP	effective air-gap length	cm	0	
К	domain anisotopy parameter (pinning constant) $(K)$		A/M	500
MS	magnetization saturation $(M_S)$		A/M	$10^{6}$
PACK	pack (stacking) factor	$(F_{\rm PACK})$	cm	0
PATH	mean magnetic path length in the core	$(L_{\rm PATH})$	cm	1

Table 7.7: Model parameters.

The CORE model models a transformer core. It is assumed that the model parameters were determined or measured at the nominal temperature  $T_{\text{NOM}}$  (default 27°C) specified in the most recent .OPTIONS statement preceeding the .MODEL statement.

The CORE model uses the Jiles-Atherton model described in [25]. This model is based on domain wall motion and includes flexing of the domain wall, interdomain coupling, coercivity, remanence and magnetic saturation. Hysteresis due to domain wall pinning at defect sites is modeled. This impedance to domain wall motion dominates the characteristics of magnetic devices.

As with the default mutually coupled inductor model, the CORE model calculates the voltage across the *i*th set of windings from the total ampere turns which is the magnetomotive force MMF. Thus

$$V_i = \frac{d\phi_i}{dt} = f(MMF) \tag{7.242}$$

where

$$MMF = \sum_{j=1}^{N} N_j I_j \tag{7.243}$$

Here the number of turns of the *j*th winding,  $N_j$ , is the "Inductance Value" of  $L_j$  the name of which is the *j*th Lname given on the K element line.  $I_i$  is the current flowing through the *i*th winding.  $A_{\text{TURNS}}$  produces the magnetic field  $H_{\text{CORE}}$  in the core. This in turn produces the *B* field. The *B* field is proportional to the flux, in the core and hence to the voltage  $V_i$ . The relationship between *B* and *H* in the core is nonlinear and hysteretic. The airgap also affects the B-H relationship.

#### Air-Gap Effect

Along the complete magnetic path

$$H_{\rm CORE}L_{\rm PATH} + H_{\rm GAP}L_{\rm GAP} = MMF \tag{7.244}$$

where  $H_{\text{CORE}}$  is the magnetic field in the core and  $H_{\text{GAP}}$  is the magnetic field in the air gap.  $L_{\text{PATH}}$  and  $L_{\text{GAP}}$  are the model parameters PATH and GAP. If the air gap is small then all of the flux in the core passes through the air gap so that  $B_{\text{GAP}} = B_{\text{CORE}}$ . In the air-gap the magnetization is negligible so that  $B_{\text{GAP}} = H_{\text{GAP}}$ 

This leads to a relationship between the B and H fields in the core:

$$H_{\rm CORE}L_{\rm PATH} + B_{\rm CORE}L_{\rm GAP} = MMF \tag{7.245}$$

It is a simple matter to solve for  $B_{\text{CORE}}$  and  $H_{\text{CORE}}$  if  $L_{\text{GAP}} = 0$  as then

$$H_{\rm CORE} = \frac{MMF}{L_{\rm PATH}} \tag{7.246}$$

If  $L_{\text{GAP}} > 0$  then (7.245) must be solved in conjunction with the relationship between  $H_{\text{CORE}}$  and magnetization M in the core. This relationship is based on the theory of loosely coupled domains developed by Jiles and Atherton.

Jiles-Atherton Model

The B-H curve of a magnetic material biased by AC and DC magnetic fields is called the anhysteric and is mathematically described by the Jiles-Atherton model. This model determines an anhysteric magnetization  $M_{\rm AN}$  which is related to the saturation magnetization  $M_S$  by

$$M_{\rm AN} = M_S \left[ \coth\left(\frac{H_{\rm EFF}}{Size\,A}\right) - \frac{Size\,A}{H_{\rm EFF}} \right]$$
(7.247)

where A is the shape parameter and the effective field in the core

$$H_{\rm EFF} = H_{\rm CORE} + \alpha M_{\rm AN} \tag{7.248}$$

Here H is the magnetizing influence. Domain wall flux is magnetic current which is proportional to the change in magnetization. The change in magnetization consists of a reversible component due to flexing of the domain walls and an irreversible component due to movement of domain walls from one pinning location to another. Energy is dissipated (hence the motion is irreversible) in moving the domain wall from one pinning location to another but energy is stored (hence reversible) when the domain wall flexs. This is mathematicly modeled by

$$\frac{dM}{dH_{\rm CORE}} = \left(\frac{dM}{dH_{\rm CORE}}\right)_{\rm REVERSIBLE} + \left(\frac{dM}{dH_{\rm CORE}}\right)_{\rm IRREVERSIBLE}$$
(7.249)

where the reversible component

$$\left(\frac{dM}{dH_{\rm CORE}}\right)_{\rm REVERSIBLE} = C \frac{d(M_{\rm AN} - M)}{dH}$$
(7.250)

and the irreversible component

$$\left(\frac{dM}{dH_{\rm CORE}}\right)_{\rm IRREVERSIBLE} = \frac{M_{\rm AN} - M}{K}$$
(7.251)

where K is the pinning energy per volume and is akin to mechanical drag. M and  $H_{\text{CORE}}$  are found by solving (7.249) and (7.245) simultaneously.

The small signal relative permeability of the core is

$$\mu_r = \left\{ \left[ \left( \frac{dM}{dH_{\text{CORE}}} + 1 \right) F_{\text{PACK}} \right]^{-1} + \frac{L_{\text{GAP}}}{L_{\text{PATH}}} \right\}^{-1}$$
(7.252)

and the flux passing through the ith winding is

$$\phi_i = \mu_0 (M + H_{\text{CORE}}) N_i F_{\text{PACK}} Size Area \tag{7.253}$$

The voltage across the *i*th winding is then found as

$$V_i = \frac{d\phi_i}{dt} \tag{7.254}$$

AC Analysis

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# $Mutual \ Inductor$

For AC analysis the mutual inductor model is used even if a CORE model is specified. This allows a different coefficient of mutual coupling to be used in AC analysis than would otherwise be determined by nonlinear model evaluation.

# Noise Analysis

The K element does not contribute to noise.

# L

# Inductor

$$n_1 \longrightarrow m_2$$
  
 $I_L L$ 

	Figure	7.45:	L —	Inductor	element.
--	--------	-------	-----	----------	----------

Form

Lname  $N_1 N_2$  Inductor Value [IC= $I_L$ ]

#### PSPICEForm

Lname  $N_1 N_2$  [ModelName] InductorValue [IC= $I_L$ ]

- $N_1$  is the positive element node,
- $N_2$  is the negative element node, and

*ModelName* is the optional model name.

InductorValue is the inductance. (Units: H; Required; Symbol: InductorValue)

IC is the optional initial condition specification Using  $IC=I_L$  is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired with an initial current  $I_L$  through the inductor rather than the quiescent operating current. Specification of the transient initial conditions using the .IC statement (see page 66) is preferred and is more convenient.

#### Example

IND1 1 2 1.3N IND1 1 2 1.3NH IC=1M

Model Type

IND

IND Model

**PSPICE** Only

Inductor Model

PSPICE only

#### Form

٧D

.MODEL ModelName IND( [[keyword = value] ...])

#### Example

.MODEL SMALLIND IND(L=4.5 IL1=0.1 IL2 = 0.01 TC1=0.01 TC2=0.001)

# Inductor

## Model Keywords

Name	Description		Units	Default
L	inductance multiplier (1	L <sub>MULTIPLIER</sub> )	-	1
IL1	linear current coefficient	$(I_{C1})$	1/A	0
IL2	quadratic current coefficient	$(I_{C2})$	1/A	0
TC1	linear temperature coefficient	$(T_{C1})$	$1/^{\circ}C$	0
TC2	quadratic temperature coefficient	$(T_{C1})$	$^{\circ}C^{-2}$	0

The PSPICE inductance model is a nonlinear temperature dependent inductor model. It is assumed that the model parameters were determined or measured at the nominal temperature  $T_{\text{NOM}}$  (default 27°C) specified in the most recent .OPTIONS statement preceding the .MODEL statement.

The inductance is

$$L = InductorValue L_{MULTIPLIER} \left[ 1 + I_{L1}I_L + I_{L2}I_L^2 \right] \\ \times \left[ 1 + T_{C1}(T - T_{NOM}) + T_{C2}(T - T_{NOM})^2 \right]$$
(7.255)

where  $I_L$  is the current flowing through the inductor as in figure 7.45 and T is the current temperature.

# М

MOSFET



Figure 7.46: M — MOSFET element: (a) n-channel enhancement-mode MOSFET; (b) p-channel enhancement-mode MOSFET; (c) n-channel depletion-mode MOSFET; and (d) p-channel depletion-mode MOSFET.

#### Form

Mname NDrain NGate NSsource NBulk ModelName [L=Length] [W=Width]

- + [AD=DrainDiffusionArea] [AS=SourceDiffusionArea]
- + [PD=DrainPerimeter] [PS=SourcePerimeter]
- + [NRD=RelativeDrainResistivity] [NRS=RelativeSourceResistivity]
- + [OFF]  $[IC=V_{DS}, V_{GS}, V_{BS}]$

# PSPICEForm

Mname NDrain NGate NSsource NBulk ModelName [L=Length] [W=Width]

+ [AD=DrainDiffusionArea] [AS=SourceDiffusionArea]

+ [PD=DrainPerimeter] [PS=SourcePerimeter]

- + [NRD = RelativeDrainResistivity] [NRS = RelativeSourceResistivity]
- + [NRG=RelativeGateResistivity] [NRB=RelativeBulkResistivity]

NDrain is the drain node.

NGate is the gate node.

- *NSource* is the source node.
  - *NBulk* is the bulk or substrate node.

ModelName is the model name.

#### MOSFET

L is the channel lateral diffusion *Length*.

(Units: m; Optional; Symbol: L; The default is version dependent. SPICE2G6 and SPICE3 Default: the length DEFL most recently specified in a .OPTION statement which in-turn defaults to 100  $\mu$ m (100U); PSPICE Default: the length L – length specified in model *ModelName* which in turn defaults to the default length DEFL most recently specified in a .OPTION statement which in-turn defaults to 100  $\mu$ m (100U).)

W is the channel lateral diffusion *Width*.

(Units: m; Optional; Symbol: W; The default is version dependent.

SPICE2G6 and SPICE3 Default: the width DEFW most recently specified in a .0PTION statement which in-turn defaults to 100  $\mu$ m (100U);

PSPICE Default: the width W – width specified in model *ModelName* which in turn defaults to the default width DEFW most recently specified in a .OPTION statement which in-turn defaults to 100  $\mu$ m (100U).)

- AD is the area of the drain diffusion (*DrainDiffusionArea*). The default is DEFAD most recently specified in a .OPTIONS statement. (Units: m<sup>2</sup>; Optional; Default: DEFAD; Symbol: A<sub>D</sub>)
- AS is the area of the source diffusion (SourceDiffusionArea). The default is DEFAS most recently specified in a .OPTIONS statement. (Units: m<sup>2</sup>; Optional; Default: DEFAS; Symbol: A<sub>S</sub>)
- PD is the perimeter of the drain junction (*DrainPerimeter*). (Units: m; Optional; Default: 0; Symbol:  $P_D$ )
- **PS** is the perimeter of the source junction (*SourcePerimeter*). (Units: m; Optional; Default: 0; symbol:  $P_S$ )
- NRD is the relative resistivity in squares of the drain region (*RelativeDrainResistivity*). The sheet resistance RSH specified in the model *ModelName* is divided by this factor to obtain the parasitic drain resistance. (Units: squares; Optional; Default: 0; Symbol:  $N_{RD}$ )
- NRS is the relative resistivity in squares of the source region (*RelativeSourceResistivity*). The sheet resistance RSH specified in the model *ModelName* is divided by this factor to obtain the parasitic source resistance. (Units: squares; Optional; Default: 0; Symbol:  $N_{RS}$ )
- NRG is the relative resistivity in squares of the gate region (*RelativeGateResistivity*). The sheet resistance RSH specified in the model *ModelName* is divided by this factor to obtain the parasitic gate resistance. (Units: squares; Optional; Default: 0; Symbol:  $N_{RG}$ )
- NRB is the relative resistivity in squares of the bulk (substrate) region (*RelativeBulkResistivity*). The sheet resistance RSH specified in the model *ModelName* is divided by this factor to obtain the parasitic bulk resistance. (Units: squares; Optional; Default: 0; Symbol:  $N_{RB}$ )

- **DFF** indicates an (optional) initial condition on the device for **DC** analysis. If specified the **DC** operating point is calculated with the terminal voltages set to zero. Once convergence is obtained, the program continues to iterate to obtain the exact value of the terminal voltages. The OFF option is used to enforce the solution to correspond to a desired state if the circuit has more than one stable state.
- IC is the optional initial condition specification. Using  $IC=V_{DS}$ ,  $V_{GS}$ ,  $V_{BS}$  is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired starting from other than the quiescent operating point. Specification of the transient initial conditions using the .IC statement (see page 66) is preferred and is more convenient.

#### Example

M1 24 2 0 20 TYPE1 M31 2 17 6 10 MODM L=5U W=2U M1 2 9 3 0 MOD1 L=10U W=5U AD=100P AS=100P PD=40U PS=40U

#### Note

- 1. The parameters of a MOSFET can be completely specified in the model *ModelName*. This facilitates the use of standard transistors by using absolute quantities in the model. Alternatively scalable process parameters can be specified in the model *ModelName* and these scaled by geometric parameters on the MOSFET element line.
- 2. In SPICE2G6 and SPICE3 the width W can not be specified in the model statement. For these simulators absolute device parameters must be specified in the model statement if parameters are not input on the element line.

Model Type

NMOS PMOS

Example

NMOS Model

N-CHANNEL MOSFET MODEL

# **PMOS Model**

P-CHANNEL MOSFET MODEL

#### MOSFET

Two groups of model parameters define the linear and nonlinear elements of the MOSFET models. One group defines absolute quantities and another group defines quantities that are multiplied by scaling parameters related to area and dimension which are specified on the element line. This enables the MOSFET element to be used in two ways. Using the absolute quantities the characteristics of a device can be defined independent of the parameters on the element line. Thus the model of a standard transistor, perhaps resident in a library, can be used without user-knowledge required. Using the scalable quantities the parameters of a fabrication process can be defined in the model statement and scaling parameters such as the lateral diffusion length (specified by L) and the lateral diffusion width (specified by W), and the drain and source diffusion areas (specified by AD and AS specified on the element line). An example is the specification of the drain-bulk saturation current  $I_{D,SAT}$ . This parameter can be specified by the absolute parameter  $I_S$  specified by the IS model keyword. It can also be determined as  $I_S = J_S \cdot A_D$  using the scalable parameter  $J_S$  specified by the JS model keyword and  $A_D$  specified by the AD element keyword.

SPICE provides four MOSFET device models. The first three models, known as LEVELS 1, 2 and 3 differ in the formulation of the I-V characteristic. The fourth model, known as the BSIM model, uses a completely different formulation utilizing extensive semiconductor parameters. The parameter LEVEL specifies the model to be used:

LEVEL = 1	$\rightarrow$	"Shichman-Hodges", MOS1 This model was the first SPICE MOSFET model and was devel- oped in 1968 [3]. It is an elementary model and has a limited scaling capability. It is applicable to fairly large devices with gate lengths greater than 4 $\mu$ m. Its main attribute is that only a few parameters need be specified and so it is good for preliminary analyses.
LEVEL = 2	$\rightarrow$	MOS2 This is an analytical model which uses a combination of processing parameters and geometry. The major development over the LEVEL 1 model is improved treatment of the capacitances due to the chan- nel charge. [4–6]. The model dates from 1980 and is applicable for chanel lengths of 2 $\mu$ m and higher [7].
IFVFI — 2	,	The LEVEL 2 model has convergence problems and is slower and less accurate than the LEVEL 3 model.
LEVEL = 3	$\rightarrow$	This is a semi-empirical model developed in 1980 [7]. It is also used for gate lengths of 2 $\mu$ m and more. The parameters of this model are determined by experimental characterization and so it is more accurate than the LEVEL 1 and 2 models that use the more indirect process parameters.
LEVEL = 4	$\rightarrow$	BSIM The BSIM model is an advanced empirical model which uses pro- cess information and a larger number of parameters (more than 60) to describe the operation of devices with gate lengths as short as 1 $\mu$ m. It was developed in 1985 [9].

Other MOSFET models or LEVELs are available in various versions of SPICE. These LEVELs are optimized for MOSFETs fabricated in a particular foundary or provide a proprietary edge for the advanced commercial SPICE programs. The reader interested in more advanced MOSFET models is referred to [8].



Figure 7.47: Schematic of LEVEL 1, 2 and 3 MOSFET models.  $V_{GS}$ ,  $V_{DS}$ ,  $V_{GD}$ ,  $V_{GB}$ ,  $V_{DB}$  and  $V_{BS}$  are voltages between the internal gate, drain, bulk and source terminals designated G, D, B and C respectively.

#### LEVEL 1, 2 and 3 MOSFET models.

The schematic of the LEVEEL 1, 2 and 3 MOSFET models is shown in Figure 7.47.

The LEVEL 1, 2 and 3 models have much in common. These models evaluate the junction depletion capacitances and parasitic resistances of a transistor in the same way. They differ in the procedure used to evaluate the overlap capacitances ( $C_{GD}$ ,  $C_{GS}$  and  $C_{GB}$ ) and that used to determine the current-voltage characteristics of the active region of a transistor. The overlap capacitances model charge storage as nonlinear thin-oxide capacitance distributed among the gate, source drain and bulk regions. These capacitances are important in describing the operation of MOSFETs. The LEVEL 1, 2 and 3 models are intimately intertwined as combinations of parameters can result in using equations from more than one model. The LEVEL parameter resolves conflicts when there is more than one way to calculate the transistor characteristics with the parameters specified by the user. Antognetti and Massobrio provide a comprehensive discussion of the development of the LEVEL 1, 2 and 3 models [2].

The parameters of the LEVEL 1, 2 and 3 models are given in table 7.9. Parameter extensions are given in table ??. It is assumed that the model parameters were determined or measured at the nominal temperature  $T_{\text{NOM}}$  (default  $27^{\circ}C$ ) specified in the most recent .OPTIONS statement preceeding the .MODEL statement. In PSPICE this is overwritten by the T\_MEASURED parameter. Most of the parameters have default values. Those parameters that have INFERRED defaults are calculated from other parameters.

Name	Description	Units	Default
AF	flicker noise exponent $(A_F)$	-	1
CBD	zero-bias B-D junction capacitance $(C'_{BD})$	F	0
CBS	zero-bias B-S junction capacitance $(C'_{BS})$	F	0
CGBO	gate-bulk overlap capacitance per meter of channel length	F/m	0
	(PARASITIC) $(C_{GBO})$		
CGDO	gate-drain overlap capacitance per meter of channel width	F/m	0
	$(PARASITIC)   (C_{GDO})$		
CGSO	gate-source overlap capacitance per meter of channel width	F/m	0
	(PARASITIC) $(C_{GSO})$		
		Continued of	n next page

Table 7.9: MOSFET model keywords for LEVELs 1, 2, 3.

Name	Description	Units	Default
CJ	zero-bias bulk junction bottom capcitance per square me-	$F/m^2$	0
	ter of junction area		
	$(PARASITIC)   (C_J)$		
CJSW	zero-bias bulk junction sidewall capacitance per meter of	F/m	0
	junction perimeter		
	$(PARASITIC)   (C_{J,SW})$		
DELTA	width effect on threshold voltage (LEVEL=2 and LEVEL=3)	-	0
	$(\delta)$		
ETA	static feedback (LEVEL=3 only) $(\eta)$	-	INFERRED
FC	coefficient for forward-bias depletion capacitance	-	0.5
	formula		
	$(PARASITIC)   (F_C)$		
GAMMA	bulk threshold parameter $(\gamma)$	$V^{\frac{1}{2}}$	INFERRED
IS	bulk junction saturation current	А	$10^{-14}$
	$(PARASITIC)   (I_S)$		
JS	bulk junction saturation current per sq-meter of junction	$A/m^2$	0
	area		
	$(PARASITIC)   (J_S)$		
KAPPA	saturation field factor (LEVEL=3 only) $(\kappa)$	-	0.2
KF	flicker noise coefficient $(K_F)$	-	0
KP	transconductance parameter $(K_P)$	$A/V^2$	$2.10^{-5}$
LAMBDA	channel-length modulation	1/V	0
	$(\text{LEVEL}=1, 2 \text{ only})$ ( $\lambda$ )		
LD	lateral diffusion $(X_{JL})$	m	0
LEVEL	model index	-	1
MJ	bulk junction bottom grading coefficient	-	0.5
	$(PARASITIC) \qquad (M_J)$		
MJSW	bulk junction sidewall grading coefficient	-	0.33
	$(PARASITIC) \qquad (M_{J,SW})$		
NSUB	substrate doping $(N_B)$	$\rm cm^{-3}$	INFERRED
NSS	surface state density $(N_{\rm SS})$	$\rm cm^{-2}$	INFERRED
NFS	fast surface state density $(N_{\rm FS})$	$\rm cm^{-2}$	0
NEFF	total channel charge (fixed and mobile) coefficient	-	1
	$(\text{LEVEL}=2 \text{ only}) \tag{N_{EFF}}$		
PB	bulk junction potential $(\phi_J)$	V	0.8
	(This is the interface potential in the channel relative to		
	the source at threshold.)		
PHI	surface inversion potential $(2\phi_B)$	V	0.6
RD	drain ohmic resistance	Ω	0
	$(PARASITIC) (R_D)$	-	
RS	source ohmic resistance	\$2	0
	$(PARASITIC) (R_S)$	<u>, , , , , , , , , , , , , , , , , , , </u>	_
RSH	drain and source diffusion sheet resistance	$\Omega$ /square	0
	$(PARASITIC) \qquad (R_{SH})$		
THETA	mobility modulation (LEVEL=3 only) $(\theta)$	1/V	0
		Continued of	n next page

Table 7.9: MOSFET model keywords for LEVELs 1, 2, 3.

Name	Description	Units	Default
TOX	oxide thickness $(T_{OX})$	m	-
	Default for LEVEL 2 and 3 is 0.1 $\mu$ m.		
	If LEVEL 1 and TOX is omitted then the process oriented		
	model is not used.		
TPG	type of gate material: $(T_{\rm PG})$	-	1
	$1 \rightarrow \text{polysilicon, opposite type to substrate}$		
	$-1 \rightarrow \text{polysilicon}$ , same type as substrate		
UCDIT	$0 \rightarrow \text{aluminum gate}$	V/am	104
UCRII	critical field for mobility degradation (LEVEL=2 only) $(U_C)$	v/cm	10
ULAF	degradation (LEVEL $-2$ only) (U <sub>EVED</sub> )	-	0
τιο	$\frac{\text{degradation}(\text{LEVEL}-2 \text{ only})}{\text{surface mobility}(\text{U-ob})}$	$cm^2/V_{-S}$	600
UTRA	transverse field coefficient (mobility) (LEVEL = 1 and 3	-	0
01101	$\begin{array}{l} \text{only} \\ \text{only} \end{array} = \begin{array}{l} \text{i and } \text{o} \\ (U_{\text{TPA}}) \end{array}$		Ū.
VMAX	$\begin{array}{c} (0 \text{ IRA}) \\ \text{maximum drift velocity of carriers} \\ (V_{MAX}) \end{array}$	m/s	0
VTO	zero-bias threshold voltage	V	0
	N-channel devices: positive for enhancement mode		-
	and negative for depletion mode devices.		
	P-channel devices: negative for enhancement mode		
	and positive for depletion mode devices.		
	$(VT-oh)   (V_{T0})$		
XJ	metallurgical junction depth $(X_J)$	m	0
JSSW	bulk $p$ - $n$ junction sidewall current per unit length	A/m	0
	$(PARASITIC) \qquad (J_{S,SW})$		
L	channel length (L)	m	DEFL
N	bulk $p$ - $n$ emission coefficient	-	0
	$(PARASITIC) \qquad (N)$	3.7	
PBSW	bulk $p$ - $n$ sidewall potential	V	РВ
DD	$(\varphi_{J,SW})$	0	0
КB	$(\mathbf{P}_{\mathbf{A}}) = \mathbf{P}_{\mathbf{A}} $	27	0
PC	(RB)	0	0
110	$(PARASITIC) (R_{P})$	32	0
RDS	$\frac{(R_B)}{(R_B)}$	Ω	$\infty$
TABS	$(T_{ABS})$	°C	current
	(* AD5)	C	temp.
T_MEASUREI	)	°C	TNOM
	$(T_{\text{MEASURED}})$		
T_REL_GLOE	AL	°C	0
	$(T_{\text{REL-GLOBAL}})$		
T_REL_LOCA	Ĺ	°C	0
	$(T_{ m REL,LOCAL})$		
TT	bulk $p$ - $n$ transit time $(\tau_T)$	s	0
W	channel width $(W)$	m	DEFW
WD	lateral diffusion width $(W_D)$	m	0
		Continued c	on next page

Table 7.9: MOSFET model keywords for LEVELs 1, 2, 3.

Name	Description	$\mathbf{Units}$	Default
XQC	fraction of channel charge attributable to drain in satura-	-	1
	tion region $(X_{QC})$		
	If $X_{QC} > 0.5$ the Meyer Capacitance Model is used.		
	If $X_{QC} \leq 0.5$ the Ward-Dutton Capacitance Model is used.		

Table 7.9: MOSFET model keywords for LEVELs 1, 2, 3.

The MOSFET LEVEL 1,2 and 3 parameters fall into three categories: absolute device parameters, scalable and process parameters and geometric parameters. In most cases the absolute device parameters can be derived from the scalable and process parameters and the geometry parameters. However, if specified, the values of the device parameters are used.

The physical constants used in the model evaluation are

k	Boltzman's constant	$1.3806226  10^{-23}  \mathrm{J/K}$
q	electronic charge	$1.6021918  10^{-19} \mathrm{C}$
$\epsilon_0$	free space permittivity	$8.85421487110^{-12}\mathrm{F/m}$
$\epsilon_{ m Si}$	permittivity of silicon	$11.7\epsilon_0$
$\epsilon_{\rm OX}$	permittivity of silicon dioxide	$3.9\epsilon_0$
$n_i$	intrinsic concentration of silicon @ 300 K	$1.4510^{16} \mathrm{\ m}^{-3}$

Standard Calculations

Absolute temperatures (in kelvins, K) are used. The thermal voltage

$$V_{\rm TH}(T_{\rm NOM}) = \frac{kT_{\rm NOM}}{q}.$$
(7.256)

The silicon bandgap energy

$$E_G(T_{\rm NOM}) = 1.16 - 0.000702 \frac{4T_{\rm NOM}^2}{T_{\rm NOM} + 1108}.$$
(7.257)

The difference of the gate and bulk contact potentials

$$\phi_{\rm MS} = \phi_{\rm GATE} - \phi_{\rm BULK}. \tag{7.258}$$

The gate contact potential

$$\phi_{\text{GATE}} = \begin{cases} 3.2 & T_{\text{PG}} = 0\\ 3.25 & \text{NMOS } \& \ T_{\text{PG}} = 1\\ 3.25 + E_G & \text{NMOS } \& \ T_{\text{PG}} = -1\\ 3.25 + E_G & \text{PMOS } \& \ T_{\text{PG}} = 1\\ 3.25 & \text{PMOS } \& \ T_{\text{PG}} = -1 \end{cases}$$
(7.259)

The potential drop across the oxide

$$\phi_{\rm OX} = -\frac{Q_0'}{C_{\rm OX}'}.$$
(7.260)

The contact potential of the bulk material

$$\phi_{\text{BULK}} = \begin{cases} 3.25 + E_G & \text{if NMOS} \\ 3.25 & \text{if PMOS} \end{cases}$$
(7.261)

The equivalent gate oxide interface charge per unit area

$$Q_0' = q N_{\rm SS}.$$
 (7.262)

The capacitance per unit area of the oxide is

$$C'_{OX} = \frac{\epsilon_{OX}}{T_{OX}}.\tag{7.263}$$

The effective length  $L_{\text{EFF}}$  of the channel is reduced by the amount  $X_{JL}$  (= LD) of the lateral diffusion at the source and drain regions:

$$L_{\rm EFF} = L - 2X_{JL} \tag{7.264}$$

Similarly the effective length  $W_{\text{EFF}}$  of the channel is reduced by the amount  $W_D$  (= WD) of the lateral diffusion at the edges of the channel.

$$W_{\rm EFF} = W - 2W_D \tag{7.265}$$

 $\kappa$  is limited: if the specified value of  $\kappa$  is less than or equal to zero the following parameters are set:

$$\kappa = 0.2 \tag{7.266}$$

$$\lambda = 0 \tag{7.267}$$

$$U_C = 0$$
 (7.268)

$$U_{\rm EXP} = 0 \tag{7.269}$$

$$U_{\text{TRA}} = 0 \tag{7.270}$$

Process Oriented Model

#### MOSFET

If omitted, device parameters are computed from process parameters using defaults if necessary provided that both  $TOX = T_{OX}$  and  $NSUB = N_B$  are specified. If either TOX or NSUB is not specified then the critical device parameters must be specified. Which parameters are critical depends on the model LEVEL.

If VTO is not specified in the model statement then it is evaluated as

$$\mathsf{VTO} = V_{T0} = \begin{cases} V_{\mathrm{FB}} + \gamma \sqrt{2\phi_B} + 2\phi_B & \text{if NMOS} \\ V_{\mathrm{FB}} - \gamma \sqrt{2\phi_B} + 2\phi_B & \text{if PMOS} \end{cases}$$
(7.271)

where

$$V_{\rm FB} = \phi_{\rm MS} - \phi_{\rm OX} \tag{7.272}$$

is the flat-band voltage. Otherwise if VTO is specified in the model statement

$$V_{\rm FB} = \begin{cases} V_{T0} - \gamma \sqrt{2\phi_B} + 2\phi_B & \text{if NMOS} \\ V_{T0} + \gamma \sqrt{2\phi_B} + 2\phi_B & \text{if PMOS} \end{cases}$$
(7.273)

If GAMMA is not specified in the model statement then

$$\mathsf{GAMMA} = \gamma = \frac{\sqrt{2\epsilon_{\mathrm{Si}}qN_B}}{C'_{OX}} \tag{7.274}$$

If PHI is not specified in the model statement then

$$\mathsf{PHI} = 2\phi_B = 2V_{\mathrm{TH}} \ln \frac{N_B}{n_i} \tag{7.275}$$

and is limited to 0.1 if calculated.  $N_B = NSUB$  as supplied in the model statement and  $n_i$  at 300 K are used. If KP is not specified in the model statement then

$$\mathsf{KP} = K_P = \mu_0 C'_{OX} \tag{7.276}$$

If UCRIT is not specified in the model statement then

$$\text{UCRIT} = U_C = \frac{\epsilon_{Si}}{T_{OX}} \tag{7.277}$$

$$X_d = \sqrt{\frac{2\epsilon_{\rm Si}}{qN_B}} \tag{7.278}$$

is proportional to the depletion layer widths at the source and rdain regions.

# Temperature Dependence

Temperature effects are incorporated as follows where T and  $T_{\text{NOM}}$  are absolute temperatures in Kelvins (K).

$$V_{\rm TH} = \frac{kT}{q} \tag{7.279}$$

$$I_S(T) = I_S e^{\left(E_g(T)\frac{T}{T_{\text{NOM}}} - E_G(T)\right)/V_{\text{TH}}}$$
(7.280)

$$J_S(T) = J_S e^{\left(E_g(T)\frac{T}{T_{\text{NOM}}} - E_G(T)\right)/V_{\text{TH}}}$$
(7.281)

$$J_{S,SW}(T) = J_{S,SW}e^{\left(E_g(T)\frac{T}{T_{NOM}} - E_G(T)\right)/V_{TH}}$$
(7.282)

$$\phi_J(T) = \phi_J \frac{T}{T_{\text{NOM}}} - 3V_{\text{TH}} \ln \frac{T}{T_{\text{NOM}}} + E_G(T_{\text{NOM}}) \frac{T}{T_{\text{NOM}}} - E_G(T)$$
(7.283)

$$\phi_{J,SW}(T) = \phi_{J,SW} \frac{T}{T_{NOM}} - 3V_{TH} \ln \frac{T}{T_{NOM}} + E_G(T_{NOM}) \frac{T}{T_{NOM}} - E_G(T)$$
(7.284)

$$2\phi_B(T) = 2\phi_B \frac{T}{T_{\text{NOM}}} - 3V_{\text{TH}} \ln \frac{T}{T_{\text{NOM}}} + E_G(T_{\text{NOM}} - E_G(T))$$
(7.285)

$$C'_{BD}(T) = C'_{BD} \{ 1 + M_J [0.0004(T - T_{\text{NOM}}) + (1 - \phi_J(T)/\phi_J)] \}$$
(7.286)

$$C'_{BS}(T) = C'_{BS}\{1 + M_J[0.0004(T - T_{\text{NOM}}) + (1 - \phi_J(T)/\phi_J)]\}$$
(7.287)

$$C_J(T) = C_J \{ 1 + M_J [0.0004(T - T_{\text{NOM}}) + (1 - \phi_{J,\text{SW}}(T)/\phi_{J,\text{SW}})] \}$$
(7.288)

$$C_{J,SW}(T) = C_{J,SW}\{1 + M_{J,SW}[0.0004(T - T_{NOM}) + (1 - \phi_J(T)/\phi_J)]\}$$
(7.289)

$$K_P(T) = K_P (T_{\text{NOM}}/T)^{3/2}$$
(7.290)
$$\mu_0(T) = \mu_0 (T_{\text{NOM}}/T)^{3/2}$$
(7.291)

$$\mu_0(I) = \mu_0(I_{\text{NOM}}/I)^{-r}$$

$$T^2$$
(7.291)

$$E_g(T) = 1.16 - 0.000702 \frac{T}{T + 1108}$$
(7.292)

## Parasitic Resistances

The resistive parasities  $R_S$ ,  $R_G$ ,  $R_D$  and  $R_B$  are treated in the same way for the LEVEL 1, 2 and 3 models. They may be specified as the absolute device parameters RS, RG, RD, and RB or calculated from the sheet resistivity  $R_{\rm SH}$  (= RSH) and area parameters  $N_{RS}$  (= NRS),  $N_{RG}$  (= NRG),  $N_{RD}$  (= NRD) and  $N_{RB}$  (= NRB). As always the absolute device parameters take precedence if they are specified. Otherwise

$$R_S = N_{RS} R_{\rm SH} \tag{7.294}$$

$$R_G = N_{RG} R_{\rm SH} \tag{7.295}$$

$$R_D = N_{RD} R_{\rm SH} \tag{7.296}$$

$$R_B = N_{RB}R_{\rm SH} \tag{7.297}$$

Note that neither geometry parameters nor process parameters are required if the absolute device resistances are specified. The parasitic resistance parameter dependencies are summarized in figure 7.48. Leakage Currents

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PROCESS	+	GEO	METRY	$\rightarrow$		DEVICE
PARAMETERS		PARA	METERS			PARAMETERS
RSH $R_{\rm SH}$		NRS	$N_{RS}$		RD	$R_D = f(R_{\rm SH}, N_{RD})$
		NRD	$N_{RD}$		RS	$R_S = f(R_{\rm SH}, N_{RS})$
		NRG	$N_{RG}$		RG	$R_B = f(R_{\rm SH}, N_{RG})$
		NRB	$N_{RB}$		RB	$R_B = f(R_{\rm SH}, N_{RB})$

Figure 7.48: MOSFET LEVEL 1, 2 and 3 parasitic resistance parameter relationships.

PROCESS PARAMETERS	+	GEO PARA	METRY METERS	$\rightarrow$	DEVICE PARAMETERS
JS $J_S$		AD AS	$A_D$ $A_S$		$IS \qquad I_S = f(J_S, J_{S,SW}, A_D, A_S, P_D, P_S)$
		PD PS	$P_D$ $P_S$		

Figure 7.49: MOSFET leakage current parameter dependecies.

Current flows across the normally reverse biased source-bulk and drain-bulk junctions. The bulk-source leakage current

$$I_{BS} = I_{BSS} \left( e^{(V_{BS}/V_{\rm TH})} - 1 \right)$$
(7.298)

where

$$I_{BSS} = \begin{cases} I_S & \text{if IS specified} \\ A_S J_S + P_S J_{S,SW} & \text{if IS not specified} \end{cases}$$
(7.299)

The bulk-drain leakage current

$$I_{BD} = I_{BDS} \left( e^{(V_{BD}/V_{\rm TH})} - 1 \right)$$
(7.300)

where

$$I_{BDS} = \begin{cases} I_S & \text{if IS specified} \\ A_D J_S + P_S J_{S,SW} & \text{if IS not specified} \end{cases}$$
(7.301)

The parameter dependencies of the parameters describing the leakage current in the LEVEL 1, 2 and 3 MOSFET models are summarized in figure 7.49.

Depletion Capacitances

 $C_{BS}$  and  $C_{BD}$  are the depletion capacitances at the bulk-source and bulk-drain depletion regions respectively. These depletion capacitances are calculated and used in the same way in all three (LEVEL = 1, 2 and 3) models. Although they may be specified as absolute device parameters they are strong functions of the voltages across the junction and are complex functions of geometry and of semiconductor doping. As such they are usually calculated from process parameters. They are the sum of component capacitances

$$C_{BS} = C_{BS,JA} + C_{BS,SW} + C_{BS,TT} \tag{7.302}$$

where the sidewall capacitance

$$C_{BS,SW} = P_S C_{J,SW} C_{BSS} \tag{7.303}$$

$$C_{BSS} = \begin{cases} \left(1 - \frac{V_{BS}}{\phi_{J,SW}}\right)^{-M_{J,SW}} & \text{for } V_{BS} \le F_C \phi_J \\ (1 - F_C)^{-(1 + M_{J,SW})} \left(1 - F_C (1 + M_{J,SW}) + \frac{M_{J,SW} V_{BS}}{\phi_{J,SW}}\right) \end{cases}$$
(7.304)

$$\begin{pmatrix} (1 - F_C)^{-(1 + M_{J,SW})} \left( 1 - F_C (1 + M_{J,SW}) + \frac{M_{J,SW} V_{BS}}{\phi_{J,SW}} \right) \\ \text{for } V_{BS} > F_C \phi_J \end{cases}$$
(7.305)

the area capacitance

$$C_{BS,JA} = \begin{cases} C'_{BS}C_{BSJ} & \text{if CBS } (=C'_{BS}) \text{ is specified in the model} \\ A_SC_JC_{BSJ} & \text{otherwise} \end{cases}$$
(7.306)

$$C_{BSJ} = \begin{cases} \left(1 - \frac{V_{BS}}{\phi_J}\right)^{-M_J} & \text{for } V_{BS} \le F_C \phi_J \\ \left(1 - F_T\right)^{-(1+M_J)} \left(1 - F_T (1+M_J) + \frac{M_J V_{BS}}{M_J}\right) & \text{for } V_{TT} \ge F_T \phi_T \end{cases}$$
(7.307)

$$\left((1-F_C)^{-(1+M_J)}\left(1-F_C(1+M_J)+\frac{M_J V_{BS}}{\phi_J}\right) \text{ for } V_{BS} > F_C \phi_J\right)$$

and the transit time capacitance

$$C_{BS,\mathrm{TT}} = \tau_T G_{BS} \tag{7.308}$$

where the bulk-source conductance  $G_{BS} = \partial I_{BS} / \partial V_{BS}$  and  $I_{BS}$  is defined in (7.298).

$$C_{BD} = C_{BD,\mathrm{JA}} + C_{BD,\mathrm{SW}} \tag{7.309}$$

where the sidewall capacitance

$$C_{BD,SW} = P_D C_{J,SW} C_{BDS}$$

$$\left( \left( 1 - \frac{V_{BD}}{\phi_{LSW}} \right)^{-M_{J,SW}} \quad \text{for } V_{BD} \le F_C \phi_J$$

$$(7.310)$$

$$C_{BDS} = \begin{cases} \begin{pmatrix} 1 & \phi_{J,SW} \end{pmatrix} & \text{for } V_{BD} \ge TC\phi_J \\ (1 - F_C)^{-(1 + M_{J,SW})} \begin{pmatrix} 1 - F_C(1 + M_{J,SW}) + \frac{M_{J,SW}V_{BD}}{\phi_{J,SW}} \\ \text{for } V_{BD} > F_C\phi_J \end{cases}$$
(7.311)

for 
$$V_{BD} > F_C \phi_J$$

the area capacitance

$$C_{BD,JA} = \begin{cases} C'_{BD}C_{BDJ} & \text{if CBD} (= C'_{BD}) \text{ is specified in the model} \\ A_DC_JC_{BDJ} & \text{otherwise} \end{cases}$$
(7.313)

$$C_{BDJ} = \begin{cases} \left(1 - \frac{V_{BD}}{\phi_J}\right)^{-1/3} & \text{for } V_{BS} \le F_C \phi_J \\ (1 - F_C)^{-(1 + M_J)} \left(1 - F_C (1 + M_J) + \frac{M_J V_{BD}}{\phi_J}\right) & \text{for } V_{BD} > F_C \phi_J \end{cases}$$
(7.314)

and the transit time capacitance

PRC	DCESS	+	GEO	METRY	$\rightarrow$	DEVICE
PARAM	METERS		PARA	METERS		PARAMETERS
CJ	$C_J$		AD	$A_D$		CBD
CJSW	$C_{J,\mathrm{SW}}$		AS	$A_S$		CBS $C'_{BS} = f(C_J, A_S)$
MJ	$M_J$		PD	$P_D$		$\{C_{BS} = f(P_S, C'_{BS}, C_{J,SW}, \tau_T$
MJSW	$M_{J,\mathrm{SW}}$		PS	$P_S$		$M_J, M_{J,SW}, \phi_J, \phi_{J,SW}, F_C) \}$
PB	$\phi_J$					$\{C_{BD} =$
PBSW	$\phi_{J,\mathrm{SW}}$					$f(P_D, C'_{BD}, C_{J, SW}, \tau_T$
FC	$F_C$					$M_J, M_{J,SW}, \phi_J, \phi_{J,SW}, F_C)\}$

Figure 7.50: MOSFET LEVEL 1, 2 and 3 junction depletion capacitance parameter relationships.

$$C_{BS,\mathrm{TT}} = \tau_T G_{BS} \tag{7.315}$$

where the bulk-source conductance  $G_{BD} = \partial I_{BD} / \partial V_{BD}$  and  $I_{BD}$  is defined in (7.300).

In the LEVEL 1 MOSFET model the depletion capacitances are piecewise linear. They are calculated at the current operating point and then treated as linear. In the LEVEL 2 and 3 models they are treated as nonlinear. The depletion capacitance parameter dependencies are summarized in figure 7.50.

#### LEVEL 1 I/V Characteristics

For the LEVEL 1 model the device parameters (other than capacitances and resistances) are evaluated using  $T_{OX}$  (TOX),  $\mu_0$  (UO),  $N_{SS}$  (NSS and  $N_B$  (NSUB) if they are not specified in the .MODEL statement.

The LEVEL 1 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point.

Normal Mode:  $(V_{DS} \ge 0)$ 

The regions are as follows:

$$\begin{array}{ll} \text{cutoff region:} & V_{GS} < V_T \\ \text{linear region:} & V_{GS} > V_T \text{ and } V_{DS} < V_{GS} - V_T \\ \text{saturation region:} & V_{GS} > V_T \text{ and } V_{DS} > V_{GS} - V_T \end{array}$$

where the threshold voltage

$$V_{T} = \begin{cases} V_{FB} + 2\phi_{B} + \gamma\sqrt{2\phi_{B} - V_{BS}} & V_{BS} \ge 2\phi_{B} \\ V_{FB} + 2\phi_{B} & V_{BS} < 2\phi_{B} \end{cases}$$
(7.316)

Then

$$I_{D} = \begin{cases} 0 & \text{cutoff region} \\ \frac{W_{\text{EFF}}}{L_{\text{EFF}}} \frac{K_{P}}{2} (1 + \lambda V_{DS}) V_{DS} [2(V_{GS} - V_{T}) - V_{DS}] & \text{linear region} \\ \frac{W_{\text{EFF}}}{L_{\text{EFF}}} \frac{K_{P}}{2} (1 + \lambda V_{DS}) [V_{GS} - V_{T}]^{2} & \text{saturation region} \end{cases}$$
(7.317)

Inverted Mode:  $(V_{DS} < 0)$ 

PROCESS PARAMETERS	+	GEOMETRY PARAMETERS	$\rightarrow$	DEVICE PARAMETERS
$\begin{array}{c c} \text{NSUB} & N_B \\ \text{TOX} & T_{OX} \\ \text{NSS} & N_{\text{SS}} \\ \text{UO} & \mu_0 \end{array}$		$\begin{tabular}{ccc} \hline & - & \\ \hline & & Required \\ \hline & & L \\ \hline & & W \\ \hline & & W \\ \hline & & Optional \\ \hline & & LD & X_{JL} \\ \hline & & WD & W_D \\ \hline \end{tabular}$		$\label{eq:VTO} \begin{array}{l} \text{VTO} \\ V_{T0} = f(2\phi_B, N_{\text{SS}}, T_{OX}, \gamma) \\ \text{KP} \qquad K_P = f(\mu_0, T_{OX}) \\ \text{LAMBDA} \qquad \lambda \\ \text{PHI} \qquad 2\phi_B = f(N_B) \\ \text{GAMMA} \qquad \gamma = f(T_{OX}, N_B) \\ \{I_D = f(W, L, W_D, X_{JL} \\ V_{T0}, K_P, \lambda, 2\phi_B, \gamma)\} \end{array}$

Figure 7.51: LEVEL 1 I/V dependencies.



Figure 7.52: MOSFET LEVEL 1 overlap capacitance parameter relationships.

In the inverted mode the MOSFET I/V characteristics are evaluated as in the normal mode (7.317) but with the drain and source subscripts interchanged. The relationships of the parameters describing the I/V characteristics for the LEVEL 1 model are summarized in figure 7.51.

## LEVEL 1 Overlap Capacitances

In the LEVEL 1 model the gate overlap capacitances  $C_{GS}$ ,  $C_{GD}$  and  $C_{GB}$  are constant and are calculated using the per unit width overlap capacitances  $C_{GSO}$  (CGSO),  $C_{GDO}$  (CGDO) and  $C_{GBO}$  (CGBO):

$$C_{GS} = C_{GSO}W (7.318)$$

$$C_{GD} = C_{GDO}W \tag{7.319}$$

$$C_{GB} = C_{GBO}W \tag{7.320}$$

The overlap capacitance parameter dependencies are summarized in Figure 7.52.
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#### LEVEL 2 I/V Characteristics

The LEVEL 2 I/V characteristics are based on empirical fits resulting in a more accurate description of the I/V response than obtained with the LEVEL 1 model. The LEVEL 2 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current  $(V_{DS}, V_{GS})$  operating point. Normal Mode:  $(V_{DS} \ge 0)$ 

The regions are as follows:

 $V_{GS} < V_T$ cutoff region:  $V_T < V_{GS} \le V_{\rm ON}$ weak inversion region:  $V_{GS} > V_{ON}$  and  $V_{DS} < V_{DS,SAT}$ linear region (strong inversion):  $V_{GS} > V_{ON}$  and  $V_{DS} > V_{DS,SAT}$ saturation region (strong inversion): where V

$$V_T = V'_{\rm FB} + \gamma_{\rm EFF} X_S \tag{7.321}$$

$$V_{\rm ON} = \begin{cases} V_T & N_{\rm FS} = 0\\ V_T + V_{\rm TH} x_n & N_{\rm FS} \neq 0 \end{cases}$$
(7.322)

$$X_{S} = \begin{cases} \frac{\sqrt{2\phi_{B}}}{[1 + \frac{1}{2}V_{BS}/(2\phi_{B})]} & V_{BS} > 0\\ \sqrt{2\phi_{B} - V_{BS}} & V_{BS} \le 0 \end{cases}$$
(7.323)

where

$$x_n = 1 + F_N - \gamma_{\rm EFF} X_1 - X_2 X_S + W_{\rm EFF} L_{\rm EFF} \frac{q N_{\rm FS}}{C'_{OX}}$$
(7.324)

$$\eta = 1 + F_N \tag{7.325}$$

the effect of channel width on threshold voltage is modeled by

$$V'_{\rm FB} = V_{\rm FB} + F_N (2\phi_B - V_{BS}) \tag{7.326}$$

and the flat band voltage,  $V_{\rm FB}$ , is calculated using (7.272) or (7.273).

$$V_{GST} = V_{GS} - V_{ON} \tag{7.327}$$

The factor describing the effect of channel width on threshold is

$$F_N = \frac{\epsilon_s \delta \pi}{4C'_{OX} W_{\rm EFF}} \tag{7.328}$$

The effective bulk threshold parameter is affected by charge in the drain and source depletion regions. This is important for short channels. The factor describing short channel effects is

$$\gamma_{\rm EFF} = \begin{cases} \gamma & \gamma \le 0 \text{ or } N_B \le 0\\ \gamma(1 - F_{DD} - F_{SD}) & \gamma > 0 \text{ and } N_B > 0 \end{cases}$$
(7.329)

where the effect of depletion charge at the drain is described by

$$F_{DD} = \begin{cases} \frac{1}{2} \left( \sqrt{1 + 2X_D X_B} - 1 \right) & V_{DS} \leq V_{DS,SAT} \\ \frac{1}{2} \left( \sqrt{1 + 2X_D X_{B,SAT}} - 1 \right) \frac{X_J}{L_{EFF}} & V_{DS} > V_{DS,SAT} \end{cases}$$
(7.330)

the effect of depletion charge at the source is described by

$$F_{SD} = \frac{1}{2} \left( \sqrt{1 + 2X_D X_S} - 1 \right) \frac{X_J}{L_{\rm EFF}}$$
(7.331)

and

$$X_{B} = \begin{cases} \frac{\sqrt{2\phi_{B}}}{[1 + \frac{1}{2}(V_{BS} - V_{DS})/(2\phi_{B})]} & V_{DS} < V_{BS} \\ \sqrt{2\phi_{B} + V_{DS} - V_{BS}} & V_{DS} \le V_{BS} \end{cases}$$
(7.332)

and for saturation

$$X_{B,SAT} = \begin{cases} \frac{\sqrt{2\phi_B}}{[1 + \frac{1}{2}(V_{BS} - V_{DS,SAT})/(2\phi_B)]} & V_{DS,SAT} < V_{BS} \\ \sqrt{2\phi_B + V_{DS,SAT} - V_{BS}} & V_{DS,SAT} \ge V_{BS} \end{cases}$$
(7.333)

 $X_S$  is evaluated using (7.323) and  $X_D$  using (7.402).

$$X_{1} = \begin{cases} \frac{-X_{S}^{2}}{2(2\phi_{B})^{(3/2)}} & V_{BS} > 0\\ -\frac{1}{2X_{S}} & V_{BS} \le 0 \end{cases}$$
(7.334)

and

$$X_{2} = \begin{cases} -\gamma \frac{1}{2} \frac{X_{D} X_{1}}{L_{EFF} X_{S}} & X_{J} > 0 \\ 0 & X_{J} \le 0 \end{cases}$$
(7.335)

The effective mobility due to modulation by the gate

$$\mu_{\rm EFF} = \begin{cases} \mu_0 \left( \frac{U_C}{V_{GS} - V_{\rm ON}} \right)^{U_{\rm EXP}} & C_{\rm OX} \neq 0 \text{ and } (V_{GS} - V_{ON}) > U_C \\ \mu_0 & C_{\rm OX} = 0 \text{ or } (V_{GS} - V_{ON}) \le U_C \end{cases}$$
(7.336)

and the factor describing this effect

$$F_G = \frac{\mu_{\rm EFF}}{\mu_0} \tag{7.337}$$

The channel shortening factor

$$F_D = \frac{L_{\rm EFF}}{L'_{EFF}} \tag{7.338}$$

where the effective channel length due to channel shortening is

$$L'_{\rm EFF} = \begin{cases} \frac{X_{WB}}{1 + (\Delta_L - L_{\rm EFF} + X_{WB})/X_{WB}} & (1 - \lambda V_{DS})L_{\rm EFF} < X_{WB} \\ (1 - \lambda V_{DS})L_{\rm EFF} & (1 - \lambda V_{DS})L_{\rm EFF} \ge X_{WB} \end{cases}$$
(7.339)

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The expression for  $L'_{EFF}$  when  $(1 - \lambda V_{DS})L_{EFF} < X_{WB}$  limits channel shortening at punch-through. In (7.339)

$$\Delta_L = \lambda V_{DS} L_{\rm EFF} \tag{7.340}$$

and the distance that the depletion region at the drain extends into the channel is

$$X_{WB} = \begin{cases} X_D \sqrt{\phi_J} & N_B \neq 0\\ 0.25 \ 10^{-6} & N_B = 0 \end{cases}$$
(7.341)

The pinch-off voltage

$$V_{P} = \begin{cases} MAX((V_{GSX} - V'_{FB}), 0) & \frac{\gamma_{EFF}}{\eta} \leq 0 \\ V_{T} & \frac{\gamma_{EFF}}{\eta} > 0 \text{ and } X_{V} \leq 0 \\ V_{T} & \frac{\gamma_{EFF}}{\eta} > 0 \text{ and } X_{3} < 0 \\ V'_{FB} + \eta V_{DS} + \sqrt{X_{3}} & \frac{\gamma_{EFF}}{\eta} > 0 \text{ and } X_{3} \geq 0 \text{ and } X_{V} > 0 \end{cases}$$
(7.342)

where

$$X_3 = (V_{DS} + 2\phi_B - V_{BS}) \left(\frac{\gamma_{\rm EFF}}{\eta}\right)^2 \tag{7.343}$$

The drain-source saturation voltage

$$V_{DS,SAT} = \begin{cases} V_P \text{ (Grove Frohman approximation)} & V_{MAX} \leq 0 \\ V_{DS,SAT} \text{ from Baum's theory of} & V_{MAX} > 0 \\ \text{velocity saturation} \end{cases}$$
(7.344)

In Baum's theory of velocity saturation the saturation voltage,  $V_{DS,SAT}$ , is the solution of the quartic equation

$$aV_{DS,SAT}^4 + bV_{DS,SAT}^3 + cV_{DS,SAT}^2 + dV_{DS,SAT} = 0$$
(7.345)

where

$$a = \frac{3}{4} \frac{\gamma_{\rm EFF}}{\eta} \tag{7.346}$$

$$b = -2(V_1 + V_X) \tag{7.347}$$

$$c = -2\frac{\gamma_{\rm EFF}}{\eta}V_X \tag{7.348}$$

$$d = 2V_1(V_2 + V_X) - V_2^2 - \frac{3}{4} \frac{\gamma_{\text{EFF}}}{\eta} X_S^3$$
(7.349)

$$V_1 = \frac{(V_{GSX} - V'_{FB})}{\eta} + 2\phi_B - V_{BS}$$
(7.350)

$$V_2 = 2\phi_B - V_{BS} \tag{7.351}$$

$$V_X = \frac{V_{\text{MAX}} L_{\text{EFF}}}{\mu_{\text{EFF}}} \tag{7.352}$$

The body effect factor is

$$F_B = X_B^3 - X_S^3 \tag{7.353}$$

and the body effect factor in saturation is

$$F_{B,\rm EFF} = X_{B,\rm SAT}^3 - X_S^3 \tag{7.354}$$

 ${\rm cutoff\ region}$ 

$$I_D = 0 \tag{7.355}$$

PROC	CESS	+	GEOMETRY	$\rightarrow$	DEVICE
PARAM	ETERS		PARAMETERS		PARAMETERS
DELTA	$\delta$		Required		I/V
LAMBDA	$\lambda$		L L		VTO $V_{T0} = f(2\phi_B, N_{SS}, T_{OX})$
NSS	$N_{\rm SS}$		W $W$		$KP    K_P = f(\mu_0, T_{OX})$
NSUB	$N_B$		Optional		PHI $2\phi_B = f(N_B)$
PB	$\phi_J$		LD XII		GAMMA $\gamma = f(\mu_0, T_{OX}, N_B)$
TOX	$T_{OX}$		WD $W_D$		$\{I_D = f(W, L, W_D, X_{JL},$
UCRIT	$U_C$				$K_P, 2\phi_B, \mu_0, \gamma, V_{T0}, \phi_J$
UEXP	$U_{\rm EXP}$				$V_{\text{MAX}}, X_J, \lambda, U_{\text{EXP}}, U_C, \delta) \}$
VMAX	$V_{\rm MAX}$				
UO	$\mu_0$				
XJ	$X_J$				

Figure 7.53: MOSFET LEVEL 2 I/V parameter relationships.

linear region

$$I_D = K_P \frac{W_{\rm EFF}}{L_{\rm EFF}} F_G F_D \left[ \left( V_{GS} - V_{\rm FB}' - \frac{\eta}{2} V_{DS} \right) V_{DS} - \frac{3}{2} \frac{\gamma_{\rm EFF}}{\eta} F_B \right]$$
(7.356)

weak inversion region

When  $V_{GS}$  is slightly above  $V_T$ ,  $I_D$  increases slowly over a few thermal voltages  $V_{TH}$  in exponential manner becoming  $I_D$  calculated for strong inversion. This effect is handled empirically by defining two exponential which, as well as ensuring an exponential increase in  $I_D$ , also ensure that the transconductance  $G_M$  (=  $\partial I_D / \partial V_{GS}$ ) is continuous at  $V_{GS} = V_{ON}$ .

$$I_D = \begin{cases} I_{D,\text{ON}} \left[ \frac{10}{11} e^{(V_{GS} - V_{\text{ON}}) / (x_n V_{TH})} + \frac{1}{11} e^{\alpha (V_{GS} - V_{\text{ON}})} \right] & \alpha > 0 \\ I_{D,\text{ON}} e^{(V_{GS} - V_{\text{ON}}) / (x_n V_{TH})} & \alpha \le 0 \end{cases}$$
(7.357)

where

$$\alpha = 11 \left( \frac{G_{M,\text{ON}}}{I_{D,\text{ON}}} - \frac{1}{x_n V_{\text{TH}}} \right)$$
(7.358)

$$G_{M,\rm ON} = \frac{\partial I_{D,\rm ON}}{\partial V_{GS}} \tag{7.359}$$

$$I_{D,ON} = \begin{cases} I_D \text{ in } (7.356) \text{ with } V_{GS} = V_{ON} & V_{DS} \le V_{DS,SAT} \\ I_D \text{ in } (7.361) \text{ with } V_{GS} = V_{ON} \text{ and } V_{DS} = V_{DS,SAT} & V_{DS} \le V_{DS,SAT} \end{cases}$$
(7.360)

saturation region

$$I_D = \frac{L_{\rm EFF}}{L_{\rm EFF-\Delta_L}} I_{D,\rm SAT}$$
(7.361)

$$I_{D,\text{SAT}} = K_P \frac{W_{\text{EFF}}}{L_{\text{EFF}}} F_G F_D \left[ \left( V_{GS} - V_{\text{FB}}' - \frac{\eta}{2} V_{DS,\text{SAT}} \right) V_{DS,\text{SAT}} - \frac{3}{2} \frac{\gamma_{\text{EFF}}}{\eta} F_{B,\text{SAT}} \right]$$
(7.362)

The LEVEL 3 current-voltage parameter dependencies are summarized in figure 7.53.

## LEVEL 2 Overlap Capacitances

In the LEVEL 2 model the gate overlap capacitances as strong functions of voltage. Two overlap capacitance models are available in PSPICEthe Meyer model based on the model originally proposed by Meyer [4] and the Ward-Dutton model [5,6]. SPICE2G6 and SPICE3 use just the Meyer model. The Meyer and Ward-Dutton models differ in the derivation of the channel charge.

#### LEVEL 2 Meyer Model

This model is selected when the parameter  $XQC = X_{QC}$  is not specified or  $X_{QC} < 0.5$ .

The voltage dependent thin-oxide capacitances are used only if  $T_{OX}$  is specified in the model statement. Four operating regions are defined in the Meyer model:

accumulation region:	$V_{GS} < V_{\rm ON} - 2\phi_B$
depletion region:	$V_{\rm ON} - 2\phi_B < V_{GS} < V_{\rm ON}$
saturation region:	$V_{\rm ON} < V_{GS} < V_{\rm ON} + V_{DS}$
linear region:	$V_{GS} > V_{ON} + V_{DS}$

where

$$V_{\rm ON} = \begin{cases} V_T + x_n V_{\rm TH} & \text{if } N_{\rm FS} = \text{NFS specified} \\ V_T & \text{if } N_{\rm FS} = \text{NFS not specified} \end{cases}$$
(7.363)

$$V_T = V_{T0} + \gamma \left[ \sqrt{2\phi_B - V_{BS}} - \sqrt{2\phi_B} \right]$$
(7.364)

$$x_n = 1 + \frac{qN_{\rm FS}}{C'_{OX}} + \frac{C_D}{C'_{OX}}$$
(7.365)

$$C'_{OX} = \frac{\epsilon_{OX}}{T_{OX}} \tag{7.366}$$

$$C_{OX} = C'_{OX} W_{\text{EFF}} L_{\text{EFF}}$$

$$C_{D} = \frac{\gamma}{2\sqrt{2/-V_{\text{EFF}}}}$$

$$(7.367)$$

$$(7.368)$$

$$a_{D} = \frac{1}{2\sqrt{2\phi_B - V_{BS}}}$$
 (7.368)

$$C_{GS} = \begin{cases} C_{GSO}W & \text{accumulation region} \\ \frac{2}{3}C_{OX}\left(1 + \frac{V_{ON} - V_{GS}}{2\phi_B}\right) + C_{GSO}W_{EFF} & \text{depletion region} \\ \frac{2}{3}C_{OX} + C_{GSO}W_{EFF} & \text{saturation region} \\ C_{OX}\left\{1 - \left[\frac{V_{GS} - V_{DS} - V_{ON}}{2(V_{GS} - V_{ON}) - V_{DS}}\right]^2\right\} + C_{GSO}W_{EFF} & \text{linear region} \end{cases}$$
(7.369)

$$C_{GD} = \begin{cases} C_{GDO}W_{\rm EFF} & \text{accumulation region} \\ C_{GDO}W_{\rm EFF} & \text{depletion region} \\ C_{GDO}W_{\rm EFF} & \text{saturation region} \\ C_{OX} \left\{ 1 - \left[ \frac{V_{GS} - V_{\rm ON}}{2(V_{GS} - V_{\rm ON}) - V_{DS}} \right]^2 \right\} + C_{GDO}W_{\rm EFF} & \text{linear region} \end{cases}$$
(7.370)

$$C_{GB} = \begin{cases} C_{OX} + C_{GBO}L_{\rm EFF} & \text{accumulation region} \\ C_{OX} \left(\frac{V_{\rm ON} - V_{GS}}{2\phi_B}\right) + C_{GBO}L_{\rm EFF} & \text{depletion region} \\ C_{GBO}L_{\rm EFF} & \text{saturation region} \\ C_{GBO}L_{\rm EFF} & \text{linear region} \end{cases}$$
(7.371)

LEVEL 2 Ward-Dutton Model PSPICE only

This model is selected when the parameter XQC is specified and less than 0.5. The charge in the gate  $Q_G$  and the substrate  $Q_B$  is calculated and the difference of these is taken as the channel charge  $Q_{\text{CHANNEL}}$ . This charge is then partitioned and allocated between the source as  $Q_S$  and the drain  $Q_D$  as follows:

$$Q_{\text{CHANNEL}} = Q_D + Q_S \tag{7.372}$$

$$Q_D = X_{QC}Q_{\text{CHANNEL}} \tag{7.373}$$

(7.374)

so that  $Q_S = (1 - X_{QC})Q_{\text{CHANNEL}}$ . This partitioning is somewhat arbitrary but produces transient results that more closely match measurements than does the Meyer capacitance model. However this is at the price of poorer convergence properties and sometimes error. This is particularly so when  $V_{DS}$  is changing sign.

Two operating regions are defined in the Ward-Dutton model:

off region: 
$$V_{GS} \le V_T$$
  
on region:  $V_{GS} > V_T$ 

where

$$V_T = V_{T0} + \gamma \left[ \sqrt{2\phi_B - V_{BS}} - \sqrt{2\phi_B} \right]$$
(7.375)

$$C_{OX} = C'_{OX} W_{\rm EFF} L_{\rm EFF} \tag{7.376}$$

$$C'_{OX} = \frac{\epsilon_{OX}}{T_{OX}} \tag{7.377}$$

(7.378)

In the charge evaluations the following terms are used:

$$v_G = v_{GB} - V'_{FB} + 2\phi_B \tag{7.379}$$

$$v_D = \begin{cases} 2\phi_B - v_{BD} & v_{BD} > 2\phi_B \\ 0 & v_{BD} \le 2\phi_B \end{cases}$$
(7.380)

$$v_{S} = \begin{cases} 2\phi_{B} - v_{BS} & v_{BS} > 2\phi_{B} \\ 0 & v_{BS} \le 2\phi_{B} \end{cases}$$
(7.381)

$$v_E = \begin{cases} v_D & v_D < v_{DS,SAT} \\ v_{DS,SAT} & v_D \ge v_{DS,SAT} \end{cases}$$
(7.382)

$$x_5 = (v_E + v_S)(\sqrt{v_E} + \sqrt{v_S}) \tag{7.383}$$

$$x_6 = ((v_E^2 + v_S^2) + v_E v_S) + \sqrt{v_E} \sqrt{v_S} (v_E + v_S)$$
(7.384)

$$D = v_G(\sqrt{v_E} + \sqrt{v_S}) - \gamma_{\rm EFF}((v_E + v_S) + \sqrt{v_E}\sqrt{v_S})/1.5 -.5(\sqrt{v_E} + \sqrt{v_S})(v_E + v_S)$$
(7.385)

where  $V'_{FB}$  is defined in (7.326) and  $V_{DS,SAT}$  in (7.344). off region

$$Q_G = \begin{cases} \gamma_{\rm EFF} C_{OX} (\sqrt{\frac{1}{4} \gamma_{\rm EFF}^2 + v_G} - \gamma_{\rm EFF}/2) & v_G > 0\\ C_{OX} v_G & v_G \le 0 \end{cases}$$
(7.386)

$$Q_B = -Q_G \tag{7.387}$$

$$Q_{\text{CHANNEL}} = -(Q_G + Q_B) \tag{7.388}$$

on region

PRC	OCESS	+	GEOMETRY	$\rightarrow$	DEVICE	
PARAM	METERS		PARAMETERS		PARAMETERS	
CJ	$C_J$		AD $A_D$		Constant Overlap	
CJSW	$C_{J,\mathrm{SW}}$		AS $A_S$		Capacitances	
MJ	$M_J$		PD $A_D$		CGSO	$C_{GSO}$
MJSW	$M_{J,SW}$		PS $A_S$	J	CGDO	$C_{GDO}$
PB	$\phi_J$				CGBO	$C_{GBO}$
PBSW	$\phi_J$					
FC	$\phi_J$					

Figure 7.54: MOSFET LEVEL 2 overlap capacitance parameter relationships.

$$Q_{B} = -\gamma_{\rm EFF} C_{OX} \left( \frac{v g_{3}^{2} ((v_{E} + v_{S}) + \sqrt{v_{E}} \sqrt{v_{S}}) - \frac{1}{2} \gamma_{\rm EFF} x_{5} - .4 x_{6}}{D} \right)$$

$$Q_{G} = C_{OX}$$
(7.389)

$$\begin{pmatrix} vg - \frac{.5vgx_5 - .4\gamma_{\rm EFF}x_6 - ((v_E^2 + v_S^2) + v_E v_S)(\sqrt{v_E} + \sqrt{v_S})/3}{D} \end{pmatrix}$$
(7.390)

where  $V_{FB}^{\prime}$  is defined in (7.326). The overlap capacitances are then evaluated as

$$C_{GDB} = \partial Q_G / \partial v_D \tag{7.391}$$
  

$$C_{GSB} = \partial Q_G / \partial v_S \tag{7.392}$$

$$C_{GSB} = \partial Q_G / \partial v_S \tag{7.392}$$

$$C_{CCP} = \partial Q_C / \partial v_C \tag{7.393}$$

$$C_{GGB} = \partial Q_G / \partial v_G \tag{7.393}$$
$$C_{BDB} = \partial Q_B / \partial v_D \tag{7.394}$$

$$C_{BSB} = \partial Q_B / \partial v_S$$

$$(7.395)$$

$$C_{BGB} = \partial Q_B / \partial v_G \tag{7.396}$$

The LEVEL 2 overlap capacitance parameter dependencies are summarized in figure 7.54.

#### LEVEL 3 I/V Characteristics

The LEVEL 3 I/V characteristics are based on empirical fits resulting in a more accurate description of the I/V response than obtained with the LEVEL 2 model. The LEVEL 3 current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point. Normal Mode: ( $V_{DS} \ge 0$ )

The regions are as follows:

 $\begin{array}{ll} \mbox{cutoff region:} & V_{GS} < V_T \\ \mbox{weak inversion region:} & V_T < V_{GS} \leq V_{\rm ON} \\ \mbox{linear region (strong inversion):} & V_{GS} > V_{\rm ON} \mbox{ and } V_{DS} < V_{DS,\rm SAT} \\ \mbox{saturation region (strong inversion):} & V_{GS} > V_{\rm ON} \mbox{ and } V_{DS} > V_{DS,\rm SAT} \\ \mbox{where} & \end{array}$ 

$$V_T = V_{T0} - \sigma V_{DS} + F_C \tag{7.397}$$

the effect of short and narrow channel on threshold voltage

$$F_C = \gamma F_S \sqrt{2\phi_B - V_{BS}} + F_N (2\phi_B - V_{BS})$$
(7.398)

and

$$V_{\rm ON} = \begin{cases} V_T & NFS = 0\\ V_T + V_{TH}x_n & NFS \neq 0 \end{cases}$$
(7.399)

The effect of the short channel is described by

$$F_{S} = 1 - \frac{X_{J}}{L_{\rm EFF}} \left( \frac{X_{JL} + W_{C}}{X_{J}} \sqrt{1 - \frac{W_{P}}{X_{J} + W_{P}}} - \frac{X_{JL}}{X_{J}} \right)$$
(7.400)

where

$$W_P = X_D \sqrt{\phi_J - V_{BS}} \tag{7.401}$$

$$X_D = \sqrt{\frac{2\epsilon_s}{qN_B}} \tag{7.402}$$

$$W_C = X_J \left[ 0.0831353 + 0.8013929 \frac{W_P}{X_J} + 0.0111077 \frac{W_P}{X_J} \right]$$
(7.403)

and

$$\sigma = \eta \frac{8.15^{-22}}{C'_{OX} L_{\rm EFF}^3} \tag{7.404}$$

The effect of channel width on threshold is

$$F_N = \frac{\epsilon_s \delta \pi}{4C'_{OX} W_{\rm EFF}} \tag{7.405}$$

The effective mobility due to modulation by the gate

$$\mu_S = \mu_0 F_G \tag{7.406}$$

and the factor describing mobility modulation by the gate is

$$F_G = \frac{1}{1 + \theta(V_{GSX} - V_T)}$$
(7.407)

where

$$V_{GSX} = \begin{cases} V_{GS} & V_{GS} < V_{ON} \\ V_{ON} & V_{GS} \ge V_{ON} \end{cases}$$
(7.408)

#### MOSFET

The drain-source saturation voltage

$$V_{DS,SAT} = \begin{cases} V_A + V_B - \sqrt{V_A^2 + V_B^2} & V_{MAX} > 0\\ V_P & V_{MAX} \le 0 \end{cases}$$
(7.409)

where

$$V_A = \frac{V_{GSX} - V_T}{1 + F_B} \tag{7.410}$$

$$V_B = \frac{v_{\text{MAX}} L_{\text{EFF}}}{\mu_S} \tag{7.411}$$

$$V_P = V_{GSX} - V_T \tag{7.412}$$

The body effect factor

$$F_B = \frac{\gamma F_S}{4\sqrt{\phi_{BS}}} + F_N \tag{7.413}$$

where

$$\phi_{BS} = \begin{cases} 2\phi_B - V_{BS} & V_{BS} \le 0\\ \frac{2\phi_B}{\sqrt{1 + \frac{1}{2}V_{BS}/(2\phi_B)}} & V_{BS} > 0 \end{cases}$$
(7.414)

The velocity saturation factor is

$$F_D = \begin{cases} \frac{1}{1 + V_{DS}/V_B} & \text{for} V_{\text{MAX}} \neq 0\\ 1 & \text{for} V_{\text{MAX}} = 0 \end{cases}$$
(7.415)

cutoff region

$$I_D = 0$$
 (7.416)

linear region

$$I_{D} = K_{P} \frac{W_{\rm EFF}}{L_{\rm EFF}} F_{G} F_{D} \left[ V_{GSX} - V_{T} - \frac{1 + F_{\rm B}}{2} V_{DS} \right] V_{DS}$$
(7.417)

weak inversion region

When  $V_{GS}$  is slightly above  $V_T$ ,  $I_D$  increases slowly over a few thermal voltages  $V_{\text{TH}}$  in exponential manner becoming  $I_D$  calculated for strong inversion. This effect is handled empirically by defining two exponential which, as well as ensuring an exponential increase in  $I_D$ , also ensure that the transconductance  $G_M$  (=  $\partial I_D / \partial V_{GS}$ ) is continuous at  $V_{GS} = V_{\text{ON}}$ .

$$I_{D} = \begin{cases} I_{D,\text{ON}} \left[ \frac{10}{11} e^{(V_{GS} - V_{\text{ON}})/(x_{n}V_{TH})} + \frac{1}{11} e^{\alpha(V_{GS} - V_{\text{ON}})} \right] & \alpha > 0 \\ \\ I_{D,\text{ON}} e^{(V_{GS} - V_{\text{ON}})/(x_{n}V_{TH})} & \alpha \le 0 \end{cases}$$
(7.418)

where

$$\alpha = 11 \left( \frac{G_{M,\text{ON}}}{I_{D,\text{ON}}} - \frac{1}{x_n V_{\text{TH}}} \right)$$
(7.419)

$$G_{M,\rm ON} = \frac{\partial I_{D,\rm ON}}{\partial V_{GS}} \tag{7.420}$$

and

$$I_{D,ON} = \begin{cases} I_D \text{ in } (7.417) \text{ with } V_{GS} = V_{ON} & V_{DS} \le V_{DS,SAT} \\ I_D \text{ in } (7.422) \text{ with } V_{GS} = V_{ON} \text{ and } V_{DS} = V_{DS,SAT} & V_{DS} \le V_{DS,SAT} \end{cases}$$
(7.421)

PROC	CESS	$\pm$	GEO	METRY		DEVICE
PARAM	ETERS		PARA	METERS	, ,	PARAMETERS
KAPPA	$\kappa$		Re	equired		I/V
NSS	$N_{\rm SS}$		L	L		VTO $V_{T0} = f(2\phi_B, N_{SS}, T_{OX})$
NSUB	$N_B$		W	W		KP $K_P = f(\mu_0, T_{OX})$
PB	$\phi_J$		Oı	otional		PHI $2\phi_B = f(N_B)$
THETA	$\theta$		LD	X 11		GAMMA $\gamma = f(\mu_0, T_{OX}, N_B)$
TOX	$T_{OX}$		WD	$W_D$		$\{I_D = f(W, L, W_D, X_{JL})$
UO	$\mu_0$				1	$K_P, 2\phi_B, N_B, T_{OX}, \mu_0, \theta$
VMAX	$V_{\rm MAX}$					$\gamma, V_{T0}, \phi_J, V_{MAX}, X_J, \kappa, \eta) \}$
XJ	$X_J$					

Figure 7.55: MOSFET LEVEL 3 I/V parameter relationships.

saturation region

$$I_D = \frac{L_{\rm EFF}}{L_{\rm EFF} - \Delta_L} I_{D,\rm SAT} \tag{7.422}$$

$$I_{D,SAT} = K_P \frac{W_{EFF}}{L_{EFF}} F_G F_D \left[ V_{GSX} - V_T - \frac{1+F_B}{2} V_{DS,SAT} \right] V_{DS,SAT}$$
(7.423)

The reduction in the channel length due to  $V_{DS}$  modulation is

$$\Delta_L = \begin{cases} \Delta'_L & \Delta'_L < \frac{1}{2}L_{\rm EFF} \\ L_{\rm EFF} - \frac{L_{\rm EFF}}{\Delta'_L} & \Delta'_L \ge \frac{1}{2}L_{\rm EFF} \end{cases}$$
(7.424)

where the punch through approximation is used for  $\Delta'_L \geq \frac{1}{2}L_{\text{EFF}}$ . In (7.424) the distance that the depletion region at the drain extends into the channel is

$$\Delta'_{L} = \sqrt{\left(\frac{E_{P}X_{D}^{2}}{2}\right)^{2} + \kappa X_{D}^{2}(V_{DS} - V_{DS,SAT})} - \frac{E_{P}X_{D}^{2}}{2}$$
(7.425)

and

$$E_P = \frac{I_{D,\text{SAT}}}{G_{DS,\text{SAT}}L_{\text{EFF}}} \tag{7.426}$$

Here

$$G_{DS,\text{SAT}} = \frac{\partial I_{D,\text{SAT}}}{\partial V_{DS,\text{SAT}}}$$
(7.427)

The LEVEL 3 current-voltage parameter dependencies are summarized in Figure 7.55.

## LEVEL 3 Overlap Capacitances

In the LEVEL 3 model the gate overlap capacitances as strong functions of voltage. Two overlap capacitance models are available the Meyer model based on the model originally proposed by Meyer [4] and the Ward-Dutton model [5,6]. These models differ in the derivation of the channel charge.

### LEVEL 3 Meyer Model

This model is selected when the parameter  $XQC = X_{QC}$  is not specified or  $X_{QC} < 0.5$ . The voltage dependent thin-oxide capacitances are used only if  $T_{OX}$  is specified in the model statement. Four operating regions are defined in the Meyer model:

$V_{GS} < V_{\rm ON} - 2\phi_B$
$V_{\rm ON} - 2\phi_B < V_{GS} < V_{\rm ON}$
$V_{\rm ON} < V_{GS} < V_{\rm ON} + V_{DS}$
$V_{GS} > V_{\rm ON} + V_{DS}$

where

$$V_{\rm ON} = \begin{cases} V_T + x_n V_{\rm TH} & \text{if } N_{\rm FS} = \text{NFS specified} \\ V_T & \text{if } N_{\rm FS} = \text{NFS not specified} \end{cases}$$
(7.428)

$$V_T = V_{T0} + \gamma \left[ \sqrt{2\phi_B - V_{BS}} - \sqrt{2\phi_B} \right]$$
(7.429)

$$x_n = 1 + \frac{qN_{\rm FS}}{C'_{OX}} + \frac{C_D}{C'_{OX}}$$
(7.430)

$$C'_{OX} = \frac{\epsilon_{OX}}{T_{OX}} \tag{7.431}$$

$$C_{OX} = C'_{OX} W_{\text{EFF}} L_{\text{EFF}}$$

$$C_{D} = \frac{\gamma}{2\sqrt{2}}$$
(7.432)
(7.433)

$$C_D = \frac{V}{2\sqrt{2\phi_B - V_{BS}}}$$
(7.433)

$$C_{GS} = \begin{cases} C_{GSO}W & \text{accumulation region} \\ \frac{2}{3}C_{OX}\left(1 + \frac{V_{ON} - V_{GS}}{2\phi_B}\right) + C_{GSO}W_{\text{EFF}} & \text{depletion region} \\ \frac{2}{3}C_{OX} + C_{GSO}W_{\text{EFF}} & \text{saturation region} \\ C_{OX}\left\{1 - \left[\frac{V_{GS} - V_{DS} - V_{ON}}{2(V_{GS} - V_{ON}) - V_{DS}}\right]^2\right\} + C_{GSO}W_{\text{EFF}} & \text{linear region} \end{cases}$$
(7.434)

$$C_{GD} = \begin{cases} C_{GDO}W_{\rm EFF} & \text{accumulation region} \\ C_{GDO}W_{\rm EFF} & \text{depletion region} \\ C_{GDO}W_{\rm EFF} & \text{saturation region} \\ C_{OX} \left\{ 1 - \left[ \frac{V_{GS} - V_{\rm ON}}{2(V_{GS} - V_{\rm ON}) - V_{DS}} \right]^2 \right\} + C_{GDO}W_{\rm EFF} & \text{linear region} \\ C_{GB} = \begin{cases} C_{OX} + C_{GBO}L_{\rm EFF} & \text{accumulation region} \\ C_{OX} \left( \frac{V_{ON} - V_{GS}}{2\phi_B} \right) + C_{GBO}L_{\rm EFF} & \text{depletion region} \\ C_{GBO}L_{\rm EFF} & \text{saturation region} \\ C_{GBO}L_{\rm EFF} & \text{saturation region} \\ \end{array}$$
(7.436)

LEVEL 3 Ward-Dutton Model

This model is selected when the parameter XQC is specified and less than 0.5. The charge in the gate  $Q_G$  and the substrate  $Q_B$  is calculated and the difference of these is taken as the channel charge  $Q_{\text{CHANNEL}}$ . This charge is then partitioned and allocated between the source as  $Q_S$  and the drain  $Q_D$  as follows:

$$Q_{\text{CHANNEL}} = Q_D + Q_S \tag{7.437}$$

$$Q_D = X_{QC} Q_{\text{CHANNEL}} \tag{7.438}$$

(7.439)

so that  $Q_S = (1 - X_{QC})Q_{\text{CHANNEL}}$ . This partitioning is somewhat arbitrary but produces transient results that more closely match measurements than does the Meyer capacitance model. However this is at the price of poorer convergence properties and sometimes error. This is particularly so when  $V_{DS}$  is changing sign. Two operating regions are defined in the Ward-Dutton model:

off region: 
$$V_{GS} \leq V'_T$$
  
on region:  $V_{GS} > V'_T$ 

where

$$V_T' = v_{BIX} + F_C \tag{7.440}$$

$$v_{BIX} = V_{FB} - \sigma V_{DS} \tag{7.441}$$

 $F_C$  is defined in (7.398),  $\sigma$  in (7.404) and  $V_{FB}$  is defined in (7.272) or (7.272). off region

$$Q_{G} = \begin{cases} \gamma F_{S} C_{OX} \left[ \sqrt{\left(\frac{\gamma F_{S}}{2}\right)^{2} + (v_{GB} - V_{FB} + 2\phi_{B})} - \frac{\gamma F_{S}}{2} \right] \\ v_{GB} > (V_{FB} - 2\phi_{B}) \\ C_{OX} (v_{GB} - V_{FB} + 2\phi_{B}) \\ v_{GB} \le (V_{FB} - 2\phi_{B}) \end{cases}$$
(7.442)  
$$Q_{B} = -Q_{G}$$
(7.443)

on region

PROCESS						
PARAMETERS						
NSUB	$N_B$					
CJ	$C_J$					
CJSW	$C_{J,\mathrm{SW}}$					
MJ	$M_J$					
MJSW	$M_{J,\rm SW}$					
PB	$\phi_J$					
PBSW	$\phi_{J,\mathrm{SW}}$					
FC	$F_C$					

GEOMETRY	$\rightarrow$		DEVICE
PARAMETERS			PARAMETERS
AD $A_D$		Constant Overlap	
AS $A_S$			Capacitances
PD $P_D$		CGSO	$C_{GSO}$
PS $P_S$		CGDO	$C_{GDO}$
		CGBO	$C_{GBO}$

Figure 7.56: MOSFET LEVEL 3 overlap capacitance parameter relationships.

$$Q_G = \begin{cases} C_{OX}(V_{GS} - V_{FB}) & V_{DSX} = 0\\ C_{OX}(V_{GS} - v_{BIX} - \frac{1}{2}V_{DSX} + x_a) & V_{DSX} \neq 0 \end{cases}$$
(7.444)

$$Q_B = \begin{cases} -C_{\text{OX}}F_C & V_{DSX} = 0\\ -C_{\text{OX}}(F_C + \frac{1}{2}F_B V_{DSX} - x_a F_B) & V_{DSX} \neq 0 \end{cases}$$
(7.445)

where

$$x_a = \frac{(1+F_B)V_{DSX}^2}{12V_{GSX} - V_T' - \frac{1}{2}(1+F_B)V_{DSX}}$$
(7.446)

$$Q_{\text{CHANNEL}} = -(Q_G + Q_B) \tag{7.447}$$

where  $F_B$  is defined in (7.413),  $V_{GSX}$  in (7.408) and

+

$$V_{DSX} = \begin{cases} V_{DS,SAT} & V_{DS} > V_{D,SAT} \\ V_{DS} & V_{DS} \le V_{D,SAT} \end{cases}$$
(7.448)

The overlap capacitances are then evaluated as

$$C_{GDB} = \partial Q_G / \partial v_D \tag{7.449}$$

$$C_{GSB} = \partial Q_G / \partial v_S \tag{7.450}$$

$$C_{GGB} = \partial Q_G / \partial v_G \tag{7.451}$$

$$C_{BDB} = \partial Q_B / \partial v_D \tag{7.452}$$

$$C_{BSB} = \partial Q_B / \partial v_S \tag{7.453}$$

$$C_{BGB} = \partial Q_B / \partial v_G \tag{7.454}$$

The overlap capacitance parameter dependencies are summarized in figure 7.56.

# BSIM (LEVEL 4) MOSFET models.

The parameters of the BSIM (LEVEL 4 model are all values obtained from process characterization, and can be generated automatically. J. Pierret [10] describes a means of generating a 'process' file, and the program Proc2Mod provided in the UC Berkeley standard SPICE3 distribution converts this file into a sequence of .MODEL lines suitable for inclusion in a SPICE circuit file. Parameters marked below with an \* in the L/W column also have corresponding parameters with a length and width dependency.

Unlike most other models the BSIM model is designed for use with a process characterization system that provides all the parameters, thus there are no defaults for the parameters, and leaving one out is considered an error.

Name	Description	Units	Default	L/W
AO	drain saturation current for $V_{GS} = 0$ (LEVEL=4)	А	0.1	
	(VERSION: SOMEVERSIONSOFSPICE) $(A_0)$			
A1	coefficient of $V_1$ (primary transconductance parameter)			
CGBO	gate-bulk overlap capacitance per meter channel length	F/m	REQUIRED	
	$(PARASITIC)   (C_{GBO})$			
CGDO	gate-drain overlap capacitance per meter channel width	F/m	REQUIRED	
	$(PARASITIC)   (C_{GDO})$			
CGSO	gate-source overlap capacitance per meter channel width	F/m	REQUIRED	
	$(PARASITIC)   (C_{GSO})$			
CJ	source-drain junction capacitance per unit area	$F/m^2$	REQUIRED	
	(PARASITIC) $(C_J)$			
CJSW	source-drain junction sidewall capacitance per unit length	F/m	REQUIRED	
	(PARASITIC) $(C_{J,SW})$			
DL	shortening of channel $(\Delta_L)$	$\mu \mathrm{m}$	REQUIRED	
DW	narrowing of channel $(\Delta_W)$	$\mu \mathrm{m}$	REQUIRED	
DELL	source-drain junction length	m	REQUIRED	
	reduction (DELL)			
ETA	zero-bias drain-induced barrier lowering coefficient $(\eta)$	-	REQUIRED	*
JS	source-drain junction current	$A/m^2$	REQUIRED	
	density $(J_S)$			
K1	body effect coefficient $(K_1)$	$V^{\frac{1}{2}}$	REQUIRED	*
К2	drain/source depletion charge sharing	-	REQUIRED	*
	coefficient $(K_2)$			
MJ	grading coefficient of source-drain junction $(M_J)$	-	REQUIRED	
MJSW	grading coefficient of source-drain junction sidewall	-	REQUIRED	
	$(M_{J,\mathrm{SW}})$			
MUS	mobility at zero substrate bias and at $V_{DS} = V_{DD}$ ( $\mu_S$ )	$\mathrm{cm}^2/\mathrm{V}^2\mathrm{s}$	REQUIRED	*
MUZ	zero-bias mobility $(\mu_Z)$	$\mathrm{cm}^2/\mathrm{Vs}$	REQUIRED	
NO	zero-bias subthreshold slope coefficient (N-zero) $(N_0)$	-	REQUIRED	*
NB	sensitivity of subthreshold slope to substrate bias	-	REQUIRED	*
	$(PARASITIC) \qquad (N_B)$			
ND	sensitivity of subthreshold slope to drain bias $(N_D)$	-	REQUIRED	*
		•	Continued or	next page

Table 7.10: SPICE BSIM (level 4) parameters.

Name	Description	Units	Default	L/W
PB	built in potential of source/	V	REQUIRED	
	drain junction $(\phi_J)$			
PBSW	built in potential of source/	V	REQUIRED	
	drain juntion sidewall			
	(PARASITIC) $(\phi_{J,SW})$			
PHI	surface inversion potential $(2\phi_B)$	V	REQUIRED	*
RSH	drain and source diffusion sheet resistance	$\Omega$ -square	REQUIRED	
	$(PARASITIC)   (R_{SH})$			
TEMP	temperature at which parameters were measured $(T)$	С	REQUIRED	
TOX	gate oxide thickness $(T_{OX})$	$\mu m$	REQUIRED	
UO	zero-bias transverse-field mobility degradation coefficient	$V^{-1}$	REQUIRED	*
	$(U-zero$ $(U_0)$			
U1	zero-bias velocity saturation coefficient $(U_1)$	$\mu m/V$	REQUIRED	*
VDD	measurement bias range $(V_{DD})$	V	REQUIRED	
WDF	source-drain junction default width	m	REQUIRED	
	$(W_{ m DF})$			
VFB	flat-band voltage $(V_{\rm FB})$	V	REQUIRED	*
X2E	sensitivity of drain-induced barrier lowering	$V^{-1}$	REQUIRED	*
	effect to substrate bias $(X_{2E})$			
X2MS	sensitivity of mobility to substrate bias at $V_{DS} = V_{DD}$	$\mathrm{cm}^2/\mathrm{V}^2\mathrm{s}$	REQUIRED	*
	$(X_{2\rm MS})$			
X2MZ	sensitivity of mobility to substrate bias at $V_{DS} = 0$ (X <sub>2MZ</sub> )	$\mathrm{cm}^2/\mathrm{V}^2\mathrm{s}$	REQUIRED	*
X2U0	sensitivity of transverse field mobility	$V^{-2}$	REQUIRED	*
	degradation effect to substrate bias			
	$(X2U-zero)   (X_{2U0})$			
X2U1	sensitivity of velocity saturation effect to substrate bias	$\mu m V^{-2}$	REQUIRED	*
	$(X_{2U1})$			
X3E	sensitivity of drain-induced barrier lowering effect to drain	$V^{-1}$	REQUIRED	*
	bias at $V_{DS} = V_{DD}$ $(X_{3E})$			
X3MS	sensitivity of mobility to drain bias at $V_{DS} = V_{DD}$ (X <sub>3MS</sub> )	$\mathrm{cm}^2/\mathrm{V}^2\mathrm{s}$	REQUIRED	*
X3U1	sensitivity of velocity saturation effect on drain bias at $V_{DS}$	$\mu V^{-2}$	REQUIRED	*
	$=V_{DD} \tag{X_{3U1}}$			
XPART	gate oxide capacitance charge partition model flag	-	REQUIRED	
	$(X_{\mathrm{PART}})$			
	XPART = 0: selects a 40:60 drain:source			
	charge partition			
	XPART = 1: selects a 0:100 drain:source			
	charge partition			

Table 7.10: SPICE BSIM (level 4) parameters.

Table 7.11 continued: BSIM (LEVEL) 4 model keywords, extensions.

Name	Description		Units	Default
AF	flicker noise exponent	$(A_F)$	-	1
CBD	zero-bias B-D junction capacitance	$(C_{BD}')$	F	0
CBS	zero-bias B-S junction capacitance	$(C_{BS}')$	F	0
FC	coefficient for forward-bias depletion capacitance		-	0.5
	formula	$(F_C)$		
IS	bulk junction saturation current	$(I_S)$	А	1E-14
KF	flicker noise coefficient	$(K_F)$	-	0
L	channel length	(L)	m	DEFL
N	bulk $p$ - $n$ emission coefficient		-	0
	(PARASITIC)	(N)		
PBSW	bulk $p$ - $n$ sidewall potential		V	PB
	(PARASITIC)	$(\phi_{J,SW})$		

Table 7.11: SPICE BSIM	(level 4)	parameters,	extensions.
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Name	Description	Units	Default
JSSW	bulk junction sidewall current per unit length	A/m	0
	(PARASITIC) $(J_{S,SW})$		
RB	bulk ohmic resistance	Ω	0
	(PARASITIC) $(R_B)$		
RD	drain ohmic resistance	Ω	0
	(PARASITIC) $(R_D)$		
RDS	drain-source shunt resistance $(R_{DS})$	Ω	0
RG	gate ohmic resistance	Ω	0
	(PARASITIC) $(R_B)$		
RS	source ohmic resistance	Ω	0
	(PARASITIC) $(R_S)$		
TT	bulk <i>p</i> - <i>n</i> transit time $( au_T)$	S	0
W	channel width (W)	m	DEFL

# AC Analysis

The AC analysis uses the model of figure 7.46 with the capacitor values evaluated at the  $\tt DC$  operating point with  $$\tt at$$ 

$$g_m = \frac{\partial I_{DS}}{\partial V_{GS}} \tag{7.455}$$

 $\quad \text{and} \quad$ 

$$R_{DS} = \frac{\partial I_{DS}}{\partial V_{DS}} \tag{7.456}$$

#### MOSFET

# Noise Analysis

The MOSFET noise model accounts for thermal noise generated in the parasitic resistances and shot and flicker noise generated in the drain source current generator. The rms (root-mean-square) values of thermal noise current generators shunting the four parasitic resistance  $R_B$ ,  $R_D$ ,  $R_G$  and  $R_S$  are

$$I_{n,B} = \sqrt{4kT/R_B} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.457}$$

$$I_{n,D} = \sqrt{4kT/R_D} \,\mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.458}$$

$$I_{n,G} = \sqrt{4kT/R_G} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.459}$$

$$I_{n,S} = \sqrt{4kT/R_S} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.460}$$

The rms value of noise current generators in series with the drain-source current generator

$$I_{n,DS} = \left(I_{\text{SHOT},DS}^2 + I_{\text{FLICKER},DS}^2\right)^{1/2}$$
(7.461)

$$I_{\text{SHOT},DS} = \sqrt{4kTg_m \frac{2}{3}} \quad \text{A}/\sqrt{\text{Hz}} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.462)

$$I_{\text{FLICKER},DS} = \sqrt{\frac{K_F I_D^{A_F}}{f K_{\text{CHANNEL}}}} \quad A/\sqrt{\text{Hz}}$$
(7.463)

where the transconductance

$$g_m = \frac{\partial I_D}{\partial V_{GS}} \tag{7.464}$$

is evaluated at the DC operating point, and

$$K_{\rm CHANNEL} = \frac{\partial L_{\rm EFF}^2 \epsilon_{\rm Si}}{\partial T_{OX}} \tag{7.465}$$

# Digital Input Interface



Figure 7.57: N — Digital input interface element. Converts from a digital (state) signal to an analog signal.

Form

Nname InterfaceNode LowLevelNode HighLevelNode ModelName [SIGNAME = DigitalSignalName] [IS = InitialState]

InterfaceNode Identifier of node interfacing between digital signal and continuous time circuit.

LowLevelNode Identifier of low level reference node. Normally this is the logic "zero" voltage.

HighLevelNode Identifier of high level reference node. Normally this is the logic "one" voltage.

- ModelName Name of the model specifying transitions times and resistances and capacitances of each logic state
  - SIGNAME Keyword for digital signal name. (optional)
- DigitalSignalName Digital signal name. DigitalSignalName is the name of the signal specified in the input file specified in the element model. If it is omitted then DigitalSignalName defaults element name Nname stripped of the prefix N (i.e. name).
  - **IS** Keyword for initial state. (optional)
  - *InitialState* Integer specifitying the initial state. If specified, it must be 0, 1, ..., or 19. This over rides the state specified at TIME=0 in the digital input file (see the model specification). The state of the digital interface input (N) element remains as the *InitialState* state until a state (other than the state at TIME=0 is input from the specified file.

Example

N100 1 0 2 INTERFACE\_FROM\_REGISTER SIGNAME=REG1 IS=0 NCONTROL 1 0 2 CONTROL

Model Type

DINPUT

Ν

#### Digital Input Interface

The digital input interface is modeled by time variable resistances between the *Interface Node* and the *Low Level Node* and between the the *Interface Node* and the *High Level Node*. The variable resistances are shunted by fixed capacitances. The resistance are controlled by parameters specified in the model *ModelName*. The resistance varies exponentially from the old state to the new state over the time period indicated for the new state. This approximates the output of a digital gate.

# **DINPUT** Model

Digital Input Interface Model



Figure 7.58: Digital input interface model.

The digital input interface is modeled by time variable resistances between the Interface Node and the Low Level Node and between the Interface Node and the High Level Node. The variable resistances are shunted by fixed capacitances. The parameters are controlled by parameters specified in the model. Upon a state transition the two resistances vary exponentially from the old state to the new state over the time period indicated for the new state. This approximates the output of a digital gate. The sequence of states and the state change times are specified in the file specified by the FILE = (InputFileName) keyword in the model. The initial state at TIME 0 is taken from this file unless the IS keyword is specified on the element line. In the  $I_S$  (= InitialState) keyword is specified then the state of the digital input interface is InitialState until a state transition at TIME > 0 is specified in the file InputFileName.

Keywords:

Name	Description	Units	Default
FILE	digital input filename. If more than one model refers to the	-	REQUIRED
	same file then the filenames specified must be identical and		
	not logicly equivalent. This ensures that the file is opened		
	only once.		
FORMAT	digital input file format	-	1
TIMESTEP	digital input file time step	S	1NS
CLO	capacitance to low level node	F	0
CHI	capacitance to high level node	F	0
SnNAME	state "n" character abreviation	-	REQUIRED
	n = 0, 2,,  or  19		
SnTSW	state "n" switching time	S	REQUIRED
	n = 0, 2,,  or  19		
SnRLO	state "n" resistance to low level node	Ω	REQUIRED
	n = 0, 2,,  or  19		
SnRHI	state "n" resistance to high level node	Ω	REQUIRED
	n = 0, 2,,  or $19$		





Figure 7.59: O — Digital output interface element.

Form

Oname InterfaceNode ReferenceNode ModelName [SIGNAME = DigitalSignalName ]

- InterfaceNode Identifier of node interfacing between digital signal and continuous time circuit.
- ReferenceNode Identifier of reference node. Normally this is ground
  - *ModelName* Name of the model specifying transistions times and resistances and capacitances of each logic state.

SIGNAME Keyword for digital signal name. (optional)

DigitalSignalName Digital signal name.

#### Example

0100 1 0 INTERFACE\_TO\_MEMORY SIGNAME=MEM1 0ADD1 1 0 2 ADD1

Model Type

DOUTPUT

The digital output interface is modeled by time variable resistances between the *Interface Node* and the *Low Level Node* and between the *Interface Node* and the *High Level Node*. The variable resistances are shunted by fixed capacitances. The parameters are controlled by parameters specified in the model. The resistance varies exponentially from the old state to the new state over the time period indicated for the new state. This approximates the output of a digital gate.

# **DOUTPUT** Model

Digital Output Interface Model

Keywords:

Name	Description	Units	Default
FILE	digital output filename. If more than one model refers to the	-	REQUIRED
	same file then the filenames specified must be identical and		
	not logicly equivalent. This ensures that the file is opened		
	only once.		
FORMAT	digital output file format	-	1
TIMESTEP	digital output file time step	S	1NS
TIMESCALE	digital output file time scale	S	1
CHGONLY	Output type flag:	-	0
	= 0 $ ightarrow$ output at each TIMESTEP		
	=1  ightarrow output only on state change		
CLOAD	capacitance	F	0
RLOAD	resistance	Ω	1000
SNAME	state "n" character abreviation	-	REQUIRED
	n = 0, 2,,  or  19		
SnVLO	state "n" low level voltage	S	REQUIRED
	n = 0, 2,,  or $19$		
SnVHI	state "n" high level voltage	S	REQUIRED
	n = 0, 2,,  or $19$		

The digital output interface is modeled by a resistance *RLoad* and capacitance *CLoad* between the *InterfaceNode* and the *Reference Node*. The values of *Rload* and *CLoad* are specified in the model *ModelName*.

A state transistion from state n (n = one of 0, 1, 2, ... 19) is indicated if the interface voltage  $V_{InterfaceNode} - V_{ReferenceNode}$  between the InterfaceNode and the ReferenceNode node is outside the range SnVHI - SnVLO. If there is a state transistion then the valid voltage range of each state k is considered in order from state k = 0 to state 19 to determine which voltage range SkVHI - SkVLO brackets the current interface voltage  $V_{InterfaceNode} - V_{ReferenceNode}$ . The first valid state becomes the new state. If there is no valid state then the new state is indeterminate and designated by "?". At each TIME being a multiple integer of TIMESTEP a line is written to the digital output file OutputFileName. If the new state at the time  $t_i = i \cdot TIMESTEP$  is n then the i th line is:

#### $int(i \cdot \texttt{TIMESCALE})n$

where int() is the integer operation. An example of the first few lines of *OutputFileName* with a TIMESTEP of 1 ns and TIMESCALE of 2 is: 0.012042638?101120141

# Р

Port Element

Some versions of spice only.



Figure 7.60: P — port element.

Form

Pname  $N_+ N_-$  PNR= PortNumber [ZL= ReferenceImpedance]

- $N_+$  is the positive element node,
- $N_{-}$  is the negative element node, and
- *PNR* is the integer index of the port. The port index must be numbered sequentially beginning at 1. That is, the first occurrence of a P element in the in input netlist must have PNR=1, the second occurrence PNR=2, etc. (Units: none; Required; Symbol: *PortNumber*;)
  - ZL is the reference impedance of port (Units:  $\Omega$ ; Optional; Default: 50  $\Omega$ ; Symbol: Z<sub>L</sub>;)

#### Example

PORT1 1 0 PNR=1 ZL=75

#### Note

- 1.  $V_{AS}$  in Fig. 7.60 is not visible to the user and is used by the program to test for the S parameters. As an example of using the port specification with a source consider the partial circuit in Fig. 7.61
- . The spice code defining this is *Example*

Pname  $N_+ N_-$  PNR= PortNumber [ZL= ReferenceImpedance] [VIN  $N_-$  0 PULSE (Pulse Specification)]



Figure 7.61: Example of the usage of a P element with a pulse voltage source.

Bipolar Junction Transistor



Figure 7.62: Q — bipolar junction transistor element: (a) NPN transistor; (b) PNP transistor.

Form

Qname NCollector NBase NEmitter [NSubstrate] ModelName [Area] [OFF] + [IC=Vbe, Vce]

*NCollector* is the collector node.

NBase is the base node.

*NEmitter* is the emitter node.

- NSubstrate is the optional substrate node. If not specified, ground is used as the substrate node. If NSubstrate is a name as allowed in PSPICE) it must be enclosed in square brackets, e.g. [NSubstrate], to distinguish it from ModelName.
- ModelName is the model name.
  - Area is the area factor If the area factor is omitted, a value of 1.0 is assumed. (Units: none; Optional; Default: 1; Symbol: Area)
  - **DFF** indicates an (optional) initial condition on the device for the DC analysis. If specified the DC operating point is calculated with the terminal voltages set to zero. Once convergence is obtained, the program continues to iterate to obtain the exact value of the terminal voltages. The OFF option is used to enforce the solution to correspond to a desired state if the circuit has more than one stable state.
  - IC is the optional initial condition specification using  $IC=V_{BE}$ ,  $V_{CE}$  is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired starting from other than the quiescent operating point. See the .*IC* line description for a better way to set transient initial conditions.

Example

Q20 10 50 0 QFAST IC=0.65,15.0 Q5PUSH 10 29 14 200 MODEL1

#### NPN Model

NPN Si Bipolar Transistor Model

PNP Si Bipolar Transistor Model

# PNP Model

<b>LPNP Model</b> PSPICE Only Lateral PNP Si Bipolar Transistor Mod	LPNP Model	PSPICE Only	Lateral PNP Si Bipolar Transistor Mod
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Figure 7.63: Schematic of the NPN bipolar junction transistor model. In the NPN and PNP models node  $N_X$  is connected to node C In the LPNP model node  $N_X$  is connected to node B.

The NPN and PNP BJT models are identical but with the positive sense of currents and voltages opposite so that the model parameters are always positive. The LPNP model is used for a lateral PNP IC transistor structure. In the NPN and PNP models the node  $N_X$  in figure 7.63 is connected to node C — the internal collector node. In the LPNP model node  $N_X$  is connected to node B — the internal base node. Only the model type designated on the element line distinguishes which schematic is used.

The bipolar junction transistor model in SPICE is based on the charge control model of Gummel and Poon. Extensions in the SPICE implementation deal with effects at high bias levels. The model reduces to the simpler Ebers-Moll model with the ommission of appropriate model parameters.

Table	7.12:	BJT	model	parameters.
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Name	Description	Units	Default	Are
AF	flicker noise exponent $(A_F)$	-	1	
BF	ideal maximum forward beta $(\beta_F)$	-	100	
			Continued or	n next page

Name	Description	Units	Default	Are
BR	ideal maximum reverse beta $(\beta_R)$	-	1	
C2	alternative keyword for ISE			
	PSPICE only.			
C4	alternative keyword for ISC			
	PSPICE only.			
CCS	alternative keyword for CJS			
	PSPICE only.			
CJC	base-collector zero-bias depletion	F	0	*
	capacitance $(C_{JC})$			
CJE	base-emitter zero-bias depletion	F	0	*
	capacitance $(C_{JE})$			
CJS	zero-bias collector-substrate	F	0	*
	capacitance $(C_{JS})$			
EG	energy gap voltage (barrier height) $(E_G)$	eV	1.11	
FC	coefficient for forward-bias depletion	-	0.5	
	capacitance formula $(F_C)$			
IK	alternative keyword for IKF			
	PSPICE only.			
IKF	corner of forward beta high current	А	$\infty$	*
	roll-off $(I_{KF})$			
IKR	corner of reverse beta high current	А	$\infty$	*
	roll-off $(I_K F)$			
IRB	current where base resistance falls halfway to its minimum	-	$\infty$	*
	value $(I_{RB})$			
IS	transport saturation current $(I_S)$	А	1.0E-16	*
ISC	base-collector leakage saturation	А	0	*
	current $(I_{SC})$ If ISC is greater than 1 it is treated as a			
	multiplier. In this case $I_{SC} = ISC I_S$			
ISE	base-emitter leakage saturation	А	0	*
	current $(I_{SE})$ If ISE is greater than 1 it is treated as a			
	multiplier. In this case $I_{SE} = ISE I_S$			
ISS	substrate p-n junction saturation current $(I_{SS})$	А	0	*
	PSPICE only.			
ITF	high-current parameter for effect on TF $(I_{\tau F})$	А	0	*
KF	flicker-noise coefficient $(K_F)$	-	0	
MC	alternative keyword for MJC			
	PSPICE only.			
ME	alternative keyword for MJE			
	PSPICE only.			
MJC	base-collector junction exponential	-	0.33	
	tactor $(M_{JC})$			
MJE	base-emitter junction exponential	-	0.33	
	tactor $(M_{JE})$			
MJS	substrate junction exponential	-	0	
	tactor $(M_{JS})$			
			Continued or	n next page

Table 7.12: BJT model parameters.

Name	Description		$\mathbf{Units}$	Default	Are
MS	alternative keyword for MJS				
	PSPICE only.				
NC	base-collector leakage emission		-	2	
	coefficient	$(N_C)$			
NE	base-emitter leakage emission coefficient	$(N_E)$	-	1.5	
NF	forward current emission coefficient	$(N_F)$	_	1.0	
NR	reverse current emission coefficient	$(N_R)$	-	1	
NS	substrate p-n emission coefficient	$(N_S)$	-	1	*
	PSPICE only.	( -/			
PC	alternative keyword for VJC				
	PSPICE only.				
PE	alternative keyword for VJE				
	PSPICE only.				
PS	alternative keyword for VJS				
	PSPICE only.				
PT	alternative keyword for XTI				
	PSPICE only.				
PTF	excess phase at frequency= $1.0/(\text{TF} 2\pi)$ Hz	$(P_{\tau F})$	degree	0	
RB	zero bias base resistance	$(R_B)$	Ω	0	*
RBM	minimum base resistance at high currents	$(R_{BM})$	Ω	RB	*
RC	collector resistance	$(R_C)$	Ω	0	*
RE	emitter resistance	$(R_F)$	Ω	0	*
TF	ideal forward transit time	$(\tau_E)$	s	0	
TR.	ideal reverse trarsit time	$(\tau_P)$	s	0	
TRB1	BB linear temperature coefficient	$(T_{RB1})$	$^{\circ}\mathrm{C}^{-1}$	1	*
	PSPICE only.	(-1101)	C	-	
TRB2	BB quadratic temperature coefficient	$(T_{BB2})$	$^{\circ}\mathrm{C}^{-2}$	1	*
	PSPICE only.	(-nD2)	-	_	
TRC1	RC linear temperature coefficient	$(T_{BC1})$	$^{\circ}\mathrm{C}^{-1}$	1	*
	PSPICE only.	(-1101)	-	_	
TRC2	RC quadratic temperature coefficient	$(T_{BC2})$	$^{\circ}\mathrm{C}^{-2}$	1	*
	PSPICE only.	( 1102)	-		
TRE1	RE linear temperature coefficient	$(T_{RE1})$	$^{\circ}\mathrm{C}^{-1}$	1	*
	PSPICE only.	(-1121)	-	_	
TRE2	RE quadratic temperature coefficient	$(T_{RE2})$	$^{\circ}\mathrm{C}^{-2}$	1	*
	PSPICE only.	(11112)			
TRM1	RBM linear temperature coefficient	$(T_{RM1})$	$^{\circ}\mathrm{C}^{-1}$	1	*
	PSPICE only.	( 10001)			
TRM2	RBM quadratic temperature coefficient	$(T_{RM2})$	$^{\circ}\mathrm{C}^{-2}$	1	*
	PSPICE only.	(			
VA	alternative keyword for VAF				
	PSPICE only.				
VB	alternative keyword for VAR				
	PSPICE only.				
VAF	forward Early voltage	$(V_{AF})$	V	$\infty$	
VAR	reverse Early voltage	$(V_{AR})$	V	$\infty$	
		× -/		Continued or	n next page

Table 7.12: BJT model parameters.

Name	Description	Units	Default	Are
VJC	base-collector built-in potential $(V_{JC})$	V	0.75	
VJE	base-emitter built-in potential $(V_{JE})$	V	0.75	
VJS	substrate junction built-in potential $(V_{JS})$	V		
VTF	voltage describing $V_{BC}$ dependence of TF $(V_{\tau F})$	V	$\infty$	
XCJC	fraction of B-C depletion capacitance connected to internal	-	1	
	base node $(X_{CJC})$			
XTB	forward and reverse beta temperature	-		
	exponent $(X_{TB})$			
XTI	temperature exponent for effect on	-	3	
	IS $(X_{TI})$			
XTF	coefficient for bias dependence of	-		
	TF $(X_{\tau F})$			

Table 7.12: BJT model parameters.

# Standard Calculations

The physical constants used in the model evaluation are

k	Boltzman's constant	$1.3806226  10^{-23}  \mathrm{J/K}$
q	electronic charge	$1.6021918  10^{-19} \mathrm{C}$

Absolute temperatures (in kelvins, K) are used. The thermal voltage

$$V_{\rm TH}(T_{\rm NOM}) = \frac{kT_{\rm NOM}}{q}.$$
(7.466)

# Temperature Dependence

Temperature effects are incorporated as follows where T and  $T_{\rm NOM}$  are absolute temperatures in Kelvins (K).

$$V_{\rm TH} = \frac{kT}{q} \tag{7.467}$$

$$I_{S}(T) = I_{S}e^{\left(E_{g}(T)\frac{T}{T_{\text{NOM}}} - E_{G}(T)\right)/V_{\text{TH}}} + \left(\frac{T}{T_{\text{NOM}}}\right)^{X_{TI}/N_{F}}$$
(7.468)

$$I_{SE}(T) = I_{SE} e^{\left(E_g(T)\frac{T}{T_{\text{NOM}}} - E_G(T)\right)/V_{\text{TH}}} + \left(\frac{T}{T_{\text{NOM}}}\right)^{X_{TI}/N_E}$$
(7.469)

$$I_{SC}(T) = I_{SC} e^{\left(E_g(T)\frac{T}{T_{NOM}} - E_G(T)\right)/V_{TH}} + \left(\frac{T}{T_{NOM}}\right)^{X_{TI}/N_C}$$
(7.470)

$$I_{SS}(T) = I_{SS}e^{\left(E_g(T)\frac{T}{T_{NOM}} - E_G(T)\right)/V_{TH}} + \left(\frac{T}{T_{NOM}}\right)^{X_{TI}/N_S}$$
(7.471)

$$V_{JE}(T) = V_{JE}(T_{\rm NOM})(T - T_{\rm NOM}) - 3V_{\rm TH} \ln\left(\frac{T}{T_{\rm NOM}}\right) E_G(T_{\rm NOM})\frac{T}{T_{\rm NOM}} - E_G(T)$$
(7.472)

$$V_{JC}(T) = V_{JC}(T_{\rm NOM})(T - T_{\rm NOM}) - 3V_{\rm TH} \ln\left(\frac{T}{T_{\rm NOM}}\right) E_G(T_{\rm NOM})\frac{T}{T_{\rm NOM}} - E_G(T)$$
(7.473)

$$V_{JS}(T) = V_{JS}(T_{\rm NOM})(T - T_{\rm NOM}) - 3V_{\rm TH} \ln\left(\frac{T}{T_{\rm NOM}}\right) E_G(T_{\rm NOM})\frac{T}{T_{\rm NOM}} - E_G(T)$$
(7.474)

$$C_{JC}(T) = C_{JC}\{1 + M_{JC}[0.0004(T - T_{NOM}) + (1 - V_{JC}(T)/V_{JC}(T_{NOM}))]\}$$
(7.475)  
$$C_{TC}(T) = C_{TC}\{1 + M_{TC}[0.0004(T - T_{NOM}) + (1 - V_{TC}(T)/V_{TC}(T_{NOM}))]\}$$
(7.476)

$$C_{JE}(T) = C_{JE}\{1 + M_{JE}[0.0004(T - T_{\text{NOM}}) + (1 - V_{JE}(T)/V_{JE}(T_{\text{NOM}}))]\}$$
(7.476)  
$$C_{JE}(T) = C_{JE}\{1 + M_{JE}[0.0004(T - T_{\text{NOM}}) + (1 - V_{JE}(T)/V_{JE}(T_{\text{NOM}}))]\}$$
(7.477)

$$C_{JS}(T) = C_{JS}\{1 + M_{JS}[0.0004(T - T_{\text{NOM}}) + (1 - V_{JS}(T)/V_{JS}(T_{\text{NOM}}))]\}$$
(7.477)

$$\beta_F(T) = \beta_F(T_{\text{NOM}})^{X_{TB}}$$

$$\beta_R(T) = \beta_R(T_{\text{NOM}})^{X_{TB}}$$

$$(7.478)$$

$$(7.479)$$

$$F(T) = F(T) = 0.000702$$
  $T^2$  (7.480)

$$E_G(T) = E_G(T_{\text{NOM}}) - 0.000702 \frac{1}{T + 1108}$$

$$P_{-}(T) = P_{-}(T_{-}) \left[ 1 + T_{-}(T_{-} T_{\text{NOM}}) + T_{-}(T_{-} T_{\text{NOM}})^2 \right]$$
(7.481)

$$R_B(T) = R_B(T_{\text{NOM}}) \left[ 1 + T_{RB1}(T - T_{\text{NOM}}) + T_{RB2}(T - T_{\text{NOM}})^2 \right]$$
(7.481)  
$$R_B(T) = R_B(T_{\text{NOM}}) \left[ 1 + T_R(T - T_{\text{NOM}}) + T_R(T - T_{\text{NOM}})^2 \right]$$
(7.482)

$$R_{BM}(T) = R_{BM}(T_{\text{NOM}}) \left[ 1 + T_{RM1}(T - T_{\text{NOM}}) + T_{RM2}(T - T_{\text{NOM}})^2 \right]$$
(7.482)

$$R_C(T) = R_C(T_{\text{NOM}}) \left[ 1 + T_{RC1}(T - T_{\text{NOM}}) + T_{RC2}(T - T_{\text{NOM}})^2 \right]$$
(7.483)  
$$P_C(T) = P_C(T_{\text{NOM}}) \left[ 1 + T_{RC1}(T - T_{\text{NOM}}) + T_{RC2}(T - T_{\text{NOM}})^2 \right]$$
(7.484)

$$R_E(T) = R_E(T_{\text{NOM}}) \left[ 1 + T_{RE1}(T - T_{\text{NOM}}) + T_{RE2}(T - T_{\text{NOM}})^2 \right]$$
(7.484)

(7.485)

#### Capacitances

The base-emitter capacitance,  $C_{BE} = Area(C_{BE\tau} + C_{BEJ})$ where the base-emitter transit time or diffusion capacitance

$$C_{BE\tau} = \tau_{F,\text{EFF}} \frac{\partial I_{BF}}{\partial V_{BE}} \tag{7.486}$$

the effective base transit time is empirically modified to account for base puchout, space-charge limited current flow, quasi-saturation and lateral spreading which tend to increase  $\tau_F$ 

$$\tau_{F,\text{EFF}} = \tau_F \left[ 1 + X_{TF} (3x^2 - 2x^3) e^{(V_{BC}/(1.44V_{TF}))} \right]$$
(7.487)

and  $x = I_{BF}/(I_{BF} + AreaI_{TF})$ . The base-emitter junction (depletion) capacitance

$$C_{BEJ} = \begin{cases} C_{JE} \left( 1 - \frac{V_{BE}}{V_{JE}} \right)^{-M_{JE}} & V_{BE} \le F_C V_{JE} \\ C_{JE} \left( 1 - F_C \right)^{-(1+M_{JE})} \left( 1 - F_C (1+M_{JE}) + M_{JE} \frac{V_{BE}}{V_{JE}} \right) & V_{BE} > F_C V_{JE} \end{cases}$$
(7.488)

The base-collector capacitance,  $C_{BC} = Area(C_{BC\tau} + X_{CJC}C_{BCJ})$  (7.489) where the base-collector transit time or diffusion capacitance

$$C_{BC\tau} = \tau_R \frac{\partial I_{BR}}{\partial V_{BC}} \tag{7.490}$$

The base-collector junction (depletion) capacitance

$$C_{BCJ} = \begin{cases} C_{JC} \left( 1 - \frac{V_{BC}}{V_{JC}} \right)^{-M_{JC}} & V_{BC} \leq F_C V_{JC} \\ C_{JC} \left( 1 - F_C \right)^{-(1+M_{JC})} \left( 1 - F_C (1+M_{JC}) + M_{JC} \frac{V_{BC}}{V_{JC}} \right) & V_{BC} > F_C V_{JC} \end{cases}$$
(7.491)

The capacitance between the extrinsic base and the intrinsic collector

$$C_{BX} = \begin{cases} Area(1 - X_{CJC})C_{JC} \left(1 - \frac{V_{BX}}{V_{JC}}\right)^{-M_{JC}} & V_{BX} \le F_C V_{JC} \\ (1 - X_{CJC})C_{JC} \left(1 - F_C\right)^{-(1 + M_{JC})} & V_{BX} > F_C V_{JC} \\ \times \left(1 - F_C (1 + M_{JC}) + M_{JC} \frac{V_{BX}}{V_{JC}}\right) & (7.492) \end{cases}$$

The substrate junction capacitance

$$C_{JS} = \begin{cases} AreaC_{JS} \left(1 - \frac{V_{CJS}}{V_{JS}}\right)^{-M_{JS}} & V_{CJS} \le 0\\ AreaC_{JS} \left(1 + M_{JS} \frac{V_{CJS}}{V_{JS}}\right) & V_{CJS} > 0 \end{cases}$$
(7.493)

#### I/V Characteristics

The base-emitter current, 
$$I_{BE} = \frac{I_{BF}}{\beta_F} + I_{LE}$$
 (7.494)

the base-collector current, 
$$I_{BC} = \frac{I_{BR}}{\beta_{B}} + I_{LC}$$
 (7.495)

and the collector-emitter current, 
$$I_{CE} = \frac{I_{BF} - I_{BR}}{K_{OR}}$$
 (7.496)

where the forward diffusion current, 
$$I_{BF} = I_S \left( e^{V_{BE}/(N_F V_{\text{TH}})} - 1 \right)$$
 (7.497)

the nonideal base-emitter current, 
$$I_{LE} = I_{SE} \left( e^{V_{BE}/(N_E V_{\rm TH}) - 1} \right)$$
 (7.498)

the reverse diffusion current, 
$$I_{BR} = I_S \left( e^{V_{BC}/(N_R V_{\rm TH})} - 1 \right)$$
 (7.499)

the nonideal base-collector current, 
$$I_{LC} = I_{SC} \left( e^{V_{BC}/(N_C V_{TH}) - 1} \right)$$
 (7.500)

and the base charge factor,  $K_{QB} = \frac{1}{2} \left[ 1 - \frac{V_{BC}}{V_{AF}} - \frac{V_{BE}}{V_{AB}} \right]^{-1} \left( 1 + \sqrt{1 + 4 \left( \frac{I_{BF}}{I_{KF}} + \frac{I_{BR}}{I_{KR}} \right)} \right)$  (7.501)

Thus the conductive current flowing into the base,  $I_B = I_{BE} + I_{BC}$ (7.502)the conductive current flowing into the collector,  $I_C = I_{CE} - I_{BC}$ (7.503)and the conductive current flowing into the emitter,  $I_C = I_{BE} + I_{CE}$ (7.504)Parasitic Resistances(7.504)

The resistive parasities  $R_B$ ,  $R_E$ , are  $R_C$  are scaled by the area factor, *Area*, specified on the element line. This enables the model parameters **RB**, **RE** and **RC** to be absolute quantities if *Area* is omitted as it defaults to 1, or as sheet resistivities.

$$R'_B = R_B / Area \tag{7.505}$$

$$R'_C = R_C / Area \tag{7.506}$$

$$R'_E = R_E / Area \tag{7.507}$$

$$R'_{B} = \begin{cases} R_{BM} + \frac{R_{B} - R_{BM}}{K_{QB}} & I_{RB} \text{ omitted} \\ R_{BM} + 3(R_{B} - R_{BM}) \frac{\tan x - x}{x \tan^{2}(x)} & I_{RB} \text{ defined} \end{cases}$$
(7.508)

where 
$$x = \left(\sqrt{1 + \frac{144I_B}{I_{RB}\pi^2}} - 1\right) \left(\frac{24}{\pi^2}\sqrt{\frac{I_B}{I_{RB}}}\right)^{-1}$$
 (7.509)

#### AC Analysis

The AC analysis uses the model of figure 7.46 with the capacitor values evaluated at the DC operating point with

$$g_m = \frac{\partial I_{CE}}{\partial V_{BE}} \tag{7.510}$$

and

$$R_O = \frac{\partial I_{CE}}{\partial V_{CE}} \tag{7.511}$$

### Noise Analysis

The BJT noise model accounts for thermal noise generated in the parasitic resistances and shot and flicker noise generated in the base-emitter and base-collector junction regions. The rms (root-mean-square) values of thermal noise current generators shunting the three parasitic resistance  $R_B$ ,  $R_C$ , and  $R_E$  are

$$I_{n,B} = \sqrt{4kT/R_B} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.512}$$

$$I_{n,C} = \sqrt{4kT/R_C} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.513}$$

$$I_{n,E} = \sqrt{4kT/R_E} \,\mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.514}$$

The rms value of the base noise current generator is

$$I_{n,B} = \left(I_{\text{SHOT},B}^2 + I_{\text{FLICKER},B}^2\right)^{1/2} \tag{7.515}$$

where

$$I_{\text{SHOT},B} = \sqrt{2qI_B} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.516)

$$I_{\text{FLICKER},B} = \sqrt{K_F I_B^{A_F} / f} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.517)

and f is frequency. The rms value of the collector noise current generator is

$$I_{n,C} = \left(I_{\text{SHOT},C}^2 + I_{\text{FLICKER},C}^2\right)^{1/2}$$
(7.518)

where

$$I_{\text{SHOT},C} = \sqrt{2qI_C} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.519)

$$I_{\text{FLICKER},C} = \sqrt{K_F I_C^{A_F} / f} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.520)

# Resistor

# $R^{n_1 \circ \cdots \circ n_2}$

Figure 7.64: R — resistor element.

Form

Rname  $N_1 N_2$  Resistor Value  $IC=V_R$ ]

#### SPICE3Form

Rname  $N_1 N_2$  [ModelName] ResistorValue [IC= $V_R$ ] [L= Length] [W= Width]

#### PSPICEForm

Rname  $N_1 N_2$  [ModelName ] ResistorValue []

 $N_1$  is the positive element node,

 $N_2$  is the negative element node, and

ModelName is the optional model name.

ResistorValue is the resistance. (Units: F; Required; Symbol: ResistorValue;

IC is the optional initial condition specification Using  $IC=V_C$  is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired with an initial voltage  $V_C$  across the capacitor rather than the quiescent operating point. Specification of the transient initial conditions using the .IC statement (see page 66) is preferred and is more convenient.

#### Example

R1 1 2 12.3MEG

Model Type

RES

**RES** Model

SPICE3 Only

Resistor Model

Form

.MODEL ModelName RES( [[keyword = value] ... ])

# R

#### Example

.MODEL SMALLRES RES( )

Model Keywords

Name	Description		Units	Default
DEFW	default device width	$(W_{DEF})$	meters	1e-6
NARROW	narrowing due to side etching	$(X_{NARROW})$	meters	0.0

The SPICE3 resistor model is a process model for a monolithicly fabricated resistor enabling the capacitance to be determined from geometric information. If the parameter W is not specified on the element line then *Width* defaults to DEFW =  $W_{\text{DEF}}$ . The effective dimensions are reduced by etching so that the effective length of the capacitor is

$$L_{\rm EFF} = Length - X_{\rm NARROW} \tag{7.521}$$

and the effective width is

$$W_{\rm EFF} = Width - X_{\rm NARROW} \tag{7.522}$$

The value of the capacitance

$$Capacitor Value = C_J L_{\rm EFF} W_{\rm EFF} + C_{J,\rm SW} L_{\rm EFF} + W_{\rm EFF} + L_{\rm EFF} + W_{\rm EFF})$$
(7.523)

RES Model	PSPICE Only	Resistor Model

The resistor model consists of process-related device data that allow the resistance to be calculated from geometric information and to be corrected for temperature. The parameters available are: *Keywords:* 

Name	Description		Units	Default
R	resistance multiplier	$(R_{MULTIPLIER})$	-	1
TC1	first order temperature coefficient	$(T_{C1})$	$^{\circ}C^{-1}$	0
TC2	second order temperature coefficient	$(T_{C2})$	$^{\circ}C^{-2}$	0
TCE	exponential temperature coefficient	$(T_{CE})$	$\%/^{\circ}C^{-2}$	0

The sheet resistance is used with the narrowing parameter and L and W from the resistor line to determine the nominal resistance by the formula

1	(ResistorValue	no model specified	
$R = \langle$	ResistorValue $R_{\text{MULTIPLIER}}$ $\times \left[1 + T_{C1}(T - T_{\text{NOM}}) + T_{C2}(T - T_{\text{NOM}})^2\right]$	model specified and <b>TCE</b> not specified	(7.524)
	$ResistorValue R_{MULTIPLIER} 1.01 [T_{CE}(T - T_{NOM})]$	model and ${\tt TCE}$ specified	

Resistor

# Noise Analysis

The resistor noise model accounts for thermal noise generated in the resistance. The rms (root-mean-square) values of thermal noise current generators shunting the resistance is

$$I_n = \sqrt{4kT/R} \ \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.525}$$

Voltage Controlled Switch



Figure 7.65: S — voltage controlled switch element.

#### Form

Sname  $N_+ N_- N_{C+} N_{C-}$  ModelName [ON] [OFF]

#### **PSpice**Form

Sname  $N_+$   $N_ N_{C+}$   $N_{C-}$  ModelName

#### Example

S1 1 2 3 4 SWITCH1 S2 5 6 3 0 SM2 SWITCH1 1 2 10 0 SMODEL1

- $N_+$  is the positive node of the switch.
- $N_{-}$  is the negative node of the switch.
- $N_{C+}$  is the positive controlling node of the switch.
- $N_{C-}$  is the negative controlling node of the switch.

*ModelName* is the model name and is required.

- ON is the optional initial condition. It is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired starting from other than the quiescent operating point. It is also the initial condition on the device for DC analysis.
- **OFF** is the optional initial condition. If specified the DC operating point is calculated with the terminal voltages set to zero. Once convergence is obtained, the program continues to iterate to obtain the exact value of the terminal voltages. The OFF option is used to enforce the solution to correspond to a desired state if the circuit has more than one stable state.

The initial conditions are optional. For the voltage controlled switch, nodes  $N_{C+}$  and NC- are the positive and negative controlling nodes respectively. For the current controlled switch, the controlling current is that through the specified voltage source. The direction of positive controlling current flow is from the positive node, through the source, to the negative node.

S
Model Type

VSWITCH

# VSWITCH Model

Voltage-Controlled Switch Model



Figure 7.66: VSWITCH — voltage controlled switch model.

The voltage-controlled switch model is supported by both SPICE3 and PSPICE. However the model keywords differ slightly.

Spice3 keywords:

Name	Description	Units	Default
VT	threshold voltage $(V_{ON})$	V	0.0
VH	hysteresis voltage $(V_{OFF})$	V	0.0
RON	on resistance $(R_{ON})$	Ω	1.0
ROFF	off resistance $(R_{OFF})$	Ω	1/GMIN

**PSPICE** keywords:

Name	Description	Units	Default
VON	threshold voltage $(V_{ON})$	) V	0.0
VOFF	hysteresis voltage $(V_{OFF})$	) V	0.0
RON	on resistance $(R_{ON})$	) Ω	1.0
ROFF	off resistance (R <sub>OFF</sub>	) Ω	1/GMIN

Care must be exercised in using the switch. An instantaneous switch is highly nonlinear and will very likely lead to convergence problems. This problem is alleviated in the VSWITCH model by ramping the resistance of the switch from its off value to its on value. For this ramping action to be effective the difference between  $V_{\rm ON}$  and  $V_{\rm OFF}$  must not be too small. Also the values of  $R_{\rm ON}$  and  $R_{\rm OFF}$  should not be extreme. The ration  $R_{\rm ON}/R_{\rm OFF}$  should be be as small as possible.

If  $R_{\rm ON}/R_{\rm OFF}$  is large, e.g.  $R_{\rm ON}/R_{\rm OFF} > 10^{12}$ , then the default error tolerances TRTOL and CHGTOL, specified in a .OPTIONS statement (see page 83) may need to be changed.

TRTOL Change to 1.0 from 7.0 idf there are convergence problems during transient analysis.

CHGTOL If a switch is across a capacitor then CHGTOL should be reduced to  $10^{-16}$  if there are convergence problems during transient analysis.

### Switch Model

The switch is modeled by a voltage variable resistor R and an input input resistance  $R_{\rm IN}$ , see figure 7.66.  $R_{\rm IN} = 1/G_{\rm MIN}$  to ensure that the controlling nodes are not floating and that the voltage v between the controlling nodes can not change instantaneously.  $G_{\rm MIN} = \text{GMIN}$  is described on page ??.

### Standard Calculations

$$R_{\rm MEAN} = \sqrt{R_{\rm ON} + R_{\rm OFF}} \tag{7.526}$$

$$R_{\rm RATIO} = R_{\rm ON}/R_{\rm OFF} \tag{7.527}$$

$$V_{\rm MEAN} = \sqrt{V_{\rm ON} + V_{\rm OFF}} \tag{7.528}$$

$$V_{\Delta} = \left(\frac{v - V_{\text{MEAN}}}{V_{\text{ON}} - V_{\text{OFF}}}\right)$$
(7.529)

If  $V_{\rm ON} > V_{\rm OFF}$  the switch resistance

$$R = \begin{cases} R_{\rm ON} & v \ge V_{\rm ON} \\ R_{\rm OFF} & v \le V_{\rm OFF} \\ R_{\rm MEAN} R_{\rm RATIO}^{1.5V_{\Delta}} R_{\rm RATIO}^{1.5V_{\Delta}^3} & V_{\rm OFF} < v < V_{\rm ON} \end{cases}$$
(7.530)

If  $V_{\rm ON} < V_{\rm OFF}$  the switch resistance

$$R = \begin{cases} R_{\rm ON} & v \le V_{\rm ON} \\ R_{\rm OFF} & v \ge V_{\rm OFF} \\ R_{\rm MEAN} R_{\rm RATIO}^{1.5V_{\Delta}} R_{\rm RATIO}^{1.5V_{\Delta}^3} & V_{\rm OFF} < v < V_{\rm ON} \end{cases}$$
(7.531)

### Noise Analysis

The voltage controlled switch noise model accounts for thermal noise generated in the switch resistance. The rms (root-mean-square) values of thermal noise current generators shunting the switch resistance is

$$I_n = \sqrt{4kT/R} \ \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.532}$$

where T is the analysis temperature in kelvin (K), and  $k = 1.3806226 \, 10^{-23} \, \text{J/K}$  is Boltzmans constant.



Figure 7.67: T — transmission line element.

#### Form

Т

Thame  $n_1 n_2 n_3 n_4$  Z0=CharacteristicImpedance TD=TimeDelay [IC=V<sub>1</sub>, I<sub>1</sub>, V<sub>2</sub>, I<sub>2</sub>]

That  $n_1 n_2 n_3 n_4$  ZO=CharacteristicImpedance F=ReferenceFrequency + [NL=NormalizedElectricalLength] [IC=V<sub>1</sub>, I<sub>1</sub>, V<sub>2</sub>, I<sub>2</sub>]

### SPICE3Form

Thame  $n_1 n_2 n_3 n_4$  [ModelName ] ZO=CharacteristicImpedance TD=TimeDelay [ $IC=V_1, I_1, V_2, I_2$ ]

Tname  $n_1 n_2 n_3 n_4$  [ModelName] ZO=CharacteristicImpedance+ F=ReferenceFrequency + [NL=NormalizedElectricalLength] [IC= $V_1, I_1, V_2, I_2$ ]

#### **PSpiceForm**

Thame  $n_1 n_2 n_3 n_4 ZO = CharacteristicImpedance TD = TimeDelay$ 

Tname  $n_1 n_2 n_3 n_4$  Z0=CharacteristicImpedance +F=Frequency [NL=NormalizedElectricalLength]

- $n_1$  positive node at port 1.
- $n_2$  negative node at port 1.
- $n_3$  positive node at port 2.
- $n_4$  negative node at port 2.

#### ModelName is the model name.

- Z0 is the characteristic impedance. (Z-zero) (Units:  $\Omega$ ; Required; Symbol:  $Z_0$ ; Default: none)
- TD transmission line delay. (Units: s; Either TD or F Required; Symbol:  $T_D$ ; Default: none)
- F reference frequency. (Units: Hz; Either TD or F Required; Symbol: F; Default: none)

- NL normalized electrical length. Normalization is with respect to the wavelength in free space at the reference frequency F. (Units: none; Optional; Symbol: L<sub>NOBMALIZED</sub>; Default: 0.25)
- IC is the optional initial condition specification using  $IC = V_1, I_1, V_2, I_2$  is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired starting from other than the quiescent operating point. Specification of the transient initial conditions using

the .IC statement (see page 66) is preferred and is more convenient.

Example

T1 1 0 2 0 Z0=50 TD=10NS TLONG 1 0 2 0 Z0=50 F=1G NL=10 TLONG 1 0 2 0 Z0=50 F=1G

#### Note

- 1. The length of the line may be expressed in either of two forms. The transmission delay, *TD*, may be specified directly (as TD=10ns, for example). Alternatively, a frequency F may be given, together with NL, the normalized electrical length of the transmission line with respect to the wavelength in the line at the frequency F. If a frequency is specified but NL is omitted, 0.25 is assumed (that is, the frequency is assumed to be the quarter-wave frequency). Note that although both forms for expressing the line length are indicated as optional, one of the two must be specified.
- 2. Note that only 3 distinct nodes should be specified as this element describes a single propagating mode. With four distinct nodes specified, two propagating modes may exist on the actual line. If there are four distinct nodes then two lines are required.
- 3. The transmission line T element is modeled as a bidirectional ideal delay element. The maximum time step in SPICE is limited to half of the time delay along the line. Thus short transmission lines can result in many time steps in a transient analysis. Unnecessary short transmission lines should be avoided.

Model Type

URC

### URC Model

Lossy RC Transmission Line Model



Figure 7.68: URC — lossy RC transmission line model: (a) linear RC transmission line model; (b) nonlinear transmission line model.

### Transmission Line

### Form

.MODEL ModelName URC( [ [keyword = value] ... ] )

#### Example

.MODEL LONGLINE URC( )

### Table 7.13: URC model parameters.

Name	Description		Units	Default
K	Propagation Constant	-		2.0
FMAX	Maximum Frequency of interest	F	Ηz	1.0G
RPERL	Resistance per unit length $(I_{S,PE})$	RL) Ω	Ω/m	1000
CPERL	Capacitance per unit length $(I_{S,PE})$	<sub>RL</sub> ) F	/m	1.0E-15
ISPERL	Saturation current per unit length $(I_{S,PE})$	<sub>RL</sub> ) A	∖/m	
RSPERL	Diode Resistance per unit length $(I_{S,PE})$	RL) Ω	2/m	0

The URC model was originally proposed by Gertzberrg [?] In this model a transmission line is represented by the cascade of a number of transmission line segments each of which is modeled by an RC or R-Diode subcircuit. The lengths of the line segments increases in a geometric progression towards the middle of the line. The number of line segments is

$$N = (7.533)$$

and the length of the ith line segment is

$$l_i = \tag{7.534}$$

If ISPERL is not specified then a linear transmission line is modeled, see figure 7.68, with

$$R_i = R_{\text{PERL}} l_i \tag{7.535}$$

$$C_i = C_{\text{PERL}} l_i \tag{7.536}$$

If ISPERL is not then a diode loaded nonlinear transmission line is modeled, see figure 7.68, with

$$R_i = R_{\text{PERL}} l_i \tag{7.537}$$

$$R_{S,i} = R_{S,\text{PERL}}l_i \tag{7.538}$$

$$C_{i} = C_{J,i} \left( 1 - \frac{\phi}{V_{J,i}} \right)^{-\frac{1}{2}}$$
(7.539)

$$I_{S} = I_{S,i} \left( e^{\frac{V_{J,i}}{V_{\text{TH}}}} - 1 \right)$$
(7.540)

where the zero-bias capacitance of the ith diode is

$$C_{J,i} = C_{\text{PERL}}l_i \tag{7.541}$$

its reverse saturation current is

$$I_{S,i} = I_{S,\text{PERL}} \tag{7.542}$$

# Universal Element

??

The U element is a universal element for extending the number of elements that SPICE can handle. The element is determined by the model type. In some cases model parameters indicate further refinement.

Since the SPICE U element is used to specify many different kinds of physical elements there is no common form for it. Each physical element is distinguished by the type of the model it refers to. The format and description of each element is given in the model description as indicated in the following table. The index is used in this manual to uniquely identify the various elements. *Model Type* 

Model	Index	Description	Page
STRUC	STRUC	Geometric coupled, lossy planar transmission line	??
U	U311	Geometric coupled planar transmission line (up to 5 lines)	??
		Identifying Model Parameters: LEVEL=3 EVEL=1 PVEL=1	
U	U312	Geometric coaxial cable	??
		Identifying Model Parameters: LEVEL=3 EVEL=1 PVEL=2	
U	32	General transmission line (up to 5 lines) defined by precomputed	??
		parameters.	
		Identifying Model Parameters: LEVEL=3 EVEL=2	
U	U34	General transmission line (up to 5 lines) defined by measurements.	??
		Identifying Model Parameters: LEVEL=3 EVEL=3	
U	U4	Digital output element	??
		Identifying Model Parameter: LEVEL=4	
U	U5	Digital input element	??
		Identifying Model Parameter: LEVEL=5	
N. T. 1. 1	TNT 1		
Model	Index	Description	Page
UDLY	UDLY	Delay Line	??
UEFF	UEFF	Edge-Triggered Flip-Flop	??
UGATE	UGATE	Standard Gate Model Form	??
UGFF	UGFF	Gated Flip-Flop	??
UIO	UIO	IO Model	??
URC	URC	Lossy RC transmission line	243
USUHD	USUHD	Setup and Hold Checker	??
UTGATE	UTGATE	Tri-State Gate	??

Note

UWDTH

UWDTH

Pulse-Width Checker

1. One of the problems with SPICE is that the first letter of an element's name is used to determine the type of an element. One consequence of this is that there can only be 26 elements — one for each letter of the alphabet. SPICE2G6The original version of SPICE from which all subsequent versions of SPICE have been developed had less than 26 elements and so this was not a problem. With the addition of new element types several of the originally unised letters were used and a universal element, the U element, introduced to handle even more. The U element is used to represent many different type of elements such as lossy transmission lines and digital devices. All of the U elements refer to models and the model name, and sometimes model parameters, used to indicate the actual element referred to.

# U





Figure 7.69: V — Independent voltage source.

### Form

V

 $\begin{array}{l} \texttt{Vname } N_{+} \ N_{-} \ \left[ \ [DC] \ [DCvalue] \\ \texttt{+} \ [\texttt{AC} \ [ACmagnitude \ [ACphase] \ ] \ ] \\ \texttt{+} \ [\texttt{DISTOF1} \ [F1Magnitude \ [F1Phase] \ ] \ ] \texttt{+} \ [\texttt{DISTOF2} \ [F2Magnitude \ [F2Phase] \ ] \\ \end{bmatrix} \\ \end{array}$ 

# SPICE3Form

Vname N<sub>+</sub> N<sub>-</sub> [ [DC] [DCvalue] + [AC [ACmagnitude [ACphase] ] ] + [TransientSpecification ] + [DISTOF1 [F1Magnitude [F1Phase] ] ] + [DISTOF2 [F2Magnitude [F2Phase] ] ]

PSPICEForm

### Example

VBIAS 1 0 5.0 VCLOCK 20 5 PULSE(0 5 1N 2N 1.5N 21.9N 5N 20N) VSSIGNAL AC 1U 90

 $N_+$  is the positive voltage source node.  $N_{-}$  is the negative voltage source node. DC is the optional keyword for the DC value of the source. DCvalue is the DC voltage value of the source. (Units: V; Optional; Default: 0; Symbol:  $V_{DC}$ ) AC is the keyword for the AC value of the source. ACmagnitude is the AC magnitude of the source used during AC analysis. That is, it is the peak AC voltage so that the AC signal is AC magnitude  $\sin(\omega t + AC)$  phase). AC magnitude is ignored for other types of analyses. (Units: V; Optional; Default: 1; Symbol:  $V_{AC}$ ) ACphase is the ac phase of the source. It is used only in AC analysis. (Units: Degrees; Optional; Default: 0; Symbol:  $\phi_{AC}$ ) DISTOF1 is the distortion keyword for distortion component 1 which has frequency F1. (see the description of the .DISTO statement on page 58). F1magnitude is the magnitude of the distortion component at F1. See .DISTOF1 keyword above. (Units: V; Optional; Default: 1; Symbol:  $V_{F1}$ ) F1phase is the phase of the distortion component at F1. See .DISTOF1 keyword above. (Units: Degrees; Optional; Default: 0; Symbol:  $\phi_{F1}$ ) DISTOF2 is the distortion keyword for distortion component 2 which has frequency F2. (see the description of the .DISTO statement on page 58). F2magnitude is the magnitude of the distortion component at F2. See .DISTOF2 keyword above. (Units: V; Optional; Default: 1; Symbol:  $V_{F2}$ ) F2phase is the phase of the distortion component at F2. See .DISTOF2 keyword above. (Units: Degrees; Optional; Default: 0; Symbol:  $\phi_{F2}$ ) SNR is the input signal-to-noise ratio keyword. SOMEVERSIONSOFSPICE Input VoltageSNR is the value of the signal-to-noise ratio at the input. (Units: None; Optional; Default: use thermal noise of  $R_S$ ; Symbol: SNR<sub>I</sub>) SOMEVERSION-SOFSPICE RS is the source resistance keyword. SOMEVERSIONSOFSPICE SourceResistanceValue is the value of the source resistance. (Units: Ohms; Optional; Default:  $50\Omega$ ; Symbol:  $R_S$ ) Note: if port 1 is specified then the resistance specified for the port takes precedence. **SOMEVERSIONSOFSPICE** RL is the source resistance keyword. SOMEVERSIONSOFSPICE LoadResistanceValue is the value of the load resistance. (Units: Ohms; Optional; Default: 50 $\Omega$ ; Symbol:  $R_L$ ) Note: if port 2 is specified then the resistance specified for the port takes precedence. **SOMEVERSIONSOFSPICE** 

TransientSpecification is the optional transient specification described more fully below.

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- 1. The independent voltage source has three different sets of parameters to describe the source for DC analysis (see .DC on page 55), AC analysis (see .AC on page 53), and transient analysis (see .TRAN on page 109). The DC value of the source is used during bias point evaluation and DC analysis is *DCValue*. It is also the constant value of the voltage source if no *TransientSpecification* is supplied. It may also be used in conjunction with the PWL transient specification if a time zero value is not provided as part of the transient specification. The AC specification, indicated by the keyword AC is independent of the DC parameters and the *Transient Specification*.
- 2. See the .NOISE statement description for a discussion of how SNR<sub>I</sub>  $R_S$ ,  $R_L$  are used in noise calculations.
- 3. The original documentation distributed with SPICE2G6 and SPICE3 incorrectly stated that if a *TransientSpecification* was supplied then the time-zero transient voltage was used in DC analysis and in determiniong the operating point.

### **Transient Specification**

Five transient specification forms are supported: pulse (PULSE), exponential (EXP), sinusoidal (SIN), piece-wise linear (PWL), and single-frequency FM (SFFM). The default values of some of the parameters of these transient specifications include TSTEP which is the printing increment and TSTOP which is the final time (see the .TRAN statement on page 109 for further explanation of these quantities). In the following t is the transient analysis time.

# Exponential:

### Form

EXP( $V_1$	$V_2 \hspace{.1in} [T_{D1} \hspace{.1in}] \hspace{.1in} [ au_1 \hspace{.1in}] \hspace{.1in} [T_{D2} \hspace{.1in}] \hspace{.1in} [ au_2 \hspace{.1in}]$ )		
Name	Description	Units	Default
$V_1$	initial voltage	А	REQUIRED
$V_2$	pulsed voltage	А	REQUIRED
$T_{D1}$	rise delay time	s	0.0
$ au_1$	rise time constant	S	TSTEP
$T_{D2}$	fall delay time	S	$T_{D1} +$
			TSTEP
$ au_2$	fall time constant	S	TSTEP

The exponential transient is a single-shot event specifying two exponentials. The voltage is  $V_1$  for the first  $T_{D1}$  seconds at which it begins increasing exponentially towards  $V_2$  with a time constant of  $\tau_1$  seconds. At time  $T_{D2}$  the voltage exponentially decays towards  $V_1$  with a time constant of  $\tau_2$ . That is,

$$v = \begin{cases} V_1 & t \le T_{D1} \\ V_1 + (V_2 - V_1)(1 - e^{(-(t - T_{D1})/\tau_1)}) & T_{D1} < t \le T_{D2} \\ V_1 + (V_2 - V_1)(1 - e^{(-(t - T_{D1})/\tau_1)}) + (V_1 - V_2)(1 - e^{(-(t - T_{D2})/\tau_2)}) & t > T_{D2} \end{cases}$$
(7.543)

### Single-Frequency FM:

Form

SFFM(  $V_O~V_A~F_C~\mu~F_S$  )

Name	Description	Units	Default
$V_O$	offset voltage	А	
$V_A$	peak amplitude of AC voltage	А	
$F_C$	carrier frequency	Hz	1/TSTOP
$\mu$	modulation index	-	0
$F_S$	signal frequency	Hz	1/TSTOP

The single frequency frequency modulated transient response is described by

$$v = V_O + V_A \sin(2\pi F_C t + \mu \sin(2\pi F_S t))$$
(7.544)

Pulse:

Form

PULSE( $V_1 \ V_2$	$[T_D]$	$[T_R]$	$[T_F]$	[W]	[T])
--------------------	---------	---------	---------	-----	------

Name	Description	Units	Default
$V_1$	initial voltage	А	REQUIRED
$V_2$	pulsed voltage	А	REQUIRED
$T_D$	delay time	S	0.0
$T_R$	rise time	S	TSTEP
$T_F$	fall time	S	TSTEP
W	pulse width	S	TSTOP
Т	period	S	TSTOP

The pulse transient waveform is defined by

$$v = \begin{cases} V_1 & t \leq T_D \\ V_1 + \frac{t'}{T_R} (V_2 - V_1) & 0 < t' \leq T_R \\ V_2 & T_R < t' < (T_R + W) \\ V_2 - \frac{t' - W}{T_F} (V_1 - V_2) & (T_R + W) < t' < (T_R + W + T_F) \\ V_1 & (T_R + W + T_F) < t' < T \end{cases}$$
(7.545)

where

$$t' = t - T_D - (n-1)T \tag{7.546}$$

and t is the voltage analysis time and n is the cycle index. The effect of this is that after an initial time delay  $T_D$  the transient waveform repeats itself every cycle. **Piece-Wise Linear:** 

Form

PWL( 
$$T_1$$
  $V_1$   $[T_2$   $V_2$  ...  $T_i$   $V_i$  ...  $T_N$   $V_N$  ] )



Figure 7.70: Voltage source exponential (EXP) waveform for EXP(0.1 0.8 1 0.35 2 1)



Figure 7.71: Voltage source single frequency frequency modulation (SFFM) waveform for SFFM(0.2 0.7 4 0.9 1)

Each pair of values  $(T_i, V_i)$  specifies that the value of the source is  $V_i$  at time  $= T_i$ . At times between  $T_i$  and  $T_{i+1}$  the values are linearly interpolated. If  $T_1 > 0$  then the voltage is constant at *DCValue* (specified on the element line) until time  $T_1$ .

$$v = \begin{cases} DCvalue & t < T_1 \\ V_i & t = T_i \\ V_{i+1} & t = T_{i+1} \\ V_i + \left(\frac{t - T_i}{T_{i+1} - T_i}\right) (V_{i+1} - V_i) & T_i < t \le T_{i+1} \\ V_N & t > T_N \end{cases}$$
(7.547)

### Sinusoidal:

Form

$$SIN(V_O V_A \ [F] \ [T_D] \ [\theta])$$

**PSPICE**Form

$$SIN(V_O V_A \ [F \ ] \ [T_D \ ] \ [\theta \ \phi \ ]$$
 )

PSPICEForm

 $SIN(V_O V_A [F] [T_D] [\theta \phi])$ 

Name	Description	Units	Default
$V_O$	voltage offset	А	REQUIRED
$V_A$	voltage amplitude	А	REQUIRED
F	frequency	Hz	1/TSTOP
$T_D$	time delay	S	0
Θ	damping factor	1/s	0
$\phi$	phase	degree	0

The sinusoidal transient waveform is defined by

$$v = \begin{cases} V_0 & t \le T_D \\ V_0 + V_1 e^{-[(t - T_D)\Theta]} \sin 2\pi [F(t - T_D) + \phi/360] & t > T_D \end{cases}$$
(7.548)

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Figure 7.72: Voltage source transient pulse (PULSE) waveform for PULSE(0.3 1.8 1 2.5 0.3 1 0.7)



Figure 7.73: Voltage source transient piece-wise linear (PWL) waveform for PWL(1 0.25 1 1 2 0.5  $\dots$  3 0.5 4 1  $\dots$  4.5 1.25  $\dots$ ) with DCValue = 0.25.



Figure 7.74: Voltage source transient sine (SIN) waveform for SIN(0.1 0.8 2 1 0.3 ).



Figure 7.75: W — current controlled switch.

#### Form

W

Wname  $N_1 N_2$  VoltageSourceName ModelName [ON] [OFF]

#### **PSpiceForm**

 $\texttt{W}name \ N_1 \ N_2 \ VoltageSourceName \ ModelName$ 

- $N_+$  is the positive node of the switch.
- $N_{-}$  is the negative node of the switch.

VoltageSourceName is the name of the voltage source the current through which is the controlling current. The voltage source must be a V element.

- ON is the optional initial condition. It is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired starting from other than the quiescent operating point. It is also the initial condition on the device for DC analysis.
- **DFF** is the optional initial condition. If specified the DC operating point is calculated with the terminal voltages set to zero. Once convergence is obtained, the program continues to iterate to obtain the exact value of the terminal voltages. The OFF option is used to enforce the solution to correspond to a desired state if the circuit has more than one stable state.

Model Type

#### ISWITCH

### **ISWITCH** Model

Current-Controlled Switch Model

The current-controlled switch model is supported by both SPICE3 and PSPICE. However the model keywords differ slightly.



### Figure 7.76: ISWITCH — current controlled switch model.

Spice3 keywords:

Name	Description	Units	Default
IT	threshold current (I <sub>ON</sub> )	А	0.0
IH	hysteresis current $(I_{OFF})$	А	0.0
RON	on resistance (R <sub>ON</sub> )	Ω	1.0
ROFF	off resistance $(R_{OFF})$	Ω	1/GMIN

**PSPICE** keywords:

Name	Description	Units	Default
ION	threshold current (I <sub>ON</sub> )	А	0.0
IOFF	hysteresis current (I <sub>OFF</sub> )	А	0.0
RON	on resistance $(R_{ON})$	Ω	1.0
ROFF	off resistance $(R_{OFF})$	Ω	1/GMIN

Care must be exercised in using the switch. An instantaneous switch is highly nonlinear and will very likely lead to convergence problems. This problem is alleviated in the ISWITCH model by ramping the resistance of the switch from its off value to its on value. For this ramping action to be effective the difference between  $I_{\rm ON}$  and  $I_{\rm OFF}$  must not be too small. Also the values of  $R_{\rm ON}$  and  $R_{\rm OFF}$  should not be extreme. The ration  $R_{\rm ON}/R_{\rm OFF}$  should be be as small as possible.

If  $R_{\rm ON}/R_{\rm OFF}$  is large, e.g.  $R_{\rm ON}/R_{\rm OFF} > 10^{12}$ , then the default error tolerances TRTOL and CHGTOL, specified in a .OPTIONS statement (see page 83) may need to be changed.

TRTOL Change to 1.0 from 7.0 idf there are convergence problems during transient analysis.

CHGTOL If a switch is across a capacitor then CHGTOL should be reduced to  $10^{-16}$  if there are convergence problems during transient analysis.

### Switch Model

The switch is modeled by a current variable resistor R, see figure 7.76. Standard Calculations

$$R_{\rm MEAN} = \sqrt{R_{\rm ON} + R_{\rm OFF}} \tag{7.549}$$

$$R_{\text{RATIO}} = R_{\text{ON}}/R_{\text{OFF}}$$
(7.550)  
$$I_{\text{MEAN}} = \sqrt{I_{\text{ON}} + I_{\text{OFF}}}$$
(7.551)

$$MEAN = \sqrt{I_{\rm ON} + I_{\rm OFF}} \tag{7.551}$$

$$I_{\Delta} = \left(\frac{i - I_{\text{MEAN}}}{I_{\text{ON}} - I_{\text{OFF}}}\right) \tag{7.552}$$

If  $I_{\rm ON} > I_{\rm OFF}$  the switch resistance

$$R = \begin{cases} R_{\rm ON} & i \ge I_{\rm ON} \\ R_{\rm OFF} & i \le I_{\rm OFF} \\ R_{\rm MEAN} R_{\rm RATIO}^{1.5I_{\Delta}} R_{\rm RATIO}^{1.5I_{\Delta}^3} & I_{\rm OFF} < i < I_{\rm ON} \end{cases}$$
(7.553)

If  $I_{\rm ON} < I_{\rm OFF}$  the switch resistance

$$R = \begin{cases} R_{\rm ON} & i \le I_{\rm ON} \\ R_{\rm OFF} & i \ge I_{\rm OFF} \\ R_{\rm MEAN} R_{\rm RATIO}^{1.5I_{\Delta}} R_{\rm RATIO}^{1.5I_{\Delta}^3} & I_{\rm OFF} < i < I_{\rm ON} \end{cases}$$
(7.554)

## Noise Analysis

The current controlled switch noise model accounts for thermal noise generated in the switch resistance. The rms (root-mean-square) values of thermal noise current generators shunting the switch resistance is

$$I_n = \sqrt{4kT/R} \ \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.555}$$

where T is the analysis temperature in kelvin (K), and  $k = 1.3806226 \, 10^{-23} \, \text{J/K}$  is Boltzmanns constant.



Figure 7.77: X — subcircuit call element.

#### Form

Xname  $N_1$  [ $N_2$   $N_3$  ...  $N_N$ ] SubcircuitName

#### PSPICEForm

Xname  $N_1$  [ $N_2$   $N_3$  ...  $N_N$ ] SubcircuitName [PARAMS: [keyword = { Expression } ...] [Keyword = Value ...]]

- $N_1$  is the first node of the subcircuit.
- $N_N$  is the Nth node of the subcircuit.
- SubcircuitName is the name of the subcircuit.
  - PARAMS: indicates that parameters are to be passed to the subcircuit.
  - keyword: is keyword corresponding to the keywords defined in the .SUBCKT statement. (See page 103).
    - value: is numeric value.
  - Expression: is an algebraic expression which evaluates to a numeric value. .SUBCKT statement. (See section ?? on page ??).

#### Example

X1 2 4 17 3 1 MULTI

Subcircuits are incorporated by using the "X" element. The number of nodes of the "X" element must correspond to the number of nodes in the definition of the subcircuit (i.e. is on the .SUBCKT statement (see page 103).

Х

Ζ

Only a few versions of SPICE support this. Form



Figure 7.78: Z — distributed discontinuity.

Zname N1 ... Nn Mname

The Z element defines a subcircuit of L's and C's describing a distributed element. The L and C subcircuit is calculated using field theoretic based models and are optimized for maximum accuracy at 3GHz. In a contrast a quasistatic model is evaluated at DC and its accuracy will degrade as frequencies increase. The upper frequency of validity is selectable by the model parameter N. N is the harmonic of 3 GHz at which the model is valid. The default for N is 5 so that by default the models are valid to a frequency of 15 GHz.

*Mname* is the name of a model which can be one of several types:

ZSTEP Microstrip impedance step

LBEND Microstrip right-angle bend

MBEND Microstrip right-angle bend

TJUNC Microstrip T-junction (three way junction)

XJUNC Microstrip X-junction (four way bend)

Example

Z1 1 5 7 Tjunc1

# LBEND Model

# Microstrip Right-Angle Bend Model



Figure 7.79: LBEND — microstrip right-angle bend model.

Form

.MODEL Mname LBEND [ER=value] H=xvalue W1=xvalue W2=xvalue [N=ivalue]

Keywords:

Name	Description	Units	Default
ER	Permittivity of dielectric layer	-	1.0
Н	Height of dielectric layer	mm	REQUIRED
W1	First line width	mm	REQUIRED
W2	Second line width	mm	required
N	Number of calculated harmonics (0-15)	-	5

Example

.MODEL MB1 LBEND ER=9.8 H=0.635 W1=1.2 W2=3.2

### **MBEND** Model



Figure 7.80: MBEND — microstrip mitered right-angle bend model.

Form

.MODEL Mname MBEND [ER=value] H=xvalue W1=xvalue W2=xvalue [N=ivalue]

Keywords:

Name	Description	Units	Default
ER	Permittivity of dielectric layer	-	1.0
Н	Height of dielectric layer	mm	REQUIRED
W1	First line width	mm	REQUIRED
W2	Second line width	mm	REQUIRED
N	Number of calculated harmonics (0-15)	-	5

Example

.MODEL MB1 MBEND ER=9.8 H=0.635 W1=1.2 W2=3.2

# TJUNC Model

# Microstrip T-Junction Model



Figure 7.81: TJUNC — microstrip T-junction model.

Form

.MODEL Mname TJUNC [ER=value] H=xvalue W1=xvalue W2=xvalue W3=xvalue [S=xvalue] [N=ivalue]

Keywords:

Name	Description	$\mathbf{Units}$	Default
ER	Permittivity of dielectric layer	-	1.0
Н	Height of dielectric layer	mm	REQUIRED
W1	First line width	mm	REQUIRED
W2	Second line width	mm	REQUIRED
WЗ	Third line width	mm	REQUIRED
S	Edge offset of line 3	mm	0
N	Number of calculated harmonics (0-15)	-	5

Example

.MODEL TJ1 TJUNC ER=9.8 H=0.635 W1=1.2 W2=3.2 W3=1.1 W4=1

# XJUNC Model



Figure 7.82: XJUNC — microstrip X-junction.

Form

.MODEL Mname XJUNC [ER=value] H=xvalue W1=xvalue W2=xvalue W3=xvalue W4=xvalue [S=xvalue] [N=ivalue]

Keywords:

Name	Description	Units	Default
ER	Permittivity of dielectric layer	-	1.0
Н	Height of dielectric layer	mm	REQUIRED
W1	First line width	mm	REQUIRED
W2	Second line width	mm	REQUIRED
WЗ	Third line width	mm	REQUIRED
S	Edge offset of line 3	mm	0
N	Number of calculated harmonics (0-15)	-	5

Example

.MODEL TJ1 TJUNC ER=9.8 H=0.635 W1=1.2 W2=3.2 W3=1.1 W4=1

# **ZSTEP** Model



Figure 7.83: ZSTEP — microstrip impedance step model.

Form

.MODEL Mname ZSTEP  $[\texttt{ER}{=}value]$  <code>H=xvalue W1=xvalue W2=xvalue [S=xvalue]</code>  $[\texttt{N}{=}ivalue]$ 

Keywords:

Name	Description	$\mathbf{Units}$	Default
ER	Permittivity of dielectric layer	-	1.0
Н	Height of dielectric layer	mm	required
W1	First line width	mm	required
W2	Second line width	mm	required
S	Displacement (see figure)	mm	0
N	Number of calculated harmonics (0-15)	-	5

Example

.MODEL STEP1 ZSTEP ER=9.8 H=0.635 W1=1.2 W2=3.2





Figure 7.84: Z — GASFET element.

### Form

Zname NDrain NGate NSource ModelName [AREA] [OFF] [IC=VDS, VGS]

### Example

Z1 7 2 3 ZM1 OFF

NDrain is the drain node.

*NGate* is the gate node.

NSource is the source node.

ModelName is the model name.

- **DFF** indicates an (optional) initial condition on the device for **DC** analysis. If specified the **DC** operating point is calculated with the terminal voltages set to zero. Once convergence is obtained, the program continues to iterate to obtain the exact value of the terminal voltages. The OFF option is used to enforce the solution to correspond to a desired state if the circuit has more than one stable state.
- IC is the optional initial condition specification. Using  $IC=V_{DS}$ ,  $V_{GS}$ ,  $V_{BS}$  is intended for use with the UIC option on the .TRAN line, when a transient analysis is desired starting from other than the quiescent operating point. Specification of the transient initial conditions using the .IC statement (see page 66) is preferred and is more convenient.

Model Type

GASFET

## GASFET Model

GaAs MESFET Model

Form

.MODEL ModelName GASFET( [  $[keyword = value] \dots$  ] )



Figure 7.85: Schematic of the SPICE3GASFET model.  $V_{GS}$ ,  $V_{DS}$ , and  $V_{GD}$  are intrinsic gate-source, drainsource and gate-drain voltages between the internal gate, drain, and source terminals designated G, D, and S respectively.

Example

.MODEL GAAS12 GASFET()

Raytheon model

This model is also known as the Statz model and model was developed at Raytheon for the modeling of GaAs MESFETs used in digital circuits. It is based on empirical fits to measured data [23].

The parameters of the GASFET model for PSPICEare given in table 7.14.

### $M\!ESF\!ET$

It is assumed that the model parameters were determined or measured at the nominal temperature  $T_{\rm NOM}$  (default 27°C) specified in the most recent .OPTIONS statement preceeding the .MODEL statement. The physical constants used in the model evaluation are

Table 7.14: SPICE3GASFET model keywords.

### Keywords:

Name	Description	Units	Default	Area
VTO	pinch-off voltage $V_{T0}$ $(T_{C,VT0})$	V	-2.0	
BETA	transconductance parameter $(\beta)$	$A/V^2$	1.0E-4	*
В	doping tail extending parameter (B)	1/V	0.3	*
ALPHA	saturation voltage parameter (alpha)	1/V	2	*
LAMBDA	channel length modulation parameter $(\lambda)$	1/V	0	
RD	drain ohmic resistance $(R_D)$	Ω	0	*
RS	source ohmic resistance $(R_S)$	Ω	0	*
CGS	zero-bias G-S junction capacitance $(C'_{GS})$	F	0	*
CGD	zero-bias G-D junction capacitance $(C_{GD}')$	F	0	*
PB	gate junction potential $(V_{BI})$	V	1	
KF	flicker noise coefficient $(K_F)$	-	0	
AF	flicker noise exponent $(A_F)$	-	1	
FC	coefficient for forward-bias depletion capacitance formula	-	0.5	

k	Boltzman's constant	$1.3806226  10^{-23}  \mathrm{J/K}$
q	electronic charge	$1.6021918  10^{-19} \mathrm{C}$

# Standard Calculations

Absolute temperatures (in kelvins, K) are used. The thermal voltage

$$V_{\rm TH} = \frac{kT_{\rm NOM}}{q}.$$
(7.556)

and the band gap energy at the nominal temperature is

$$E_G(T_{\text{NOM}}) = E_G(0) - 0.000702 \frac{4T_{\text{NOM}}^2}{T_{\text{NOM}} + 1108}.$$
(7.557)

Here  $E_G(0)$  is the parameter EG — the band gap energy at 0 K.

## Temperature Dependence

Temperature effects are incorporated as follows where T and  $T_{\text{NOM}}$  are absolute temperatures in Kelvins (K).

$$\beta(T) = \beta 1.01^{(T_{C,\beta}(T - T_{\text{NOM}}))}$$
(7.558)

$$I_{S}(T) = I_{S}e^{\left(E_{g}(T)\frac{T}{T_{\text{NOM}}} - E_{G}(T)\right)/(nV_{\text{TH}})} \left(\frac{T}{T_{\text{NOM}}}\right)^{(X_{TI}/n)}$$
(7.559)

$$C'_{GS}(T) = C_{GS} \left\{ 1 + M \left[ 0.0004(T - T_{\text{NOM}}) + \left( 1 - \frac{V_{BI}(T)}{V_{BI}} \right) \right] \right\}$$
(7.560)

$$C'_{GD}(T) = C_{GD} \left\{ 1 + M \left[ 0.0004(T - T_{\text{NOM}}) + \left( 1 - \frac{V_{BI}(T)}{V_{BI}} \right) \right] \right\}$$
(7.561)

$$E_G(T) = E_G(0) - 0.000702 \frac{4T_{\text{NOM}}^2}{T_{\text{NOM}} + 1108}$$
(7.562)

$$V_{BI}(T) = V_{BI} \frac{T}{T_{\text{NOM}}} - 3V_{\text{TH}} \ln\left(\frac{T}{T_{\text{NOM}}}\right) + E_G(T_{\text{NOM}}) \frac{T}{T_{\text{NOM}}} - E_G(T)$$
(7.563)

$$V_{T0}(T) = V_{T0} + T_{C,VT0}(T - T_{NOM})$$
(7.564)

$$V_{\rm TH} = \frac{\kappa_I}{q} \tag{7.565}$$

## Parasitic Resistances

The resistive parasities  $R_S$ ,  $R_G$  and  $R_D$  are are calculated from the sheet resistivities  $RS (= R'_S)$ , RG (= $R'_G$ ) and RD (=  $R'_D$ ), and the Area specified on the element line.

$$R_D = R'_D Area \tag{7.566}$$

$$R_G = R'_G Area$$

$$R_S = R'_S Area$$

$$(7.567)$$

$$(7.568)$$

$$R_S = R'_S Area \tag{7.568}$$

The parasitic resistance parameter dependencies are summarized in figure 7.86.

PROCESS PARAMETE	RS	+	GEOMETRY PARAMETERS	$\rightarrow$	DEVICE PARAMETERS
RD	$R'_D$		Area		$R_D = f(Area, R'D)$
RG	$\vec{R_G}$			, ,	$R_G = f(Area, R'G)$
RS	$\overrightarrow{R'_S}$				$R_S = f(Area, R'S)$

Figure 7.86: MOSFET parasitic resistance parameter relationships.

### Leakage Currents

Current flows across the normally reverse biased gate-source and gate-drain junctions. The gate-source leakage current 17 /17

$$I_{GS} = Area \, I_S e^{(V_{GS}/V_{\rm TH} - 1)} \tag{7.569}$$

and the gate-drain leakage current

$$I_{GD} = Area \, I_S e^{(V_{GD}/V_{\rm TH} - 1)} \tag{7.570}$$

The dependencies of the parameters describing the leakage current are summarized in figure 7.87.

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### I/V Characteristics

The current/voltage characteristics are evaluated after first determining the mode (normal:  $V_{DS} \ge 0$  or inverted:  $V_{DS} < 0$ ) and the region (cutoff, linear or saturation) of the current ( $V_{DS}, V_{GS}$ ) operating point.

Normal Mode:  $(V_{DS} \ge 0)$ 

The regions are as follows:

cutoff region: 
$$V_{GS}(t-\tau) < V_{T0}$$
  
linear region:  $V_{GS}(t-\tau) > V_{T0}$  and  $V_{DS} \le 3/\alpha$   
saturation region:  $V_{GS}(t-\tau) > V_{T0}$  and  $V_{DS} > 3/\alpha$ 

Then

$$I_{DS} = \begin{cases} 0 & \text{cutoff region} \\ Area \,\beta \left(1 + \lambda V_{DS}\right) \frac{\left[V_{GS}(t-\tau) - V_{T0}\right]^2}{1 + B\left[V_{GS}(t-\tau) - V_{T0}\right]} \text{Ktanh} & \text{linear and saturation} \\ & \text{regions} \end{cases}$$
(7.571)

where

$$Ktanh = \begin{cases} 1 - \left(1 - V_{DS}\frac{\alpha}{3}\right)^3 & \text{linear region} \\ 1 & \text{saturation regions} \end{cases}$$
(7.572)

is a taylor series approximation to the tanh function. Inverted Mode:  $(V_{DS} < 0)$ 

In the inverted mode the MOSFET I/V characteristics are evaluated as in the normal mode (7.571) but with the drain and source subscripts exchanged.

The relationships of the parameters describing the I/V characteristics of the model are summarized in figure 7.88.

#### Capacitances



Figure 7.87: GASFET leakage current parameter dependencies.

The drain-source capacitance

$$C_{DS} = Area \, C'_{DS} \tag{7.573}$$

The gate-source capacitance

$$C_{GS} = Area \left[ C'_{GS} F_1 F_2 \left( 1 - \frac{V_{\text{new}}}{V_{BI}} \right)^{-\frac{1}{2}} + C'_{GD} F_3 \right]$$
(7.574)

The gate-source capacitance

$$C_{GD} = Area \left[ C'_{GS} F_1 F_3 \left( 1 - \frac{V_{\text{new}}}{V_{BI}} \right)^{-\frac{1}{2}} + C' GD F_2 \right]$$
(7.575)

where

$$F_{1} = \frac{1}{2} \left\{ 1 + \frac{V_{\text{eff}} - V_{T0}}{\sqrt{\left(V_{e} - V_{T0}\right)^{2} + \delta^{2}}} \right\}$$
(7.576)

$$F_{2} = \frac{1}{2} \left\{ 1 + \frac{V_{GS} - V_{GD}}{\sqrt{(V_{GS} - V_{GD})^{2} + \alpha^{-2}}} \right\}$$
(7.577)

$$F_{3} = \frac{1}{2} \left\{ 1 - \frac{V_{GS} - V_{GD}}{\sqrt{(V_{GS} - V_{GD})^{2} + \alpha^{-2}}} \right\}$$
(7.578)

$$V_{\text{eff}} = \frac{1}{2} \left\{ V_{GS} + V_{GD} + \sqrt{\left(V_{GS} - V_{GD}\right)^2 + \alpha^{-2}} \right\}$$
(7.579)

(7.580)

$$V_{\text{new}} = \begin{cases} A_1 & A_1 < V_{\text{MAX}} \\ V_{\text{MAX}} & A_1 \ge V_{\text{MAX}} \end{cases}$$
(7.581)

 $\quad \text{and} \quad$ 

$$A_1 = \frac{1}{2} \left[ V_e + V_{T0} + \sqrt{(V_e + V_{T0})^2 + \delta^2} \right]$$
(7.582)

In the model  $\delta$  and  $V_{\text{MAX}}$  are not settable by the user. Empirically they were determined to be

$$V_{\rm MAX} = 0.5$$
  $delta = 0.2$ 



Figure 7.88: LEVEL 2 (Raytheon model) I/V dependencies.

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### $M\!ESF\!ET$

The capacitance parameter dependencies are summarized in figure 7.89.

### AC Analysis

The AC analysis uses the model of figure  $\ref{eq:constraint}$  with the capacitor values evaluated at the  $\tt DC$  operating point with

$$g_m = \frac{\partial I_{DS}}{\partial V_{GS}} \tag{7.583}$$

and

$$R_{DS} = \frac{\partial I_{DS}}{\partial V_{DS}} \tag{7.584}$$

# Noise Analysis

The MOSFET noise model accounts for thermal noise generated in the parasitic resistances and shot and flicker noise generated in the drain source current generator. The rms (root-mean-square) values of thermal noise current generators shunting the four parasitic resistance  $R_D$ ,  $R_G$  and  $R_S$  are

PROC PARAM	CESS ETEBS	+	GEOMETRY PARAMETERS	$\rightarrow$	DEVICE PARAMETERS
ALPHA	$\frac{\alpha}{\alpha}$		Area		$\{C_{DS} = f(Area, C'_{DS})\}$
CGD	$C'_{GD}$				$\{C_{GD} = f(Area, C'_{GD}, \alpha, \dots, n_{GD}, \alpha)\}$
CGS	$C'_{GS}$				$B, F_C, V_{BI}, V_{T0})\}$
CDS	$C'_{DS}$				$\{C_{GS} = f(Area, C'_{GS}, \alpha, \dots, n_{GS}, \alpha)\}$
VBI	$V_{BI}$				$B, F_C, V_{BI}, V_{T0})\}$
VTO	$V_{T0}$				
М	В				

Figure 7.89: Capacitance dependencies.

$$I_{n,D} = \sqrt{4kT/R_D} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.585}$$

$$I_{n,G} = \sqrt{4kT/R_G} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.586}$$

$$I_{n,S} = \sqrt{4kT/R_S} \, \mathrm{A}/\sqrt{\mathrm{Hz}} \tag{7.587}$$

Shot and flicker noise are modeled by a noise current generator in series with the drain-source current generator. The rms value of this noise generator is

$$I_{n,DS} = \sqrt{I_{\text{SHOT},DS}^2 + I_{\text{FLICKER},DS}^2}$$
(7.588)

$$I_{\text{SHOT},DS} = \sqrt{4kTg_m \frac{2}{3}} \quad \text{A}/\sqrt{\text{Hz}} \text{ A}/\sqrt{\text{Hz}}$$
(7.589)

$$I_{\text{FLICKER},DS} = \sqrt{\frac{K_F I_{DS}^{A_F}}{f}} \quad \text{A}/\sqrt{\text{Hz}}$$
(7.590)

where the transconductance

$$g_m = \frac{\partial I_{DS}}{\partial V_{GS}} \tag{7.591}$$

is evaluated at the DC operating point and f is the analysis frequency.

# Chapter 8

# Examples

# 8.1 Simple Differential Pair

The following circuit determines the dc operating point of a simple differential pair. In addition, the ac small-signal response is computed over the frequency range 1Hz to 100MEGHz.

SIMPLE DIFFERENTIAL PAIR VCC 7 0 12 VEE 8 0 -12 VIN 1 0 AC 1 RS1 1 2 1K RS2 6 0 1K Q1 3 2 4 MOD1 Q2 5 6 4 MOD1 RC1 7 3 10K RC2 7 5 10K RE 4 8 10K .MODEL MOD1 NPN BF=50 VAF=50 IS=1.E-12 RB=100 CJC=.5PF TF=.6NS .AC DEC 10 1 100MEG .END

# 8.2 MOS Output Characteristics

The following file computes the output characteristics of a MOSFET device over the range 0-10V for VDS and 0-5V for VGS.

MOS OUTPUT CHARACTERISTICS VDS 3 0 VGS 2 0 M1 1 2 0 0 MOD1 L=4U W=6U AD=10P AS=10P .MODEL MOD1 NMOS VTO=-2 NSUB=1.0E15 U0=550 \* VIDS MEASURES ID, WE COULD HAVE USED VDS, BUT ID WOULD BE NEGATIVE VIDS 3 1 .DC VDS 0 10 .5 VGS 0 5 1 .END

# 8.3 Simple RTL Inverter

The following file determines the dc transfer curve and the transient pulse response of a simple RTL inverter. The input is a pulse from 0 to 5 Volts with delay, rise, and fall times of 2ns and a pulse width of 30ns. The transient interval is 0 to 100ns, with printing to be done every nanosecond.

SIMPLE RTL INVERTER VCC 4 0 5 VIN 1 0 PULSE 0 5 2NS 2NS 2NS 30NS RB 1 2 10K Q1 3 2 0 Q1 RC 3 4 1K .MODEL Q1 NPN BF 20 RB 100 TF .1NS CJC 2PF .DC VIN 0 5 0.1 .TRAN 1NS 100NS .END

# 8.3. SIMPLE RTL INVERTER

# 8.4 Adder

The following file simulates a four-bit binary adder, using several subcircuits to describe various pieces of the overall circuit.

```
ADDER - 4 BIT ALL-NAND-GATE BINARY ADDER
*** SUBCIRCUIT DEFINITIONS
.SUBCKT NAND 1 2 3 4
   NODES: INPUT(2), OUTPUT, VCC
*
Q1 9 5 1 QMOD
D1CLAMP 0 1 DMOD
Q2 9 5 2 QMOD
D2CLAMP 0 2 DMOD
RB 4 5 4K
R1 4 6 1.6K
Q3 6 9 8 QMOD
R2 8 0 1K
RC 4 7 130
Q4 7 6 10 QMOD
DVBEDROP 10 3 DMOD
Q5 3 8 0 QMOD
.ENDS NAND
.SUBCKT ONEBIT 1 2 3 4 5 6
   NODES: INPUT(2), CARRY-IN, OUTPUT, CARRY-OUT, VCC
*
X1 1 2 7 6 NAND
X2 1 7 8 6 NAND
X3 2 7 9 6 NAND
X4 8 9 10 6 NAND
X5 3 10 11 6 NAND
X6 3 11 12 6 NAND
X7 10 11 13 6 NAND
X8 12 13 4 6 NAND
X9 11 7 5 6 NAND
.ENDS ONEBIT
.SUBCKT TWOBIT 1 2 3 4 5 6 7 8 9
  NODES: INPUT - BITO(2) / BIT1(2), OUTPUT - BITO / BIT1,
*
*
            CARRY-IN, CARRY-OUT, VCC
X1 1 2 7 5 10 9 ONEBIT
X2 3 4 10 6 8 9 ONEBIT
.ENDS TWOBIT
.SUBCKT FOURBIT 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15
*
    NODES: INPUT - BITO(2) / BIT1(2) / BIT2(2) / BIT3(2),
*
            OUTPUT - BITO / BIT1 / BIT2 / BIT3, CARRY-IN, CARRY-OUT,
VCC
X1 1 2 3 4 9 10 13 16 15 TWOBIT
X2 5 6 7 8 11 12 16 14 15 TWOBIT
.ENDS FOURBIT
*** DEFINE NOMINAL CIRCUIT
.MODEL DMOD D
.MODEL QMOD NPN(BF=75 RB=100 CJE=1PF CJC=3PF)
VCC 99 0 DC 5V
VIN1A 1 O PULSE(O 3 O 10NS 10NS
                                  10NS
                                         50NS)
VIN1B 2 0 PULSE(0 3 0 10NS 10NS
                                  20NS 100NS)
VIN2A 3 0 PULSE(0 3 0 10NS 10NS
                                  40NS 200NS)
VIN2B 4 0 PULSE(0 3 0 10NS 10NS
                                 80NS 400NS)
VIN3A 5 0 PULSE(0 3 0 10NS 10NS 160NS 800NS)
```

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## 8.5. OPERATIONAL AMPLIFIER

Descriptions of the basic algorithms of SPICE.

# Bibliography

[1] McCalla

Descriptions of MOSFET models.

- [2] P. Antognetti and G. Massobrio (editors), Semiconductor Device Modeling with SPICE, McGraw-Hill: New York, 1988.
- [3] H. Shichman and D. A. Hodges, "Modeling and simulation of insulated-gate field-effect transistor switching circuits," *IEEE Journal of Solid-State Circuits*, Vol. 3, September 1968, Page 285.
- [4] J. E. Meyer, "MOS models and circuit simulation," RCA Review, Vol 32., 1971.
- [5] D. E. Ward and R. W. Dutton, "A channel-oriented model for MOS transistors capacitances," *IEEE J. Solid-State Circuits*, Vol. 13, 1978.
- [6] S. Y. Oh, D. E. Ward and R. W. Dutton, "Transisent analysis of MOS transistors," *IEEE Trans. Electron Devices*, Vol. 27, No. 8, 1980.
- [7] A. Vladimirescu and S. Liu, The simulation of MOS transistor integrated circuits using SPICE2, University of California, Berkeley, Memorandum No. M80/7, February 1980.
- [8] K. Lee, M. Shur, T. Fjeldly and T. Ytterdal, Semiconductor Device Modeling for VLSI, Prentice Hall: Englewood Cliffs, New Jersey, 1993.
- [9] B. J. Sheu, D.L. Scharfetter, P.-K. Ko, and M.-C. Jeng, "BSIM: Berkeley Short-Channel IGFET model for MOS transistors," *IEEE Journal of Solid-State Circuits*, Vol 22, August 1987, pp. 558-566.
- [10] J. R. Pierret, " A MOS Parameter extraction program for the BSIM model, University of California, Berkeley, Memorandum No. M84/99, November 1984.

Descriptions of MESFET models.

- [11] W. R. Curtice, "A MESFET model for use in the design of GaAs integrated circuits," IEEE Transactions on Microwave Theory and Techniques, Vol. 28, pp. 448-456, 1980.
- [12] W.R. Curtice and M. Ettenberg, "A nonlinear GaAs FET model for use in the design of output circuits for power amplifiers," *IEEE Trans. on Microwave Theory and Tech.*, Vol. MTT-33, Dec. 1985, pp. 1383-1393.
- [13] T. Kacprzak and A. Materka, "Compact dc model of GaAs FET's for large-signal computer calculation," *IEEE Journal of Solid-State Circuits*, Vol. SC-18, April 1983, pp. 211-213.
- [14] S.E. Sussman-Fort, "On the basic algorithms of SPICE with application to microwave circuit simulation," *Presented at Nonlinear CAD and Modeling Workshop*, IEEE International Microwave Symp. 1987
- [15] S.E. Sussman-Fort, S. Narasimhan, and K. Mayaram, "A complete GaAs MESFET computer model for SPICE," *IEEE Trans. Microwave Theory and Tech.*, Vol. MTT-32, April 1984, pp. 471-473.
- [16] S.E. Sussman-Fort, J.C. Hantgan, and F.L. Huang, "A SPICE model for enhancement- and depletionmode GaAs FET's," *IEEE Trans. Microwave Theory Tech.*, Vol. MTT-34, Nov. 1986, pp. 1115-1118.
- [17] J.M. Golio, J.R. Hauser, and P.A. Blakey, "A large-signal GaAs MESFET model implemented on SPICE," *IEEE Circuits and Devices Magazine*, Sep. 1985, pp. 21-30.
- [18] J.M. Golio, P.A. Blakey, and R.O. Grondin, "A general CAD tool for large-signal GaAs MESFET circuit design," *IEEE MTT-S International Microwave Symposium Digest*, June 1985, pp. 417-420.
- [19] Angelov:Zirath
- [20] J.M. Golio, J.R. Hauser and P.A. Blakey "A large-signal GaAs MESFET model implemented on SPICE," *IEEE Circuits and Devices Magazine*, Sept. 1985, pp. 21-30.
- [21] J.M. Golio, P.A. Blakey, and R.O. Grondin, "A general CAD tool for large-signal GaAs MESFET circuit design," *IEEE MTT-S Digest*, 417-420,.
- [22] P.H. Ladbrooke, "Reverse modelling of GaAs MESFETs and HEMTs," GEC Journal of Research, Vol. 6, 1988, pp. 1-9.
- [23] H. Statz, P. Newman, I. .W. Smith, R. A. Pucel and H. A. Haus, "GaAs FET Device and Circuit Simulation in SPICE," *IEEE Transactions on Electron Devices*, Vol. 34, pp 160–169, 1987.
- [24] A. J. McCamant, G. D. McCormack, and D. H. Smith, "An improved GaAs MESFET Model for SPICE," *IEEE Transactions on Microwave Theory and Techniques*, Vol. 38, pp. 822-824, June 1990. Descriptions of transformer model.
- [25] D. C. Jiles and D. L. Atherton, "Theory of ferromagnetic hysteresis," Journal of Magnetism and Magnetic Materials, Vol. 61, 1986. pp. 48
- [26] D. Divekar, "Comments no 'GaAs FET devices and circuit simulation ni SPICE,' IEEE Trans. on Electron Devices, Vol. 34, December 1987, p. 2564.
- [27] I.W. Smith, H. Statz, H.A. Haus, and R.A. Pucel, "On charge nonconservation in FETs," *IEEE Trans.* on Electron Devices, Vol. 34, December 1987, pp.2565-2568.

### BIBLIOGRAPHY

Miscellaneous

- [28] D. Knuth, The Art of Computer programming, Vol. 2.
- [29] S. M. Sze, Physics of Semiconductor Devices, 2nd Edition, John Wiley and Sons: New York, 1981
- [30] S. M. Sze, High-Speed Semiconductor Devices, John Wiley and Sons: New York, 1990.

BIBLIOGRAPHY

## Appendix A

## Error

## A.1 Introduction

SPICE errors can result from errors in syntax, errors in the wiring of the original circuit resulting in the circuit not being solvable, and convergence errors during analysis that prevent continuation of analysis. then we have not specified our circuit as drawn. In this case, we also leave one terminal of the resistor unconnected to anything else and SPICE detects the error and reports it in the output file:

O\*ERROR\*: LESS THAN 2 CONNECTIONS AT NODE 2

In a complex circuit it is always easy to get one node number wrong on one element but leave all of the nodes connected to two or more elements. In this case SPICE might detect no errors. If the output looks 'wrong' for any reason, the first thing to do is to draw your circuit by looking at the SPICE file as written and check that against your intended circuit.

Another important thing to remember about error messages is that SPICE is not very good at drawing attention to them.

More expensive commercial versions of SPICE are much more user friendly but still maintain full SPICE upwards compatibility by reporting all errors in the traditional SPICE way as well. SPICE output files tend to be long and are cryptic looking. Error and Warning messages can be found almost anywhere within them. If an error has occured it may be necessary to examine the entire output file to determine exactly what caused the error. Mainstream commercial versions of SPICE have somewhat better error reporting than less expensive commercial versions and the public domain versions.

In the following we list errors common to most versions of SPICEas they derive from SPICE2G6. Common errors for some of the commercial versions of SPICE are also included. The errors are arranged in alphabetic order. Each commercial version of SPICE supports additional elements that are particular to the particular version but generally are selfexplanatory. For errors messages indicating a particular element the syntax of the element described in the element catalog chapter (chapter 7).

## A.2 List of Errors

at least two numeric values required

Not enough numeric values are provided. See the element form for the element.

cannot use LIST with DEC or OCT sweeps See statement for correct form.

#### conflicting length

With a transmission line element either the time delay TD and the reference frequency F are both specified or the time delay TD and the normalized electrical length NL are both specified. if the parameter pairs are specified then there are two possible electrical lengths. See the input forms of the T element on page 242.

#### conflicting specifications

With an independent current source I or independent voltage sourceV element two or more transient types are specified. See the allowable element line forms on page 168 for the I element and on page 246 for the V element.

#### contrary parameters

See page ?? for description of this element.

#### coupling coefficient out of range.

The coupling coefficient for a K element must be between 0 and 1.

#### digital files option not present

The digital files (registered) option must be purchased separately. SPICE version dependent.

#### ERROR -- ... does not match nodes of ...

Commonly this is because the number of nodes of a subcircuit does not match the number of nodes of a subcircuit call (X element).

#### ERROR: CPU Time limit exceeded

The CPU time specified by the .OPTIONS parameter CPTIME, or its default, has been exceeded.

#### ERROR: less than 2 connections at node nnnn

Every node must have at least two connections or elese a node is left floating and the voltage at the node can not be determined. This may be either because the node is floating and the voltage at the node is indeterminate or else because the numerical techniques used require it.

#### ERROR: model ... referenced by ... is undefined

A model was referenced but the actual model was never specified via a .MODEL statement.

#### ERROR: Node is floating

This is either because this is only one connection between this node or there is no DC path from this node to ground as required in determining the DC voltage at the node.

#### ERROR: subcircuit ... is undefined

A subcircuit was referenced but the actual subcircuit was never specified via a .SUBCKT statement.

#### ERROR: transient analysis iterations

The number of transient iterations specified by the .OPTIONS parameters ITL4 or ITL5, or their defaults, has been exceeded.

#### ERROR: voltage loop

Voltage sources and/or elements such as inductors or transmission lines that are modeled using controlled voltage sources, are arranged in a loop. This results in a modified nodeal admittance matrix that can not be solved.

ERROR: voltage source ... which controls switch ... is undefined A voltage source was referenced but the actual element was never specified.

#### expand: parameter syntax error for ...

Error occurred during subcircuit expansion in handling parameters. With some version of SPICE parameters are supported. Parameters must be in the form Keyword = Value where Value may be a numeric value or an expression. Either the Keyword is missing or is not an alphanumeric quantity, or Value is missing or is neither a numeric quantity nor an expression that evaluates to a numeric quantity. The error is either on the X element line or on the .SUBCKT statement.

Expression evaluation error: function syntax error Error in expression evaluation or input prevents continuation.

Expression evaluation error: syntax error Error in expression evaluation or input prevents continuation.

Expression evaluation error: undefined parameter Error in expression evaluation or input prevents continuation.

Error in expression.

Error in expression evaluation or input prevents continuation.

#### Expression syntax error.

some versions of SPICE support expressions. The expression is syntactically incorrect or other error that prevents evaluation of the expression.

#### extra fields

Extra quantities on element line or statement that were not used.

function syntax error in expression. Error in expression evaluation or input prevents continuation.

incomplete range A range was indicated but is incomplete.

I(node) is not valid To specify currents a voltage source must be indicated. Specifying the current at a node is meaningless.

incorrect number of parameters Not enough parameters specified for this element.

inductor: mutual coupling requires two (or more) inductors A K element must comprise two or more inductors. This element is SPICE version dependent.

inductor part of another CORE device An inductor is specified as a component of two different K elements An inductor can only be part of one K element. This element is SPICE version dependent.

inductor part of another K element An inductor is specified as a component of two different K elements An inductor can only be part of one K element. This element is SPICE version dependent.

inductor part of another mutual coupling device An inductor is specified as a component of two different K elements An inductor can only be part of one K element. This element is SPICE version dependent.

#### inductor part of this K device

A K element contains two inductors of the same name. An inductor can only be specified once in a K element inductor list. This element is SPICE version dependent.

#### invalid .WIDTH card

The parameters on the .WIDTH card are incorrectly specified or a parameter is not supported by this version of SPICE.

#### invalid analysis type

Analysis type specified on a .FOUR .TF .NOISE .SENS .MC .PLOT .PRINT .PROBE statement is incorrect. Supported analysis types include AC, DC, TRAN and NOISE although this list is SPICE version dependent. See the full description of the allowable analysis types for the statement.

#### invalid card

The statement may be spelled incorrectly or this version of SPICE does not recognize this statement.

#### invalid device

The first letter of an element card indicates the particular device being referred to. Not all versions of SPICE support the same set of elements and here an non-supported element is being invoked.

#### invalid device in subcircuit

Generally any element may be used with a subcircuit. (between .SUBCKT and .ENDS. Some versions of SPICE support special elements or forms of elements that can only be used at the top level circuit. See the description of the element.

#### invalid dimension

The degree (dimension or order) of a polynomial must be more than 0 and less than the max polynomial order supported by the current version of SPICE.

#### invalid function

Some commercial versions of SPICE support function evaluations. An unsupported function is being used.

#### invalid increment

Usually caused by specifying an increment of zero on a .DC statement

#### invalid node number in .SUBCKT statement

The invalid node number was specified in .SUBCKT statement. This is usually because the ground node (either 0 or, in some versions of SPICE "GND") was specified in the list of nodes in the .SUBCKT statement.

#### invalid number

Due to a number being of the wrong sign or too small or zero where this is not valid. Possibly an integer was expected and a floating point number was supplied.

## invalid option

The value of the parameter is invalid.

#### invalid outside of .SUBCKT

.ENDS is used out of context and does not terminate a subcircuit.

#### invalid parameter

Invalid parameter on element line. Probably misspelled or not supported by this version of SPICE.

#### invalid parameter in model

Either the parameter is misspelled ot it is not supported by this version of SPICE.

#### invalid port name for transmission line Port name in output list is either missing or invalid.

#### invalid print interval

See the analysis statement for the requirements on specifying the output reporting interval.

invalid run number

A negative number of runs was specified in a Monte Carlo analysis.

#### invalid specification

Error in specifying element. See the form for this element.

## invalid step size

Step size must be positive.

### invalid sweep type

Sweep type not supported by this version of SPICE or sweep type incorrectly specified.

#### invalid value

Due to a value being of the wrong sign or too small or zero where this is not valid. Possibly an integer was expected and a floating point number was supplied.

## last PWL pair incomplete

The piecewise linear characteristic of an I or V element must be specified in time, value pairs.

list of runs No runs were specified in a Monte Carlo analysis

missing .ENDS in .SUBCKT A subcircuit must end with a .ENDS statement. This was missing.

#### missing analysis type

Analysis type must be specified in a .FOUR .TF .NOISE .SENS .MC .PLOT .PRINT .PROBE statement but is missing.

#### missing component value Component value for R L or C element missing

missing control node A control node is missing for an E element.

missing controlling source The name of a controlling voltage source is missing for a **G** element.

missing device or node device or node expected but missing.

missing dimension The degree (dimension or order) of a polynomial not specified. The degree of a polynomial should be specified in the form "POLY(n)" or "POLY n".

missing file name File name expected in a .INCL but missing.

missing frequency Frequency missing on a .FOUR card.

missing gain The gain must be specified for an E or F element.

missing inductor In reading K element line expected to read in the name of an inductor but it was missing. missing INOISE or ONOISE

.NOISE statement and either INOISE or ONOISE parameters required or illegal parameter.

missing model

Model Name expected on element line but was missing

missing model name

Model Name expected on element line but was missing

missing name

Subcircuit name expected on .SUBCKT (or similar) statement but not found.

missing node

A node number expected but not provided. Possibly not enough nodes specified. See the form for this element in the element catalog (chapter 7.

missing node list No nodes are specified.

missing or invalid model name or type Either the model name is missing or it is not a valid type for this element.

missing or invalid value Due to a value not being supplied where it is expected, being of the wrong sign or too small or zero where this is not valid. Possibly an integer was expected and a floating point number was supplied.

missing output variables No output variables specified for a .FOUR .TF .NOISE .SENS .MC .PLOT .PRINT .PROBE statement.

missing parameter Parameter expected but not found.

missing pnr In a .AS statement the port number is missing.

missing polynomial The POLY keyword was specified but no polynomial coefficients were found.

missing run count The number of Monte Carlo runs is incorrectly specified.

missing second port in S(pnr1,pnr2) There must be a second port in a .AS output specification.

missing second node in V(node1,node2) In this syntax two nodes must be specified.

missing seed A random number seed was expected for this element but it was missing

missing source Name of source expected but it was not supplied.

missing subcircuit name Subcircuit name expected on .SUBCKT statement but not found.

missing sweep type Sweep type not specified for .AC analysis.

#### missing transconductance

The transconductance must be specified for a G element.

#### missing transresistance

The transresistance must be specified for an H element.

#### missing value

Value (or expression) expected but not found. Either a non-numeric quantity (i.e. not a number) is in a location where a numeric value value is expected or a quantity is missing. If an expression was specified it was either incorrectly delimited or its evaluation is not supported by this version of SPICE.

#### must be >= 1

An positive integer value was expected upon input but the value was not 1 or more.

#### must be a two terminal device

To specify a current a two terminal device must be indicated. More elements with more than three terminals the edge current cannot be uniquely identified by specifying the nodes.

#### must be a voltage source name

Name of voltage source expected on element line but not supplied A voltage source name must begin with V.

#### must be an inductor

In reading K element line expected to read in the name of an inductor but the name did not begin with 'L'

#### must be I or V

In a .AC, .FOUR .TF .SENS .MC .PLOT .PRINT .PROBE statement. Only I or V can be specified. Something else is in output list. Generally this is because only I or V elements can be swept.

must be independent source (I or V) An element was specified but it was not an I or V element.

#### must be monotonically increasing or decreasing

Quantities in list must be monotonically increasing or decreasing.

must be S The keyword "S" expected.

#### must be V

A list of voltage sources is required but either a numeric value was provided an element other than a voltage source specified. (The voltage sources in list of must begin with V.) In the case of a polynomial specification the number of controlling voltage sources must be equal to the polynomial degree previously specified on the element line. Either not enough voltage sources are specified or a non-voltage source is specified.

name on .ENDS does not match .SUBCKT

An optional name may be included on a .ENDS statement. If specified it must match the name specified on the matching .SUBCKT statement.

#### nesting level exceeded

The number of files that can be included using .INCL is limited. The limit is SPICE version specific but is typically around 5.

#### node's voltage already set

Two attempts have been made to set the initial voltage at a node. The initial value may be specified using either a .NODESET statement or using the initial condition IC parameter on some elements.

not a valid parameter for model type parameter not recognized for this model.

not unique

Some versions of SPICEallow abbreviated forms of statements. The minimum allowable abbreviation must be unique. The abbreviation used in the netlist is not unique and is an abbreviation of two or more statements.

only .AC .DC and .TRAN valid The type of analysis in a Monte Carlo run must be either .DC

, .AC or .TRAN.

only .MODEL valid in subcircuit .MODEL is the only statement allowed within a subcircuit description (between /SUBCKT and .ENDS.

only one .TEMP and .DC TEMP allowed One .TEMP statement and one .DC TEMP statement allowed but not both. This is SPICE version dependent.

#### Parameter syntax error

With some version of SPICE parameters are supported. The "PARAMS:" keyword indicates that parameters are to be specified in the form Keyword = Value where Value may be a numeric value or an expression. Either the Keyword is missing or is not an alphanumeric quantity, or Value is missing or is neither a numeric quantity nor an expression that evaluates to a numeric quantity.

PNR already defined The port number can only be defined once.

PNR missing or invalid The port number was either missing or not correctly specified.

run count The number of Monte Carlo runs is incorrectly specified.

run count must be > 1
The number of Monte Carlo runs is incorrectly specified.

syntax error.

Input is in error. Often due to an non-numeric value in input where a non-numeric value expected or vice-versa.

syntax error in expression. Error in expression evaluation or input prevents continuation.

#### TD or F must be specified

With a transmission line element either the time delay TD or reference frequency F must be specified. See the T element on page 242.

temperature

A 0 K (Kelvin) temperature is not valid. The usual problem is that a 0 Celsius temperature was specified but a temperature specified by a .temp statement must be an absolute temperature (in Kelvin)Q

#### time must be increasing

In specifying the transient behavior of an I or V element times must be increasing.

time must not be negative

In specifying the transient behavior of an I or V element a negative time was specified.

too many coefficients

The number of polynomial coefficients specified exceeds that supported in this version of SPICE.

#### too many inductors

There is a limit on the number of inductors per K element. This limit has been exceeded.

#### too many tolerances

The number of tolerances that may be specified is limited. This limit is SPICE version dependent.

#### TooMany

Too many parameters, values or nodes on element line or .SUBCKT statement.

#### unable to open file

File specified in a .INCL or .LIB does not exist in the current directory or default directories.

#### undefined parameter

An unsupported parameter keyword specified. Either this version of SPICE does not support this parameter for this element or statement or the parameter is misspelled.

#### unknown parameter

A parameter was used on an element line or in a .MODEL statement which was not recognized. Either this version of SPICE does not support this parameter or the parameter is misspelled.

value may not be 0 A non-zero value expected.

voltage source name Name of voltage source expected on element line but not supplied

WIDTH must be 80 or 132 A SPICE supports two output log formats that are either 80 columns or 132 columns wide. A width other than 80 or 132 was specified.

ZO must be specified With a transmission line element the ZO parameter must always be input using the syntax ZO=CharacteristicImpedance.

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